Ref #	Hits	Search Query	DBs	Default Operator	Plurais	Time Stamp
L1	887	(resorcinol near8 (arylate\$1 or polyester\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR .	ON	2006/01/30 10:58
L2	1116	(resorcinol\$1 near8 (arylate\$1 or polyester\$1 or polycarbonate\$1 or polyestercarbonate\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:29
L3	2413	(resorcinol\$1 with (polyester\$1 or polycarbonate\$1 or polyestercarbonate\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:24
L4	8007	(resorcinol\$1 with (isophthalate or terephthalate\$1 or isopherone\$1 or bisphenol\$1 or naphthal\$6))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:52
L5	860	I3 and I4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:13
L6	160162	(exposed or exposure or exposing or irradiat\$6 or light) with (mask\$1 or photomask\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:17
L7	458	l6 and (I3 or I4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:15
L8	1	l6 same (l3 or l4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:15
L9	860271	(resorcinol\$1 or polyester\$1 or polycarbonate\$1 or polyestercarbonate\$1 or isophthalate or terephthalate\$1 or isopherone\$1 or bisphenol\$1 or naphthal\$6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:16
L10	1253	l6 same l9	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:17

						_
L11	1	I5 and I10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:17
L12	162317	(exposed or exposure or exposing or irradiat\$6 or light or uv or ultraviolet) with (mask\$1 or photomask\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:51
L13	4500281	(exposed or exposure or exposing or irradiat\$6 or light or uv or ultraviolet or photosensitive or refractive or refraction)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 11:03
L14	357	I13 same (I3 or I4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR ·	ON	2006/01/30 09:19
L15	36	(soll\$5 with general)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:20
L16	6	(sollx and I13)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:35
L17	49	I6 and I3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:24
L18	50	112 and 13	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:30
L19	733	(resorcinol\$1 near5 (arylate\$1 or polyester\$1 or polycarbonate\$1 or polyestercarbonate\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:30
L20	9	l12 and l19	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:30

L21	1	(sollx and I12)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:35
L22	85	l13 same l1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:42
L23	194	((I2 and I4) or sllx) and (waveguid\$6 or lens\$6 or hologra\$6 or data)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:43
L24	139	((I2 same I4) or sllx) and (waveguid\$6 or lens\$6 or hologra\$6 or data)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:45
L25	21	(sllx) and (waveguid\$6 or lens\$6 or hologra\$6 or data)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:44
L26	0	(sllx) and (waveguid\$6 or lens\$6 or hologra\$6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:45
L27	3	(sllx) and (fries)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:45
L28	55	((I2 same I4) or sllx) and (fries)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:51
L29	521140	(light or uv or ultraviolet) with (expos\$6 or dosag\$6 or irradia\$6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 10:47
L30	4612	(resorcinol\$1 near5 (isophthalate or terephthalate\$1 or isopherone\$1 or bisphenol\$1 or naphthal\$6))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 10:46

			Luc popus	00		2006/04/22 22 53
L31	5421	(resorcinol\$1 near8 (isophthalate or terephthalate\$1 or isopherone\$1 or bisphenol\$1 or naphthal\$6))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:52
L32	1048	I29 and I31	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:53
L33	84	129 and 131 and 12	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 09:53
L34	475	(resorcinol\$1 near5 (isophthalate or terephthalate\$1 or isopherone\$1 or bisphenol\$1 or naphthal\$6 or arylate))	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 10:46
L35	48	(light or uv or ultraviolet) and I34	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 11:02
L36	49	(light or uv or ultraviolet or mask\$1 or photomask\$1) and I34	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 10:58
L37	1	(resorcinol near3 arylate\$1) same (mask or photomask\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 10:59
L38	38	(resorcinol) same (mask or photomask\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 11:02
L39	1238	(polycarbonate) same (mask or photomask\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 11:02
L40	347	(light or uv or ultraviolet) same I39	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 11:02

L41	211640	(exposed or exposure or exposing or irradiat\$6 or light or uv or ultraviolet or photosensitive or refractive or refraction or fries) same (mask\$1 or photomask\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 11:04
L42	347	l40 and l41	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 11:04
L43	9062	(refractive or refraction or fries) same (mask\$1 or photomask\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 11:04
L44	62	l40 and l43	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/30 11:04

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Welcome to STN International! Enter x:x
LOGINID:ssspta1756mja
PASSWORD:
TERMINAL (ENTER 1, 2, 3, OR ?):2
                      Welcome to STN International
                  Web Page URLs for STN Seminar Schedule - N. America
 NEWS
      1
                  "Ask CAS" for self-help around the clock
 NEWS 2
 NEWS 3 DEC 05
                  CASREACT(R) - Over 10 million reactions available
 NEWS 4 DEC 14
                  2006 MeSH terms loaded in MEDLINE/LMEDLINE
 NEWS 5 DEC 14 2006 MeSH terms loaded for MEDLINE file segment of TOXCENTER
 NEWS 6 DEC 14 CA/CAplus to be enhanced with updated IPC codes
 NEWS 7 DEC 21
                  IPC search and display fields enhanced in CA/CAplus with the
                  IPC reform
          DEC 23
 NEWS
      8
                  New IPC8 SEARCH, DISPLAY, and SELECT fields in USPATFULL/
                  USPAT2
 NEWS 9
          JAN 13
                  IPC 8 searching in IFIPAT, IFIUDB, and IFICDB
 NEWS 10
         JAN 13
                  New IPC 8 SEARCH, DISPLAY, and SELECT enhancements added to
                  INPADOC
 NEWS 11
         JAN 17
                  Pre-1988 INPI data added to MARPAT
 NEWS 12
         JAN 17
                  IPC 8 in the WPI family of databases including WPIFV
 NEWS 13
         JAN 30
                  Saved answer limit increased
 NEWS EXPRESS
               JANUARY 03 CURRENT VERSION FOR WINDOWS IS V8.01,
               CURRENT MACINTOSH VERSION IS V6.0c(ENG) AND V6.0Jc(JP),
               AND CURRENT DISCOVER FILE IS DATED 19 DECEMBER 2005.
               V8.0 USERS CAN OBTAIN, THE UPGRADE TO V8.01 AT
               http://download.cas.org/express/v8.0-Discover/
 NEWS HOURS
               STN Operating Hours Plus Help Desk Availability
 NEWS INTER
               General Internet Information
 NEWS LOGIN
               Welcome Banner and News Items
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               Direct Dial and Telecommunication Network Access to STN
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=> file caplus
COST IN U.S. DOLLARS
                                                 SINCE FILE
                                                                 TOTAL
                                                               SESSION
                                                      ENTRY
FULL ESTIMATED COST
                                                       0.21
                                                                  0.21
FILE 'CAPLUS' ENTERED AT 11:23:08 ON 30 JAN 2006
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\$%^STN; HighlightOn= \*\*\*; HighlightOff=\*\*\*

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FILE COVERS 1907 - 30 Jan 2006 VOL 144 ISS 6
                                (20060129/ED).
FILE LAST UPDATED: 29 Jan 2006
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http://www.cas.org/infopolicy.html
=> s resorcinol
         28794 RESORCINOL
           834 RESORCINOLS
L1
         28980 RESORCINOL
                 (RESORCINOL OR RESORCINOLS)
=> s l1 and (uv or ultraviolet)
        475320 UV
           333 UVS
        475436 UV
                 (UV OR UVS)
        206232 ULTRAVIOLET
            11 ULTRAVIOLETS
        206240 ULTRAVIOLET
                 (ULTRAVIOLET OR ULTRAVIOLETS)
        475320 UV
           333 UVS
        475436 UV
                 (UV OR UVS)
        593728 ULTRAVIOLET
                 (ULTRAVIOLET OR UV)
          1449 L1 AND (UV OR ULTRAVIOLET)
L2
=> s l1 and (mask? or photomask?)
        113347 MASK?
         14888 PHOTOMASK?
           200 L1 AND (MASK? OR PHOTOMASK?)
=> s 13 and (arylate or carbonate or polycarbonate or isophorone or isophthalate or terephthalate
           310 ARYLATE
           111 ARYLATES
           395 ARYLATE
                 (ARYLATE OR ARYLATES)
        273281 CARBONATE
         65315 CARBONATES
        305292 CARBONATE
                 (CARBONATE OR CARBONATES)
         45695 POLYCARBONATE
         54169 POLYCARBONATES
         64390 POLYCARBONATE
                 (POLYCARBONATE OR POLYCARBONATES)
          9198 ISOPHORONE
            38 ISOPHORONES
          9207 ISOPHORONE
                 (ISOPHORONE OR ISOPHORONES)
          8578 ISOPHTHALATE
           241 ISOPHTHALATES
          8684 ISOPHTHALATE
                 (ISOPHTHALATE OR ISOPHTHALATES)
         93060 TEREPHTHALATE
          2024 TEREPHTHALATES
         93422 TEREPHTHALATE
                 (TEREPHTHALATE OR TEREPHTHALATES)
         69330 BISPHENOL
          4723 BISPHENOLS
         70727 BISPHENOL
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## 5 L3 AND (ARYLATE OR CARBONATE OR POLYCARBONATE OR ISOPHORONE OR ISOPHTHALATE OR TEREPHTHALATE OR BISPHENOL)

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=> d all 1-5
    ANSWER 1 OF 5 CAPLUS COPYRIGHT 2006 ACS on STN
L4
    2001:717332 CAPLUS
ΑN
    135:257980
DN
    Entered STN: 02 Oct 2001
ED
    Acrylic polymer-based plastisol compositions with good flowability,
TI
     storage stability, and processability
    Oba, Yoichi; Hashimoto, Hitoshi; Tashiro, Toshiya; Iwasa, Takahiro
IN
     Asahi Kagaku Kenkyusho K. K., Japan
PΑ
     Jpn. Kokai Tokkyo Koho, 9 pp.
so
     CODEN: JKXXAF
    Patent
DT
    Japanese
LA
     ICM C08L033-04
IC
     ICS C08K005-101; C08K005-521
CC
     37-6 (Plastics Manufacture and Processing)
     Section cross-reference(s): 38, 76
FAN.CNT 1
                                      APPLICATION NO. DATE
    PATENT NO.
                      KIND DATE
                      ----
     -----
                              -----
                                         -----
                                                               -----
    JP 2001270971
                        A2
                                       JP 2000-85532
                              20011002
                                                             20000327
                              20000327
PRAI JP 2000-85532
CLASS
              CLASS PATENT FAMILY CLASSIFICATION CODES
 PATENT NO.
 -----
 JP 2001270971 ICM
                     C08L033-04
                ICS
                      C08K005-101; C08K005-521
                IPCI
                      C08L0033-04 [ICM,7]; C08K0005-101 [ICS,7]; C08K0005-521
                       [ICS, 7]
AB
    The compns., useful for strippable soldering ***masks*** , spacers for
    membrane keyboards, etc., contain acrylic polymer powders and condensed
    phosphate esters as plasticizers. Thus, 100 parts F 320 (acrylic polymer
    powder) was mixed with 120 parts ***resorcinol*** bis(di-Ph phosphate)
     to give a plastisol showing good film-forming property, storage stability,
     low plasticizer volatilization at .ltoreq.319.degree..
ST
    plastisol acrylic polymer plasticizer condensed phosphate;
       ***resorcinol*** phosphate plasticizer acrylic polymer plastisol
IT
        (condensed phosphates; acrylic polymer-based plastisol compns. with
       good flowability, storage stability, and processability)
IT
     Fatty acids, uses
     RL: MOA (Modifier or additive use); USES (Uses)
        (hydroxy, esters; acrylic polymer-based plastisol compns. with good
       flowability, storage stability, and processability)
IT
    Soldering
          ***masks*** ; acrylic polymer-based plastisol compns. with good
       flowability, storage stability, and processability)
IT
    Electric switches
        (spacers; acrylic polymer-based plastisol compns. with good
       flowability, storage stability, and processability)
IT
               151-13-3, Butyl ricinoleate 26402-31-3, Propylene glycol
    monoricinoleate 67025-99-4, Trimethylolpropane monoricinoleate
    83707-54-4, Sorbitan monoricinoleate
    RL: MOA (Modifier or additive use); USES (Uses)
        (acrylic polymer-based plastisol compns. with good flowability, storage
       stability, and processability)
IT
    80-62-6D, Methyl methacrylate, polymers
                                            9011-14-7, Poly(methyl
    methacrylate) 179241-49-7, F 301 260248-10-0, F 340 299432-92-1, F
    303
    RL: POF (Polymer in formulation); PRP (Properties); TEM (Technical or
    engineered material use); USES (Uses)
        (acrylic polymer-based plastisol compns. with good flowability, storage
       stability, and processability)
    5945-33-5,
                ***Bisphenol***
IT
                                A bis (diphenyl phosphate) 57583-54-7,
      ***Resorcinol***
                        bis(diphenyl phosphate) 93981-32-9, ***Bisphenol***
```

A bis (dicresyl phosphate)

RL: MOA (Modifier or additive use); USES (Uses)

(plasticizer; acrylic polymer-based plastisol compns. with good flowability, storage stability, and processability)

- L4 ANSWER 2 OF 5 CAPLUS COPYRIGHT 2006 ACS on STN
- AN 1998:486456 CAPLUS
- DN 129:183510
- ED Entered STN: 05 Aug 1998
- TI Quantitative separation of zinc traces from cadmium matrixes by solid-phase extraction with polyurethane foam
- AU De Jesus, Djane Santiago; De Carvalho, Marcelo Souza; Costa, Antonio Celso Spinola; Ferreira, Sergio Luis Costa
- CS Centro Federal de Educacao Tecnologica da Bahia, Salvador, Brazil
- SO Talanta (1998), 46(6), 1525-1530
  - CODEN: TLNTA2; ISSN: 0039-9140
- PB Elsevier Science B.V.
- DT Journal
- LA English
- CC 79-4 (Inorganic Analytical Chemistry)
- A system for sepn. of Zn traces from large amts. of Cd is proposed. AΒ based on the solid-phase extn. of the Zn as thiocyanate complexes by the polyurethane foam. The following parameters were studied: effect of pH and of the thiocyanate concn. on the Zn extn., shaking time required for quant. extn., amt. of PU foam necessary for complete extn., conditions for the sepn. of Zn from Cd, influence of other cations and anions on the Zn sorption by PU foam, and required conditions for back extn. of Zn from the Zn traces can be sepd. from large amts. of Cd at pH 3.0 .+-. 0.50, with the range of thiocyanate concn. from 0.15 to 0.20 mol L-1, and the shaking time of 5 min. The back extn. of Zn can be done by shaking it with H2O for 10 min. Ca, Ba, Sr, Mg, Al, Ni and Fe(II) are efficiently sepd. Fe(III), Cu(II) and Co(II) are extd. simultaneously with Zn, but the Fe redn. with ascorbic acid and the use of citrate to \*\*\*mask\*\*\* Cu(II) and Co(II) increase the selectivity of the Zn extn. The anions nitrate, chloride, sulfate, acetate, thiosulfate, tartrate, oxalate, fluoride, citrate, and \*\*\*carbonate\*\*\* do not affect the Zn extn. Phosphate and EDTA must be absent. The method proposed was applied to det. Zn in Cd salts using 4-(2-pyridylazo) - \*\*\*resorcinol\*\*\* (PAR) as a spectrophotometric reagent. The result achieved did not show significant difference in the accuracy and precision (95% confidence level) with those obtained by ICP-AES anal.
- ST zinc sepn cadmium solid phase extn; polyurethane foam zinc sepn cadmium
- IT Polyurethanes, analysis
  - RL: ARU (Analytical role, unclassified); ANST (Analytical study) (quant. sepn. of zinc traces from cadmium matrixes by solid-phase extn. with polyurethane foam)
- IT Extraction
  - (solid-phase; quant. sepn. of zinc traces from cadmium matrixes by solid-phase extn. with polyurethane foam)
- IT 333-20-0, Potassium thiocyanate
  - RL: ARG (Analytical reagent use); ANST (Analytical study); USES (Uses) (in quant. sepn. of zinc traces from cadmium matrixes by solid-phase extn. with polyurethane foam)
- IT 543-90-8, Cadmium acetate 7440-43-9, Cadmium, analysis 10124-36-4, Cadmium sulfate
  - RL: AMX (Analytical matrix); ANST (Analytical study)
    - (quant. sepn. of zinc traces from cadmium matrixes by solid-phase extn. with polyurethane foam)
- IT 7440-66-6, Zinc, analysis
  - RL: ANT (Analyte); PEP (Physical, engineering or chemical process); ANST (Analytical study); PROC (Process)
    - (quant. sepn. of zinc traces from cadmium matrixes by solid-phase extn. with polyurethane foam)
- RE.CNT 24 THERE ARE 24 CITED REFERENCES AVAILABLE FOR THIS RECORD RE
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     ANSWER 3 OF 5 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     1979:549511 CAPLUS
DN
     91:149511
ED
     Entered STN: 12 May 1984
TI
     Improvements in ***masks***
IN
     Wolf, Horst
PA
     Hoechst A.-G., Fed. Rep. Ger.
     S. African, 20 pp.
     CODEN: SFXXAB
DT
     Patent
LA
     English
IC
     G03B027-28
     74-8 (Radiation Chemistry, Photochemistry, and Photographic Processes)
FAN.CNT 1
     PATENT NO.
                       KIND
                               DATE
                                          APPLICATION NO.
     _____
                       ----
                               _____
                                           ______
                                                                  _____
PI ZA 7802739 A 19790530 ZA 1978-2739
DE 2721687 C2 19861120 DE 1977-2721687
NL 7805046 A 19781115 NL 1978-5046
GB 1603359 A 19811125 GB 1978-18659
SE 7805429 A 19781114 SE 1978-5429
PRAI DE 1977-2721687 A 19770513
                                                                19780512
                                19790530 ZA 1978-2739
                                                             19780510
19780511
CLASS
               CLASS PATENT FAMILY CLASSIFICATION CODES
 PATENT NO.
 ------
 ZA 7802739 IC
                       G03B027-28
                IPCI G03B0027-28
 IPCI G03C0005-00; G03F0001-00
     A copying process using a ***mask*** and the prodn. of this
       ***mask*** are discussed. The ***mask*** is produced by imagewise
     exposure under a master of a material composed of polymeric org. carrier
     film, a metallic cover foil, and a light-sensitive layer. The exposed
     light-sensitive layer is developed to yield a pos. or a neg. image.
     Particular contours corresponding to a desired partial area of the image
     produced in this manner are incised into the cover foil, and .gtoreq.1
     partial area of the cover foil enclosed by such an incised line is
     stripped off from the carrier film. Thus, a 0.15 poly(ethylene
       ***terephthalate***  ) support whose surfaces had been treated to render
     them antistatic was laminated with a 0.03 nm layer of Al with an acrylic
     resin adhesive, and a light-sensitive layer composed of MeOAc 70, EtOH 30,
     H2O 5, 1-diazo-2-naphthol-4-sulfonic acid 0.6, ***resorcinol***
     glycol Me phthalate 0.6, ethylene glycol mono-Me ether 5, and cellulose
     acetate 5 parts was coated thereon. This layer was then exposed and
     developed by applying a 10% aq. monoethanolamine soln. The image was then
     further processed by incise and stripping to give the required
       ***mask***
       ***photomask***
ST
                        prodn photosensitive material
       ***Photomasks***
IT
        (photosensitive material and process for fabrication of)
IT
     Phenolic resins, uses and miscellaneous
     RL: USES (Uses)
```

```
(photosensitive materials contg., for ***photomasks***
                                                                 prodn.)
IT
     7440-31-5, uses and miscellaneous
     RL: USES (Uses)
        (photosensitive material contg. layer of, for ***photomask***
        prodn.)
IT
     19778-85-9
                  65846-95-9
     RL: USES (Uses)
        (photosensitive material contg., for ***photomask***
                                                                 prodn.)
IT
     7440-50-8, uses and miscellaneous
     RL: USES (Uses)
        (photosensitive materials contg. layer of, for
                                                         ***photomask***
        prodn.)
IT
     108-46-3, uses and miscellaneous 109-86-4 131-56-6
                                                             548-62-9
     1096 - 84 - 0 \qquad 1143 - 72 - 2 \qquad 2481 - 94 - 9 \qquad 6192 - 52 - 5 \qquad 9004 - 35 - 7 \qquad 16501 - 01 - 2
     20541-54-2
                 71510-01-5
     RL: USES (Uses)
        (photosensitive materials contg., for ***photomasks***
                                                                 prodn.)
IT
     7429-90-5, uses and miscellaneous
     RL: USES (Uses)
        (photosensitive materials with layers of, for ***photomasks***
        prodn.)
     ANSWER 4 OF 5 CAPLUS COPYRIGHT 2006 ACS on STN
L4
     1972:60745 CAPLUS
AN
DN
     76:60745
     Entered STN: 12 May 1984
ED
TI
     Vulcanizable compositions
IN
     Corish, Patrick J.; Kirkham, Malcolm C.
PA
     Dunlop Holdings Ltd.
SO
     Ger. Offen., 11 pp.
     CODEN: GWXXBX
DT
     Patent
LA
     German
IC
     C08C
     38 (Elastomers, Including Natural Rubber)
CC
FAN.CNT 1
                       KIND
     PATENT NO.
                               DATE
                                          APPLICATION NO.
                                                                 DATE
     -----
                                                                 -----
                        ____
                               -----
                                           -----
PI DE 2114745 A 19711014
GB 1349740 A 19740410
FR 2085075 A5 19711217
PRAI GB 1970-14735 A 19700326
GB 1970-49903 A 19701021
GB 1970-49904 A 19701021
                              19711014 DE 1971-2114745 19710326
                                                                19700326
19710324
                              19740410 GB 1970-14735
                                         FR 1971-10361
CLASS
             CLASS PATENT FAMILY CLASSIFICATION CODES
 PATENT NO.
 -----
                ----
 DE 2114745 IC
                      C08C
 IPCI C08C0009-00
                IPCI C08C0009-00; C08C0011-00; B29H0005-00
     The title compns., useful in the tire manuf., contain natural rubber and
       ***masked***
                     diisocyanate, e.g. p-nitrosophenol-methylenedi-p-phenylene
     diisocyanate adduct (I), ***bisphenol*** -methylenedi-p-phenylene
     diisocyanate adduct (II), and (or) ***resorcinol***
     -methylenedi-p-phenylene diisocyanate adduct, have long scorch times and
     favorable mech. properties after crosslinking. Thus, a mixt. of natural
     rubber 100.0, HAF carbon black 50, naphthenic oil (Edilex 27) 5.0,
     CaO-wax-oil dispersion (Calaxol W 3) 5.0, (Et2NCS2)2Zn 1.0, I 4.0, and II
     (Hylene MP) 8.75 parts had Mooney scorch time 7.0 min at 120.deg., and
     tensile strength 205 kg/cm2, elongation at break 395%, hardness 63.deg.BS,
     resilience 56% at 50.deg., and 300% modulus 154 kg/cm2 after hardening 50
     min at 150.deg..
ST
     rubber natural isocyanate crosslinked
IT
     Vulcanizing agents
        (blocked isocyanates, for rubber)
IT
     Rubber, natural, uses and miscellaneous
        (vulcanizing agents for, blocked isocyanates as)
     28266-21-9
IT
                 35385-18-3 35385-19-4
     RL: USES (Uses)
        (vulcanizing agents for rubber)
```

```
ED
     Entered STN: 22 Apr 2001
     Complexometric determination of multicationic drug mixtures
TI
ΑU
     Koval'chuk, T. V.; Kogan, O. M.
     Farmatsevtichnii Zhurnal (Kiev) (1965), 20(2), 29-35
SO
     CODEN: FRZKAP; ISSN: 0367-3057
DT
     Journal
LA
     Ukrainian
     30 (Pharmaceuticals)
CC
     Procedures are described for (1) the detn. of ZnSO4 and Al alum in a drug
AB
     contg. both salts based on the titrn. of ZnSO4 with 0.05M Trilon B using
     Xylenol Orange as indicator, after ***masking***
                                                          the Al3+ ions with
     NaF; (2) the detn. of ZnSO4, Al alum, and CuSO4 in a drug, consisting of
     the titrn. of the excess of a standardized Trilon B soln. with
     standardized ZnSO4 soln. with Chromogene Black as indicator, after
     screening Al3+ ions with NaF and Cu++ ions with a mixt. of NH4OAc and
     Na2S2O3; (3) the detn. of ZnSO4 and Pb(OAc)2 in a drug, based on
     trilonometric titrn. of the former according to a method described in
     Russian Pharmacopeia IX. Pb(OAc)2 was estd. after sepn. of ZnSO4, by the
     titrn. with Trilon B; (4) the detn. of CaCO3, Fe++ lactate, and Ca++
     gluconate in a drug, based on the trilonometric titrn. of the Ca salts
     after screening Fe++ ions with tartaric acid; (5) the detn. of CaCO3 MgO,
     and BiONO3 in a drug also contq. NaHCO3, based on the trilonometric titrn.
     of Ca++ and Bi3+ ions with murexide and Xylenol Orange, resp., as
     indicators. The joint detn. of the 3 components was carried out by the
     titrn. with a Trilon B soln. with Chromogene Blue as indicator; the MgO
     content was computed from the difference between the results of this and
     the two preceding titrns.; (6) the detn. of HgO and BiONO3 in an ointment
     also contg.
                   ***resorcinol***
                                     and petrolatum, based on a joint
     trilonometric estn. of both components using 0.05M Trilon B soln. in
     excess, Chromogene Black indicator and standardized ZnSO4 soln. as a
     titrant followed by a sep. estn. of BiONO3 by the titrn. of an aliquot
     with the Trilon B soln. using Pyrocatechol Violet as indicator; and (7)
     the detn. of BiONO3 and Dermatol in a powder contq. also anesthesin and
     belladonna ext., based on different soly. of the components in alk. soln.
     Exptl. details are given for each detn.
IT
     Belladonna and (or) Atropa
        (Dermatol detn. in prepn. contg.)
     94-09-7, Benzoic acid, p-amino-, ethyl ester
IT
        (Dermatol detn. in prepn. contg.)
     301-04-2, Lead acetate, Pb(OAc)2
                                       5673-35-8, Gallic acid, bismuth salt
IT
     21908-53-2, Mercury oxide, HqO
        (detn. in pharmaceuticals)
IT
     144-55-8, Sodium
                       ***carbonate*** , NaHCO3
                                                   299-28-5, Calcium gluconate
                       ***carbonate***
                                             1309-48-4, Magnesium oxide
     471-34-1, Calcium
     1707-15-9, Isonicotinic acid, 2,2'-methylenedihydrazide
                                                               2779-55-7,
     Phthalaldehydic acid, 5,6-dimethoxy-, isonicotinoylhydrazone
                                                                    3688-05-9,
     Isonicotinic acid, [3-(2-furyl)-1-methylallylidene]hydrazide
                    7733-02-0, Zinc sulfate 7758-98-7, Copper sulfate
     Iron lactate
     10043-01-3, Aluminum sulfate
                                    66120-60-3, Bismuth nitrate oxide
        (detn. of, in pharmaceuticals)
=> d his
     (FILE 'HOME' ENTERED AT 11:23:01 ON 30 JAN 2006)
     FILE 'CAPLUS' ENTERED AT 11:23:08 ON 30 JAN 2006
L1
          28980 S RESORCINOL
L2
           1449 S L1 AND (UV OR ULTRAVIOLET)
L3
            200 S L1 AND (MASK? OR PHOTOMASK?)
L4
              5 S L3 AND (ARYLATE OR CARBONATE OR POLYCARBONATE OR ISOPHORONE O
=> s 12 and (arylate or carbonate or polycarbonate or isophorone or isophthalate or terephthalate
           310 ARYLATE
           111 ARYLATES
           395 ARYLATE
                 (ARYLATE OR ARYLATES)
        273281 CARBONATE
```

ANSWER 5 OF 5 CAPLUS COPYRIGHT 2006 ACS on STN

L4 ΔN

DN

1966:43010 CAPLUS

64:43010 OREF 64:7970a-d

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65315 CARBONATES
       305292 CARBONATE
                (CARBONATE OR CARBONATES)
        45695 POLYCARBONATE
        54169 POLYCARBONATES
        64390 POLYCARBONATE
                (POLYCARBONATE OR POLYCARBONATES)
         9198 ISOPHORONE
           38 ISOPHORONES
         9207 ISOPHORONE
                (ISOPHORONE OR ISOPHORONES)
         8578 ISOPHTHALATE
          241 ISOPHTHALATES
         8684 ISOPHTHALATE
                (ISOPHTHALATE OR ISOPHTHALATES)
        93060 TEREPHTHALATE
         2024 TEREPHTHALATES
        93422 TEREPHTHALATE
                (TEREPHTHALATE OR TEREPHTHALATES)
        69330 BISPHENOL
         4723 BISPHENOLS
        70727 BISPHENOL
                (BISPHENOL OR BISPHENOLS)
          136 L2 AND (ARYLATE OR CARBONATE OR POLYCARBONATE OR ISOPHORONE OR
              ISOPHTHALATE OR TEREPHTHALATE OR BISPHENOL)
=> s 15 not 14
       136 L5 NOT L4
L6
=> s 16 and (refractive or refraction or fries)
        74892 REFRACTIVE
            6 REFRACTIVES
        74896 REFRACTIVE
                (REFRACTIVE OR REFRACTIVES)
        33699 REFRACTION
         1108 REFRACTIONS
        34120 REFRACTION
                (REFRACTION OR REFRACTIONS)
         2841 FRIES
            5 L6 AND (REFRACTIVE OR REFRACTION OR FRIES)
=> d all 1-5
    ANSWER 1 OF 5 CAPLUS COPYRIGHT 2006 ACS on STN
    2003:524038 CAPLUS
    139:86127
    Entered STN: 09 Jul 2003
    Epoxy-amine compositions containing latent catalysts undergoing
    intramolecular rearrangement upon irradiation
    Rappoport, Leonid; Vainer, Alex; Yam, Aleksander
    Polymeright, Inc., USA
    U.S., 7 pp.
    CODEN: USXXAM
    Patent .
    English
    ICM C08F002-46
    ICS C08F002-50
INCL 522170000; 522168000; 522169000; 522181000; 522014000; 522065000;
    522068000; 522069000; 522031000; 522030000
    37-6 (Plastics Manufacture and Processing)
FAN.CNT 1
    PATENT NO.
                                        APPLICATION NO.
                      KIND DATE
                                                               DATE
    -----
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                                         -----
                              -----
   US 6590011
                        B1
                              20030708
                                       US 2001-846448
                                                               20010430
                      P
PRAI US 2000-200753P
                              20000501
CLASS
PATENT NO.
               CLASS PATENT FAMILY CLASSIFICATION CODES
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               ----
                      -----
US 6590011
               ICM
                      C08F002-46
                ICS
                      C08F002-50
                INCL
                      522170000; 522168000; 522169000; 522181000; 522014000;
                      522065000; 522068000; 522069000; 522031000; 522030000
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C08F0002-46 [ICM,7]; C08F0002-50 [ICS,7]
            IPCI
                   522/170.000; 522/006.000; 522/007.000; 522/014.000;
            NCL
                   522/030.000; 522/031.000; 522/038.000; 522/065.000;
                   522/068.000; 522/069.000; 522/168.000; 522/169.000;
                   522/181.000
                   C08G059/18; C08G059/68
            ECLA
An epoxy-amine compn. comprises (a) an epoxy resin, (b) an amine curative,
and (c) a latent catalyst that generates an active catalyst of epoxy-amine
interaction upon exposure to a radiation source by undergoing an intramol.
               The active catalyst is generated by undergoing a
rearrangement.
  ***Fries***
                rearrangement of the latent catalyst upon exposure to
visible light.
                 ***UV***
                            or electron beam radiation. The latent
catalyst is selected from esters of phenols and esters of derivs. of
phenols, such as acetylsalicylic acid,
                                         ***resorcinol***
                                  ***resorcinol***
  ***resorcinol***
                    diacetate,
                                                     monobenzoate, Ph
acetate, Ph benzoate, naphthyl acetate, and diacetate of
                                                           ***bisphenol***
    Thus, a sample comprising novolac epoxy resin (DEN 431) (5) with epoxy
equiv. wt. of 172-179, dimethylthiotoluenediamine (Ethacure 300) (1.5),
      ***resorcinol***
                         monoacetate (1 g) was subjected to
                                                              ***UV***
radiation for 30 min while keeping temp. of the sample below 50.degree..
After exposure, the sample was kept at ambient temp. for 60 min and at
                                                         ***resorcinol***
50.degree. for 5 h producing a cured solid product. A
monoacetate-free sample subjected to the same procedure remained liq.
phenol ester latent catalyst epoxy resin amine curative compn
Phenolic resins, uses
RL: POF (Polymer in formulation); TEM (Technical or engineered material
use); USES (Uses)
   (epoxy, novolak; epoxy-amine compns. contq. latent catalysts undergoing
   intramol. rearrangement upon irradn.)
Crosslinking agents
    ***Fries***
                  rearrangement
Light
    ***!!!/***
               radiation
   (epoxy-amine compns. contg. latent catalysts undergoing intramol.
   rearrangement upon irradn.)
Epoxy resins, uses
RL: POF (Polymer in formulation); TEM (Technical or engineered material
use): USES (Uses)
   (epoxy-amine compns. contg. latent catalysts undergoing intramol.
   rearrangement upon irradn.)
Amines, uses
RL: TEM (Technical or engineered material use); USES (Uses)
   (epoxy-amine compns. contg. latent catalysts undergoing intramol.
   rearrangement upon irradn.)
Electron beams
   (irradn.; epoxy-amine compns. contg. latent catalysts undergoing
   intramol. rearrangement upon irradn.)
Crosslinking catalysts
   (latent; epoxy-amine compns. contg. latent catalysts undergoing
   intramol. rearrangement upon irradn.)
Epoxy resins, uses
RL: POF (Polymer in formulation); TEM (Technical or engineered material
use); USES (Uses)
   (phenolic, novolak; epoxy-amine compns. contg. latent catalysts
   undergoing intramol. rearrangement upon irradn.)
Crosslinking catalysts
   (photosensitizers; epoxy-amine compns. contg. latent catalysts
   undergoing intramol. rearrangement upon irradn.)
75389-89-8, Diethyltoluenediamine 106264-79-3, Ethacure 300
RL: TEM (Technical or engineered material use); USES (Uses)
   (crosslinking agent; epoxy-amine compns. contg. latent catalysts
   undergoing intramol. rearrangement upon irradn.)
26764-44-3D, derivs.
RL: TEM (Technical or engineered material use); USES (Uses)
   (crosslinking agents; epoxy-amine compns. contq. latent catalysts
   undergoing intramol. rearrangement upon irradn.)
50-78-2, Acetylsalicylic acid
                               93-99-2, Phenyl benzoate
                                                           102-29-4.
  ***Resorcinol***
                                             ***Resorcinol***
                    monoacetate
                                   108-58-7,
                                                                  diacetate
108-95-2D, Phenol, derivs., esters
                                   122-79-2, Phenyl acetate
                                                               136-36-7,
  ***Resorcinol***
                    monobenzoate
                                                 ***Bisphenol***
                                    10192-62-8,
            29692-55-5, Naphthyl acetate
RL: CAT (Catalyst use); USES (Uses)
```

AB

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(epoxy-amine compns. contg. latent catalysts undergoing intramol.
        rearrangement upon irradn.)
                            37348-52-0, DEN 431
IT
     25068-38-6, Epon 828
    RL: POF (Polymer in formulation); TEM (Technical or engineered material
    use); USES (Uses)
        (epoxy-amine compns. contg. latent catalysts undergoing intramol.
        rearrangement upon irradn.)
IT
     119-61-9, Benzophenone, uses
                                    120-12-7, Anthracene, uses
                                                                 129-00-0,
     Pyrene, uses
     RL: CAT (Catalyst use); USES (Uses)
        (photosensitizer; epoxy-amine compns. contg. latent catalysts
        undergoing intramol. rearrangement upon irradn.)
              THERE ARE 17 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE.CNT
RE
(1) Azarnia; US 5393806 A 1995 CAPLUS
(2) Bertram; US 4925901 A 1990 CAPLUS
(3) Corley; US 4668758 A 1987 CAPLUS
(4) Debergalis; US 4636431 A 1987
(5) Gupta; US 4749726 A 1988 CAPLUS
(6) Gupta; US 4945001 A 1990 CAPLUS
(7) Ham; US 4540750 A 1985 CAPLUS
(8) Hardy; US 5541000 A 1996 CAPLUS
(9) Kawachi; US 5892118 A 1999 CAPLUS
(10) Kirchmayr; US 4510290 A 1985 CAPLUS
(11) Kirchmayr; US 4636575 A 1987 CAPLUS
(12) Pond; US 4000148 A 1976 CAPLUS
(13) Qureshi; US 4593056 A 1986 CAPLUS
(14) Shimp; US 4447586 A 1984 CAPLUS
(15) Starkey; US 5516813 A 1996 CAPLUS
(16) Trecker; US 3622482 A 1971 CAPLUS
(17) Wiggins; US 4775736 A 1988 CAPLUS
    ANSWER 2 OF 5 CAPLUS COPYRIGHT 2006 ACS on STN
T.7
ΑN
     2003:211094 CAPLUS
DN
     138:402741
     Entered STN: 18 Mar 2003
ĖD
     Weatherable polyarylate-CO- ***polycarbonate***
ΤI
                                                        engineering
     thermoplastic
     Suriano, Joseph A.; Siclovan, Tiberiu M.; Pickett, James E.; Brunelle,
ΑU
    Daniel J.; O'Neil, Gregory A.; Zhou, Hongyi
     Polymer and Specialty Materials Technologies, GE Global Research,
CS
     Niskayuna, NY, 12309, USA
     Polymer Preprints (American Chemical Society, Division of Polymer
SO
     Chemistry) (2003), 44(1), 748-749
     CODEN: ACPPAY; ISSN: 0032-3934
     American Chemical Society, Division of Polymer Chemistry
PB
DT
     Journal; (computer optical disk)
LA
     English
     38-3 (Plastics Fabrication and Uses)
CC
     Section cross-reference(s): 37
AB
       ***Polvcarbonates***
                            and polyesters, esp. poly(alkylene
     dicarboxylates), and blends thereof are widely employed classes of
     polymers, in part because of their excellent phys. properties including
     high impact strength. However, their long-term color and gloss
     instability, weatherability, is a major problem. Yellowing of
       ***polycarbonates*** and polyesters is caused largely by the action of
                radiation, frequently designated as photo-yellowing.
                     ***resorcinol***
                                       with mixts. of
                                                         ***isophthalate***
     Polyesters of
           ***terephthalate***
                               chain members typically have good weathering
    properties. On exposure to
                                   ***UV***
                                              light these polymers undergo
                   ***Fries***
                                rearrangement converting at least a portion of
     the polymer from polyarylate to o-hydroxybenzophenone-type chain members.
     The o-hydroxybenzophenone-type chain members act to screen further
       ***UV***
                 light and protect
                                     ***UV*** -sensitive components.
     Plastics has recently invented a novel polyarylate-co-
       ***polycarbonate*** , SOLLX, which has excellent gloss and color
                                ***UV***
     stability on exposure to
                                          light. In this paper we wish to
     report on synthetic approaches to these materials, a simplified reaction
    mechanism, and the phys. properties of this new engineering thermoplastic.
ST
    weathering polyarylate
                              ***polycarbonate***
                                                   engineering thermoplastic
IT
     Polyesters, properties
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
```

```
( ***polycarbonate*** -, block; prepn. and mech. properties of
       weathered polyarylate-CO- ***polycarbonate***
                                                       engineering
        thermoplastic)
IT
       ***Polycarbonates*** , properties
    RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (polyester-, block; prepn. and mech. properties of weathered
       polyarylate-CO- ***polycarbonate***
                                              engineering thermoplastic)
IT
    Elongation, mechanical
    Glass transition temperature
     Impact strength
     Luster
         ***Refractive***
                           index
     Tensile strength
        (prepn. and mech. properties of weathered polyarylate-CO-
          ***polycarbonate***
                              engineering thermoplastic)
     Polymer degradation
        (weathering; prepn. and mech. properties of weathered polyarylate-CO-
          ***polycarbonate***
                              engineering thermoplastic)
                     ***Bisphenol***
                                      A-isophthaloyl dichloride-phosgene-
     265997-77-1P,
       ***resorcinol*** -terephthaloyl dichloride block copolymer
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (prepn. and mech. properties of weathered polyarylate-CO-
          ***polycarbonate***
                               engineering thermoplastic)
RE.CNT
              THERE ARE 7 CITED REFERENCES AVAILABLE FOR THIS RECORD
(1) Brunelle, D; US 6265522 2001 CAPLUS
(2) Brunelle, D; US 6291589 2001 CAPLUS
(3) Brunelle, D; US 6294647 2001 CAPLUS
(4) Brunelle, D; US 6306507 2001 CAPLUS
(5) Cohen, S; Jour Poly Sci 1971, V9(A-1), P3263
(6) Webb, J; US 5916997 1999 CAPLUS
(7) Webb, J; US 6143839 2000 CAPLUS
1.7
    ANSWER 3 OF 5 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     2003:186826 CAPLUS
     Entered STN: 11 Mar 2003
ED
    Weatherable polyarylate-co- ***polycarbonate***
                                                       engineering
TI
     thermoplastic
     Suriano, Joseph A.; Siclovan, Tiberiu M.; Pickett, James E.; Brunelle,
ΑU
    Daniel J.; O'Neil, Gregory A.; Zhou, Hongyi
     Polymer and Specialty Chemicals Technologies, GE Global Research,
CS
    Niskayuna, NY, 12309, USA
    Abstracts of Papers, 225th ACS National Meeting, New Orleans, LA, United
SO
     States, March 23-27, 2003 (2003), POLY-674 Publisher: American Chemical
     Society, Washington, D. C.
     CODEN: 69DSA4
DT
     Conference; Meeting Abstract
LA
     English
       ***Polycarbonates***
                             and polyesters, esp. poly(alkylene
AB
     dicarboxylates), and blends thereof are widely employed classes of
     polymers, in part because of their excellent phys. properties including
     high impact strength. However, their long-term color and gloss
     instability, "weatherability", is a major problem. Yellowing of
       ***polycarbonates*** and polyesters is caused largely by the action of
       ***UV*** radiation, frequently designated as "photoyellowing".
                    ***resorcinol*** with mixts. of
     Polyesters of
                                                       ***isophthalate***
          ***terephthalate*** chain members typically have good weathering
     properties. On exposure to
                                  ***UV***
                                              light these polymers undergo
                 ***Fries***
                              rearrangement converting at least a portion of
     the polymer from polyarylate to o-hydroxybenzophenone-type chain members.
     The o-hydroxybenzophenone-type chain members act to screen further
                light and protect
                                    ***UV*** -sensitive components.
     Plastics has recently invented a novel polyarylate-co-
       ***polycarbonate*** , SOLLX, which has excellent gloss and color
     stability on exposure to
                               ***UV*** light. In this paper we wish to
     report on synthetic approaches to these materials, a simplified reaction
     mechanism, and the phys. properties of this new engineering thermoplastic.
    ANSWER 4 OF 5 CAPLUS COPYRIGHT 2006 ACS on STN
L7
     1973:160979 CAPLUS
AN
DN
     78:160979
```

Entered STN: 12 May 1984

```
***ultraviolet*** -barrier coatings
ΤI
     Transparent
     Cohen, S. M.; Young, R. H.; Markhart, A. H.
ΑU
     Plast. Prod. Resins Div., Monsanto Co., Springfield, MA, USA
CS
     Papers presented at [the] Meeting - American Chemical Society, Division of
SO
     Organic Coatings and Plastics Chemistry (1971), 31(2), 637-47
     CODEN: ACOCAO; ISSN: 0096-512X
DT
     Journal
LA
     English
     42-9 (Coatings, Inks, and Related Products)
CC
     Polyesters that underwent a photochem. ***Fries***
AB
                                                            rearrangement to
     polymeric o-hydroxybenzophenones, e.g. 2:1:1 ***bisphenol***
     A-isophthaloyl chloride-terephthaloyl chloride polymer [25639-68-3] and
     1:1:2 isophthaloyl chloride-terephthaloyl chloride- ***resorcinol***
     polymer [40472-46-6], were effective ***UV*** -barriers for clear
                                                  ***UV***
     coatings. The polyesters rearranged under
                                                             irradn. to form a
                                      ***UV***
     thin skin, which was opaque to
                                                 light but visually
     transparent. As the skin degraded under extended irradn., more of the
     exposed underlying polyester layer rearranged to compensate for the loss.
                      ***UV***
                                resistant; hydroxybenzophenone polymer
ST
     arom polyester
       ***UV***
                resistant; isophthaloyl polymer ***UV***
                                                             resistant;
     terephthaloyl polymer
                            ***UV***
                                       resistant; phenol terephthaloyl polymer
               ***resorcinol***
                                  polyester coating
     Polyesters, reactions
     RL: RCT (Reactant); RACT (Reactant or reagent)
           ***Fries***
                         rearrangement of, photochem.)
     Light stabilizers
IT
                    , polymeric hydroxybenzophenones, by
          ***UV***
                                                            ***Fries***
        rearrangement of polyester coatings)
IT
     Coating materials
                    -barrier transparent, from polyesters)
          ***UV***
       ***Ultraviolet***
IT
                          light
                                  ***Fries***
        (barrier coatings, from
                                               rearrangement of polyesters to
        polymeric hydroxybenzophenones)
IT
       ***Fries***
                    rearrangement
        (photochem., of polyesters to polymeric hydroxybenzophenones, in
          ***UV*** -barrier coatings)
     25639-68-3
IT
                 40472-46-6
     RL: TEM (Technical or engineered material use); USES (Uses)
                     * * * AN * * *
                              -barrier,
        leoatings,
                                          ***Fries***
                                                       rearrangement in)
    ANSWER 5 OF 5 CAPLUS COPYRIGHT 2006 ACS on STN
L7
AN
     `L967:65993 CAPLUS
DN
     66:65993
     Entered STN: 12 May 1984
ED
       ***Fries*** rearrangement of polyphenyl esters to polyhydroxy phenones
TI
ΑIJ
     Bellus, Daniel; Manasek, Zdenek; Hrdlovic, Pavol; Slama, Peter
CS
     Slovak Acad. Sci., Bratislava, Czech.
SO
     Journal of Polymer Science, Polymer Symposia (1966), No. 16, 267-77
     CODEN: JPYCAQ; ISSN: 0360-8905
DT
     Journal
LA
     English
CC
     35 (Synthetic High Polymers)
AB
     Poly(m-phenylene adipate), poly(isopropylidenedi-p-phenylene adipate),
     poly(isopropylidenedi-p-phenylene thiapimelate), poly[m-
                                                  ***isophthalate*** ],
     phenylene/isopropylidene-p-phenylene (70:30)
                     ***isophthalate*** ), and poly(isopropylidenedi-p-
     poly(mphenylene
               ***isophthalate*** ) (I) were rearranged to polyhydroxy
     phenylene
     phenones in PhNO2 soln. or a melt, using AlCl3, TiCl4, and SnCl4 as
     catalysts, or in CHCl3 using
                                   ***uv*** light as a catalyst. In the
     rearrangement of I in PhNO2 with AlCl3 catalysis, the mol. wt. decreased
     sharply after a short time, and cross-linking occurred when the ester
     group content reached 55-65 mol. %. A characteristic ir absorption band
     appeared at 1638 cm.-1 and increased in intensity with reaction time. The
     ester group content decrease was 1st order only during the initial stages,
                  ***Fries***
                               rearrangement. The color of the product went
     from light yellow through brown, and finally turned black in most cases.
     The ir absorption in the other polymers varied from 1636 to 1656 cm.-1
       ***Uv*** -catalyzed rearrangement of low-mol.-wt. model compds. (p-cresyl
                    ***resorcinol***
                                      monobenzoate) gave quantum yields of
     benzoate and
     0.55 and 0.36 mole-einstein-1, resp., for 254 m.mu. radiation. A
     mechanism for the rearrangement is postulated.
ST
       ***RESORCINOL***
                         POLYESTERS; POLYESTERS AROM
                                                        ***FRIES***
```

```
REARRANGEMENT; REARRANGEMENT POLYESTERS AROM;
     REARRANGEMENT POLYESTERS; POLYHYDROXYPHENONES; POLYPHENYL ESTERS
     REARRANGEMENT;
                     ***BISPHENOL***
                                        POLYESTERS
IT
     Polyesters, reactions
     RL: RCT (Reactant); RACT (Reactant or reagent)
        ( ***Fries***
                         rearrangement of, mechanism of)
       ***Fries*** rearrangement
IT
        (of polyesters, mechanism of)
     Benzenethiol, 4,4'-isopropylidenedi-, polyester with pimelic acid
IT
     RL: RCT (Reactant); RACT (Reactant or reagent)
        ( ***Fries*** rearrangement of)
     25189-11-1 25212-77-5 26618-61-1
TΤ
                                             26637-46-7
                                                          29255-72-9
                 31325-49-2
                               31325-50-5
                                             32200-90-1
     31325-48-1
                                                          32200-91-2
     32200-92-3
     RL: RCT (Reactant); RACT (Reactant or reagent)
        ( ***Fries***
                         rearrangement of)
=> d his
     (FILE 'HOME' ENTERED AT 11:23:01 ON 30 JAN 2006)
     FILE 'CAPLUS' ENTERED AT 11:23:08 ON 30 JAN 2006
          28980 S RESORCINOL
L1
L2
           1449 S L1 AND (UV OR ULTRAVIOLET)
L3
            200 S L1 AND (MASK? OR PHOTOMASK?)
L4
              5 S L3 AND (ARYLATE OR CARBONATE OR POLYCARBONATE OR ISOPHORONE O
            136 S L2 AND (ARYLATE OR CARBONATE OR POLYCARBONATE OR ISOPHORONE O
L5
L6
            136 S L5 NOT L4
              5 S L6 AND (REFRACTIVE OR REFRACTION OR FRIES)
L7
=> s 12 and polyester
        253316 POLYESTER
        215638 POLYESTERS
        325565 POLYESTER
                 (POLYESTER OR POLYESTERS)
           117 L2 AND POLYESTER
L8
=> s 18 and (mask? or photomask?)
        113347 MASK?
         14888 PHOTOMASK?
L9
             0 L8 AND (MASK? OR PHOTOMASK?)
=> s l1 and polyester
        253316 POLYESTER
        215638 POLYESTERS
        325565 POLYESTER
                 (POLYESTER OR POLYESTERS)
L10
          2215 L1 AND POLYESTER
=> s 110 and (mask? or photomask?)
        113347 MASK?
         14888 PHOTOMASK?
L11
             1 L10 AND (MASK? OR PHOTOMASK?)
=> s 110 and (uv or ultraviolet)
        475320 UV
           333 UVS
        475436 UV
                 (UV OR UVS)
        206232 ULTRAVIOLET
            11 ULTRAVIOLETS
        206240 ULTRAVIOLET
                 (ULTRAVIOLET OR ULTRAVIOLETS)
        475320 UV
           333 UVS
        475436 UV
                 (UV OR UVS)
        593728 ULTRAVIOLET
                 (ULTRAVIOLET OR UV)
L12
           117 L10 AND (UV OR ULTRAVIOLET)
```

\*\*\*FRIES\*\*\*

```
=> s 112 and (pattern6 or refractive or refraction or fries)
6 IS NOT A RECOGNIZED COMMAND
The previous command name entered was not recognized by the system.
For a list of commands available to you in the current file, enter
"HELP COMMANDS" at an arrow prompt (=>).
=> s 112 and (pattern? or refractive or refraction or fries)
        689980 PATTERN?
         74892 REFRACTIVE
             6 REFRACTIVES
         74896 REFRACTIVE
                 (REFRACTIVE OR REFRACTIVES)
         33699 REFRACTION
          1108 REFRACTIONS
         34120 REFRACTION
                 (REFRACTION OR REFRACTIONS)
          2841 FRIES
             5 L12 AND (PATTERN? OR REFRACTIVE OR REFRACTION OR FRIES)
L13
=> d all 1-5
    ANSWER 1 OF 5 CAPLUS COPYRIGHT 2006 ACS on STN
     2003:211094 CAPLUS
AN
DN
     138:402741
ED
     Entered STN: 18 Mar 2003
ΤI
     Weatherable polyarylate-CO-polycarbonate engineering thermoplastic
ΑU
     Suriano, Joseph A.; Siclovan, Tiberiu M.; Pickett, James E.; Brunelle,
     Daniel J.; O'Neil, Gregory A.; Zhou, Hongyi
CS
     Polymer and Specialty Materials Technologies, GE Global Research,
     Niskayuna, NY, 12309, USA
SO
     Polymer Preprints (American Chemical Society, Division of Polymer
     Chemistry) (2003), 44(1), 748-749
     CODEN: ACPPAY; ISSN: 0032-3934
PR
     American Chemical Society, Division of Polymer Chemistry
DT
     Journal; (computer optical disk)
LA
     English
     38-3 (Plastics Fabrication and Uses)
CC
     Section cross-reference(s): 37
                         ***polyesters*** , esp. poly(alkylene
AB
     Polycarbonates and
     dicarboxylates), and blends thereof are widely employed classes of
     polymers, in part because of their excellent phys. properties including
     high impact strength. However, their long-term color and gloss
     instability, weatherability, is a major problem. Yellowing of
                         ***polyesters***
                                            is caused largely by the action of
     polycarbonates and
                radiation, frequently designated as photo-yellowing.
       ***Polyesters*** of
                             ***resorcinol***
                                                 with mixts. of isophthalate and
     terephthalate chain members typically have good weathering properties.
     exposure to
                 ***UV***
                             light these polymers undergo photochem.
                   rearrangement converting at least a portion of the polymer
     from polyarylate to o-hydroxybenzophenone-type chain members. The
     o-hydroxybenzophenone-type chain members act to screen further
                        ***UV*** -sensitive components. GE Plastics has
     light and protect
     recently invented a novel polyarylate-co-polycarbonate, SOLLX, which has
     excellent gloss and color stability on exposure to ***UV***
     this paper we wish to report on synthetic approaches to these materials, a
     simplified reaction mechanism, and the phys. properties of this new
     engineering thermoplastic.
ST
     weathering polyarylate polycarbonate engineering thermoplastic
IT
       ***Polyesters*** , properties
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (polycarbonate-, block; prepn. and mech. properties of weathered
       polyarylate-CO-polycarbonate engineering thermoplastic)
IT
     Polycarbonates, properties
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
           ***polyester*** -, block; prepn. and mech. properties of weathered
       polyarylate-CO-polycarbonate engineering thermoplastic)
IT
     Elongation, mechanical
    Glass transition temperature
     Impact strength
     Luster
         ***Refractive***
                            index
    Tensile strength
```

```
(prepn. and mech. properties of weathered polyarylate-CO-polycarbonate
        engineering thermoplastic)
IT
     Polymer degradation
        (weathering; prepn. and mech. properties of weathered
        polyarylate-CO-polycarbonate engineering thermoplastic)
     265997-77-1P, Bisphenol A-isophthaloyl dichloride-phosgene-
IT
       ***resorcinol*** -terephthaloyl dichloride block copolymer
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (prepn. and mech. properties of weathered polyarylate-CO-polycarbonate
        engineering thermoplastic)
              THERE ARE 7 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE.CNT
RE
(1) Brunelle, D; US 6265522 2001 CAPLUS
(2) Brunelle, D; US 6291589 2001 CAPLUS
(3) Brunelle, D; US 6294647 2001 CAPLUS
(4) Brunelle, D; US 6306507 2001 CAPLUS
(5) Cohen, S; Jour Poly Sci 1971, V9(A-1), P3263
(6) Webb, J; US 5916997 1999 CAPLUS
(7) Webb, J; US 6143839 2000 CAPLUS
L13
     ANSWER 2 OF 5 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     2003:186826 CAPLUS
ED
     Entered STN: 11 Mar 2003
ΤÌ
     Weatherable polyarylate-co-polycarbonate engineering thermoplastic
AU
     Suriano, Joseph A.; Siclovan, Tiberiu M.; Pickett, James E.; Brunelle,
     Daniel J.; O'Neil, Gregory A.; Zhou, Hongyi
CS
     Polymer and Specialty Chemicals Technologies, GE Global Research,
     Niskayuna, NY, 12309, USA
SO
     Abstracts of Papers, 225th ACS National Meeting, New Orleans, LA, United
     States, March 23-27, 2003 (2003), POLY-674 Publisher: American Chemical
     Society, Washington, D. C.
     CODEN: 69DSA4
DT
     Conference; Meeting Abstract
LA
     English
AΒ
     Polycarbonates and
                          ***polyesters***
                                           , esp. poly(alkylene
     dicarboxylates), and blends thereof are widely employed classes of
     polymers, in part because of their excellent phys. properties including
     high impact strength. However, their long-term color and gloss
     instability, "weatherability", is a major problem. Yellowing of
     polycarbonates and
                          ***polyesters*** is caused largely by the action of
                 radiation, frequently designated as "photoyellowing".
       ***Polyesters***
                               ***resorcinol***
                                                 with mixts. of isophthalate and
                        of
     terephthalate chain members typically have good weathering properties.
                  ***UV***
     exposure to
                             light these polymers undergo photochem.
       ***Fries***
                    rearrangement converting at least a portion of the polymer
     from polyarylate to o-hydroxybenzophenone-type chain members. The
     o-hydroxybenzophenone-type chain members act to screen further
                        ***UV*** -sensitive components. GE Plastics has
     light and protect
     recently invented a novel polyarylate-co-polycarbonate, SOLLX, which has
     excellent gloss and color stability on exposure to
                                                         ***UV***
     this paper we wish to report on synthetic approaches to these materials, a
     simplified reaction mechanism, and the phys. properties of this new
     engineering thermoplastic.
L13
     ANSWER 3 OF 5 CAPLUS COPYRIGHT 2006 ACS on STN
ΑN
     1973:160979 CAPLUS
DN
     78:160979
ED
     Entered STN: 12 May 1984
TI
     Transparent
                  ***ultraviolet*** -barrier coatings
ΑU
     Cohen, S. M.; Young, R. H.; Markhart, A. H.
CS
     Plast. Prod. Resins Div., Monsanto Co., Springfield, MA, USA
     Papers presented at [the] Meeting - American Chemical Society, Division of
SO
     Organic Coatings and Plastics Chemistry (1971), 31(2), 637-47
     CODEN: ACOCAO; ISSN: 0096-512X
DT
     Journal
LA
     English
CC
     42-9 (Coatings, Inks, and Related Products)
AB
       ***Polyesters***
                         that underwent a photochem.
                                                        ***Fries***
     rearrangement to polymeric o-hydroxybenzophenones, e.g. 2:1:1 bisphenol
     A-isophthaloyl chloride-terephthaloyl chloride polymer [25639-68-3] and
     1:1:2 isophthaloyl chloride-terephthaloyl chloride- ***resorcinol***
     polymer [40472-46-6], were effective
                                            ***UV*** -barriers for clear
```

```
***polyesters*** rearranged under
                                                        ***UV***
     coatings. The
                                                                    irradn.
    to form a thin skin, which was opaque to ***UV*** light but visually
    transparent. As the skin degraded under extended irradn., more of the
                       ***polyester***
                                         layer rearranged to compensate for
    exposed underlying
    the loss.
           ***polyester***
                              ***UV***
    arom
                                         resistant; hydroxybenzophenone
    polymer ***UV***
                        resistant; isophthaloyl polymer
                                                         ***[JV***
    resistant; terephthaloyl polymer ***UV***
                                                resistant; phenol
                                  ***resorcinol***
    terephthaloyl polymer coating;
                                                       ***polyester***
    coating
       ***Polyesters***
                        , reactions
    RL: RCT (Reactant); RACT (Reactant or reagent)
        ( ***Fries*** rearrangement of, photochem.)
    Light stabilizers
        ( ***UV*** , polymeric hydroxybenzophenones, by
                                                         ***Fries***
       rearrangement of ***polyester***
                                          coatings)
    Coating materials
        ( ***UV*** -barrier transparent, from
                                              ***polyesters*** )
       ***Ultraviolet*** light
                                ***Fries***
        (barrier coatings, from
                                              rearrangement of
         ***polyesters***
                          to polymeric hydroxybenzophenones)
      ***Fries***
                  rearrangement
        (photochem., of ***polyesters***
                                          to polymeric hydroxybenzophenones,
           ***UV*** -barrier coatings)
       in
    25639-68-3
                 40472-46-6
    RL: TEM (Technical or engineered material use); USES (Uses)
                   ***UV*** -barrier,
                                       ***Fries***
                                                     rearrangement in)
        (coatings,
    ANSWER 4 OF 5 CAPLUS COPYRIGHT 2006 ACS on STN
L13
    1972:73017 CAPLUS
    76:73017
    Entered STN: 12 May 1984
    Photopolymerizable acrylic compositions containing rearrangeable
       ***ultraviolet*** stabilizer precursors
    Zunker, David W.
    du Pont de Nemours, E. I., and Co.
    U.S., 4 pp.
    CODEN: USXXAM
    Patent
    English
    C08F; C08G
INCL 204159160
    35 (Synthetic High Polymers)
FAN.CNT 1
    PATENT NO.
                       KIND
                              DATE.
                                        APPLICATION NO.
                                                              DATE
    ______
                       ----
                              -----
                                          -----
    US 3616367
                       Α
                              19711026
                                         US 1968-778827
                                                              19681125
PRAI US 1968-778827
                       Α
                              19681125
CLASS
PATENT NO.
               CLASS PATENT FAMILY CLASSIFICATION CODES
 -----
               ----
                     -----
US 3616367
                IC
                      C08F; C08G
                      204159160
                INCL
                IPCI
                      C08F0045-58; C08G0051-58
                NCL
                       522/021.000; 522/011.000; 522/028.000; 522/079.000;
                       522/120.000; 522/121.000; 522/907.000; 524/290.000;
                       524/291.000; 524/336.000; 524/853.000; 525/305.000;
                       525/309.000
    A photopolymerizable compn. is described contq. monoesters and
      ***polyesters*** of acrylic acid or methacrylic acid, 50-1000 ppm of a
    photopolymn initiator, 5-100 ppm polymn. inhibitor and 0.001-5.0% of a
    phenolic ester ***uv*** -stabilizer precursor. The precursor undergoes
                   rearrangement to hydroxybenzophenones after polymn. and on
                                                       ***uv*** stability
    exposure to sunlight. These compds. in part yield
    to the polymers. The compns. are esp. useful in continuous prodn. of
    acrylic sheet where they are heated and extruded through a sheeting die.
    After the sheet leaves the die, it travels vertically between fluorescent
    black-light lamps which produce the
                                        ***uv*** light necessary for
    polymn. and between heaters. The hardened polymd. sheet is then removed
    from the polymn. tower by pinch rolls. Thus, Me methacrylate 56.7,
    poly(Me methacrylate) [9011-14-7] 43.3, benzoin 0.01, 2,4-dimethyl-6-tert-
    butylphenol 0.003, and ***resorcinol*** monobenzoate [136-36-7] 0.03%
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were mixed and agitated to remove dissolved gases until the viscosity
neared the point at which it would not flow. Then it was poured into a
cell formed by 2 glass plates sepd. by a poly(vinyl chloride) gasket and
stored in darkness for 1 day to allow the compn. to gel. The cell was
suspended in an air circulating oven and irradiated by black-light
fluorescent bulbs. The temp. increased from 60 to 78.deg. in 24 min.
polymn. rate is proportional to the temp. rise divided by the time
necessary for that rise. For the compn. described this ratio was
0.75.deq./min. After the temp. within the compn. had reached its max.
value due to exothermic polymn., the oven temp. was increased to 118.deg.
and maintained at this level for 69 min. to facilitate the complete
polymn. After cooling, the sheet was sepd. from the glass plates and
             ***uv***
                        irradn. in an accelerated weathering test for 2
exposed to
       Visible-light transmission through the sheet was measured before
and after exposure. A yellowness index was calcd. for the fresh and
exposed sheets. The yellowness was 0.1 initially and 1.6 after 2 weeks'
exposure, compared with 0.2 and 4.6, resp., for control samples.
                                    ***\<u>\</u>\\
photopolymerizable acrylic compn;
                                               stabilizers acrylic compns;
                       ***UV***
hydroxybenzophenones
                                  stabilizers; polymethacrylate sheets
        ***resorcinol***
                            monobenzoate
                                          ***UV***
                                                      stabilizer
Polymerization catalysts
   (azobisisobutyronitrile andbenzoin, for methyl methacrylate)
Polymerization
   (by light, of methyl methacrylate temp. in relation to)
Polymerization inhibitors
   (dimethylbutylphenol, for methyl methacrylate)
Light stabilizers
   ( ***resorcinol***
                         monobenzoate, for methyl methacrylate)
78-67-1
          119-53-9
RL: CAT (Catalyst use); USES (Uses)
   (catalysts, for polymn. of methyl methacrylate)
1879-09-0
RL: USES (Uses)
   (polymn. inhibitors, for methyl methacrylate)
9011-14-7P
RL: PREP (Preparation)
   (prepn. of, catalysts and inhibitors for)
136-36-7
RL: USES (Uses)
     ***uv***
                 light stabilizers, for methyl methacrylate polymers)
ANSWER 5 OF 5 CAPLUS COPYRIGHT 2006 ACS on STN
1967:65993 CAPLUS
66:65993
Entered STN: 12 May 1984
  ***Fries***
               rearrangement of polyphenyl esters to polyhydroxy phenones
Bellus, Daniel; Manasek, Zdenek; Hrdlovic, Pavol; Slama, Peter
Slovak Acad. Sci., Bratislava, Czech.
Journal of Polymer Science, Polymer Symposia (1966), No. 16, 267-77
CODEN: JPYCAQ; ISSN: 0360-8905
Journal
English
35 (Synthetic High Polymers)
Poly(m-phenylene adipate), poly(isopropylidenedi-p-phenylene adipate),
poly(isopropylidenedi-p-phenylene thiapimelate), poly[m-
phenylene/isopropylidene-p-phenylene (70:30) isophthalate],
poly(mphenylene isophthalate), and poly(isopropylidenedi-p-phenylene
isophthalate) (I) were rearranged to polyhydroxy phenones in PhNO2 soln.
or a melt, using AlCl3, TiCl4, and SnCl4 as catalysts, or in CHCl3 using
  ***uv***
             light as a catalyst. In the rearrangement of I in PhNO2 with
AlCl3 catalysis, the mol. wt. decreased sharply after a short time, and
cross-linking occurred when the ester group content reached 55-65 mol. %.
A characteristic ir absorption band appeared at 1638 cm.-1 and increased
in intensity with reaction time. The ester group content decrease was 1st
order only during the initial stages, unlike the
                                                   ***Fries***
rearrangement. The color of the product went from light yellow through
brown, and finally turned black in most cases.
                                                The ir absorption in the
                                                 ***Uv*** -catalyzed
other polymers varied from 1636 to 1656 cm.-1
rearrangement of low-mol.-wt. model compds. (p-cresyl benzoate and
  ***resorcinol***
                    monobenzoate) gave quantum yields of 0.55 and 0.36
mole-einstein-1, resp., for 254 m.mu. radiation. A mechanism for the
rearrangement is postulated.
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AB

```
***RESORCINOL***
                            ***POLYESTERS*** ; ***POLYESTERS***
                                                                       AROM
       ***FRIES*** REARRANGEMENT; REARRANGEMENT ***POLYESTERS***

***FRIES*** REARRANGEMENT ***POLYESTERS*** : POLYHYDROXYP
                                                                         AROM:
                                    ***POLYESTERS*** ; POLYHYDROXYPHENONES;
     POLYPHENYL ESTERS REARRANGEMENT; BISPHENOL
                                                  ***POLYESTERS***
       ***Polyesters*** , reactions
IT
     RL: RCT (Reactant); RACT (Reactant or reagent)
       ( ***Fries*** rearrangement of, mechanism of)
       ***Fries*** rearrangement
ΙT
        (of ***polyesters*** , mechanism of)
     Benzenethiol, 4,4'-isopropylidenedi-, ***polyester*** with pimelic
IT
     RL: RCT (Reactant); RACT (Reactant or reagent)
        ( ***Fries*** rearrangement of)
     25189-11-1 25212-77-5 26618-61-1
                                             26637-46-7
                                                          29255-72-9
IT
     31325-48-1 31325-49-2
                               31325-50-5
                                             32200-90-1
                                                          32200-91-2
     32200-92-3
     RL: RCT (Reactant); RACT (Reactant or reagent)
        ( ***Fries*** rearrangement of)
=> s sllx
             0 SLLX
L14
             0 SLLX
=> d hsi
L14 HAS NO ANSWERS
              O SEA FILE=CAPLUS ABB=ON PLU=ON SLLX
=> d his
     (FILE 'HOME' ENTERED AT 11:23:01 ON 30 JAN 2006)
     FILE 'CAPLUS' ENTERED AT 11:23:08 ON 30 JAN 2006
          28980 S RESORCINOL
L2
           1449 S L1 AND (UV OR ULTRAVIOLET)
L3
            200 S L1 AND (MASK? OR PHOTOMASK?)
              5 S L3 AND (ARYLATE OR CARBONATE OR POLYCARBONATE OR ISOPHORONE O
L5
            136 S L2 AND (ARYLATE OR CARBONATE OR POLYCARBONATE OR ISOPHORONE O
L6
            136 S L5 NOT L4
L7
              5 S L6 AND (REFRACTIVE OR REFRACTION OR FRIES)
            117 S L2 AND POLYESTER
L8
              0 S L8 AND (MASK? OR PHOTOMASK?)
L9
           2215 S L1 AND POLYESTER
L10
L11
              1 S L10 AND (MASK? OR PHOTOMASK?)
            117 S L10 AND (UV OR ULTRAVIOLET)
L12
L13
              5 S L12 AND (PATTERN? OR REFRACTIVE OR REFRACTION OR FRIES)
              0 S SLLX
L14
=> s l1 and (grating or hologra?)
         31994 GRATING
         18847 GRATINGS
         37577 GRATING
                 (GRATING OR GRATINGS)
         18143 HOLOGRA?
         16360 HOLOG
            14 HOLOGS
         16362 HOLOG
                 (HOLOG OR HOLOGS)
         21207 HOLOGRA?
                 (HOLOGRA? OR HOLOG)
L15
            15 L1 AND (GRATING OR HOLOGRA?)
=> d all 1-15
L15 ANSWER 1 OF 15 CAPLUS COPYRIGHT 2006 ACS on STN
AN
    2005:182219 CAPLUS
DN
    142:287868
ED
     Entered STN: 04 Mar 2005
TT
     Methods of photoaddressing a polymer composition and the articles derived
IN
     Chisholm, Bret Ja; McLaughlin, Michael Jeffrey
```

```
PA
     USA
so
     U.S. Pat. Appl. Publ., 9 pp.
     CODEN: USXXCO
DT
     Patent
LA
     English
IC
     ICM G11B007-24
INCL 430270140; 430945000; 219121650
     74-8 (Radiation Chemistry, Photochemistry, and Photographic and Other
     Reprographic Processes)
     Section cross-reference(s): 38
FAN.CNT 1
                                                            DATE
     PATENT NO.
                       KIND DATE
                                         APPLICATION NO.
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     ______
                        _ _ _ _
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                                                           20030829
20040827
                                        US 2003-652016
     US 2005048401
                         A1
                               20050303
ΡI
     WO 2005022525
                        A1
                               20050310 WO 2004-US28084
         W: AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH,
            CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD,
            GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC,
            LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI,
            NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY,
            TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW
         RW: BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW, AM,
            AZ, BY, KG, KZ, MD, RU, TJ, TM, AT, BE, BG, CH, CY, CZ, DE, DK,
            EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE,
            SI, SK, TR, BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE,
            SN, TD, TG
PRAI US 2003-652016
                         Α
                               20030829
CLASS
 PATENT NO.
                CLASS PATENT FAMILY CLASSIFICATION CODES
                ----
 US 2005048401 ICM
                       G11B007-24
                       430270140; 430945000; 219121650
                INCL
                IPCI
                       G11B0007-24 [ICM, 7]
                NCL
                       430/270.140
 WO 2005022525
                IPCI
                       G11B0007-24 [ICM, 7]
     A method for manufg. data storage media comprising irradiating at least a
     portion of an org. polymer comprising a ***resorcinol*** arylate
     polyester with a UV beam having a wavelength of about 290 to about 700 nm
     so as to impart an energy of about 1 to about 20 mW/square centimeter to
     the irradiated portion of the org. polymer.
ST
     photoaddressing polymer compn
                                   ***holog***
                                                 recording
ΙT
     Polycarbonates, uses
     RL: TEM (Technical or engineered material use); USES (Uses)
        (methods of photoaddressing a polymer compn. and the articles derived
        therefrom)
IT
       ***Holographic***
                         recording materials
        (polymeric; methods of photoaddressing a polymer compn. and the
        articles derived therefrom)
IT
     100-21-0D, Terephthalic acid, ester, polymer with isophthalate,
       ***resorcinol*** , carbonate 108-46-3D, ***Resorcinol***
     with isophthalate, terephthalate, carbonate 121-91-5D, Isophthalic acid,
     ester, polymer with terephthalate, ***resorcinol*** , carbonate
     3812-32-6D, Carbonate, polymer with isophthalate, terephthalate,
       ***resorcinol***
     RL: TEM (Technical or engineered material use); USES (Uses)
        (methods of photoaddressing a polymer compn. and the articles derived
        therefrom)
    ANSWER 2 OF 15 CAPLUS COPYRIGHT 2006 ACS on STN
L15
ΑN
    2004:633307 CAPLUS
DN
     141:166768
ED
     Entered STN: 06 Aug 2004
TI
     Synthesis, spectroscopy, and photophysics of multi-chromophoric Zn(II)
     Group 8 metal complexes
IN
     Therien, Michael J.; Uyeda, Harry Tetsuo
PA
     The Trustees of the University of Pennsylvania, USA
SO
     U.S. Pat. Appl. Publ., 40 pp.
     CODEN: USXXCO
DT
     Patent
LA
     English
IC
     ICM C08L001-00
INCL 524543000; 524556000; 546002000; 548402000
```

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Section cross-reference(s): 26, 72, 73, 74
FAN.CNT 1
    PATENT NO.
                      KIND
                             DATE
                                        APPLICATION NO.
                                                            DATE
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                               -----
                                          -----
PI US 2004152826 A1
PRAI US 2002-368493P P
                               20040805
                                          US 2003-403387 20030328
                              20020328
CLASS
             CLASS PATENT FAMILY CLASSIFICATION CODES
PATENT NO.
                ----
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 US 2004152826 ICM
                       C08L001-00
                       524543000; 524556000; 546002000; 548402000
                INCL
                IPCI
                       C08L0001-00 [ICM,7]
                NCL
                       524/543.000
                       C07D487/22+257E+209C+209C+209C+209C
                ECLA
os
     MARPAT 141:166768
GΙ
/ Structure 1 in file .gra /
     Novel multichromophoric complexes comprising R1-RA-[MC]-([RM]z-[MC])m-RA-
AB
     R2 [MC = conjugated macrocycle; RA = covalent bond, C2-C20 alkenyl or
     alkynyl, C4-C14 cumulenyl; RM = C1-C20 alkyl, C2-C20 alkenyl or alkynyl,
     C4-C14 cumulenyl, C3-C50 aryl, and various arylalkynyl, heterocycloalkyl,
     heteroaryl, etc.; R1 = H, halo, protecting group, etc.; m = 0-50, z = 0 or
     1] and their metal complexes, are provided. Polymeric compns. and devices
     comprising the same are also discussed. The complexes are characterized
     by a central bridging moiety comprising one or a plurality of linked
     conjugated macrocyclic mols. [MC] coupled to at least one inorg. moiety
     (R1 and/or R2 ) through org. linker RA. Prepn. methods include
     metal-mediated cross-coupling techniques. The complexes can be useful in
     nonlinear optical devices and other optoelectronic applications. The
     UV-visible spectra, cyclic voltammetry, and mol. first order
     hyperpolarizability of some prepd. example compds. of the invention, e.q.,
     ethynyl-bridged ruthenium(II)/osmium(II) terpyridine zinc porphyrinato
     complexes I(PF6)2 (M = Ru, Os), are measured.
ST
     zinc porphyrin Group 8 metal terpyridine ethynyl linked prepn; NLO zinc
     porphyrin Group 8 metal terpyridine multichromophoric; optoelectronic zinc
     porphyrin Group 8 metal terpyridine multichromophoric; electrochem redox
     zinc porphyrin Group 8 metal terpyridine multichromophoric; polymer zinc
     Group 8 metal multichromophoric complex optoelectronic application
    Group VIII element complexes
     RL: DEV (Device component use); PRP (Properties); SPN (Synthetic
     preparation); PREP (Preparation); USES (Uses)
        (Group 8; prepn., UV-visible spectra, and mol. first-order
       hyperpolarizability of multichromophoric zinc(II) Group 8 metal
       complexes for nonlinear optical devices and optoelectronic
        applications)
IT
    Redox reaction
        (electrochem.; of multichromophoric ethynyl-linked zinc(II)
       porphyrinato Group 8 metal terpyridine complexes)
IT
    Nonlinear optical materials
        (ethynyl-linked zinc(II) porphyrinato Group 8 metal terpyridine
       complexes and related multichromophoric complexes for NLO devices)
IT
       ***Holographic***
                        recording materials
     Optical detectors
     Optical limiting
     Optical waveguides
     Photorefractive materials
        (ethynyl-linked zinc(II) porphyrinato Group 8 metal terpyridine
       complexes and related multichromophoric complexes for NLO devices and
       other optoelectronic applications)
IT
     Photoelectric devices
        (ethynyl-linked zinc(II) porphyrinato Group 8 metal terpyridine
       complexes and related multichromophoric complexes for optoelectronic
       applications)
IT
    Optical hyperpolarizability
        (mol. first-order hyperpolarizability of ethynyl-bridged
       ruthenium(II)/osmium(II) terpyridine zinc porphyrinato complexes and
```

related multichromophoric zinc(II) Group 8 metal complexes)

78-7 (Inorganic Chemicals and Reactions)

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IT
     UV and visible spectra
        (of multichromophoric ethynyl-linked zinc(II) porphyrinato Group 8
        metal terpyridine complexes)
IT
     Optical instruments
        (phase shifters; ethynyl-linked zinc(II) porphyrinato Group 8 metal
        terpyridine complexes and related multichromophoric complexes for NLO
        devices and other optoelectronic applications)
TT
     Fluoropolymers, uses
     Polyamic acids
     Polycarbonates, uses
     Polyesters, uses
     Polyimides, uses
     Polyolefins
     Polyurethanes, uses
     RL: DEV (Device component use); USES (Uses)
        (polymer compns. contg. ethynyl-linked zinc(II) porphyrinato Group 8
        metal terpyridine complexes and related multichromophoric complexes for
        NLO devices and other optoelectronic applications)
TT
     Porphyrins
     RL: DEV (Device component use); RCT (Reactant); SPN (Synthetic
     preparation); PREP (Preparation); RACT (Reactant or reagent); USES (Uses)
        (prepn. of ethynyl-linked porphyrins and related multichromophoric
        complexes for NLO devices and other optoelectronic applications)
IT
     Metalloporphyrins
     RL: DEV (Device component use); PRP (Properties); SPN (Synthetic
     preparation); PREP (Preparation); USES (Uses)
        (zinc; prepn. of ethynyl-linked zinc(II) porphyrinato Group 8 metal
        terpyridine complexes and related multichromophoric complexes for NLO
        devices and other optoelectronic applications)
                   478183-91-4
                                 478183-93-6
IT
     171204-91-4
     RL: DEV (Device component use); PRP (Properties); USES (Uses)
        (mol. first-order hyperpolarizability as multichromophoric complex for
        NLO devices and other optoelectronic applications)
TТ
     9003-53-6
     RL: DEV (Device component use); USES (Uses)
        (polymer compns. contg. ethynyl-linked zinc(II) porphyrinato Group 8
        metal terpyridine complexes and related multichromophoric complexes for
        NLO devices and other optoelectronic applications)
IT
     478183-87-8P
                    478183-89-0P
                                   478183-95-8P
     RL: DEV (Device component use); PRP (Properties); SPN (Synthetic
     preparation); PREP (Preparation); USES (Uses)
        (prepn. of ethynyl-linked zinc(II) porphyrinato Group 8 metal
        terpyridine complexes and related multichromophoric complexes for NLO
        devices and other optoelectronic applications)
IT
     478184-19-9P
                    478184-20-2P
                                   478184-33-7P
                                                  731794-51-7P
                                                                  731794-55-1P
     RL: DEV (Device component use); SPN (Synthetic preparation); PREP
     (Preparation); USES (Uses)
        (prepn. of ethynyl-linked zinc(II) porphyrinato Group 8 metal
        terpyridine complexes and related multichromophoric complexes for NLO
        devices and other optoelectronic applications)
TT
     108-46-3,
                 ***Resorcinol***
                                   , reactions
                                                 624-95-3, 3,3-Dimethyl-1-
               1066-54-2, Trimethylsilylacetylene
     butanol
                                                    21211-65-4, Dipyrrylmethane
     72905-30-7
                  78389-87-4
                               97393-18-5
                                            478184-36-0
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (prepn. of ethynyl-linked zinc(II) porphyrinato Group 8 metal
        terpyridine complexes and related multichromophoric complexes for NLO
        devices and other optoelectronic applications)
IT
     149817-62-9P
                    183803-99-8P
                                   211450-16-7P
                                                  478184-21-3P
                                                                  478184-24-6P
     478184-27-9P
                    478184-29-1P
                                   478184-31-5P
                                                   478184-34-8P
                                                                  478184-35-9P
     478184-37-1P
                    478184-38-2P
                                   478184-39-3P
                                                  478184-40-6P
                                                                  478184-41-7P
     478184-42-8P
                    478184-44-0P
                                   731794-60-8P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (prepn. of ethynyl-linked zinc(II) porphyrinato Group 8 metal
        terpyridine complexes and related multichromophoric complexes for NLO
        devices and other optoelectronic applications)
    ANSWER 3 OF 15 CAPLUS COPYRIGHT 2006 ACS on STN
L15
AN
     2003:944770 CAPLUS
DN
     140:147679
```

New azobenzene chromophores as monomers for synthesis of polyesters

04 Dec 2003

ED

Entered STN:

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Schab-balcerzak, Ewa; Grabiec, Eugenia; Sek, Danuta; Miniewicz, Andrzej
AU
CS
     Centre of Polymer Chemistry, Polish Academy of Sciences, Zabrze, 41-819,
SO
     Polymer Journal (Tokyo, Japan) (2003), 35(11), 851-858
     CODEN: POLJB8; ISSN: 0032-3896
PB
     Society of Polymer Science, Japan
DT
     Journal
LA
     English
     41-3 (Dyes, Organic Pigments, Fluorescent Brighteners, and Photographic
CC
     Sensitizers)
     Section 'cross-reference(s): 25, 35, 73
     CASREACT 140:147679
os
     Two new azo chromophores: 2,4-dihydroxy-4'-nitroazobenzene and
AB
     2,4-dihydroxy-4-azo-(4'-nitroazobenzeno)benzene have been prepd.
     diols have been applied as monomers for polyesters synthesized in
     condensation with isophthaloyl chloride and/or sebacoyl chloride.
     polymers were identified by IR spectra and elemental anal. The character
     of the polymers was detd. using X-ray spectroscopy. Thermal properties
     such as glass transition temp. and thermal stability were investigated
     using differential scanning calorimetry and thermogravimetric anal.
     polymers with azobenzene groups could find potential applications as
       ***holog***
                   . recording materials. Preliminary investigations of optical
       ***grating*** recording were carried out.
       ***resorcinol***
                          azo dye deriv polyester prepn
ST
IT
     Polyesters, preparation
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (azobenzene chromophores as monomers for synthesis of polyesters)
                   ***gratings***
IT
     Diffraction
         ***Holographic***
                            diffraction
                                           ***gratings***
        (from polyesters based on azobenzene chromophore monomers)
     Glass transition temperature
IT
     Thermal stability
     UV and visible spectra
        (of polyesters based on azobenzene chromophore monomers)
IT
     Azo dyes
        (polymerizable; azobenzene chromophores as monomers for synthesis of
        polyesters)
     649729-60-2P, 4-(4-Nitrophenylazo) ***resorcinol*** -sebacoyl chloride
IT
     copolymer
                 649729-61-3P, Isophthaloyl chloride-4-(4-nitrophenylazo)
       ***resorcinol***
                          copolymer
                                      649729-62-4P
                                                     649729-63-5P
                                                                    649729-64-6P
                   651329-00-9P
     649729-65-7P
                                  651329-05-4P
                                                  651329-13-4P
                                                                651329-14-5P
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (azobenzene chromophores as monomers for synthesis of polyesters)
IT
     108-46-3,
                 ***Resorcinol*** , reactions
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (coupling component; azobenzene chromophores as monomers for synthesis
        of polyesters)
IT
     100-01-6, p-Nitroaniline, reactions
                                           730-40-5, 4-Amino-4'-nitroazobenzene
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (diazo component; azobenzene chromophores as monomers for synthesis of
        polyesters)
TT
     649729-58-8P
                    649729-59-9P
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (model compd.; azobenzene chromophores as monomers for synthesis of
       polyesters)
IT
     74-39-5P
                649729-57-7P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (monomer; azobenzene chromophores as monomers for synthesis of
        polyesters)
IT
     98-88-4, Benzoyl chloride
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (starting material for model compd.; azobenzene chromophores as
        monomers for synthesis of polyesters)
RE.CNT 9
              THERE ARE 9 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE
(1) Ahlheim, M; Macromol Chem Phys 1994, V195, P361 CAPLUS
(2) Dudek, G; J Am Chem Soc 1966, V88, P2407 CAPLUS
(3) Eich, M; Macromol Chem Rapid Commun 1987, V8, P467 CAPLUS
(4) Eichler, H; Laser-Induced Dynamic Gratings 1986
(5) Labarthet, F; J Phys Chem B 1999, V103, P6690 CAPLUS
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```

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(9) Yamamoto, T; J Phys Chem B 2001, V105, P2308 CAPLUS
    ANSWER 4 OF 15 CAPLUS COPYRIGHT 2006 ACS on STN
L15
     2003:855018 CAPLUS
AN
DN
     140:67554
     Entered STN: 31 Oct 2003
ED
     Investigations of polymers with chromophore units I. Synthesis and
TI
     properties of new poly(ester-imide)s from 2,4-dihydroxy-4'-nitroazobenzene
     Sek, Danuta; Grabiec, Eugenia; Miniewicz, Andrzej
ΑU
     Centre of Polymer Chemistry, Polish Academy of Sciences, Zabrze, 41-800,
CS
     Polymer Journal (Tokyo, Japan) (2003), 35(10), 749-756
SO
     CODEN: POLJB8; ISSN: 0032-3896
     Society of Polymer Science, Japan
PB
DT
     Journal
LA
     English
     74-8 (Radiation Chemistry, Photochemistry, and Photographic and Other
CC
     Reprographic Processes)
     Section cross-reference(s): 38
     A series of poly(ester-imide)s based on new azobenzene deriv.
AB
     2,4-dihydroxy-4'-nitroazobenzene has been synthesized and characterized.
     An influence of macromols. structures on the phys. and chem. properties
                                                     ***holog*** . recording
     was investigated. The preliminary results of
     in poly(ester-imide) foils are presented.
       ***holog***
                                   ***grating***
ST
                     diffraction
                                                   recording polyester
     polyimide synthesis property
IT
     Polyimides, properties
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (polyester-; synthesis and properties of new poly(ester-imide)s from
        2,4-dihydroxy-4'-nitroazobenzene)
     Polyimides, properties
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (polyester-polyether-; synthesis and properties of new
        poly(ester-imide)s from 2,4-dihydroxy-4'-nitroazobenzene)
     Polyethers, properties
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (polyester-polyimide-; synthesis and properties of new
        poly(ester-imide)s from 2,4-dihydroxy-4'-nitroazobenzene)
     Polyesters, properties
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (polyether-polyimide-; synthesis and properties of new
        poly(ester-imide)s from 2,4-dihydroxy-4'-nitroazobenzene)
     Polyesters, properties
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (polyimide-; synthesis and properties of new poly(ester-imide)s from
        2,4-dihydroxy-4'-nitroazobenzene)
       ***Holographic***
                         diffraction
                                         ***gratings***
IT
         ***Holographic***
                             recording materials
        (synthesis and properties of new poly(ester-imide)s from
        2,4-dihydroxy-4'-nitroazobenzene for
                                               ***holog***
                                                            recording)
IT
     74-39-5P, 2,4-Dihydroxy-4'-nitroazobenzene
                                                  186248-20-4P
     RL: PRP (Properties); RCT (Reactant); SPN (Synthetic preparation); PREP
     (Preparation); RACT (Reactant or reagent)
        (synthesis and properties of new poly(ester-imide)s from
        2,4-dihydroxy-4'-nitroazobenzene)
IT ·
     187327-19-1P
                    639065-30-8P
                                   639065-31-9P
                                                  639065-36-4P
                                                                  639065-37-5P
     639065-43-3P
                    639065-60-4P
                                   639065-61-5P
                                                  639065-87-5P
                                                                  639065-92-2P
     639065-97-7P
                    639065-99-9P
                                   639066-03-8P
                                                  639066-07-2P
                                                                  639066-32-3P
     639066-45-8P
                    639066-65-2P
                                   639066-67-4P
                                                  639066-69-6P
                                                                  639066-71-0P
     639066-72-1P
                    639066-73-2P
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     639066-79-8P
                    639066-81-2P
                                   639066-82-3P
                                                  639066-83-4P
                                                                  639066-84-5P
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (synthesis and properties of new poly(ester-imide)s from
        2,4-dihydroxy-4'-nitroazobenzene)
IT
                                     95-54-5, 1,2-Phenylenediamine, reactions
     92-87-5, 4,4'-Diaminobiphenyl
     101-77-9, 4,4'-Methylenedianiline
                                         101-80-4, 4,4'-Diaminodiphenylether
     106-50-3, 1,4-Phenylenediamine, reactions
                                                 108-45-2, 1,3-
     Phenylenediamine, reactions
                                               ***Resorcinol***
                                  108-46-3,
                                                                  , reactions
     119-90-4, [1,1'-Biphenyl]-4,4'-diamine, 3,3'-dimethoxy
                                                              119-93-7,
     o-Tolidine
                  838-88-0, 4,4'-Methylenedi-o-toluidine
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Trimellitic anhydride acid chloride 2479-46-1 3102-87-2, 2,3,5,6-Tetramethyl-1,4-phenylenediamine 4073-98-7, 4,4'-Methylene 13680-35-8, 4,4'-Methylene bis(2,6bis (2,6-dimethylaniline) 54827-17-7, 3,3',5,5'-Tetramethylbenzidine diethylaniline) RL: RCT (Reactant); RACT (Reactant or reagent) (synthesis and properties of new poly(ester-imide)s from 2,4-dihydroxy-4'-nitroazobenzene) THERE ARE 26 CITED REFERENCES AVAILABLE FOR THIS RECORD RE.CNT 26 (1) Ahlheim, M; Macromol Chem Phys 1994, V195, P361 CAPLUS (2) Barrett, K; Macromolecules 1998, V31, P4845 (3) Blanche, P; Opt Commun 2000, V185, P1 CAPLUS (4) Boogers, J; Macromolecules 1994, V27, P205 CAPLUS (5) Buffeteau, T; Macromolecules 1988, V31, P7312 (6) Choi, D; Polym Bull 2001, V46, P395 CAPLUS (7) Cipparrone, G; J Opt Soc Am 2002, VB19, P1157 (8) Constantino, C; J Macromol Sci, Pure Appl Chem 2001, VA38, P1549 CAPLUS (9) Eastmond, G; Polymer 1993, V13, P2865 (10) Eastmond, G; React Funct Polym 1996, V30, P27 CAPLUS (11) Huang, T; J Opt Soc Am 1996, VB13, P282 (12) Jung, C; High Perform Polym 2000, V12, P205 CAPLUS (13) Lefin, P; Opt Mater 1998, V9, P323 CAPLUS (14) Meng, X; J Polym Sci, Part A: Polym Chem 1996; V34, P1461 CAPLUS (15) Naydenova, I; J Opt Soc Am 1998, VB15, P1257 (16) Sek, D; Synth Met 2002, V127, P89 CAPLUS (17) Sekkat, Z; J Appl Phys 1992, V71, P1543 CAPLUS (18) Tervo, J; Opt Commun 2001, V190, P51 CAPLUS (19) Todorov, T; Appl Opt 1984, V23, P4309 CAPLUS (20) Varnavski, O; Macromolecules 2000, V33, P4061 CAPLUS (21) Viswanathan, N; J Mater Chem 1999, V9, P1941 CAPLUS (22) Xu, Z; J Macromol Sci, Pure Appl Chem 2001, VA38, P1305 CAPLUS (23) Yang, S; J Macromol Sci, Pure Appl Chem 2001, VA38, P1345 CAPLUS (24) Yokoyama, S; Langmuir 1993, V9, P1086 CAPLUS (25) Yokoyama, S; Langmuir 1994, V10, P4599 CAPLUS (26) Yuxi, Z; Eur Polym J 2001, V37, P445 ANSWER 5 OF 15 CAPLUS COPYRIGHT 2006 ACS on STN 2003:527010 CAPLUS 139:264932 Entered STN: 10 Jul 2003 A novel quantitative structure-biodegradability relationship (QSBR) of substituted benzenes based on MHDV descriptor Liu, Yan; Liu, Shu-Shen; Cui, Shi-Hai; Cai, Shao-Xi School of Life Science, Southwest China Normal University, Chungking, 400715, Peop. Rep. China Journal of the Chinese Chemical Society (Taipei, Taiwan) (2003), 50(2), CODEN: JCCTAC; ISSN: 0009-4536 Chinese Chemical Society Journal English 60-1 (Waste Treatment and Disposal) \*\*\*holog\*\*\* . distance vector (MHDV) is used to characterize the structures of 51 substituted benzenes. Descriptors (29) from 91 MHDV ones have nonzero values where 3 descriptors have only 1 nonzero sample and 1 descriptor only 2 nonzero samples. A genetic algorithm is used to select an optimal combination of the variables from the remaining 25 nonzero descriptors. Then the optimal descriptors are used to relate to the relative biodegradability using multiple linear regression method. The 6-variable linear model developed has high quality where the correlation coeff. of estns. and the root mean square error of estns. are 0.9604 and 0.280, resp., and the correlation coeff. of predictions and the root mean square error of predictions for leave-one-out procedure are 0.9471 and 0.324, resp. quant structure biodegradability relationship substituted benzene; substituted benzene mol \*\*\*holog\*\*\* distance vector descriptor Wastewater treatment (biol.; novel quant. structure-biodegradability relationship of substituted benzenes based on mol. \*\*\*holog\*\*\* . distance vector descriptor) Algorithm Simulation and Modeling

RE

DN

ED

ΤI

ΑU

CS

so

PB

DT

LA

CC

AΒ

ST

IT

IT

```
(novel quant. structure-biodegradability relationship of substituted
        benzenes based on mol. ***holog*** . distance vector descriptor)
     62-23-7, 4-Nitrobenzoic acid 62-53-3, Aniline, occurrence
IT
     Benzoic acid, occurrence 69-72-7, Salicylic acid, occurrence 2-Nitrotoluene 88-74-4, 2-Nitroaniline 88-75-5, 2-Nitropher
                                                88-75-5, 2-Nitrophenol
     88-99-3, Phthalic acid, occurrence 95-48-7, 2-Hydroxytoluene, occurrence 95-51-2, 2-Chloroaniline 95-53-4, 2-Aminotoluene, occurrence 95-55-6,
                     95-57-8, 2-Chlorophenol 98-11-3, Benzenesulfonic acid,
     2-Aminophenol
                  98-48-6, 1,3-Benzene disulfonic acid 98-95-3, Nitrobenzene,
     occurrence
                  99-05-8, 3-Aminobenzoic acid 99-08-1, 3-Nitrotoluene
     occurrence
                                99-61-6, 3-Nitrobenzaldehyde
     99-09-2, 3-Nitroaniline
                                                                99-65-0,
     1,3-Dinitrobenzene 99-96-7, 4-Hydroxybenzoic acid, occurrence
                                                                         99-99-0,
                      100-01-6, 4-Nitroaniline, occurrence
                                                              100-02-7,
     4-Nitrotoluene
                                100-52-7, Benzaldehyde, occurrence
     4-Nitrophenol, occurrence
                                                                        104-15-4.
     4-Toluenesulfonic acid, occurrence
                                           106-44-5, 4-Hydroxytoluene,
                  106-47-8, 4-Chloroaniline, occurrence
                                                            106-48-9,
     occurrence
     4-Chlorophenol
                      106-49-0, 4-Aminotoluene, occurrence
                                                               108-39-4,
     3-Hydroxytoluene, occurrence
                                     108-42-9, 3-Chloroaniline
                                                                  108-43-0,
                     108-44-1, 3-Aminotoluene, occurrence
     3-Chlorophenol
                                                               108-46-3,
                         , occurrence
       ***Resorcinol***
                                         108-95-2, Phenol, occurrence
                                                                         118-92-3,
     2-Aminobenzoic acid
                          120-80-9, Pyrocatechol, occurrence
                                                                  121-57-3,
     Sulfanilic acid 121-91-5, Isophthalic acid, occurrence
                                                                  121-92-6,
     3-Nitrobenzoic acid
                          123-30-8, 4-Aminophenol
                                                      123-31-9, Hydroquinone,
     occurrence
                  150-13-0, 4-Aminobenzoic acid 552-16-9, 2-Nitrobenzoic acid
     552-89-6, 2-Nitrobenzaldehyde
                                     554-84-7, 3-Nitrophenol
                                                                 555-16-8,
     4-Nitrobenzaldehyde, occurrence 591-27-5, 3-Aminophenol
     RL: POL (Pollutant); OCCU (Occurrence)
        (novel quant. structure-biodegradability relationship of substituted
        benzenes based on mol.
                                  ***holog*** . distance vector descriptor)
              THERE ARE 23 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE.CNT
(1) Barros, A; Chemom Intell Lab Syst 1998, V40, P65 CAPLUS
(2) Boethling, R; Environ Sci Technol 1994, V28, P459 CAPLUS
(3) Cramer, R; J Am Chem Soc 1988, V110, P5959 CAPLUS
(4) Geladi, P; Anal Chim Acta 1986, V185, P1 CAPLUS
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(10) Kier, L; Pharm Res 1990, V7, P801 CAPLUS
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(14) Liu, S; J Chin Chem Soc, in press 2002, V49 CAPLUS
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(16) Parsons, J; Ecotoxicol Environ Safety 1990, V19, P212 CAPLUS
(17) Peijnenburg, W; Pure Appl Chem 1994, V66, P1931 CAPLUS
(18) Pitter, P; Biodegradability of organic substances in the aquatic
    environment 1990, P289
(19) Raymonda, J; J Hazard Mater 2001, VB84, P189
(20) Robinson, D; J Med Chem 1999, V42, P573 CAPLUS
(21) Rogers, D; J Chem Inf Comput Sci 1994, V34, P854 CAPLUS
(22) Tong, W; Abstr Pap Am Chem Soc 1997, V214(81-COMP)
(23) Tong, W; J Chem Inf Comput Sci 1998, V38, P669 CAPLUS
L15
     ANSWER 6 OF 15 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     2003:409513
                 CAPLUS
DN
     139:134467
ED
     Entered STN: 29 May 2003
TI
     Structural design of nonlinear optical chromophores for high-performance
     photorefractive polymers
ΑU
     Jung, Gyeong Bok; Honda, Kayoko; Mutai, Toshiki; Matoba, Osamu; Ashihara,
     Satoshi; Shimura, Tsutomu; Araki, Koji; Kuroda, Kazuo
CS
     Institute of Industrial Science, University of Tokyo, Tokyo, 153-8505,
SO
     Japanese Journal of Applied Physics, Part 1: Regular Papers, Short Notes &
     Review Papers (2003), 42(5A), 2699-2704
     CODEN: JAPNDE
PR
     Japan Society of Applied Physics
DT
     Journal
LΑ
     English
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38-3 (Plastics Fabrication and Uses)
     Section cross-reference(s): 73
     Photorefractive response rate in a polymer composite of
AB
     poly(N-vinylcarbazole)/2,4,7-trinitro-9-fluorenone, doped with
     2,5-dimethyl-4-(4'-nitrophenylazo)anisole (DMNPAA) is improved by
     modifying the structure of DMNPAA. We found that four kinds of modified
     DMNPAA with alkyl substituents have fast orientational response to an
     external elec. field and keep large anisotropy in polarizability.
     them, 4-butoxy-3-propyl-1-(4'-nitorophenylazo)benzene has the shortest
     reorientation time const. of 19 ms (E = 54 V/.mu.m) and photorefractive
     time const. of 80 ms (I = 2 \text{ W/cm}2, E = 54 \text{ V/.mu.m}) that are 2,300 times
     and 63 times faster than those of the DMNPAA composite. The mechanism of
     the fast reorientation in new polymer composites is investigated.
     fast reorientational response is achieved by the improvement of the
     dispersivity in the polymer composites and the decrease of the glass
     transition temp.
                         ***grating***
st
     photorefractivity
                                         optical gain nitroazobenzene deriv
     chromophore synthesis
IT
     Refractive index
        (nonlinear; structural design of nonlinear optical chromophores for
        high-performance photorefractive polymers)
IT
     Polarizability
        (of NLO chromophores; structural design of nonlinear optical
        chromophores for high-performance photorefractive polymers)
IT
     Four wave mixing
     Optical gain
     Photorefractive effect
     Photorefractive
                       ***gratings***
        (structural design of nonlinear optical chromophores for
        high-performance photorefractive polymers)
ΙT
     75-26-3, 2-Bromopropane
                               100-01-6, 4-Nitroaniline, reactions
     1-Bromobutane
                     110-46-3, Isoamyl nitrite
                                                 1809-10-5, 3-Bromopentane
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (dopant synthesis; structural design of nonlinear optical chromophores
        for high-performance photorefractive polymers)
IT
     74-39-5P, 4-(4'-Nitrophenylazo)
                                       ***resorcinol***
                                                             1435-64-9P,
     2,5-Dimethyl-4-(4'-nitrophenylazo)-phenol
                                                 2780-21-4P,
     4-(4'-Nitrophenylazo)-2-propylphenol
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (dopant synthesis; structural design of nonlinear optical chromophores
        for high-performance photorefractive polymers)
IT
     153800-56-7, 2,5-Dimethyl-4-(4'-nitrophenylazo)anisole
     RL: MOA (Modifier or additive use); PRP (Properties); USES (Uses)
        (dopant; structural design of nonlinear optical chromophores for
        high-performance photorefractive polymers)
IT
     568565-39-9P, 2,5-Dimethyl-1-(4'-nitrophenylazo)-4-isopropoxybenzene
     568565-40-2P, 2,5-Dimethyl-1-(4'-nitrophenylazo)-4-isopentoxybenzene
     568565-41-3P, 2,4-Dibutoxy-1-(4'-nitrophenylazo)benzene
                                                                568565-42-4P,
     4-Butoxy-3-propyl-1-(4'-nitrophenylazo)benzene
     RL: MOA (Modifier or additive use); PRP (Properties); SPN (Synthetic
     preparation); PREP (Preparation); USES (Uses)
        (dopant; structural design of nonlinear optical chromophores for
        high-performance photorefractive polymers)
IT
     25067-59-8, Poly(N-vinylcarbazole)
     RL: POF (Polymer in formulation); PRP (Properties); USES (Uses)
        (polymer matrix; structural design of nonlinear optical chromophores
        for high-performance photorefractive polymers)
TT
     129-79-3, 2,4,7-Trinitrofluorenone
     RL: MOA (Modifier or additive use); USES (Uses)
        (structural design of nonlinear optical chromophores for
        high-performance photorefractive polymers)
RE.CNT
              THERE ARE 14 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE
(1) Bitner, B; Appl Opt 1998, V37, P2843
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(4) Kippelen, B; Science 1998, V279, P54 CAPLUS
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(6) Meerholz, K; Nature 1994, V371, P497 CAPLUS
(7) Moerner, W; Chem Rev 1994, V94, P127 CAPLUS
(8) Moerner, W; J Opt Soc Am B 1994, V22, P320
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(9) Nagayama, N; Mol Cryst Liq Cryst 1999, V327, P19 CAPLUS
(10) Rahn, M; J Appl Phys 2000, V87, P627 CAPLUS
(11) Sandalphon; Appl Opt 1996, V35, P2346 CAPLUS
(12) Volodin, B; Nature 1996, V383, P58 CAPLUS
(13) Volodin, B; Opt Eng 1995, V34, P2213 CAPLUS
(14) Wright, D; Appl Phys Lett 1998, V73, P1490 CAPLUS
    ANSWER 7 OF 15 CAPLUS COPYRIGHT 2006 ACS on STN
L15
     1989:76955 CAPLUS
AN
     110:76955
DN
     Entered STN: 04 Mar 1989
ED
                                           interferometry and acoustic emission
     Combined use of ***holographic***
TI
     to study the fracture mechanism of adhesive joints
     Koval'chuk, S. L.; Shtan'ko, A. E.
ΑU
     Mosk. Lesotekh. Inst., Moscow, USSR
CS
     Defektoskopiya (1988), (11), 90-3
SO
     CODEN: DEFKAG; ISSN: 0130-3082
DT
     Journal
     Russian
LA
     38-3 (Plastics Fabrication and Uses)
CC
     Section cross-reference(s): 43
       ***Holog*** . interferometry and acoustic emission (AE) were used to
AB
     study the adhesive strength of pinewood toothed joints with FRF-50 (
       ***resorcinol*** -PhOH-HCHO copolymer) under tensile loading. The
     initial AE signals during joint deformation were registered at .apprx.0.1
     of the fracture load (Pp), and their rate increased at .apprx.0.3 Pp due
     to the formation of microcracks at sites with increased initial stress
     concn. were obsd. at 0.6 Pp in form of concentric interference bands.
     Thus, the stress concentrator zones in the tooth apex are the main causes
     for fracture and the sources of AE signals.
                                               ***holog***
     fracture mechanism adhesive joint wood;
                                                             interferometry
     fracture adhesive joint; acoustic emission fracture adhesive joint
IT
        (joints, of toothed wood parts with phenolic adhesive, fracture
        mechanism of, ***holog*** . interferometry and acoustic emission in
        study of)
IT
        (pine, adhesive joints of toothed parts of, with phenolic adhesive,
        fracture mechanism of,
                               ***holog*** . interferometry and acoustic
        emission in study of)
IT
     25986-71-4, FRF 50
     RL: USES (Uses)
        (adhesive, toothed wood parts bonded with, fracture mechanism of,
          ***holog*** . interferometry and acoustic emission in study of)
    ANSWER 8 OF 15 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     1981:4309 CAPLUS
DN
     94:4309
ED
     Entered STN: 12 May 1984
         ***holographic***
                            correlometer with phase modulation for the study
     of viscous and superviscous light-scattering media
ΑU
     Gurari, M. L.; Magomedov, A. A.; Sakharov, V. K.; Davydova, A. B.;
     Bel'govskii, I. M.; Enikolopyan, N. S.
CS
     Inst. Khim. Fiz., Moscow, USSR
SO
     Vysokomolekulyarnye Soedineniya, Seriya A (1980), 22(8), 1900-4
     CODEN: VYSAAF; ISSN: 0507-5475
דת
     Journal
LA
    Russian
CC
     35-5 (Synthetic High Polymers)
     Section cross-reference(s): 73
AB
         ***holog*** . correlometric method is described for studying the
     scattering of light by the extremely slow motion of individual scattering
     centers or by the collective motion in a viscous scattering medium. The
    parameter measured is the autocorrelation function of a scattered field.
     The method was used for measuring the correlation times of relaxation in
     crosslinked
                  ***resorcinol***
                                     diglycidyl ether-m-phenylenediamine
     copolymer [66485-73-2] in a glassy state.
       ***holog***
ST
                    correlometry light scattering; epoxy resin light
     scattering; relaxation polymer light scattering
       ***Holography***
ΙT
        (correlometric, light scattering by viscous media in relation to)
IT
    Relaxation
```

```
(in viscous polymers, light scattering with ***holog***
        correlometry in detn. of)
IT
     Polymers, properties
     RL: PRP (Properties)
        (light scattering by viscous,
                                       ***holog***
                                                     . correlometric
        measurement of)
     Epoxy resins, properties
IT
     RL: USES (Uses)
        (relaxation in, light scattering with
                                                ***holog***
                                                             . correlometry in
        detn. of)
IT
        (scattering of, by viscous media, ***holog*** . correlometry in)
IT
     66485-73-2
     RL: USES (Uses)
        (relaxation in, light scattering with ***holog***
                                                             . correlometry in
        detn: of)
    ANSWER 9 OF 15 CAPLUS COPYRIGHT 2006 ACS on STN
     1965:406694 CAPLUS
AN
DN
     63:6694
OREF 63:1209h,1210a-d
     Entered STN: 22 Apr 2001
ΤI
     Spectrographic determination of rare earth elements
AU
     Kul'skaya, O. A.
     Tr. Inst. Geol. Nauk, Akad. Nauk Ukr. SSR, Ser. Petrogr., Mineralog. i
SO
    Geokhim. (1964), No. 21, 76-120
DT
     Journal
    Russian
LA
CC
     2 (Analytical Chemistry)
     Flame-photometric, spectrophotometric, x-ray spectrographic, fluorescent,
AΒ
     luminescent, neutron activation, mass spectroscopic, chromatographic,
    polarographic, and emission spectrographic detns. of rare earth elements
     are compared. The advantages of the emission spectrographic analysis are:
     speed, high sensitivity, sufficient accuracy, and universality. The
     extreme complexity of the rare earths spectra necessitates a spectrograph
     of large dispersion such as KS-55, KSA-1 (at 2500-3500 A.), ISP-51 with
     the glass optics (in the visible region), and
                                                    ***grating***
     instruments DFS-3 and DFS-13. D.c., a.c., and high-frequency arc
     excitation are employed. For the detn. of the rare earth elements, Ce,
     La, Sm, Nd, Y, Yb, Ba, Fe, Mo, Sr, Mg, Sc, and Zr can be used as an
     internal standard. In this paper Zr is proposed as an internal standard
     in the uv region. The anal. line pairs are as follows: La 2610.34/Zr
     2567.64, La 3245.12/Zr 3182.86, Y 3179.42/Zr 3182.858, Y 3200.27/Zr
     3182.858, Nd 3328.27/Zr 3182.858, Nd 3328.27/background, Sm 3183.92/Zr
     3182.858, Sm 3183.92/background, Pr 3172.27/Zr 3182.858, Lu 2615.42/Zr
     2567.64, Tb 3324.40/Zr 3182.858, Ce 3063.01/Zr 3182.858, Ce
     3063.01/background, Gd 3032.85/Zr 3182.858, Gd 2796.94/Zr 2722.61, Er
     2910.36/Zr 2722.61, Eu 2727.78/Zr 2722.61, Yb 2891.38/Zr 2722.61, Yb
     3289.37/Zr 3182.858, Dy 3319.89/Zr 3182.858, Tm 2869.22/Zr 2722.61, and Ho
     3425.35/Zr 3182.858 A. Content of 1% and less of the base elements causes
    no interferences, hence, the samples are dild. (1:10-1:20) with C powder.
    The C powder is also added to decrease the effect of sample compn. and to
     stabilize burning of the arc. The volatilization curves corresponding to
    volatilization direct from minerals and to that from the total rare earth
    oxides are given. For the detn. of the rare earth elements their oxides
    were purified to remove Th (interference). Standards and samples were
    mixed (1:10) with the C powder and the resulting mixt. was mixed (1:1)
    with the internal standard prepd. from ZrO2; 3 series of standards were
    used. A KSA-1 spectrograph was used at 2500-3500 A. under the following
     conditions: crater, 2.5 mm. deep and 2.5 mm. in diam.; d.c. arc current 10
     amp.; slit 0.008 mm.; arc gap 2 mm.; exposure time 3 min. Procedure
     applies to the following concns.: La 0.1-3, Ce 0.3-3, Nd 0.3-3, Pr 0.3-1,
     Sm 0.1-1, Gd 0.03-1, Y 0.03-3, Er 0.01-0.5, Yb 0.01-0.5, Eu 0.01-0.5, Dy
     0.03-1, Tb 0.03-1, Tm 0.03-1, Ho 0.03-1, and Lu 0.01-1%. The relative
     error in the detns. averages .+-.12 for Ce and Nd and .+-.5% for the other
    rare earth elements. 100 references.
IT
    Rare earth metals
        (analysis, detn., spectrographic)
IT
    7440-00-8, Neodymium
        (analysis, 4-(2-pydridylazo) ***resorcinol***
                                                         in, spectrographic)
IT
    7429-91-6, Dysprosium 7439-91-0, Lanthanum 7439-94-3, Lutetium
     7440-10-0, Praseodymium 7440-19-9, Samarium 7440-27-9, Terbium
```

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7440-30-4, Thulium 7440-45-1, Cerium 7440-52-0, Erbium
                                                                 7440-53-1,
              7440-54-2, Gadolinium 7440-60-0, Holmium
     Europium
                                                            7440-64-4,
     Ytterbium
                7440-65-5, Yttrium
        (analysis, detn., spectrographic)
    ANSWER 10 OF 15 CAPLUS COPYRIGHT 2006 ACS on STN
     1964:35783 CAPLUS
     60:35783
OREF 60:6344e-f
     Entered STN: 22 Apr 2001
              ***grating***
                               spectrophotometer for far-infrared (40-
     A narrow
     150.mu.)
     Lorenzelli, Vincenzo; Randi, Giuseppe; Gesmundo, Francesco
     C.N.R., Genoa
     Annali di Chimica (Rome, Italy) (1963), 53(3), 213-23
     CODEN: ANCRAI; ISSN: 0003-4592
     Journal
     Italian
     10 (Spectra and Some Other Optical Properties)
    A spectrophotometer is described for use in the far-infrared region.
     Interference from atm. H2O vapor is eliminated through the use of a dry
     box. Absorption spectra of some solid and liquid org. compds., (PhOH,
       ***resorcinol*** , urea, glycine, HCO2Me, AcOMe, etc.) are presented and
     discussed.
     Spectrophotometers
        (infrared)
     Spectra, infrared
        (of org. compds.)
                      57-13-6, Urea 62-56-6, Urea, thio- 64-18-6, Formic
     56-40-6, Glycine
           79-20-9, Acetic acid, methyl ester 108-46-3, ***Resorcinol***
     108-95-2, Phenol
                      120-80-9, Pyrocatechol 149-32-6, Erythritol
     471-46-5, Oxamide
                       3225-29-4, Hydroquinone, semiquinone
        (spectrum of)
    ANSWER 11 OF 15 CAPLUS COPYRIGHT 2006 ACS on STN
     1962:433024 CAPLUS
     57:33024
OREF 57:6595f-i
     Entered STN: 22 Apr 2001
     Evaluation of flame photometry for the determination of elements of the
     rare earth group
     Meni, Oscars
     Oak Ridge Natl. Lab., Oak Ridge, TN
    U.S. At. Energy Comm. (1959), Volume CF-59-8-141, 20 pp.
     From: Nucl. Sci. Abstr. 14, Abstr. No. 16610(1960).
     Report
    Unavailable
     2 (Analytical Chemistry)
     Flame spectra are presented of all rare earth elements, except Ce and Pm,
     and of the closely related elements, Sc and Y. The precise wavelength and
     relative spectral intensity of each line and band, as well as the band
     width of all bands, are tabulated. In addn., the major bands and lines of
     each element are listed sep., together with the half-band width of all
     bands. Also included are the relative spectral interferences of other
     elements of the group studied, with the emissivity measurements of the
    bands and lines listed. The wavelengths of band crests and lines were
     fixed from spectral data recorded photographically with a prism
     spectrograph. The remaining data are based on the spectra of the several
                                                            ***grating***
     elements which were recorded with a high-sensitivity,
     flame spectrophotometer. Details of operating conditions are given. La,
     Yb, and Nd can be detd. without spectral interference by other elements of
     the group studied. For all other elements of the group, some spectral
     interference is encountered. Nevertheless, by judicious selection of
     wavelength, certain of the elements can be detd. flame photometrically in
     the presence of many others without serious interference.
    Rare earth metals
        (analysis, detn., spectrophotometric)
     7440-00-8, Neodymium
        (analysis, 4-(2-pydridylazo) ***resorcinol***
        spectrophotometric)
                           7440-64-4, Ytterbium
     7439-91-0, Lanthanum
        (analysis, detn., spectrophotometric)
```

L15 AN

DN

ED

ΤI

ΑU CS

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LA

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IT

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CS SO

DT

LA

CC

AB

IT

IT

IT

AB .

```
7439-91-0, Lanthanum
IT
     7429-91-6, Dysprosium
                                                    7439-94-3, Lutetium
                            7440-10-0, Praseodymium 7440-19-9, Samarium
     7440-00-8, Neodymium
                           7440-27-9, Terbium
                                               7440-30-4, Thulium
     7440-20-2, Scandium
                                                                     7440-52-0,
                                    7440-54-2, Gadolinium 7440-60-0, Holmium
              7440-53-1, Europium
     Erbium
     7440-64-4, Ytterbium
        (spectrum of)
    ANSWER 12 OF 15 CAPLUS COPYRIGHT 2006 ACS on STN
L15
AN
     1961:123431 CAPLUS
DN
     55:123431
OREF 55:23170f-h
ED
     Entered STN: 22 Apr 2001 .
     Spectrometric determination of carbon and phosphorus in steels and cast
TI
     irons without special atmospheres
ΑU
     Giavino, A.
     Optica S.p.A., Milan
ĆS
     Metallurgia Italiana (1961), 53, 229-32
SO
     CODEN: MITLAC; ISSN: 0026-0843
DT
     Journal
     Unavailable
LA
     7 (Analytical Chemistry)
CC
     Sufficient dispersion and resolution for C and P analysis in Fe alloys can
AB
                                ***grating***
     be obtained with a plane
                                               of 1200 lines/mm. in stigmatic
     mounting on a 2-m. spectrometer without necessitating a special protective
           The spectral range is located in conventional ultraviolet wave
     lengths, C 2296.89, Fe 2739.5, Mn 2705.7, Si 2516, P 2149.11, Cu 2218.1,
     Ni 2253.9, Cr 2677.1, Al 3082.1, and Sn 3262.3 A. Special attention is
     qiven to the optimum conditions of excitation and to the counterelectrode
     (Aq for C detn.). With good samples, up to 4.5% C in cast iron can be
     detd.
       ***Resorcinol***
                        , 5-methyl-2(or 4)-(p-nitrophenylazo)-
IT
        (in beryllium detn.)
IT
     7439-89-6, Iron
        (alloys; analysis of, for C and P)
IT
     7440-44-0, Carbon
                         7723-14-0, Phosphorus
        (analysis, detn. in Fe and steel)
IT
     7440-41-7, Beryllium
        (analysis, detn. in air)
IT
     7439-89-6, Iron
        (analysis, detn. of C and P in cast iron and steel)
     ANSWER 13 OF 15 CAPLUS COPYRIGHT 2006 ACS on STN
L15
AN
     1954:27774 CAPLUS
DN
     48:27774
OREF 48:4977b-c
ED
     Entered STN: 22 Apr 2001
TI
     The OH-vibration frequencies of carboxylic acids and phenols
ΑU
     Goulden, J. D. S.
CS
     Boots Pure Drug Co., Nottingham, UK
     Spectrochimica Acta (1954), 6, 129-33
SO
     CODEN: SPACA5; ISSN: 0038-6987
DT
     Journal
LA
     Unavailable
     3 (Electronic Phenomena and Spectra)
CC
         ***grating***
                        spectrometer was used to measure the infrared OH
AΒ
     frequencies of 49 carboxylic acids and 18 phenols, both in CCl4 solns.
     The frequencies range from 3504 to 3614 cm.-1 .+-. 1 cm.-1 All the values
     for phenols fell on a straight line, enabling approx. pKa, dissocn.
     consts. to be found from detns. of OH frequencies. The values for the
     carboxylic acids fell on 3 straight lines so that it is necessary to det.
     first the type of carboxylic acid, from infrared or other data, before
     approx. pKa values can be predicted from infrared measurements of OH
     frequencies.
ΙT
     Acids
        (hydroxyl group vibration frequencies in org.)
IT
     Phenols
        (hydroxyl-group vibration frequencies in)
IT
     Spectra
        (of hydroxyl group, in acids and phenols)
IT
     Hydroxyl group
        (vibrations of, in acids and phenols)
IT
     Propionic acid, (p-nitrophenyl) -
```

```
(spectrum of)
     62-23-7, Benzoic acid, p-nitro- 74-11-3, Benzoic acid, p-chloro-
IT
     99-06-9, Benzoic acid, m-hydroxy- 99-96-7, Benzoic acid, p-hydroxy-
     100-02-7, Phenol, p-nitro- 100-83-4, Benzaldehyde, m-hydroxy- 106-48-9, Phenol, p-chloro- 108-43-0, Phenol, m-chloro- 121-92-6,
    Benzoic acid, m-nitro- 123-08-0, Benzaldehyde, p-hydroxy- 535-80-8, Benzoic acid, m-chloro- 554-84-7, Phenol, m-nitro- 940-31-8, Propionic
     acid, 2-phenoxy-
                      7170-38-9, Propionic acid, 3-phenoxy-
        (spectra of)
                           64-69-7, Acetic acid, iodo-
                                                           75-98-9, Pivalic acid
IT
     64-19-7, Acetic acid
     76-03-9, Acetic acid, trichloro- 76-05-1, Acetic acid, trifluoro-
     79-08-3, Acetic acid, bromo- 79-11-8, Acetic acid, chloro- 79-43-6,
    Acetic acid, dichloro-
                              80-58-0, Butyric acid, 2-bromo- 80-59-1, Tiglic
            86-55-5, 1-Naphthoic acid 89-83-8, Thymol
                                                          90-15-3, 1-Naphthol
     93-07-2, Veratric acid 93-09-4, 2-Naphthoic acid
                                                           95-65-8, 3,4-Xylenol
     95-87-4, 2,5-Xylenol 98-89-5, Cyclohexanecarboxylic acid 100-09-4,
     p-Anisic acid 103-82-2, Acetic acid, phenyl-
                                                     104-03-0, Acetic acid,
                                                         ***Resorcinol***
     (p-nitrophenyl) - 106-44-5, p-Cresol 108-46-3,
     108-95-2, Phenol
                      110-44-1, Sorbic acid 117-34-0, Acetic acid,
                122-59-8, Acetic acid, phenoxy- 123-30-8, Phenol, p-amino-
     124-07-2, Octanoic acid
                              135-19-3, 2-Naphthol
                                                      150-13-0, Benzoic acid,
     p-amino- 150-76-5, Phenol, p-methoxy- 372-09-8, Acetic acid, cyano-
     492-38-6, Atropic acid
                            532-32-1, Benzoic acid, sodium salt
     Cinnamic acid, m-nitro- 590-92-1, Propionic acid, 3-bromo- 590-93-2,
     Tetrolic acid
                     595-91-5, Acetic acid, triphenyl-
                                                        619-84-1, Benzoic
     acid, p-dimethylamino- 621-82-9, Cinnamic acid 625-45-6, Acetic acid,
               637-44-5, Propiolic acid, phenyl- 767-00-0, Benzonitrile,
     methoxy-
                  830-09-1, Cinnamic acid, p-methoxy- 1552-94-9,
    p-hydroxy-
     2,4-Pentadienoic acid, 5-phenyl-
                                       1689-82-3, Phenol, p-phenylazo-
     1727-53-3, Cinnamic acid, .alpha.-bromo- 1798-11-4, Acetic acid,
                        3724-65-0, Crotonic acid
                                                   7400-08-0, Cinnamic acid,
     (p-nitrophenoxy) -
     p-hydroxy- 29720-22-7, Propionic acid, phenyl-
        (spectrum of)
L15
    ANSWER 14 OF 15 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     1947:14824 CAPLUS
     41:14824
OREF 41:2994c-f
     Entered STN: 22 Apr 2001
     A recording vacuum- ***grating***
TΙ
                                          spectrometer for the infrared
     Bell, E. E.; Noble, R. H.; Nielsen, H. H.
ΑU
CS
     Ohio State Univ., Columbus
     Review of Scientific Instruments (1947), 18, 48-56
SO
     CODEN: RSINAK; ISSN: 0034-6748
DT
     Journal
LA
     Unavailable
CC
     3 (Subatomic Phenomena and Radiochemistry)
     cf. C.A. 41, 1504i. The vacuum chamber is made of 1/4-in. steel plate
     base and wall with a cast steel top with a flange on the under side which
     fits into a groove in the top of the tank. The spectrometer rests on 3
     leveling screws which turn on extensions of the 3 feet which support the
     tank. The radiation source is a Nernst filament so ballasted that the
     glower power is practically independent of line and glower fluctuations.
     The recording system consists of four units: relay, amplifier and power
     supply, control panel, and recorder. Infrared energy received by a
     thermocouple, after passing through the spectrometer, activates a
     galvanometer, which in turn activates a photocell circuit. This current
     is recorded by an Esterline-Angus 5-ma. recording milliameter or a Leeds
     and Northrup Speedomax recorder. The region covered is from 1 to 20
     microns. The fundamental absorption band of HCl is given showing the
     sepn. of the lines from the two isotopes in the fundamental band obtained
     in the first order. A record of the 2.7-micron band in water vapor is
            The sepn., in the first-order spectrum, of the rotational lines of
     the 4.3 micron band of CO2 is also shown.
IT
        (infrared, recording vacuum- ***grating*** )
IT
        (of fluoromethane)
IT
     593-53-3, Methane, fluoro-
        (spectrum of)
IT
     7647-14-5, Sodium chloride
        (spectrum of
                       ***resorcinol***
```

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L15 ANSWER 15 OF 15 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     1928:27091 CAPLUS
DN
     22:27091
OREF 22:3168d-g
ED
     Entered STN: 16 Dec 2001
     Some new procedures for obtaining hemin derivatives. I
TΙ
ΑU
     Schumm, O.
     Z. physiol. Chem. (1928), 176, 122-6
SO
     Journal
DT
     Unavailable
LA
CC
     10 (Organic Chemistry)
     Although hemin loses Fe and yields porphyrin when boiled with AcCO2H
AB
     alone, a mixt. of PhNH2 and Acco2H or N2H4.H2O does not convert it into
     porphyrin but merely saturates the side chains. The product gives the
     spectrum of mesohemin. Treatment of this with N2H4-AcOH removes the Fe
     with formation of mesoporphyrin. An Fe-porphyratin corresponding
     spectroscopically to the above intermediate may be obtained by boiling a
     soln. of hemin in PhNH2 with AcOH and Fe powder. If hemin is boiled with pure N2H4.H2O such transformation does not occur. The reaction takes
     place when N2H4.H2O is added to hemin in boiling p-toluidine or PhOH, or
     to a boiling suspension of hemin in glycerol, glycol, AmOH, olive oil or
     liquid paraffin, or when hemin is heated with N2H4.H2O under pressure at
     200.degree.. Hemin undergoes a characteristic alteration when melted with
                     ***resorcinol*** . At first a product is formed which
     pyrogallol or
     behaves spectroscopically like meso-hemin. Further heating yields an
     Fe-porphyratin which behaves like the Fe complex of copratoporphyrin.
     progress of this 2-stage reaction can be followed accurately by means of a
       ***grating*** spectrometer. On removal of the Fe by N2H4.AcOH a
     porphyrin is then obtained which shows all the properties of
     copratoporphyrin. The above chem. method represents a distinct advance
     over the tedious and unpleasant prepn. of copratoporphyrin by means of
     bacterial putrefaction.
IT
     16009-13-5, Hemin
        (derivs., prepn. of)
IT
     448-65-7, Deuteroporphyrin 493-90-3, Mesoporphyrin
        (prepn. of)
=> s l1 and (waveguide)
) IS NOT A RECOGNIZED COMMAND
The previous command name entered was not recognized by the system.
For a list of commands available to you in the current file, enter
"HELP COMMANDS" at an arrow prompt (=>).
=> s l1 and (waveguide)
         44400 WAVEGUIDE
         34914 WAVEGUIDES
         50896 WAVEGUIDE
                 (WAVEGUIDE OR WAVEGUIDES)
L16
             3 L1 AND (WAVEGUIDE)
=> d all 1-3
L16 ANSWER 1 OF 3 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     2004:669744 CAPLUS
DN
     141:184209
ED .
     Entered STN: 17 Aug 2004
ΤI
     Integrated optical ***waveguide***
IN
     Boss, Pamela A.; Lieberman, Stephen H.
PA
     United States Dept. of the Navy, USA
SO
     U.S., 13 pp., Cont.-in-part of U.S. 6,406,777.
     CODEN: USXXAM
DT
     Patent
LΑ
     English
     ICM G01N021-65
TC
INCL 422082110; 356301000
     79-2 (Inorganic Analytical Chemistry)
     Section cross-reference(s): 61, 73, 80
FAN.CNT 6
     PATENT NO.
                         KIND
                                DATE
                                             APPLICATION NO.
                                                                    DATE
                         ----
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                                             -----
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В1
                                20040817
                                            US 2002-97765
                                                                   20020313
     US 6776962
PΙ
                         B1
                                20020618
                                           US 2000-593675
                                                                  20000614
     US 6406777
PRAI US 2000-593675
                         A2
                                20000614
CLASS
 PATENT NO.
                CLASS PATENT FAMILY CLASSIFICATION CODES
                ----
 -----
                ICM
                       G01N021-65
 US 6776962
                        422082110; 356301000
                 INCL
                 IPCI
                        G01N0021-65 [ICM, 7]
                NCL
                        422/082.110; 356/301.000
                        C03C017/38; G01N033/543K2; G01N033/552
                 ECLA
                        B32B0015-00 [ICM,7]; B32B0015-20 [ICS,7]; B32B0003-00
                 IPCI
 US 6406777
                        [ICS, 7]
                 NCL
                        428/209.000; 428/201.000; 428/203.000; 428/210.000;
                        428/426.000; 428/672.000; 428/673.000; 428/674.000
                        C03C017/38; G01N033/543K2; G01N033/552
                 ECLA
                            ***waveguide***
                                             sensor system includes: an
AΒ
     An integrated optical
     optical ***waveguide*** having a monolithic and roughened metallic
     layer on which a self-assembled monolayer is formed; an optical energy
     source for generating an optical excitation signal; and a spectrometer for
     detecting spectra of optical energy emitted from the optical
       ***waveguide*** . The ***waveguide***
                                                 facilitates multiple SERS
     responses resulting from interactions between the optical excitation
     signal and an analyte of interest that may be present on the surface of
     the self-assembled monolayer. Thus, the sensor system provides a sensor
     for detecting org. contaminants with a sensitivity of ppm and even ppb in
     some cases. By varying the thiol used for forming the self-assembled
     monolayer different analytes, such as VOCs, nitrate and sulfate anions,
     heavy metal ions and alkali metals, can be detected.
     integrated optical ***waveguide***
st
                                          sensor system
IT
     Optical filters
        (bandpass; integrated optical ***waveguide***
                                                          sensor system)
IT
     Fiber optic sensors
     Glass substrates
     Raman spectrometers
     SERS (Raman scattering)
     Self-assembled monolayers
     Surface roughness
        (integrated optical
                            ***wavequide*** sensor system)
IT
     Borosilicate glasses
     Thiols, uses
     RL: DEV (Device component use); USES (Uses)
        (integrated optical
                             ***waveguide***
                                              sensor system)
IT
     Optical ***waveguides***
        (integrated; integrated optical
                                         ***waveguide*** sensor system)
IT
     Metals, uses
     RL: DEV (Device component use); USES (Uses)
        (layer; integrated optical ***wavequide***
                                                      sensor system)
IT
     107-03-9, 1-Propanethiol 156-57-0, Cysteamine hydrochloride
     1141-59-9D, 4-(2-Pyridylazo) ***resorcinol*** , disulfide modified
     7440-22-4, Silver, uses 7440-50-8, Copper, uses
                                                       7440-57-5, Gold, uses
     14187-32-7D, Dibenzo 18-crown-6, thiol derivs.
                                                    60676-86-0, Vitreous
     silica
     RL: DEV (Device component use); USES (Uses)
        (integrated optical
                             ***waveguide***
                                              sensor system)
              THERE ARE 8 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE.CNT
RE
(1) Boss, P; Applied Spectroscopy 2000, V54(8), P1126
(2) Burgess; US 5082629 A 1992 CAPLUS
(3) Heyns, J; Anal Chem 1994, V66, P1572 CAPLUS
(4) Hubbel; US 20020128234 A1 2002
(5) Sheehy; US 5527712 A 1996 CAPLUS
(6) Tarcha; US 5266498 A 1993 CAPLUS
(7) Vo-Dinh; US 5814516 A 1998 CAPLUS
(8) Xu, W; Opt Soc American Technical Digest 1995, V21, P378
L16 ANSWER 2 OF 3 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     2004:633307 CAPLUS
DN
     141:166768
ED
     Entered STN: 06 Aug 2004
     Synthesis, spectroscopy, and photophysics of multi-chromophoric Zn(II)
     Group 8 metal complexes
```

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SO
    U.S. Pat. Appl. Publ., 40 pp.
    CODEN: USXXCO
DТ
    Patent
LA
    English
    ICM C08L001-00
IC
INCL 524543000; 524556000; 546002000; 548402000
     78-7 (Inorganic Chemicals and Reactions)
     Section cross-reference(s): 26, 72, 73, 74
FAN.CNT 1
                                        APPLICATION NO.
                                                            DATE
    PATENT NO.
                      KIND
                              DATE
                                          -----
                                                                 ------
     -----
                        ____
                              -----
PI US 2004152826
PRAI US 2002-368493P
                               20040805 US 2003-403387
                        A1
                                                               20030328
                       P
                              20020328
CLASS
 PATENT NO.
               CLASS PATENT FAMILY CLASSIFICATION CODES
                ____
 _____
                       C08L001-00
 US 2004152826 ICM
                       524543000; 524556000; 546002000; 548402000
                INCL
                       C08L0001-00 [ICM,7]
                IPCI
                NCL 
                       524/543.000
                ECLA
                       C07D487/22+257E+209C+209C+209C+209C
os
    MARPAT 141:166768
GΙ
/ Structure 2 in file .gra /
     Novel multichromophoric complexes comprising R1-RA-[MC]-([RM]z-[MC])m-RA-
     R2 [MC = conjugated macrocycle; RA = covalent bond, C2-C20 alkenyl or
     alkynyl, C4-C14 cumulenyl; RM = C1-C20 alkyl, C2-C20 alkenyl or alkynyl,
     C4-C14 cumulenyl, C3-C50 aryl, and various arylalkynyl, heterocycloalkyl,
     heteroaryl, etc.; R1 = H, halo, protecting group, etc.; m = 0-50, z = 0 or
     1) and their metal complexes, are provided. Polymeric compns. and devices
     comprising the same are also discussed. The complexes are characterized
     by a central bridging moiety comprising one or a plurality of linked
     conjugated macrocyclic mols. [MC] coupled to at least one inorg. moiety
     (R1 and/or R2 ) through org. linker RA. Prepn. methods include
     metal-mediated cross-coupling techniques. The complexes can be useful in
     nonlinear optical devices and other optoelectronic applications. The
     UV-visible spectra, cyclic voltammetry, and mol. first order
     hyperpolarizability of some prepd. example compds. of the invention, e.g.,
     ethynyl-bridged ruthenium(II)/osmium(II) terpyridine zinc porphyrinato
     complexes I(PF6)2 (M = Ru, Os), are measured.
     zinc porphyrin Group 8 metal terpyridine ethynyl linked prepn; NLO zinc
ST
     porphyrin Group 8 metal terpyridine multichromophoric; optoelectronic zinc
     porphyrin Group 8 metal terpyridine multichromophoric; electrochem redox
     zinc porphyrin Group 8 metal terpyridine multichromophoric; polymer zinc
     Group 8 metal multichromophoric complex optoelectronic application
IT
     Group VIII element complexes
     RL: DEV (Device component use); PRP (Properties); SPN (Synthetic
     preparation); PREP (Preparation); USES (Uses)
        (Group 8; prepn., UV-visible spectra, and mol. first-order
        hyperpolarizability of multichromophoric zinc(II) Group 8 metal
        complexes for nonlinear optical devices and optoelectronic
        applications)
IT
     Redox reaction
        (electrochem.; of multichromophoric ethynyl-linked zinc(II)
       porphyrinato Group 8 metal terpyridine complexes)
IT
     Nonlinear optical materials
        (ethynyl-linked zinc(II) porphyrinato Group 8 metal terpyridine
        complexes and related multichromophoric complexes for NLO devices)
TT
     Holographic recording materials
     Optical detectors
     Optical limiting
     Optical
              ***waveguides***
     Photorefractive materials
        (ethynyl-linked zinc(II) porphyrinato Group 8 metal terpyridine
```

Therien, Michael J.; Uyeda, Harry Tetsuo

The Trustees of the University of Pennsylvania, USA

IN

PA

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complexes and related multichromophoric complexes for NLO devices and
        other optoelectronic applications)
IT
     Photoelectric devices
        (ethynyl-linked zinc(II) porphyrinato Group 8 metal terpyridine
        complexes and related multichromophoric complexes for optoelectronic
        applications)
IT
     Optical hyperpolarizability
        (mol. first-order hyperpolarizability of ethynyl-bridged
        ruthenium(II)/osmium(II) terpyridine zinc porphyrinato complexes and
        related multichromophoric zinc(II) Group 8 metal complexes)
     UV and visible spectra
IT
        (of multichromophoric ethynyl-linked zinc(II) porphyrinato Group 8
        metal terpyridine complexes)
ΙT
     Optical instruments
        (phase shifters; ethynyl-linked zinc(II) porphyrinato Group 8 metal
        terpyridine complexes and related multichromophoric complexes for NLO
        devices and other optoelectronic applications)
IT
     Fluoropolymers, uses
     Polyamic acids
     Polycarbonates, uses
     Polyesters, uses
     Polyimides, uses
     Polyolefins
     Polyurethanes, uses
     RL: DEV (Device component use); USES (Uses)
        (polymer compns. contq. ethynyl-linked zinc(II) porphyrinato Group 8
        metal terpyridine complexes and related multichromophoric complexes for
        NLO devices and other optoelectronic applications)
IT
     Porphyrins
     RL: DEV (Device component use); RCT (Reactant); SPN (Synthetic
     preparation); PREP (Preparation); RACT (Reactant or reagent); USES (Uses)
        (prepn. of ethynyl-linked porphyrins and related multichromophoric
        complexes for NLO devices and other optoelectronic applications)
IT
     Metalloporphyrins
     RL: DEV (Device component use); PRP (Properties); SPN (Synthetic
     preparation); PREP (Preparation); USES (Uses)
        (zinc; prepn. of ethynyl-linked zinc(II) porphyrinato Group 8 metal
        terpyridine complexes and related multichromophoric complexes for NLO
        devices and other optoelectronic applications)
IT
     171204-91-4
                   478183-91-4
                                 478183-93-6
     RL: DEV (Device component use); PRP (Properties); USES (Uses)
        (mol. first-order hyperpolarizability as multichromophoric complex for
        NLO devices and other optoelectronic applications)
IT
     9003-53-6
     RL: DEV (Device component use); USES (Uses)
        (polymer compns. contg. ethynyl-linked zinc(II) porphyrinato Group 8
        metal terpyridine complexes and related multichromophoric complexes for
        NLO devices and other optoelectronic applications)
                    478183-89-0P
                                   478183-95-8P
     RL: DEV (Device component use); PRP (Properties); SPN (Synthetic
     preparation); PREP (Preparation); USES (Uses)
        (prepn. of ethynyl-linked zinc(II) porphyrinato Group 8 metal
        terpyridine complexes and related multichromophoric complexes for NLO
        devices and other optoelectronic applications)
ΙT
                    478184-20-2P
                                   478184-33-7P
                                                  731794-51-7P
                                                                731794-55-1P
     RL: DEV (Device component use); SPN (Synthetic preparation); PREP
     (Preparation); USES (Uses)
        (prepn. of ethynyl-linked zinc(II) porphyrinato Group 8 metal
        terpyridine complexes and related multichromophoric complexes for NLO
        devices and other optoelectronic applications)
IT
     108-46-3,
                 ***Resorcinol***
                                   , reactions
                                                624-95-3, 3,3-Dimethyl-1-
              1066-54-2, Trimethylsilylacetylene
     butanol
                                                   21211-65-4, Dipyrrylmethane
     72905-30-7
                 78389-87-4
                               97393-18-5
                                            478184-36-0
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (prepn. of ethynyl-linked zinc(II) porphyrinato Group 8 metal
        terpyridine complexes and related multichromophoric complexes for NLO
        devices and other optoelectronic applications)
ΤT
     149817-62-9P
                    183803-99-8P
                                   211450-16-7P
                                                  478184-21-3P
                                                                 478184-24-6P
     478184-27-9P
                    478184-29-1P
                                   478184-31-5P
                                                  478184-34-8P
                                                                  478184-35-9P
     478184-37-1P
                    478184-38-2P
                                   478184-39-3P
                                                  478184-40-6P
                                                                 478184-41-7P
     478184-42-8P
                    478184-44-0P
                                   731794-60-8P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
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```
(Reactant or reagent)
        (prepn. of ethynyl-linked zinc(II) porphyrinato Group 8 metal
        terpyridine complexes and related multichromophoric complexes for NLO
        devices and other optoelectronic applications)
L16
    ANSWER 3 OF 3 CAPLUS COPYRIGHT 2006 ACS on STN
     2003:321371 CAPLUS
     139:16629
     Entered STN: 27 Apr 2003
     Selective measurement of gaseous hydrogen peroxide with light emitting
     diode-based liquid-core
                              ***waveguide***
                                                 absorbance detector
     Li, Jianzhong; Dasgupta, Purnendu K.
     Department of Chemistry and Biochemistry, Texas Tech University, Lubbock,
     TX, 79409-1061, USA
     Analytical Sciences (2003), 19(4), 517-523
     CODEN: ANSCEN; ISSN: 0910-6340
     Japan Society for Analytical Chemistry
     Journal
     English
     79-2 (Inorganic Analytical Chemistry)
     Section cross-reference(s): 59
     Atm. H2O2 is typically detd. by enzymically mediated fluorogenic reactions
     that do not discriminate between H2O2 and org. peroxides. Reactions of
     Ti(IV) with H2O2 also was the basis of colorimetric measurements of H2O2
     but is too insensitive. A more sensitive detn. is possible with the
     Ti(IV)-4-(2-pyridylazo) ***resorcinol***
                                                 (PAR) complex, however,
     unreacted PAR must be chromatog. sepd. A titanium(IV)-porphyrin complex,
     oxo[5,10,15,20-tetra(4-pyridyl)porphyrinato]titanium(IV) [TiO(tpypH4)4+],
     (TiTPyP) was introduced for the measurement of aq. H2O2. TiTPyP can be
     used for measuring H2O2(g), it does not respond to MeHO2. With a proper
     membrane collector, practically there is no interference from concurrently
     present gaseous SO2 and O3. The approach permits a S/N = 3 limit of
     detection (LOD) of 26 pptv with a 50 mm path liq. core
                                                             ***waveguide***
     (LCW) absorbance detector and a light emitting diode based light source.
    This is adequate for real atm. measurements.
    hydrogen peroxide detn LED lig core
                                          ***wavequide***
                                                             absorbance
     detector
     Colorimetry
     Electroluminescent devices
     Gas analysis
     Optical gas sensors
              ***wavequides***
     Optical
        (gaseous hydrogen peroxide detn. by optical gas sensor with light
        emitting diode-based liq.-core ***waveguide***
                                                         and tetrapyridyl
        porphyrinato titanium)
     7722-84-1, Hydrogen peroxide, analysis
     RL: ANT (Analyte); ANST (Analytical study)
        (qaseous hydrogen peroxide detn. by optical gas sensor with light
        emitting diode-based lig.-core ***waveguide***
                                                           and tetrapyridyl
        porphyrinato titanium)
     105250-49-5, Oxo[5,10,15,20-tetrakis(4-pyridyl)porphyrinato]titanium(IV)
     RL: ARG (Analytical reagent use); ANST (Analytical study); USES (Uses)
        (gaseous hydrogen peroxide detn. by optical gas sensor with light
        emitting diode-based liq.-core ***waveguide***
                                                           and tetrapyridyl
        porphyrinato titanium)
RE.CNT
              THERE ARE 40 CITED REFERENCES AVAILABLE FOR THIS RECORD
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(2) Chung, H; Talanta 1993, V40, P981 CAPLUS
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(5) de Serves, C; Environ Sci Technol 1983, V27, P2712
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(12) Hwang, H; Environ Sci Technol 1985, V19, P255 CAPLUS
(13) Itoh, J; Anal Chim Acta 1975, V74, P53 CAPLUS
(14) Jambunathan, S; Talanta 1999, V50, P481 CAPLUS
(15) Komazaki, Y; Analyst 2001, V126, P587 CAPLUS
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(16) Komazaki, Y; Analyst 2001, V126, P587 CAPLUS
(17) Lazrus, A; Anal Chem 1985, V57, P917 CAPLUS
(18) Lee, M; Atmos Environ 2000, V34, P3475 CAPLUS
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(20) Li, J; Anal Chim Acta 2001, V442, P63 CAPLUS
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(27) Matsubara, C; Bunseki Kagaku 1993, V42, P363 CAPLUS
(28) Matsubara, C; Bunseki Kagaku 1993, V42, P773 CAPLUS
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(30) Matsubara, C; Yakugaku Zasshi 1993, V114, P48
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(40) Zhang, G; Anal Chim Acta 1992, V260, P57 CAPLUS
=> s l1 and ((optical or laser or information)(5a)(med? or disk or disc))
        861336 OPTICAL
            19 OPTICALS
        861344 OPTICAL
                 (OPTICAL OR OPTICALS)
        512525 LASER
        159629 LASERS
        525731 LASER
                 (LASER OR LASERS)
        395419 INFORMATION
          3003 INFORMATIONS
        397821 INFORMATION
                 (INFORMATION OR INFORMATIONS)
       1859557 MED?
        118533 DISK
         58469 DISKS
        148548 DISK
                 (DISK OR DISKS)
         15398 DISC
          3330 DISCS
         18213 DISC
                 (DISC OR DISCS)
         45497 (OPTICAL OR LASER OR INFORMATION) (5A) (MED? OR DISK OR DISC)
L17
            12 L1 AND ((OPTICAL OR LASER OR INFORMATION)(5A) (MED? OR DISK OR
               DISC))
=> d all 1-12
     ANSWER 1 OF 12 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     2005:300753
                 CAPLUS
DN
     142:382265
ED
     Entered STN: 07 Apr 2005
ΤI
       ***Optical***
                         ***disk***
                                       having specific hydroxyphenol derivative
     and silver-based reflective layer
IN
     Fujii, Koichi; Murakami, Kazuo
PA
     Dainippon Ink and Chemicals, Inc., Japan
SO
     PCT Int. Appl., 36 pp.
     CODEN: PIXXD2
DT
     Patent
LA
     Japanese
IC
     ICM G11B007-24
     74-12 (Radiation Chemistry, Photochemistry, and Photographic and Other
     Reprographic Processes)
FAN.CNT 1
     PATENT NO.
                         KIND
                                DATE
                                             APPLICATION NO.
                                                                     DATE
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                                        WO 2004-JP14556 20040928
                        A1 20050407
ΡI
    WO 2005031729
        W: AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH,
            CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD,
            GE, GH, GM, HR, HU, ID, IL, IN, IS, KE, KG, KP, KR, KZ, LC, LK,
            LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI, NO,
            NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ,
            TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW
        RW: BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW, AM,
            AZ, BY, KG, KZ, MD, RU, TJ, TM, AT, BE, BG, CH, CY, CZ, DE, DK,
            EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE,
            SI, SK, TR, BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE,
            SN, TD, TG
                              20030930
                        Α
PRAI JP 2003-340350
                        Α
    JP 2003-424804
                              20031222
CLASS
                CLASS PATENT FAMILY CLASSIFICATION CODES
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WO 2005031729
                ICM
                      G11B007-24
                IPCI
                      G11B0007-24 [ICM, 7]
os
    MARPAT 142:382265
    The invention relates to an ***optical***
                                                  ***disk***
                                                               comprising a
AB
    first substrate and, sequentially superimposed thereon, a first reflection
    film for reflecting laser radiation beams for information reading and a
    resin layer consisting of a coating process resulting from hardening of an
    UV hardenable compn., wherein the first reflection film is one constituted
    of silver or an alloy whose main component is silver and wherein the UV
    hardenable compn. comprises a radical polymerizable compd. (a), a
    hydroxyphenol deriv. (b) and a radical photopolymn. initiator (c).
    disk generates little color change of the Ag-based reflective layer under
    UV light.
ST
       ***optical***
                      ***disk***
                                    hydroxyphenol silver reflective layer
    98-29-3, 4-tert-Butylcatechol
                                   108-46-3,
                                              ***Resorcinol*** , uses
IT
    121-79-9, Propyl gallate
                             123-31-9, Hydroquinone, uses 149-91-7, Gallic
                533-73-3, Hydroxyhydroquinone
    RL: TEM (Technical or engineered material use); USES (Uses)
          ***optical***
                           ***disk*** having phenolic deriv. and
       silver-based reflective layer)
    7440-22-4D, Silver, alloy
    RL: DEV (Device component use); USES (Uses)
        (reflective layer;
                           ***optical***
                                             ***disk***
                                                         having phenolic
       deriv. and silver-based reflective layer)
             THERE ARE 4 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE.CNT
(1) Asahi Chemical Industry Co Ltd; JP 02-141284 A 1990 CAPLUS
(2) Asahi Chemical Industry Co Ltd; EP 361204 A2 1990
(3) Asahi Chemical Industry Co Ltd; US 5578415 A1 1990 CAPLUS
(4) Nippon Kayaku Co Ltd; JP 2002265886 A 2002 CAPLUS
    ANSWER 2 OF 12 CAPLUS COPYRIGHT 2006 ACS on STN
L17
AN
    2005:185484 CAPLUS
DN
    142:287883
ED
    Entered STN: 04 Mar 2005
    Limited-play recordable data storage media and associated methods of
    manufacture
    Wisnudel, Marc Brian; Van De Grampel, Hendrik Theodorus; Robertson,
    Randall Allen; Bakos, Yannis; Thompson, Robert F.
PA
SO
    U.S. Pat. Appl. Publ., 22 pp.
    CODEN: USXXCO
DT
    Patent
LA
    English
IC
    ICM G11B003-70
        G11B005-84; G11B007-26; B32B003-02
INCL 720718000; 369288000; 428064400
    74-12 (Radiation Chemistry, Photochemistry, and Photographic and Other
    Reprographic Processes)
FAN.CNT 1
    PATENT NO.
                       KIND
                              DATE
                                          APPLICATION NO.
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                              _____
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ΡI
    US 2005050571
                       A1
                              20050303
                                                                20030829
                                        US 2003-651403
    WO 2005024811
                        A1
                              20050317
                                          WO 2004-US22691
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AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH,
            CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD,
            GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI,
            NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY,
             TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW
        RW: BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW, AM,
             AZ, BY, KG, KZ, MD, RU, TJ, TM, AT, BE, BG, CH, CY, CZ, DE, DK,
             EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE,
             SI, SK, TR, BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE,
             SN, TD, TG
                                20030829
PRAI US 2003-651403
                         Α
                CLASS PATENT FAMILY CLASSIFICATION CODES
 PATENT NO.
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                ____
                       ______
 US 2005050571
                ICM
                       G11B003-70
                       G11B005-84; G11B007-26; B32B003-02
                ICS
                       720718000; 369288000; 428064400
                 INCL
                       G11B0003-70 [ICM,7]; G11B0005-84 [ICS,7]; G11B0007-26
                 IPCI
                        [ICS,7]; B32B0003-02 [ICS,7]
                NCL
                       720/718.000
                 ECLA
                       G11B007/241; G11B007/257
 WO 2005024811
                 IPCI
                       G11B0007-24 [ICM, 7]
                ECLA
                       G11B007/241; G11B007/257
     The present invention provides a digital content kiosk system operable for
     delivering selected digital content to a user. The digital content kiosk
     system of the present invention includes a limited-play recordable data
     storage medium configured to receive selected digital content and a data
     storage media recording device operable for recording the selected digital
     content on the limited-play recordable data storage medium at the request
                The limited-play recordable data storage medium of the present
     invention includes a reflective layer, a recording layer disposed directly
     or indirectly adjacent to the reflective layer, and at least one of a
     reactive layer and a reactive bonding adhesive layer disposed between the
     data storage media recording device and at least one of the reflective
     layer and the recording layer.
     limited play recordable data storage media manuf
                        ***disks***
       ***Optical***
     Optical recording
        (limited-play recordable data storage media)
     89-86-1, 2,4-Dihydroxybenzoic acid 95-88-5, 4-Chloro- ***resorcinol***
                ***Resorcinol*** , uses 136-77-6, 4-Hexylresorcinol
     108-46-3,
     59269-51-1, Polyhydroxystyrene
     RL: TEM (Technical or engineered material use); USES (Uses)
        (photobleaching retarder; limited-play recordable data storage media
        contg.)
    ANSWER 3 OF 12 CAPLUS COPYRIGHT 2006 ACS on STN
     2005:98916 CAPLUS
     142:186624
     Entered STN: 04 Feb 2005
     Limited play data storage media and associated methods of manufacture
     Wisnudel, Marc Brian; Longley, Kathryn Lynn; Olson, Daniel Robert; Lens,
     Jan Pleun; Lindholm, Edward Paul
     General Electric Company, USA
     U.S. Pat. Appl. Publ., 21 pp.
     CODEN: USXXCO
     Patent
     English
     ICM B32B027-32
     ICS B32B027-42; C09J011-00
INCL 428523000; 156327000; 156334000; 156335000
     74-12 (Radiation Chemistry, Photochemistry, and Photographic and Other
     Reprographic Processes)
     Section cross-reference(s): 38, 77
FAN.CNT 1
     PATENT NO.
                        KIND
                                DATE
                                            APPLICATION NO.
                                                                   DATE
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    US 2005025988
                         A1
                                20050203
                                            US 2003-633473
                                                                   20030801
    US 6925051
                        B2
                                20050802
     WO 2005014751
                        A1
                                20050217
                                            WO_2004-US20691
                                                                   20040625
        W: AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH,
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            GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC,
            LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI,
            NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY,
            TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW
        RW: BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW, AM,
            AZ, BY, KG, KZ, MD, RU, TJ, TM, AT, BE, BG, CH, CY, CZ, DE, DK,
            EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE,
            SI, SK, TR, BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE,
            SN, TD, TG
                               20030801
PRAI US 2003-633473
                         Α
CLASS
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                       PATENT FAMILY CLASSIFICATION CODES
PATENT NO.
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                ICM
                       B32B027-32
US 2005025988
                ICS
                       B32B027-42; C09J011-00
                       428523000; 156327000; 156334000; 156335000
                INCL
                IPCI
                       B32B0027-32 [ICM,7]; B32B0027-42 [ICS,7]; C09J0011-00
                        [ICS, 7]
                NCL
                       428/523.000
                       C09J009/00; C09J011/06; C09J011/08; G11B007/253;
                ECLA
                       G11B007/257
                       C09J0011-06 [ICM,7]; C09J0011-08 [ICS,7]; G11B0007-24
WO 2005014751
                IPCI
                        [ICS, 7]
                       C09J009/00; C09J011/06; C09J011/08; G11B007/253;
                ECLA
                       G11B007/257
     The present invention provides a reactive adhesive formulation for use in
     a limited play data storage medium, the reactive adhesive formulation
     including at least one adhesive material, at least one reactive material
     disposed within the at least one adhesive material and at least one
    photo-bleaching retarder material disposed within the at least one
     adhesive material. The at least one photo-bleaching retarder material
               ***resorcinol*** , 4-hexylresorcinol and/or
     polyhydroxystyrene.
               ***optical***
                                                          ***disk***
    magnetic
                               magnetooptical recording
                                                                       photo
     bleaching retarder adhesive
     Recording apparatus
        (disks; photo-bleaching retarder material contained adhesive for
        limited play data storage medium)
     Magnetic disks
         ***Optical***
                          ***disks***
                         ***disks*** ; photo-bleaching retarder material
        (magnetooptical
        contained adhesive for limited play data storage medium)
     Adhesives
     Magnetic disks
         ***Optical***
                          ***disks***
        (photo-bleaching retarder material contained adhesive for limited play
        data storage medium)
     79-97-0, 2,2-Bis (4-hydroxy-3-methylphenyl) propane
                                                       80-05-7, Bisphenol A,
           93-51-6, 2-Methoxy-4-methylphenol 99-89-8, 4-Isopropylphenol
                                 ***Resorcinol*** , uses
                                                            136-77-6,
     102-60-3, THPE 108-46-3,
                        622-62-8, 4-Ethoxyphenol 2082-79-3, Irganox 1076
     4-Hexylresorcinol
                              26983-52-8, Biphenol 41484-35-9, Irganox 1035
     6683-19-8, Irganox 1010
     59269-51-1, Polyhydroxystyrene
     RL: NUU (Other use, unclassified); USES (Uses)
        (photo-bleaching retarder material contained adhesive for limited play
        data storage medium)
     ANSWER 4 OF 12 CAPLUS COPYRIGHT 2006 ACS on STN
     2004:993183 CAPLUS
     141:412099
     Entered STN: 19 Nov 2004
     Fire-resistant thermoplastic resin composition with thermal conductivity
     Kikuchi, Kiyoharu
     Teijin Chemicals Ltd., Japan
     Jpn. Kokai Tokkyo Koho, 26 pp.
     CODEN: JKXXAF
     Patent
     Japanese
     ICM C08L069-00
         C08K003-34; C08K005-521; C08L071-12
     38-3 (Plastics Fabrication and Uses)
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FAN.CNT 1
                                         APPLICATION NO.
                                                                 DATE
    PATENT NO.
                       KIND
                              DATE
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                       A2
                              20041118 JP 2003-116707
PΙ
    JP 2004323565
                                                                20030422
                               20030422
PRAI JP 2003-116707
CLASS
             CLASS PATENT FAMILY CLASSIFICATION CODES
PATENT NO.
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                ICM
                      C08L069-00
JP 2004323565
                ICS
                       C08K003-34; C08K005-521; C08L071-12
                       C08L0069-00 [ICM,7]; C08K0003-34 [ICS,7]; C08K0005-521
                IPCI
                       [ICS, 7]; C08L0071-12 [ICS, 7]
                       4J002/BC022; 4J002/BC032; 4J002/BC062; 4J002/BC072;
                FTERM
                       4J002/BC112; 4J002/BD153; 4J002/BD163; 4J002/CG001;
                       4J002/CG011; 4J002/CG021; 4J002/CG041; 4J002/CH071;
                       4J002/DJ008; 4J002/DJ047; 4J002/DJ058; 4J002/EH039;
                       4J002/EH049; 4J002/EW046; 4J002/EW156; 4J002/FD017;
                       4J002/FD018; 4J002/FD050; 4J002/FD060; 4J002/FD070;
                       4J002/FD100; 4J002/FD136; 4J002/FD169; 4J002/GP00
    The compn. contains (A) an arom. polycarbonate, a styrene (I)-based hard
AB
    polymer, and/or a poly(phenylene ether), (B) 0.1-30% of an org. P compd.
    fireproofing agent, (C-1) c1% of talc with av. particle diam. 0.5-30
     .mu.m, and (C-2) c2% of mica and/or wollastonite filler at 10 .ltoreq. c1
     + c2 .ltoreq. 50 and 0.5 .ltoreq. c1/(c1 + c2) .ltoreq. 0.9. A chassis
     for optical device unit, e.g., a laser printer, a copying machine, etc.,
    made of the compn. is also claimed. Thus, bisphenol A-phosgene copolymer
     (Panlite L 1225 WP) 58, acrylonitrile-I copolymer (HF 5670) 12,
       ***resorcinol*** bis(dixylenyl phosphate) (ADK Stab FP 500) 5, talc
     (Victorylight R) 16, muscovite (MC 40) 9, PTFE (Polyflon MPA FA 500) 0.3,
     ethylene glycol montanate (WAX-E Powder) 0.3, and carbon black 1 part were
    mixed, pelletized, and injection-molded to give test pieces showing UL-94
     flame retardance V-1, impact strength 40 J/m, and thermal cond. 0.35
    W/m-k.
     fire resistant thermoplastic resin thermal cond; arom polycarbonate
ST
    phosphorus compd fireproofing agent; styrene acryonitrile copolymer
     fireproofing agent; polyoxyphenylene fireproofing agent talc mica; optical
     device unit chassis thermoplastic blend
IT
       ***Optical***
                        ***disks***
        (chassis of driving app. for; fire-resistant thermoplastic resin compn.
       with thermal cond. for)
IT
     Fire-resistant materials
     Impact-resistant materials
     Thermal conductors
        (fire-resistant thermoplastic resin compn. with thermal cond.)
     Polycarbonates, uses
     Polyoxyphenylenes
     RL: POF (Polymer in formulation); TEM (Technical or engineered material
     use): USES (Uses)
        (fire-resistant thermoplastic resin compn. with thermal cond.)
IT
     Polymer blends
     RL: TEM (Technical or engineered material use); USES (Uses)
        (fire-resistant thermoplastic resin compn. with thermal cond.)
IT
     Fluoropolymers, uses
     RL: MOA (Modifier or additive use); USES (Uses)
        (in fire-resistant thermoplastic resin compn. with thermal cond.)
IT
     Fatty acids, uses
    RL: MOA (Modifier or additive use); USES (Uses)
        (montan-wax, butylene ethylene esters, WAX E; in fire-resistant
        thermoplastic resin compn. with thermal cond.)
IT
     Fireproofing agents
        (phosphorus compd.; fire-resistant thermoplastic resin compn. with
       thermal cond.)
IT
     1318-94-1, MC 250
     RL: MOA (Modifier or additive use); USES (Uses)
        (MC 40; in fire-resistant thermoplastic resin compn. with thermal
       cond.)
IT
     14807-96-6, Victorylight R, uses
    RL: MOA (Modifier or additive use); USES (Uses)
        (Victorylight SG-A; in fire-resistant thermoplastic resin compn. with
       thermal cond.)
     9003-53-6, Denka Styrol GP-1 9003-54-7, HF 5670
IT
                                                       24936-68-3, Panlite L
```

Section cross-reference(s): 73

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1225WP, uses
                   25037-45-0
    RL: POF (Polymer in formulation); TEM (Technical or engineered material
    use); USES (Uses)
        (fire-resistant thermoplastic resin compn. with thermal cond.)
    31870-48-1, CR 741
IT
                       139189-30-3, ADK Stab FP 500
    RL: MOA (Modifier or additive use); TEM (Technical or engineered material
    use); USES (Uses)
        (fireproofing agent; fire-resistant thermoplastic resin compn. with
       thermal cond.)
    9002-84-0, Polyflon MPA FA500 13983-17-0, PH 450
IT
    RL: MOA (Modifier or additive use); USES (Uses)
        (in fire-resistant thermoplastic resin compn. with thermal cond.)
    ANSWER 5 OF 12 CAPLUS COPYRIGHT 2006 ACS on STN
L17
    2003:1007908 CAPLUS
AN
DN
    140:60508
    Entered STN: 28 Dec 2003
ED
    Method for making an aromatic polycarbonate
ΤI
    Silvi, Norberto; Giammattei, Mark Howard; McCloskey, Patrick Joseph;
IN
    Nisoli, Alberto; Day, James; Ramesh, Narayan; Smigelski, Paul Michael;
    Wilson, Paul Russell
PA
    General Electric Company, USA
SO
    U.S. Pat. Appl. Publ., 41 pp., Cont.-in-part of U.S. Ser. No. 167,901.
    CODEN: USXXCO
DT
    Patent
LA
    English
IC
     ICM C08G064-00
INCL 528086000; 528196000
    37-3 (Plastics Manufacture and Processing)
    Section cross-reference(s): 38
FAN.CNT 3
                                        APPLICATION NO.
    PATENT NO.
                      KIND DATE
                                                                DATE
     _____
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                              _____
                                          ---------------
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PI
    US 2003236384
                       A1
                              20031225 US 2003-389009
                                                                20030317
    US 6790929
                       B2
                               20040914
                                        US 2002-167901
                       A1
    US 2003232957
                               20031218
                                                                 20020612
    WO 2003106149
                        A1
                               20031224
                                         WO 2003-US16354
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            GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR,
            LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NO, NZ, OM, PH,
            PL, PT, RU, SD, SE, SG, SK, SL, TJ, TM, TN, TR, TT, TZ, UA, UG,
            UZ, VN, YU, ZA, ZM, ZW
        RW: GH, GM, KE, LS, MW, MZ, SD, SL, SZ, TZ, UG, ZM, ZW, AM, AZ, BY,
            KG, KZ, MD, RU, TJ, TM, AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES,
            FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PT, RO, SE, SK, TR, BF,
            BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG
    EP 1519831
                         A1
                               20050406
                                         EP 2003-760224
                                                                 20030523
            AT, BE, CH, DE, DK, ES, FR, GB, GR, IT, LI, LU, NL, SE, MC, PT,
            IE, SI, LT, LV, FI, RO, MK, CY, AL, TR, BG, CZ, EE, HU, SK
    JP 2005529995
                        T2
                               20051006
                                          JP 2004-513013
                                                                20030523
PRAI US 2002-167901
                        A2
                               20020612
    US 2003-389009
                        Α
                               20030317
    WO 2003-US16354
                        W
                               20030523
CLASS
PATENT NO.
                CLASS PATENT FAMILY CLASSIFICATION CODES
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                      ______
US 2003236384
                ICM
                       C08G064-00
                       528086000; 528196000
                INCL
                IPCI
                       C08G0064-00 [ICM,7]
                NCL
                       528/086.000
                       B29C047/00B; B29C047/76C; B29C067/24D; C08G064/30F
                ECLA
                IPCI
US 2003232957
                       C08G0002-00 [ICM,7]; C08G0064-00 [ICS,7]
                NCL
                       528/086.000
                       B29C047/00B; B29C047/76C; B29C067/24D; C08G064/30F
                ECLA
WO 2003106149
                IPCI
                       B29C0067-24 [ICM,7]; B29C0047-76 [ICS,7]; C08G0064-30
                       [ICS, 7]
                ECLA
                       C08G064/30F
EP 1519831
                IPCI
                       B29C0067-24 [ICM,7]; B29C0047-76 [ICS,7]; C08G0064-30
JP 2005529995
                IPCI
                       C08G0064-30 [ICM,7]; C08G0064-14 [ICS,7]
                FTERM
                       4J029/AA09; 4J029/AA10; 4J029/AB02; 4J029/AB04;
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4J029/AB07; 4J029/AC01; 4J029/AC02; 4J029/AD01;
                   4J029/AE04; 4J029/AE05; 4J029/BB13A; 4J029/BH02;
                   4J029/DB12; 4J029/DB13; 4J029/HC05A; 4J029/JA091;
                   4J029/JA251; 4J029/JB062; 4J029/JB063; 4J029/JC061;
                   4J029/JC631; 4J029/KB15; 4J029/KD01; 4J029/KD02;
                   4J029/KE02; 4J029/LA01; 4J029/LA05
MARPAT 140:60508
This invention relates to an extrusion method prepg. high mol. wt.
polycarbonates (greater than 20,000 daltons) from a soln. of an oligomeric
polycarbonate. A mixt. of bis(Me salicyl)carbonate, bisphenol A and a
transesterification catalyst (usually tetrabutylphosphonium acetate or its
combination with NaOH) are first equilibrated at moderate temps. to
provide a soln. of polycarbonate oligomer in Me salicylate. The soln. is
then fed to a devolatilizing extruder, where the polymn. reaction is
completed and the Me salicylate solvent is removed. The soln. comprising
the oligomeric polycarbonate can also be pre-heated under pressure to a
temp. above the b.p. of Me salicylate and subsequently fed to a
devolatilizing extruder equipped for rapid flashing off the solvent. The
method of the invention does not require the isolation of a precursor
polycarbonate comprising ester-substituted phenoxy terminal groups and
gives the colorless product. Fries rearrangement products (usual side
products) are not obsd. in the product polycarbonates.
polycarbonate extrusion melt polymn method methyl salicyl carbonate; high
mol wt polycarbonate melt polymn ester substituted; Fries rearrangement
suppression
Polycarbonates, preparation
RL: IMF (Industrial manufacture); PREP (Preparation)
   (arom.; extrusion method for making high mol. wt. arom. polycarbonate
   from an oligomeric polycarbonates) .
Polycarbonates, preparation
RL: IMF (Industrial manufacture); PREP (Preparation)
   (branched; extrusion method for making high mol. wt. arom.
   polycarbonate from an oligomeric polycarbonates)
Molded plastics, uses
RL: TEM (Technical or engineered material use); USES (Uses)
   (extrusion method for making high mol. wt. arom. polycarbonate from an
   oligomeric polycarbonates for molded plastics)
  ***Optical***
                    ***disks***
   (extrusion method for making high mol. wt. arom. polycarbonate from an
                                                     ***disks*** )
                                  ***optical***
   oligomeric polycarbonates for
Polysulfones, preparation
RL: IMF (Industrial manufacture); PREP (Preparation)
   (polycarbonate-; extrusion method for making high mol. wt. arom.
   polycarbonate from an oligomeric polycarbonates)
Polycarbonates, preparation
RL: IMF (Industrial manufacture); PREP (Preparation)
   (polysulfone-; extrusion method for making high mol. wt. arom.
   polycarbonate from an oligomeric polycarbonates)
Extrusion of plastics and rubbers
   (reactive; extrusion method for making high mol. wt. arom.
   polycarbonate from an oligomeric polycarbonates)
Carboxylic acids, uses
RL: CAT (Catalyst use); USES (Uses)
   (salts, with alkali- or alkali earth metals, transesterification
   catalyst; extrusion method for making high mol. wt. arom. polycarbonate
   from an oligomeric polycarbonates)
Alkali metal hydroxides
Alkaline earth hydroxides
Phosphonium compounds
Quaternary ammonium compounds, uses
RL: CAT (Catalyst use); USES (Uses)
   (transesterification catalyst; extrusion method for making high mol.
   wt. arom. polycarbonate from an oligomeric polycarbonates)
Polymerization catalysts
   (transesterification, transesterification; extrusion method for making
   high mol. wt. arom. polycarbonate from an oligomeric polycarbonates)
637781-43-2P
RL: IMF (Industrial manufacture); PREP (Preparation)
   (branched; extrusion method for making high mol. wt. arom.
   polycarbonate from an oligomeric polycarbonates)
                                       638132-24-8, Bis(methyl
24936-68-3D, p-cumylphenyl-terminated
salicyl)carbonate-bisphenol A copolymer, p-cumylphenyl ester
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RL: RCT (Reactant); RACT (Reactant or reagent)
        (chain stopper; extrusion method for making high mol. wt. arom.
        polycarbonate from an oligomeric polycarbonates)
IT
     82091-13-2P, Bis(methyl salicyl)carbonate-bisphenol A copolymer
     474083-68-6P
                    474084-87-2P, Bis (methyl salicyl) carbonate-bisphenol
     A-4,4'-sulfonyldiphenol copolymer 474084-95-2P, Bis(methyl
     salicyl)carbonate-bisphenol A-4,4'-dihydroxybiphenyl copolymer
     477527-64-3P, Bis(methyl salicyl)carbonate-bisphenol A-hydroquinone-
       ***resorcinol***
                          copolymer
                                     636600-75-4P, Bis(methyl
     salicyl)carbonate-bisphenol A-methylhydroquinone-copolymer
     RL: IMF (Industrial manufacture); PREP (Preparation)
        (extrusion method for making high mol. wt. arom. polycarbonate from an
        oligomeric polycarbonates)
IT
     24936-68-3P, preparation
     RL: IMF (Industrial manufacture); POF (Polymer in formulation); PREP
     (Preparation); USES (Uses)
        (extrusion method for making high mol. wt. arom. polycarbonate from an
        oligomeric polycarbonates)
     119-36-8, Methyl salicylate
     RL: NUU (Other use, unclassified); USES (Uses)
        (solvent; extrusion method for making high mol. wt. arom. polycarbonate
        from an oligomeric polycarbonates)
     75-59-2, Tetramethylammonium hydroxide
                                              7558-79-4, Phosphoric acid,
                                7778-77-0, Phosphoric acid, monopotassium salt
     disodium salt
                     7558-80-7
     14402-88-1, Disodium magnesium ethylenediaminetetraacetate
                                                                  14518-27-5
     18649-05-3, Phosphoric acid, monocesium salt
                                                    30345-49-4,
     Tetrabutylphosphonium acetate
                                     33943-65-6, Phosphoric acid, dicesium salt
     634558-37-5
                  634558-39-7
     RL: CAT (Catalyst use); USES (Uses)
        (transesterification catalyst; extrusion method for making high mol.
        wt. arom. polycarbonate from an oligomeric polycarbonates)
     1310-73-2, Sodium hydroxide, uses
IT
     RL: CAT (Catalyst use); USES (Uses)
        (transesterification co-catalyst; extrusion method for making high mol.
        wt. arom. polycarbonate from an oligomeric polycarbonates)
              THERE ARE 12 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE.CNT
(1) Anon; EP 0738579 1996 CAPLUS
(2) Anon; EP 0976772 2000 CAPLUS
(3) Anon; EP 980861 2000 CAPLUS
(4) Anon; EP 1114841 2001 CAPLUS
(5) Anon; WO 02060855 2002 CAPLUS
(6) Anon; EP 1191049 2002 CAPLUS
(7) Brunelle; US 4323668 A 1982 CAPLUS
(8) Cobb; US 6506781 B1 2003 CAPLUS
(9) Day; US 6339109 B1 2002 CAPLUS
(10) Kaneko; US 5696222 A 1997 CAPLUS
(11) Kaneko; US 6300459 B1 2001 CAPLUS
(12) McCloskey; US 6420512 B1 2002 CAPLUS
L17
    ANSWER 6 OF 12 CAPLUS COPYRIGHT 2006 ACS on STN
    2003:170360 CAPLUS
AN
DN
    138:205503
    Entered STN: 06 Mar 2003
ED
TI
    Polyester-polycarbonates from spirochromandiols
IN
    Wehrmann, Rolf; Heuer, Helmut Werner
PA
    Bayer AG, Germany
    Ger. Offen., 18 pp.
SO
    CODEN: GWXXBX
DT
    Patent
LA
    German
IC
    ICM C08G063-80
    ICS C08G063-64; C08J005-10; C08J005-18; G02B001-04
     35-5 (Chemistry of Synthetic High Polymers)
    Section cross-reference(s): 27
FAN.CNT 1
    PATENT NO.
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                                          APPLICATION NO.
                                                                   DATE
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                         _ - - -
PΙ
    DE 10141621
                                            DE 2001-10141621
                         A1
                                20030306
                                                                   20010824
    WO 2003020714 ·
                                          WO 2002-EP8997
                         A1
                                20030313
                                                                   20020812
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GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR,
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             PL, PT, RO, RU, SD, SE, SG, SI, SK, SL, TJ, TM, TN, TR, TT,
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             TJ, TM
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                                             EP 2002-762440
     EP 1421072
                                20040526
                                                                    20020812
                          A1
            AT, BE, CH, DE, DK, ES, FR, GB, GR, IT, LI, LU, NL, SE, MC, PT,
             IE, SI, LT, LV, FI, RO, MK, CY, AL, TR, BG, CZ, EE, SK
                                             JP 2003-524984
     JP 2005507956
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                                                                    20020812
                                             US 2002-224004
     US 2003120024
                          A1
                                20030626
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                          B2
     US 6696543
                                20040224
                          В .
                                             TW 2002-91119066
                                                                    20020823
     TW 583183
                                20040411
                          Α
PRAI DE 2001-10141621
                                20010824
                          W
     WO 2002-EP8997
                                20020812
CLASS
 PATENT NO.
                 CLASS
                        PATENT FAMILY CLASSIFICATION CODES
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 DE 10141621
                 ICM
                        C08G063-80
                 ICS
                        C08G063-64; C08J005-10; C08J005-18; G02B001-04
                 IPCI
                        C08G0063-80 [ICM,7]; C08G0063-64 [ICS,7]; C08J0005-10
                        [ICS,7]; C08J0005-18 [ICS,7]; G02B0001-04 [ICS,7]
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                        C07D493/10+311B+311B+4; C08G063/64
 WO 2003020714
                 IPCI
                        C07D0311-96 [ICM,7]; C08G0063-64 [ICS,7]
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                        C07D493/10+311B+311B+4; C08G063/64
 EP 1421072
                 IPCI
                        C07D0311-96 [ICM,7]; C08G0063-64 [ICS,7]
 JP 2005507956
                 IPCI
                        C08G0063-64 [ICM,7]; C07D0493-10 [ICS,7]
                 FTERM
                        4C071/AA04; 4C071/AA07; 4C071/BB01; 4C071/BB06;
                        4C071/BB08; 4C071/CC12; 4C071/DD21; 4C071/EE07;
                        4C071/FF17; 4C071/GG01; 4C071/HH05; 4C071/JJ01;
                        4C071/KK01; 4C071/LL03; 4J029/AA08; 4J029/AB01;
                        4J029/AC02; 4J029/AD01; 4J029/AE04; 4J029/AE05;
                        4J029/BB06C; 4J029/BB12C; 4J029/BB13A; 4J029/BD09C;
                        4J029/BF30; 4J029/CA02; 4J029/HA01; 4J029/HB01;
                        4J029/HC01; 4J029/KB02; 4J029/KE09; 4J029/KE11
 US 2003120024
                 IPCI
                        C08G0064-00 [ICM, 7]
                 IPCR
                        C07D0493-00 [I,C]; C07D0493-10 [I,A]; C08G0063-00
                        [I,C]; C08G0063-64 [I,A]
                 NCL
                        528/196.000
                 ECLA
                        C07D493/10+311B+311B+4; C08G063/64
 TW 583183
                 IPCI
                        C07D0311-96 [ICM,7]; C08G0063-64 [ICS,7]
os
     MARPAT 138:205503
AB
     Moldable polyester-polycarbonates are manufd. from spirochromandiols I
     (R1-7 = H, halo, C1-14 alkyl, C6-19 aryl, or C7-14 aralkyl).
st
     polyester polycarbonate spirochromandiol deriv manuf
IT
     Polyesters, preparation
     RL: IMF (Industrial manufacture); PREP (Preparation)
        (polycarbonate-; polyester-polycarbonates from spirochromandiols)
IT
     Polycarbonates, preparation
     RL: IMF (Industrial manufacture); PREP (Preparation)
        (polycarbonates from spirochromandiols)
IT
     Polycarbonates, preparation
     RL: IMF (Industrial manufacture); PREP (Preparation)
        (polyester-; polyester-polycarbonates from spirochromandiols)
IT
       ***Optical***
                         ***disks***
        (polyester-polycarbonates from spirochromandiols for
                                                                ***optical***
          ***disks***
IT
        (polyester-polycarbonates from spirochromandiols for optical lenses)
IT
     Plastic films
        (polyester-polycarbonates from spirochromandiols for plastic films)
IT
    Molded plastics, miscellaneous
    RL: MSC (Miscellaneous)
        (sheets; polyester-polycarbonates from spirochromandiols for sheets)
IT
     67-64-1, Acetone, reactions
                                   78-93-3, Methyl ethyl ketone, reactions
                 ***Resorcinol***
     108-46-3,
                                   , reactions
                                                 110-12-3, 5-Methyl-2-hexanone
     136-77-6, 4-Hexylresorcinol
                                   504-20-1, Phorone
                                                        2896-60-8,
     4-Ethylresorcinol 35225-79-7, trans, trans-1,5-Diphenyl-1,4-pentadien-3-
```

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RL: RCT (Reactant); RACT (Reactant or reagent)
        (monomer precursor; polyester-polycarbonates from spirochromandiols)
IT
                                   500343-78-2P
                                                  500343-79-3P
     154778-81-1P
                    288149-09-7P
                                                                 500343-80-6P
    RL: IMF (Industrial manufacture); PREP (Preparation)
        (monomer; polyester-polycarbonates from spirochromandiols)
IT
    3127-14-8P
    RL: IMF (Industrial manufacture); RCT (Reactant); PREP (Preparation); RACT
     (Reactant or reagent)
        (monomer; polyester-polycarbonates from spirochromandiols)
     500343-76-0P
IT
    RL: IMF (Industrial manufacture); PREP (Preparation)
        (polyester-polycarbonates from spirochromandiols)
    ANSWER 7 OF 12 CAPLUS COPYRIGHT 2006 ACS on STN
L17
     2002:700058 CAPLUS
AN
     138:106837
DN
ED
     Entered STN: 16 Sep 2002
    Synthesis of optically active tricyclic ethers by reactions of
ΤI
     (-)-.beta.-pinene with phenols in organized media
     Fomenko, Vladislav V.; Korchagina, Dina V.; Salakhutdinov, Nariman F.;
ΑU
    Barkhash, Vladimir A.
    Novosibirsk Institute of Organic Chemistry, Novosibirsk, 630090, Russia
CS
SO
    Helvetica Chimica Acta (2002), 85(8), 2358-2363
     CODEN: HCACAV; ISSN: 0018-019X
PB
    Verlag Helvetica Chimica Acta
DT
     Journal
LA
    English
CC
     30-10 (Terpenes and Terpenoids)
os
    CASREACT 138:106837
    The reactions of (-)-.beta.-pinene with some methyl- and
AB
    hydroxy-substituted phenols on H.beta.-zeolite yield optically active
    products - tricyclic terpenyl Ph ethers - in contrast to reactions in
                   ***media*** , which occur with loss of
                                                             ***optical***
     activity. The formation of these products is promoted by the presence of
     meta-substituents in the phenol mol.
ST
     tricyclic ether optically active prepn pinene phenol reaction zeolite
IT
    Asymmetric synthesis and induction
        (synthesis of optically active tricyclic ethers from (-)-.beta.-pinene
        and phenols on H.beta.-zeolite)
IT
     Beta zeolites
     RL: CAT (Catalyst use); USES (Uses)
        (synthesis of optically active tricyclic ethers from (-)-.beta.-pinene
        and phenols on H.beta.-zeolite)
     108-39-4, m-Cresol, reactions
                                     108-46-3,
                                                 ***Resorcinol***
                                                                   , reactions
     108-68-9, 3,5-Dimethylphenol
                                    120-80-9, Pyrocatechol, reactions
     18172-67-3, (-)-.beta.-Pinene
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (synthesis of optically active tricyclic ethers from (-)-.beta.-pinene
        and phenols on H.beta.-zeolite)
IT
     66465-58-5P
                  66465-60-9P
                                 488758-91-4P
                                                488758-92-5P
                                                                488758-93-6P
     488758-94-7P
                    488758-95-8P
                                   488758-96-9P
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (synthesis of optically active tricyclic ethers from (-)-.beta.-pinene
        and phenols on H.beta.-zeolite)
RE.CNT
              THERE ARE 12 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE
(1) Ewing, D; Org Magn Reson 1979, V12, P499 CAPLUS
(2) Fomenko, V; Helv Chim Acta 2001, V84, P3477 CAPLUS
(3) Fomenko, V; Zh Org Khim 2000, V36, P1819
(4) Fomenko, V; Zh Org Khim 2000, V36, P564
(5) Polovinka, M; Zh Org Khim 1985, V21, P2102 CAPLUS
(6) Popova, L; Zh Org Khim 1982, V18, P815 CAPLUS
(7) Pottier, E; Bull Soc Chim Fr 1977, P557 CAPLUS
(8) Salakhutdinov, N; Chemistry Reviews 1998, V23, P1
(9) Salakhutdinov, N; Tetrahedron 1998, V54, P15619 CAPLUS
(10) Stern, M; J Org Chem 1973, V38, P1264 CAPLUS
(11) Stevens, K; Tetrahedron 1972, V28, P2949
(12) Wadlinger, R; 1967 CAPLUS
L17
    ANSWER 8 OF 12 CAPLUS COPYRIGHT 2006 ACS on STN
AN
    2000:356346 CAPLUS
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DN

132:348743

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ED
    Entered STN: 30 May 2000
    Fire-resistant polycarbonate-styrene polymer blend compositions with good
ΤI
    melt fluidity, their antifriction moldings, and their products
    Nodera, Akio; Manda, Naoki; Takeuchi, Takanao
IN
    Idemitsu Petrochemical Co., Ltd., Japan
PA
SO
    Jpn. Kokai Tokkyo Koho, 11 pp.
    CODEN: JKXXAF
DT
    Patent
LA
    Japanese
    ICM C08L069-00
    ICS C08J005-00; C08K005-521; C08L025-04; C08L027-12; C08L051-00;
         C08L083-04
    38-3 (Plastics Fabrication and Uses)
    Section cross-reference(s): 74
FAN.CNT 1
                      KIND
                              DATE APPLICATION NO.
                                                            DATE
    PATENT NO.
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                                          ______
                                                                 -----
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                              _____
    JP 2000143965
                       A2
                               20000526 JP 1998-322422
                                                                 19981112
                       B2
                               20030804
    JP 3432434
                              20010306 US 1999-433210 19991104
US 6197857 B1
DE 19953297 A1
PRAI JP 1998-322422 A
                                         DE 1999-19953297
                               20000615
                                                               19991105
                               19981112
              CLASS PATENT FAMILY CLASSIFICATION CODES
 PATENT NO.
                ____
 JP 2000143965 ICM
                       C08L069-00
                       C08J005-00; C08K005-521; C08L025-04; C08L027-12;
                ICS
                       C08L051-00; C08L083-04
                       C08L0069-00 [ICM,7]; C08J0005-00 [ICS,7]; C08K0005-521
                IPCI
                       [ICS,7]; C08L0025-04 [ICS,7]; C08L0027-12 [ICS,7];
                       C08L0051-00 [ICS,7]; C08L0083-04 [ICS,7]
 US 6197857
                IPCI
                       C08K0005-52 [ICM, 7]
                NCL
                       524/141.000; 524/140.000; 524/143.000; 524/145.000;
                       524/267.000; 524/269.000
                ECLA
                       C08L051/04+B; C08L051/04+B4; C08L051/08S+B;
                       C08L051/08S+B4; C08L069/00+B
                IPCI
                       C08L0069-00 [ICM,7]; C08L0025-04 [ICS,7]; C08L0027-12
 DE 19953297
                       [ICS,7]; C08L0051-08 [ICS,7]
                ECLA
                       C08L051/04+B; C08L069/00+B; C08L051/04+B4;
                       C08L051/08S+B4; C08L051/08S+B
    The compns., useful for CD trays and bearings for CRT monitors, contain
AB
     60-99% polycarbonates, 1-40% styrene polymers, 1-30 parts (to 100 parts of
     the total polymers) phosphate esters, and 0.3-3 parts silicone oils with
    viscosity 1000-20,000 cs. The compns. are useful for manufg. thin
    moldings. An injection molding manufd. from Toughlon A1900 (bisphenol A
    polycarbonate, MI 20 g/10 min, at 300.degree., 1.2 kg-load) 80, PS IT44
     (styrene-grafted polybutadiene) 20, tri-Ph phosphate 10, TSF 451 (silicone
     oil, viscosity 5000 cs) 2 parts, and antioxidants showed good appearance,
    UL-94 flammability rating V-2, Izod impact strength (ASTM D256) 40 kJ/m2,
     and friction coeff. (JIS K7218) 0.25 kg.
     impact resistance polycarbonate moldability fireproofer phosphate;
    bisphenol A polycarbonate antifriction bearing silicone; styrene butadiene
    graft copolymer polycarbonate blend
     Silicone rubber, uses
     RL: DEV (Device component use); MOA (Modifier or additive use); PRP
     (Properties); USES (Uses)
        (composites with (meth)acrylate rubbers, grafted; fire-resistant
        polycarbonate-styrene polymer blend compns. for antifriction moldings)
    Acrylic rubber
     RL: DEV (Device component use); MOA (Modifier or additive use); PRP
     (Properties); USES (Uses)
        (composites with silicone rubbers, grafted; fire-resistant
        polycarbonate-styrene polymer blend compns. for antifriction moldings)
ΙT
     Antifriction materials
     Bearings
     Fire-resistant materials
     Impact-resistant materials
        (fire-resistant polycarbonate-styrene polymer blend compns. for
        antifriction moldings)
IT
     Polysiloxanes, uses
     RL: DEV (Device component use); MOA (Modifier or additive use); PRP
     (Properties); USES (Uses)
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(fire-resistant polycarbonate-styrene polymer blend compns. for
        antifriction moldings)
    Polycarbonates, uses
IΤ
    RL: DEV (Device component use); POF (Polymer in formulation); PRP
     (Properties); USES (Uses)
        (fire-resistant polycarbonate-styrene polymer blend compns. for
        antifriction moldings)
IT
    Polymer blends
    RL: DEV (Device component use); POF (Polymer in formulation); PRP
     (Properties); USES (Uses)
        (fire-resistant polycarbonate-styrene polymer blend compns. for
        antifriction moldings)
    Molded plastics, uses
IT
    RL: DEV (Device component use); PRP (Properties); USES (Uses)
        (fire-resistant polycarbonate-styrene polymer blend compns. for
        antifriction moldings)
     Fluoropolymers, uses
IT
    RL: MOA (Modifier or additive use); PRP (Properties); USES (Uses)
        (fire-resistant polycarbonate-styrene polymer blend compns. for
        antifriction moldings)
IT
     Cathode ray tubes
        (monitors, bearings for; fire-resistant polycarbonate-styrene polymer
        blend compns. for antifriction moldings)
IT
    Fireproofing agents
        (phosphates; fire-resistant polycarbonate-styrene polymer blend compns.
        for antifriction moldings)
                             ***disks***
       ***Optical***
                      ROM
IT
        (trays for; fire-resistant polycarbonate-styrene polymer blend compns.
        for antifriction moldings)
     106974-54-3, Butadiene-styrene graft copolymer
    RL: DEV (Device component use); POF (Polymer in formulation); PRP
     (Properties); USES (Uses)
        (PS IT 44; fire-resistant polycarbonate-styrene polymer blend compns.
        for antifriction moldings)
                          31900-57-9, Dimethylsilanediol polymer
                                                                    149718-92-3,
     9016-00-6, TSF 451
    Metablen S2001
     RL: DEV (Device component use); MOA (Modifier or additive use); PRP
     (Properties); USES (Uses)
        (fire-resistant polycarbonate-styrene polymer blend compns. for
        antifriction moldings)
     24936-68-3, Toughlon A 1900, uses
                                         25037-45-0, Bisphenol A-carbonic acid
     copolymer
     RL: DEV (Device component use); POF (Polymer in formulation); PRP
     (Properties); USES (Uses)
        (fire-resistant polycarbonate-styrene polymer blend compns. for
        antifriction moldings)
IT
     9002-84-0, F201L
     RL: MOA (Modifier or additive use); PRP (Properties); USES (Uses)
        (fire-resistant polycarbonate-styrene polymer blend compns. for
        antifriction moldings)
     115-86-6, Triphenyl phosphate
                                     57583-54-7,
                                                   ***Resorcinol***
    bis(diphenyl phosphate)
     RL: DEV (Device component use); MOA (Modifier or additive use); PRP
     (Properties); USES (Uses)
        (fireproofing agent; fire-resistant polycarbonate-styrene polymer blend
        compns. for antifriction moldings)
L17
    ANSWER 9 OF 12 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     1998:388371 CAPLUS
DN
     129:54735
ED
     Entered STN: 25 Jun 1998
     Preparation of copolyestercarbonates derived from hydroxyphenylindanols
ΤI
     for fabrication of
                         ***optical***
                                             ***disks***
IN
    Chatterjee, Gautam; Davis, Gary Charles
PA
    General Electric Co., USA
SO
    Eur. Pat. Appl., 7 pp.
    CODEN: EPXXDW
DT
    Patent
    English
LA
IC
     ICM C08G063-64
     ICS C08G063-695
CC
     35-5 (Chemistry of Synthetic High Polymers)
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Section cross-reference(s): 73
FAN.CNT 1
                                        APPLICATION NO.
                              DATE
                                                                DATE
    PATENT NO.
                       KIND
    _____
                              _____
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                                                                _____
PΤ
    EP 846711
                        A2
                              19980610
                                       EP 1997-309850
                                                                19971208
                       A3
    EP 846711
                              20000830
                        B1 20040324
    EP 846711
        R: AT, BE, CH, DE, DK, ES, FR, GB, GR, IT, LI, LU, NL, SE, MC, PT,
            IE, SI, LT, LV, FI, RO
                                        US 1997-927136
                              19990112
                                                                19970902
    US 5859833
                        Α
                                       JP 1997-331550
                       A2
                              19980902
    JP 10231359
                                                                19971202
    CN 1210115
                                                               19971209
                       A 19990310
                                         CN 1997-114154
PRAI US 1996-32480P P US 1997-927136 A
                             19961209
                              19970902
CLASS
                CLASS PATENT FAMILY CLASSIFICATION CODES
PATENT NO.
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               ____
                ICM
                      C08G063-64
EP 846711
                ICS
                      C08G063-695
                       C08G0063-64 [ICM, 6]; C08G0063-695 [ICS, 6]
                IPCI
                ECLA
                       C08G063/64; G11B007/253
                IPCI
                       G11B0003-70 [ICM,6]; C08G0064-00 [ICS,6]
US 5859833
                       369/288.000; 525/474.000; 528/010.000; 528/026.000;
                NCL
                       528/029.000; 528/086.000; 528/176.000; 528/193.000;
                       528/201.000; 528/204.000; 528/206.000; 528/219.000
                      C08G063/64; G11B007/253
                ECLA
 JP 10231359
                IPCI
                       C08G0064-16
 CN 1210115
                IPCI
                       C08G0064-04 [ICM, 6]; G11B0007-24 [ICS, 6]
    Title copolycarbonates having low intrinsic birefringence is prepd. from
     (a) a hydroxyphenylindanol, (b) a ***resorcinol*** carbonate,
    eugenolsiloxane or alkylenedioic acid, and (c) optionally, a bisphenol,
    preferably bisphenol A. Thus, 13.4 g 1,1,3-trimethyl-3-(4-hydroxyphenyl)-
    5-hydroxyindane, 2.9 g 1,12-dodecanedioic acid, 250 mg p-cumylphenol, 120
    mL methylene chloride, 50 mL water, 0.5 mL 75% aq. Me tri-n-butylammonium
    chloride and 125 .mu.L triethylamine, were mixed with phosgene 5.3 g at pH
    8.0 and 2.2 g at pH 10.5 to give a copolymer with MW 71,000 and Tg
    139.degree., which was cast to form a film having low birefringence.
    copolyestercarbonate prepn ***optical*** ***disk*** ;
ST
                          ***resorcinol*** reaction copolyestercarbonate
    hydroxyphenylindanol
    birefringence; alkylenedioic acid hydroxyphenylindanol reaction
    copolyestercarbonate; eugenolsiloxane hydroxyphenylindanol reaction
    polyester polycarbonate copolymer
IT
    Polymerization
        (interfacial; prepn. of copolyestercarbonates derived from
       hydroxyphenylindanols for)
    Polyesters, preparation
    Polyesters, preparation
    RL: IMF (Industrial manufacture); TEM (Technical or engineered material
    use); PREP (Preparation); USES (Uses)
        (polycarbonate-; prepn. of copolyestercarbonates derived from
       hydroxyphenylindanols for fabrication of ***optical***
         ***disks*** )
    Polycarbonates, preparation
    Polycarbonates, preparation
    RL: IMF (Industrial manufacture); TEM (Technical or engineered material
    use); PREP (Preparation); USES (Uses)
        (polyester-; prepn. of copolyestercarbonates derived from
       hydroxyphenylindanols for fabrication of ***optical***
          ***disks*** )
IT
    Redistribution reaction
        (polymn.; prepn. of copolyestercarbonates derived from
       hydroxyphenylindanols for)
IT
       ***Optical***
                      ***disks***
        (prepn. of copolyestercarbonates derived from hydroxyphenylindanols
       for)
IT
     Polymerization
        (solid-state; prepn. of copolyestercarbonates derived from
       hydroxyphenylindanols for)
IT
    Polymerization
        (transesterification; prepn. of copolyestercarbonates derived from
       hydroxyphenylindanols for)
IT
    208764-61-8P
                  208764-62-9P
                                 208764-63-0P
```

RL: IMF (Industrial manufacture); TEM (Technical or engineered material use); PREP (Preparation); USES (Uses) (Prepn. of copolyestercarbonates derived from hydroxyphenylindanols for \*\*\*disks\*\*\* ) \*\*\*optical\*\*\* fabrication of

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ANSWER 10 OF 12 CAPLUS COPYRIGHT 2006 ACS on STN
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AN 1998:118621 CAPLUS

128:141220 DN

Entered STN: 27 Feb 1998

Method for preparing polycarbonate by solid-state polymerization

Varadarajan, Godavarthi Satyanarayana; Sivaram, Swaminathan; Idage,

Bhaskar Bhairavnath; King, Joseph Anthony, Jr.

PA General Electric Co., USA

U.S., 8 pp., Cont.-in-part of U.S. Ser. No. 653,166. SO

CODEN: USXXAM

DT Patent

English LA

IC ICM C08G064-00

INCL 528196000

35-5 (Chemistry of Synthetic High Polymers)

Section cross-reference(s): 38, 67

•	ΜM	٠	CM	1	4	
			_	_		_

PATENT NO.	KIND DATE		APPLICATION NO.	DATE
PI US 5717056	Α	19980210	US 1996-767740	19961217
US 5710238	Α	19980120	US 1996-653166	19960524
SG 70588	<b>A</b> 1	20000222	SG 1997-649	19970304
EP 849305	A2	19980624	EP 1997-302927	19970429
EP 849305	A3	19980722		
R: BE, DE, ES,	FR, GI	3, IT, NL		
JP 10176047	A2	19980630	JP 1997-111675	19970430
CN 1185453	Α	19980624	CN 1997-111124	19970504
PRAI US 1996-653166	A2	19960524		
IN 1995-DE2463	Α	19951229		
US 1996-767740	Α	19961217		
CLASS				

PATENT NO.	CLASS	PATENT FAMILY CLASSIFICATION CODES
US 5717056	ICM	C08G064-00
	INCL	528196000
	IPCI	C08G0064-00 [ICM,6]
	NCL	528/196.000; 528/198.000
	ECLA	C08G064/14; C08G064/20; C08G064/30F; C08G064/42
US 5710238	IPCI	C08G0064-00
	NCL	528/196.000; 528/198.000; 528/201.000; 528/202.000
	ECLA	C08G064/14; C08G064/30F
SG 70588	IPCI	C08G0064-00 [ICM, 7]
EP 849305	IPCI	C08G0064-20 [ICM,6]; C08G0064-40 [ICS,6]; C08G0064-30 [ICS,6]
	ECLA	C08G064/14; C08G064/20; C08G064/30F; C08G064/42
JP 10176047	IPCI	C08G0064-20 [ICM,6]; C08G0064-30 [ICS,6]
CN 1185453	IPCI	C08G0064-04 [ICM,6]; C08G0064-24 [ICS,6]; C08G0064-40 [ICS,6]

The method comprises an initial step of converting a precursor AB polycarbonate to an enhanced crystallinity precursor polycarbonate and a 2nd step of polymg. the enhanced crystallinity precursor polycarbonate in the solid state. Several options are employed, including modifying the precursor polycarbonate by contact with a dihydroxy compd. or diaryl carbonate, conversion of the precursor polycarbonate to the enhanced crystallinity polymer by contact with .gtoreq.1 compd. selected from alkali metal hydroxides, tetraalkylammonium hydroxides, tetraalkylammonium carboxylates, tetraalkylphosphonium hydroxides and tetraalkylphosphonium carboxylates, and conducting the solid-state polymn. in the presence of a catalytic amt. of .gtoreq.1 tetralkylammonium or tetraalkylphosphonium carboxylate. The preferred tetralkylammonium compds. are tetramethylammonium maleate and tetramethylammonium hydroxide. may be conducted in the presence of a solvent resistance-imparting monomer \*\*\*resorcinol\*\*\* or a branching agent such as such as hydroquinone or 1,1,1-tris(4-hydroxyphenyl)ethane.

bisphenol A polycarbonate solid state polymn; tetralkylammonium carboxylate solid state polymn catalyst; tetramethylammonium maleate solid state polymn catalyst; crystallinity enhancement polycarbonate solid state

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polymn
IT
    Quaternary ammonium compounds, uses
    RL: CAT (Catalyst use); USES (Uses)
        (carboxylates; method for prepg. polycarbonate by solid-state polymn.)
     Phosphonium compounds
IT
    RL: CAT (Catalyst use); USES (Uses)
        (hydroxides or carboxylates; method for prepg. polycarbonate by
        solid-state polymn.)
    Quaternary ammonium compounds, uses
IT
    RL: CAT (Catalyst use); USES (Uses)
        (hydroxides; method for prepg. polycarbonate by solid-state polymn.)
IT
    Recycling of plastics and rubbers
        (method for prepq. polycarbonate by solid-state polymn.)
IT
    Alkali metal hydroxides
    RL: CAT (Catalyst use); USES (Uses)
        (method for prepg. polycarbonate by solid-state polymn.)
     Polycarbonates, preparation
IT
    RL: IMF (Industrial manufacture); PREP (Preparation)
        (method for prepg. polycarbonate by solid-state polymn.)
IT
       ***Optical***
                       ***disks***
        (recycling; method for prepg. polycarbonate by solid-state polymn.)
IT
    Polymerization
        (solid-state; method for prepq. polycarbonate by solid-state polymn.)
IT
     Polymerization catalysts
        (transesterification; method for prepg. polycarbonate by solid-state
       polymn.)
                                             2052-49-5, Tetrabutylammonium
IT
    75-59-2, Tetramethylammonium hydroxide
    hydroxide 56504-85-9, uses 154695-25-7
    RL: CAT (Catalyst use); USES (Uses)
        (method for prepg. polycarbonate by solid-state polymn.)
     24936-68-3P, preparation 25929-04-8P, Bisphenol A-diphenyl carbonate
IT
     copolymer 65503-32-4P, Bisphenol A-diphenyl carbonate-hydroquinone
                111707-77-8P, Bisphenol A-carbonic acid-ethylene glycol
     copolymer
     copolymer
               137593-28-3P, Bisphenol A-diphenyl carbonate-1,1,1-tris(4-
    hydroxyphenyl) ethane copolymer
                                    202122-48-3P, Bisphenol
    A-catechol-carbonic acid copolymer
     RL: IMF (Industrial manufacture); PREP (Preparation)
        (method for prepg. polycarbonate by solid-state polymn.)
             THERE ARE 3 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE.CNT
RE
(1) Fukawa; US 5204377 1993 CAPLUS
(2) Fukuoka; US 4948871 1990 CAPLUS
(3) Sivaram; US 5266659 1993 CAPLUS
    ANSWER 11 OF 12 CAPLUS COPYRIGHT 2006 ACS on STN
L17
AN
    1995:416348 CAPLUS
DN
    122:187376
    Entered STN: 16 Mar 1995
ED
    Method of preparing novel derivatives of 3,3'-(4,6-dihydroxy-m-
TI
    phenylene)bis(3-phenylphthalide)
IN
    Aleksandrzak, Krzysztof
    Uniwersytet Mikolaja Kopernika, Pol.
PΑ
SO
    Pol., 3 pp.
    CODEN: POXXA7
DT
    Patent
LA
    Polish
IC
    ICM C07D307-885
CC
    27-7 (Heterocyclic Compounds (One Hetero Atom))
FAN.CNT 1
    PATENT NO.
                        KIND
                               DATE
                                          APPLICATION NO.
                                                                 DATE
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                               -----
                                           -----
    PL 162564
                        B1
                               19931231
                                          PL 1990-284232
                                                                  19900309
PRAI PL 1990-284232
                               19900309
CLASS
 PATENT NO.
                CLASS PATENT FAMILY CLASSIFICATION CODES
                ----
PL 162564
                ICM
                       C07D307-885
                       C07D0307-885 [ICM,5]
                IPCI
    CASREACT 122:187376
os
GI
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/ Structure 3 in file .gra /
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Title compds. I [R = Me, F, Cl, Br, H] are prepd. by condensation of
AB
     monosubstituted 2-benzoylbenzoic acids II with
                                                     ***resorcinol***
                                                                          (III)
     in concd. H2SO4. I are intermediates (no data) for derivs. of
     9-acetoxy-10-phenylanthracene which have blue-violet fluorescence and are
                       ***media*** in dye
                                               ***lasers*** . For example, a
     useful as active
     mixt. of 4.3 g II (R = Me), 1.0 g III, and 50 mL concd. H2SO4 was stirred
     at room temp. for 5.5 h, then poured into water with intense stirring.
     The ppt. was filtered, dried, and crystd. from AcOH to give 4.20 g I (R =
     dihydroxyphenylenebisphenylphthalide prepn intermediate
ST
     acetoxyphenylanthracene laser dye; phthalide dihydroxyphenylenebisphenyl
     prepn intermediate laser dye; cyclocondensation benzoylbenzoic acid
       ***resorcinol***
IT
     Cyclocondensation reaction
        (cyclocondensation of benzoylbenzoic acid derivs. with
          ***resorcinol***
IT
        (laser, prepn. of (dihydroxyphenylene)bis(phenylphthalide) derivs. as
        laser dye intermediates)
     85-52-9, 2-Benzoylbenzoic acid
                                    85-55-2, 2-(4-Methylbenzoyl)benzoic acid
IT
     85-56-3, 2-(4-Chlorobenzoyl) benzoic acid 108-46-3, 1,3-Benzenediol,
                 2159-40-2, 2-(4-Bromobenzoyl)benzoic acid
     reactions
                                                            7649-92-5,
     2-(4-Fluorobenzoyl)benzoic acid
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (cyclocondensation of benzoylbenzoic acid derivs. with
          ***resorcinol***
IT
     17803-81-5DP, 9-Acetoxy-10-phenylanthracene, derivs.
     RL: PNU (Preparation, unclassified); PREP (Preparation)
        (laser dyes; prepn. of (dihydroxyphenylene)bis(phenylphthalide) derivs.
        as laser dye intermediates)
     15791-04-5P, 3,3'-(4,6-Dihydroxy-m-phenylene)bis[3-phenylphthalide]
IT
     161557-27-3P, 3,3'-(4,6-Dihydroxy-m-phenylene)bis[3-(4-
     methylphenyl)phthalide]
                              161557-28-4P, 3,3'-(4,6-Dihydroxy-m-
     phenylene) bis [3-(4-fluorophenyl) phthalide]
                                                  161557-29-5P,
     3,3'-(4,6-Dihydroxy-m-phenylene)bis[3-(4-chlorophenyl)phthalide]
     161557-30-8P, 3,3'-(4,6-Dihydroxy-m-phenylene)bis[3-(4-
     bromophenyl) phthalide]
     RL: IMF (Industrial manufacture); SPN (Synthetic preparation); PREP
     (Preparation)
        (prepn. of (dihydroxyphenylene)bis(phenylphthalide) derivs. as laser
        dye intermediates)
L17
    ANSWER 12 OF 12 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     1919:16155 CAPLUS
DN
     13:16155
OREF 13:3250c-g
     Entered STN: 16 Dec 2001
TI
     The baking powder problem
ΑU
     Pritzker, J.
CS
SO
     Schweizerische Apotheker-Zeitung (1919), 57, 363-6,380-5
     CODEN: SAZTA8; ISSN: 0036-7508
DT
     Journal
LA
    Unavailable
CC
     12 (Foods)
AB
     Tillmans and Hueblin (cf. C. A. 12, 2630) detect tartaric acid as follows:
    Heat a mixt. of 0.2-0.3 g. of baking powder (B), a little pure, white
       ***resorcinol*** . and 5 to 10 cc. H2SO4 (d. 1.84) in a test-tube over a
     small flame to 100-120-.degree.. An intensely red-violet color indicates
     tartaric acid. The test detects 2 mg. of the acid; citric and mane acids
     do not give the test. Starch must be removed previously. For the quant.
     detn. of tartaric acid, P. proceeds as follows: Stir 1 to 2 g. of B with
     50.0 cc. H2O, boil the alk. soln. for 5 min., filter while hot into a
     100-cc. flask, cool, fill up to 100 cc. Treat 50 cc. in a beaker with
     excess of glacial AcOH, add 0.5 cc. of a 20% AcOK soln. and dissolve
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therein 5 g. KCl with stirring. Rub the inner wall of the beaker with a glass rod, add race. of 96% EtOH, allow to stand overnight, filter with

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suction, wash out 5 times with 5 cc. of 45% EtOH, return the filter with
     ppt. to the beaker, add 50.0 cc. H2O, boil and titrate with 0.1 N NaOH,
     and phenolphthalein. One cc. 0.1 N NaOH indicates 0.01892 g. cream of
     tartar. Analyses of 10 com. samples 13.9 to 22.2 g. wt. per package,
     showed from 20.7 to 47.1% CaCO3 used as filler in 7 samples, and undue
     variations in the excess of NaHCO3. The following recommendations are
     made: A package for use with 500 g. of flour should liberate 1000 cc.
     (about 2 g.) of CO2. This is done by a mixt. of 6 g. (or at least 5 g.)
     of cream of tartar and 4 g. of NaHCO3. Excess of NaHCO3, may be 1 g., but
     should not exceed 3 g. per package, B contg. NH4 salts should be so
     declared. NaHSO4 being harmful, should be barred from B. The use of Al
     salts in B is unlawful in Switzerland. Ca(H2PO4)2 has been recommended;
       ***medicinal***
                           ***information***
                                              on this salt is desirable. Flour,
     starch, etc. may be used as diluents; but CaCO3 (sanctioned in Germany)
     should not exceed 20%. In judging B, dough and baking tests, observing
     taste and rising power, should be included. B should be free from harmful
     or useless ingredients.
     Baking powders
        (analysis of)
     87-69-4, Tartaric acid
        (detection and detn. in baking powder)
=> d his
     (FILE 'HOME' ENTERED AT 11:23:01 ON 30 JAN 2006)
     FILE 'CAPLUS' ENTERED AT 11:23:08 ON 30 JAN 2006
          28980 S RESORCINOL
           1449 S L1 AND (UV OR ULTRAVIOLET)
            200 S L1 AND (MASK? OR PHOTOMASK?)
              5 S L3 AND (ARYLATE OR CARBONATE OR POLYCARBONATE OR ISOPHORONE O
            136 S L2 AND (ARYLATE OR CARBONATE OR POLYCARBONATE OR ISOPHORONE O
            136 S L5 NOT L4
              5 S L6 AND (REFRACTIVE OR REFRACTION OR FRIES)
            117 S L2 AND POLYESTER
              0 S L8 AND (MASK? OR PHOTOMASK?)
           2215 S L1 AND POLYESTER
              1 S L10 AND (MASK? OR PHOTOMASK?)
            117 S L10 AND (UV OR ULTRAVIOLET)
              5 S L12 AND (PATTERN? OR REFRACTIVE OR REFRACTION OR FRIES)
              0 S SLLX
             15 S L1 AND (GRATING OR HOLOGRA?)
              3 S L1 AND (WAVEGUIDE)
             12 S L1 AND ((OPTICAL OR LASER OR INFORMATION) (5A) (MED? OR DISK OR
=> s (photomask1 or mask1) and (fries(3a)rearrang?)
1) IS NOT A RECOGNIZED COMMAND
The previous command name entered was not recognized by the system.
For a list of commands available to you in the current file, enter
"HELP COMMANDS" at an arrow prompt (=>).
=> s (photomask or mask) and (fries(3a)rearrang?)
          8024 PHOTOMASK
         11711 PHOTOMASKS
         14742 PHOTOMASK
                 (PHOTOMASK OR PHOTOMASKS)
         67468 MASK
         28022 MASKS
         78309 MASK
                 (MASK OR MASKS)
          2841 FRIES
        154673 REARRANG?
          1742 FRIES (3A) REARRANG?
             1 (PHOTOMASK OR MASK) AND (FRIES (3A) REARRANG?)
=> d all
    ANSWER 1 OF 1 CAPLUS COPYRIGHT 2006 ACS on STN
    1992:601920 CAPLUS
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DN 117:201920 Entered STN: 15 Nov 1992 ED

IT

IT

L1L2

L3 **L4** 

1.5

L6

L7

L8

L9

L10

L11

L12

L13

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T.17

L18

L18

AN

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water-soluble photosensitive compounds, photoresistant compositions
    containing them, and patterning of such photoresists
    Hayashi, Nobuaki; Ito, Masahito; Morishita, Hajime; Nonogaki, Saburo;
IN
    Odaka, Yoshiyuki; Miura, Seiji; Nishizawa, Shoko
    Hitachi, Ltd., Japan
PA
SO
    Jpn. Kokai Tokkyo Koho, 10 pp.
    CODEN: JKXXAF
DT
    Patent
LA
    Japanese
    ICM G03F007-038
    ICS G03F007-008; H01J009-227; H01L021-027
    74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other
    Reprographic Processes)
FAN.CNT 1
                              DATE APPLICATION NO.
    PATENT NO.
                      KIND
                                                               DATE
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                              _____
                                          _____
                                                                -----
    JP 04026849
                       A2 19920130 JP 1990-131283
                                                              19900523
PRAI JP 1990-131283
                              19900523
CLASS
             CLASS PATENT FAMILY CLASSIFICATION CODES
PATENT NO.
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               _____
JP 04026849
               ICM
                      G03F007-038
                ICS
                      G03F007-008; H01J009-227; H01L021-027
                IPCI
                      G03F0007-038 [ICM,5]; G03F0007-008 [ICS,5];
                      H01J0009-227 [ICS,5]; H01L0021-027 [ICS,5]
GI
/ Structure 4 in file .gra /
    The title water-sol. photosensitive compds. (I) and (II) [Z = H, OH; M =
AB
    Na, K, NH4] are obtained by condensing an acetophenone
    structure-possessing polymer with an arom. aldehyde possessing an azide
    group and an aliph. aldehyde (e.g. MeCHO, crotonaldehyde). The title
    photoresist compn. comprises the above water-sol. photosensitive compd.
    and a water-sol. polymer which reacts with the former to show reciprocity
    low failure. The title photoresist compn. coated on a substrate is
    patternwise exposed in the presence of O, and developed to produce a
    pattern in which the exposed areas produce a pattern smaller in area than
    the area of the openings in the ***photomask***
    photoresist compn high sensitivity; black matrix CRT manuf; acetophenone
    polymer condensation product
IT
    Cathode-ray tubes
       (color, black matrix, manuf. of, photoresist compn. for)
IT
    Resists
       (photo-, contg. acetophenone polymer aldehyde condensation product)
IT
    24979-70-2D, p-Hydroxystyrene homopolymer, acetylated, ***Fries***
      ***rearranged*** , condensation product with 4-azidobenzaldehyde-12-
    sulfonic acid salt and acetaldehyde 25231-54-3, Acrylamide-diacetone
    acrylamide copolymer 25300-64-5D, Maleic acid-styrene copolymer,
    acetylation product, condensation product with sodium potassium or
    ammonium 4-azidobenzaldehyde-2-sulfonate and acetaldehyde or croton
              55305-94-7D, 4-Azidobenzaldehyde-2-sulfonic acid sodium salt,
    condensation product with acetylated styrene polymer
    RL: TEM (Technical or engineered material use); USES (Uses)
       (photoresist compn. contg.)
=> s (photomask or mask) and (fries or rearrang?)
         8024 PHOTOMASK
        11711 PHOTOMASKS
        14742 PHOTOMASK
                (PHOTOMASK OR PHOTOMASKS)
        67468 MASK
        28022 MASKS
        78309 MASK
                (MASK OR MASKS)
         2841 FRIES
       154673 REARRANG?
           56 (PHOTOMASK OR MASK) AND (FRIES OR REARRANG?)
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L19 ANSWER 1 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
    2005:679964 CAPLUS
AN
ED
    Entered STN: 01 Aug 2005
TI
    Print control method and apparatus of inkjet printer
IN
    Kim, Seong Won
PA
    Lg Electronics Inc., S. Korea
    Repub. Korea, No pp. given
so
    CODEN: KRXXFC
DT
    Patent
LA
    Korean
    ICM B41J002-01
IC
FAN.CNT 1
                  KIND DATE APPLICATION NO.
    PATENT NO.
                                                           DATE
    _____
                                       ______
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                                                           _____
                     B1 19990901 KR 1997-37927 19970808
    KR 218478
PRAI KR 1997-37927
                           19970808
CLASS
 PATENT NO. CLASS PATENT FAMILY CLASSIFICATION CODES
 ______
             ICM B41J002-01
 KR 218478
              IPCI B41J0002-01 [ICM, 7]
    PURPOSE: A method and apparatus for controlling printing of an ink jet
AB
    printer is provided to prevent ink from being spread, thereby enabling
    printing of high picture quality. CONSTITUTION: A method for controlling
    printing of an ink jet printer includes the steps of dividing successive
    dots into a plurality of draft pictures and ***rearranging*** them if
    dots are successively formed in an original picture to be printed, and
    sequentially printing the respective draft pictures. An apparatus for
    controlling printing of an ink jet printer includes a DRAM(1) for storing
    data of an original picture to be printed and picture data divided at a
    lower density, a draft processor(2) for drafting the original picture from
    the DRAM to divide and output a fixture having a lower density, a
      ***mask*** pattern processor(3) for ***mask*** processing the
    original picture from the DRAM to divide and output a picture having a
    lower density, a dot counter(4) for counting the number of dots of the
    original picture from the DRAM, and a DMA for storing the picture data
    processed by the draft processor and the ***mask*** pattern processor
    in the DRAM and storing the number of the dots counted by the dot counter.
   ANSWER 2 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
    2004:1095751 CAPLUS
AN
    Entered STN: 21 Dec 2004
ED
    Method for manufacturing chip package of chip scale semiconductor
    Choi, Gwang Seong
    Hyundai Micro Electronics Co., Ltd., S. Korea
    Repub. Korean Kongkae Taeho Kongbo, No pp. given
    CODEN: KRXXA7
DT
    Patent
LA
    Korean
    ICM H01L023-48
FAN.CNT 1
                 KIND DATE APPLICATION NO. DATE
    PATENT NO.
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                                       -----
    KR 2000066832
                     A 20001115 KR 1999-14211 19990421
PRAI KR 1999-14211
                           19990421
CLASS
            CLASS PATENT FAMILY CLASSIFICATION CODES
              _____
KR 2000066832 ICM H01L023-48
              IPCI H01L0023-48 [ICM, 7]
AΒ
    PURPOSE: A method for manufacturing a chip package of a chip scale
    semiconductor is provided to improve reliability of a semiconductor
    package by filling chrome into a via hole. CONSTITUTION: A method for
    manufacturing a chip package of a chip scale semiconductor comprises the
    steps of: forming a protection layer on a semiconductor chip; forming a
    via hole; forming a first metal layer; adhering an insulating tape, a
    second metal layer, a conductive pattern for ***rearranging*** a pad
    of the first metal layer, a conductive pattern for adhering the first
    metal layer, and a pad ***rearrangement*** tape on the semiconductor
```

chip; forming a conductive layer; forming a solder \*\*\*mask\*\*\* (38);

exposing a predetermined portion of the conductive pattern for \*\*\*rearranging\*\*\* the pad; and adhering a solder ball(39) on the exposed conductive pattern.

- L19 ANSWER 3 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
- AN 2004:875158 CAPLUS
- DN 142:331590
- ED Entered STN: 22 Oct 2004
- TI Assembly of the phagocyte NADPH oxidase
- AU Nauseef, William M.
- CS Inflammation Program and Department of Medicine, Roy J. and Lucille A. Carver College of Medicine, University of Iowa, Coralville, IA 52241, USA
- SO Histochemistry and Cell Biology (2004), 122(4), 277-291
  - CODEN: HCBIFP; ISSN: 0948-6143
- PB Springer GmbH
- DT Journal; General Review
- LA English
- CC 7-0 (Enzymes)
- A review. Stimulated phagocytes undergo a burst in respiration whereby AB mol. oxygen is converted to superoxide anion through the action of an NADPH-dependent oxidase. The multicomponent phagocyte oxidase is unassembled and inactive in resting cells but assembles at the plasma or phagosomal membrane upon phagocyte activation. Oxidase components include flavocytochrome b558, an integral membrane heterodimer comprised of qp91phox and p22phox, and three cytosolic proteins, p47phox, p67phox, and Rac1 or Rac2, depending on the species and phagocytic cell. In a sense, the phagocyte oxidase is spatially regulated, with crit. elements segregated in the membrane and cytosol but ready to undergo nearly immediate assembly and activation in response to stimulation. To achieve such spatial regulation, the individual components in the resting \*\*\*mask\*\*\* phagocyte adopt conformations that potentially interactive structural domains that might mediate productive intermol. assocns. and oxidase assembly. In response to stimulation, post-translational modifications of the oxidase components release these constraints and thereby render potential interfaces accessible and interactive, resulting in translocation of the cytosolic elements to the membrane where the functional oxidase is assembled and active. This review summarizes data on the structural features of the phagocyte oxidase components and on the agonist-dependent conformational \*\*\*rearrangements\*\*\* that contribute to oxidase assembly and activation.
- ST review phagocyte NADPH oxidase component
- IT Phagocyte

(assembly and interactions of components of phagocyte NADPH oxidase) 9032-22-8, NADPH oxidase

RL: BSU (Biological study, unclassified); BIOL (Biological study)
(assembly and interactions of components of phagocyte NADPH oxidase)

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L19
    ANSWER 4 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
AN
    2004:629124 CAPLUS
ED
    Entered STN: 05 Aug 2004
TI
    Picture method of representing and picture display unit [Machine
    Translation].
IN
    Ozono,
             Jiro; Tsuji,
                           Masayuki
    Toshiba Engineering Co., Japan
PA
    Jpn. Kokai Tokkyo Koho, 10 pp.
    CODEN: JKXXAF
DT
    Patent
LA
    Japanese
     ICM G09G003-20
         G02F001-13; G02F001-1335; G02F001-1347; G09D001-00; G09F009-46;
         G09F019-14; G09G003-36
FAN.CNT 1
                        KIND
                               DATE
                                          APPLICATION NO.
                                                                 DATE
    PATENT NO.
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     JP 2004219677
                         A2
                               20040805
                                          JP 2003-6525
                                                                  20030115
PRAI JP 2003-6525
                               20030115
CLASS
                CLASS PATENT FAMILY CLASSIFICATION CODES
PATENT NO.
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                       ______
                ICM
 JP 2004219677
                       G09G003-20
                ICS
                       G02F001-13; G02F001-1335; G02F001-1347; G09D001-00;
                       G09F009-46; G09F019-14; G09G003-36
                IPCI
                       G09G0003-20 [ICM,7]; G02F0001-13 [ICS,7]; G02F0001-1335
                        [ICS,7]; G02F0001-1347 [ICS,7]; G09D0001-00 [ICS,7];
                       G09F0009-46 [ICS,7]; G09F0019-14 [ICS,7]; G09G0003-36
                        [ICS, 7]
                       2H088/EA03; 2H088/EA12; 2H088/EA14; 2H088/MA01;
                FTERM
                       2H088/MA20; 2H089/HA31; 2H089/QA16; 2H091/FA34X;
                       2H091/LA16; 2H091/LA30; 5C006/AA02; 5C006/AF11;
                       5C006/AF27; 5C006/AF38; 5C006/AF51; 5C006/BB08;
                       5C006/BF24; 5C006/BF29; 5C006/EC02; 5C006/EC08;
                       5C006/FA05; 5C080/AA10; 5C080/BB08; 5C080/CC08;
                       5C080/DD01; 5C080/DD13; 5C080/DD21; 5C080/EE01;
                       5C080/EE18; 5C080/EE26; 5C080/FF13; 5C080/GG02;
                       5C080/GG05; 5C080/GG09; 5C080/GG12; 5C080/JJ01;
                       5C080/JJ02; 5C080/JJ06; 5C080/JJ07; 5C080/KK28;
                       5C080/KK37; 5C080/KK39; 5C094/AA56; 5C094/BA43;
                       5C094/DA03; 5C094/ED15; 5C094/FA02
AB
     [Machine Translation of Descriptors]. It is not necessary to operate
    plurally, offer the picture method of representing and the display to
     which furthermore the screen information is
                                                  ***rearranged***
               Through the translucent 1st display part, after that specified
     interval separating, being the method of representing which indicates the
     picture which is indicated in the 2nd display part which is provided,
     hiding the portion of the picture which is indicated in the aforementioned
     2nd display part vis-a-vis the apparent person who possesses the
       ***mask***
                   section which cuts off light in the aforementioned 1st
     display part, sees from specified angle before the aforementioned 1st
     display part, by the aforementioned
                                          ***mask***
                                                      section the picture
     method of representing which it indicates.
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L19 ANSWER 5 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN AN 2004:344639 CAPLUS

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142:14273
ED
     Entered STN: 28 Apr 2004
    Molecular rectification and conductance switching in carbon-based
TТ
     molecular junctions by structural ***rearrangement***
                                                               accompanying
     electron injection. [Erratum to document cited in CA139:171867]
    McCreery, Richard; Dieringer, Jon; Solak, Ali Osman; Snyder, Brian; Nowak,
ΑU
     Aletha M.; McGovern, William R.; DuVall, Stacy
     Department of Chemistry, The Ohio State University, Columbus, OH, 43210,
CS
    USA
     Journal of the American Chemical Society (2004), 126(19), 6200
so
     CODEN: JACSAT; ISSN: 0002-7863
     American Chemical Society
PΒ
     Journal
DT
     English
LA
     76-3 (Electric Phenomena)
CC
     Section cross-reference(s): 66
     Residual gases in the electron beam evaporator caused titanium oxide to
AΒ
     form during Ti deposition. A lower back pressure and faster Ti deposition
     rate (4 .times. 10-7 Torr and 0.1 nm/s) resulted in a significant change
     in the appearance of Figure 3; the cor. figure is given. XPS depth
     profiling showed the formation of Ti(II) and Ti(III) oxides using the
    previous conditions. These results imply that both a Ti/TiOx layer and
     the nitroazobenzene (NAB)/NAB- layer det. the electronic behavior of the
     junction.
     erratum nitroazobenzene mol junction pyrolyzed photoresist titanium
ST
     contact rectification
IT
     Electric capacitance
     Electric current-potential relationship
     Electric rectification
     Electric resistance
     Electric switching
     Electron transfer
     Hysteresis
     Raman spectra
     Thickness
     Tunneling current
        (of nitroazobenzene mol. junctions (Erratum))
IT
     Self-assembled monolayers
     Surface roughness
     Thermal decomposition
        (rectification and switching in nitroazobenzene mol. junctions between
        pyrolyzed photoresist and titanium top contact with gold layer on
        silicon (Erratum))
IT
     Electric contacts
        (titanium; rectification and switching in nitroazobenzene mol.
        junctions between pyrolyzed photoresist and titanium top contact with
        gold layer on silicon (Erratum))
IT
     9003-53-6, Polystyrene
     RL: NUU (Other use, unclassified); PEP (Physical, engineering or chemical
     process); PYP (Physical process); PROC (Process); USES (Uses)
           ***mask*** ; rectification and switching in nitroazobenzene mol.
        junctions between pyrolyzed photoresist and titanium top contact with
        gold layer on silicon (Erratum))
IT
     195460-20-9, AZ P4330RS
     RL: CPS (Chemical process); NUU (Other use, unclassified); PEP (Physical,
     engineering or chemical process); PROC (Process); USES (Uses)
        (photoresist; rectification and switching in nitroazobenzene mol.
        junctions between pyrolyzed photoresist and titanium top contact with
        gold layer on silicon (Erratum))
IT
     37703-34-7, Nitroazobenzene
     RL: CPS (Chemical process); PEP (Physical, engineering or chemical
    process); PRP (Properties); PYP (Physical process); TEM (Technical or
     engineered material use); PROC (Process); USES (Uses)
        (rectification and switching in nitroazobenzene mol. junctions between
       pyrolyzed photoresist and titanium top contact with gold layer on
        silicon (Erratum))
IT
    1344-54-3, Titanium oxide (Ti2O3)
                                         13463-67-7, Titanium oxide (TiO2),
     formation (nonpreparative)
    RL: FMU (Formation, unclassified); FORM (Formation, nonpreparative)
        (rectification and switching in nitroazobenzene mol. junctions between
       pyrolyzed photoresist and titanium top contact with gold layer on
       silicon (Erratum))
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DN

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7440-06-4, Platinum, processes 7440-32-6, Titanium, processes
IT
     7440-57-5, Gold, processes
     RL: PEP (Physical, engineering or chemical process); PYP (Physical
     process); TEM (Technical or engineered material use); PROC (Process); USES
     (Uses)
        (rectification and switching in nitroazobenzene mol. junctions between
       pyrolyzed photoresist and titanium top contact with gold layer on
        silicon (Erratum))
IT
     7440-21-3, Silicon, uses
     RL: TEM (Technical or engineered material use); USES (Uses)
        (rectification and switching in nitroazobenzene mol. junctions between
       pyrolyzed photoresist and titanium top contact with gold layer on
       silicon (Erratum))
    ANSWER 6 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
AN
    2004:287506 CAPLUS
ED
     Entered STN: 08 Apr 2004
                 data compilation method, ***mask***
ΤI
       ***Mask***
                                                          production method,
    production method and semiconductor device of semiconductor device
     [Machine Translation].
IN
    Kurashima,
                Kenji
PA
    Seiko Epson Corp., Japan
SO
    Jpn. Kokai Tokkyo Koho, 8 pp.
    CODEN: JKXXAF
DT
     Patent
    Japanese
LA
     ICM H01L021-82
     ICS G06F017-50; H01L021-3205; H01L021-822; H01L027-04
FAN.CNT 1
    PATENT NO.
                      KIND
                               DATE
                                         APPLICATION NO.
                                                                DATE
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    JP 2004111530
                       A2
                               20040408
                                         JP 2002-270155
                                                                20020917
PRAI JP 2002-270155
                               20020917
CLASS
 PATENT NO.
                CLASS PATENT FAMILY CLASSIFICATION CODES
                _____
 JP 2004111530 ICM
                       H01L021-82
                ICS
                       G06F017-50; H01L021-3205; H01L021-822; H01L027-04
                IPCI
                       H01L0021-82 [ICM,7]; G06F0017-50 [ICS,7]; H01L0021-3205
                       [ICS,7]; H01L0021-822 [ICS,7]; H01L0027-04 [ICS,7]
                       5B046/AA08; 5B046/BA04; 5B046/JA01; 5F033/UU01;
                       5F033/UU03; 5F033/XX25; 5F038/BH19; 5F038/CA17;
                       5F038/CD05; 5F038/CD09; 5F038/CD13; 5F038/EZ09;
                       5F038/EZ10; 5F064/AA03; 5F064/AA04; 5F064/DD26;
                       5F064/EE43; 5F064/EE45; 5F064/EE46; 5F064/EE47;
                       5F064/HH06; 5F064/HH09; 5F064/HH11
AB
     [Machine Translation of Descriptors]. Common running error of plural
     signal wiring is detected automatically, the ***mask*** data
                                                        ***mask***
     compilation method of being possible to draw up the
     correcting arrangement or wiring in error place automatically is offered.
     In order to solve the topic above, as for the
                                                   ***mask***
     compilation method of relating to this invention, the step (d) which
     arranges repetition wiring the step (c) which is converted to the type
    which can be utilized the information which is outputted in step (b) and
     the step (b) which output the information regarding the common running
     error of signal wiring the step (a) which arranges signal wiring inside
     the layout territory making use of the 1st program and, making use of the
     2nd program at the time of 1st programming and, making use of the
     information which 1st it is programmed and is converted and and, making
    use of the 1st program repetition wiring In order to detour, it possesses
    with the step (e) which
                             ***rearranges***
                                                signal wiring.
L19
    ANSWER 7 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
AN
    2004:156938 CAPLUS
DN
    140:339473
ED
    Entered STN: 26 Feb 2004
TT
    Thermodynamic and kinetic data for adduct formation, cis-trans
    isomerization and redox reactions of ML4 complexes: A case study with
    rhodium- and iridium-tropp complexes in d8, d9 and d10 valence electron
    configurations (tropp = dibenzotropylidene phosphanes)
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Breher, Frank; Rueegger, Heinz; Mlakar, Marina; Rudolph, Manfred; Deblon,

Stephan; Schoenberg, Hartmut; Boulmaaz, Souad; Thomaier, Joerg;

IIA

Gruetzmacher, Hansjoerg Department of Chemistry and Applied Biology (D-CHAB), ETH Hoenggerberg, CS Zurich, 8093, Switz. Chemistry--A European Journal (2004), 10(3), 641-653 SO CODEN: CEUJED; ISSN: 0947-6539 PB Wiley-VCH Verlag GmbH & Co. KGaA DT Journal LA English 29-13 (Organometallic and Organometalloidal Compounds) CC Section cross-reference(s): 22, 27, 72, 75 The formation of adducts of the square-planar 16-electron complexes AB trans-[M(troppPh)2]+ and cis-[M(troppPh)2]+ (M = Rh, Ir; troppPh = 5-(diphenylphosphino)-5H-dibenzo[a,d]cycloheptene) with acetonitrile and Cl-, and the redox chem. of these complexes was investigated by various phys. methods (NMR and UV-visible spectroscopy, square-wave voltammetry), in order to obtain some fundamental thermodn. and kinetic data for these systems. A trans/cis isomerization cannot be detected for [M(troppPh)2]+ in non-coordinating solvents. However, both isomers are connected through equil. of the type trans-[M(troppPh)2]+ + L.dblarw.[ML(troppPh)2]n.dblarw. cis-[M(troppPh)2]+ + L, involving five-coordinate intermediates [ML(troppPh)2]n (L = MeCN, n = 1; L = Cl-, n = 0). Values of dissocn. or formation equil. const. Kd (Kf) and dissocn. or formation rate const. kd (kf) were obtained. The formation reactions are fast, esp. with the trans-isomers (kf > 1 .times. 105 M-1 s-1). The reaction with the sterically more hindered cis-isomers is at least one order of magnitude slower. The stability of the five-coordinate complexes [ML(troppPh)2]n increases with Ir > Rh and Cl- > MeCN. The dissocn. reaction has a pronounced influence on the square-wave (SW) voltammograms of trans/cis-[Ir(troppPh)2]+. With the help of the thermodn. and kinetic data independently detd. by other phys. means, these reactions could be simulated and allowed the setting up of a reaction sequence. Examn. of the data obtained showed that the trans/cis isomerization is a process with a low activation barrier for the four-coordinate 17-electron complexes[M(troppPh)2]0 and esp. that a disproportionation reaction 2(trans/cis-[M(troppPh)2]0).fwdarw.[M(troppPh)2]+ + [M(troppPh)2]- may be sufficiently fast to \*\*\*mask\*\*\* the true reactivity of the paramagnetic species, which are probably less reactive than their diamagnetic equil. partners. rhodium iridium tropylidene phosphine bidentate ligand cis trans isomerization; cis trans isomerization equil kinetics tropylidene phosphine complex; square wave voltammetry rhodium iridium tropylidene phosphine bidentate complex; tropylidene phosphine bidentate cis trans iridium rhodium complex; crystal structure rhodium iridium tropilidenylphosphine pentacoordinate complex; mol structure rhodium iridium tropylidenylphosphine pentacoordinate complex Transition metal complexes RL: CPS (Chemical process); PEP (Physical, engineering or chemical process); PRP (Properties); RCT (Reactant); PROC (Process); RACT (Reactant (alkene complexes, tropilidenylphosphine; thermodn. and kinetics of cis-trans-isomerization of rhodium and iridium tropylidenylphosphine bidentate complexes) IT Isomerization (cis-trans; thermodn. and kinetics of cis-trans-isomerization of rhodium and iridium tropylidenylphosphine bidentate complexes) IT Disproportionation (electrochem. redox reactions of rhodium and iridium tropylidenylphosphine bidentate complexes) IT Coordination number (five; prepn., isomerization kinetics and thermodn. of pentacoordinate rhodium and iridium tropylidenylphosphine bidentate complexes) Activation energy IT Dissociation constant Formation constant (formation and isomerization kinetics and thermodn. of pentacoordinate rhodium and iridium tropylidenylphosphine bidentate complexes) IT Thermodynamics (of complexation; formation and dissocn. consts. of isomeric rhodium and iridium tropylidenylphosphine bidentate complexes) IT Crystal structure Molecular structure (of rhodium and iridium tropylidenylphosphine pentacoordinate

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complexes)
IT
     Group VIII element complexes
     RL: CPS (Chemical process); PEP (Physical, engineering or chemical
     process); PRP (Properties); RCT (Reactant); PROC (Process); RACT (Reactant
        (rhodium, iridium; thermodn. and kinetics of cis-trans-isomerization of
        rhodium and iridium tropylidenylphosphine bidentate complexes)
     Redox reaction
IT
     Square wave voltammetry
        (square-wave voltammetric redox reactions of rhodium and iridium
        tropylidenylphosphine bidentate complexes)
IT
     Complexation
        (thermodn.; formation and dissocn. consts. of isomeric rhodium and
        iridium tropylidenylphosphine bidentate complexes)
IT
     Alkenes, reactions
     RL: CPS (Chemical process); PEP (Physical, engineering or chemical
     process); PRP (Properties); RCT (Reactant); PROC (Process); RACT (Reactant
     or reagent)
        (transition metal complexes, tropilidenylphosphine; thermodn. and
        kinetics of cis-trans-isomerization of rhodium and iridium
        tropylidenylphosphine bidentate complexes)
     220083-45-4
                   679433-18-2
TT
     RL: PRP (Properties)
        (crystal structure; thermodn. and kinetics of cis-trans-isomerization
        of rhodium and iridium tropylidenylphosphine bidentate complexes)
IT
     210969-25-8
     RL: CPS (Chemical process); PEP (Physical, engineering or chemical
     process); PROC (Process)
                     ***rearrangement*** ; thermodn. and kinetics of
        (fluxional
        cis-trans-isomerization of rhodium and iridium tropylidenylphosphine
        bidentate complexes)
                   400649-56-1
IT
     220083-48-7
     RL: CPS (Chemical process); FMU (Formation, unclassified); PEP (Physical,
     engineering or chemical process); FORM (Formation, nonpreparative); PROC
        (redox potential, cis-trans isomerization; thermodn. and kinetics of
        cis-trans-isomerization of rhodium and iridium tropylidenylphosphine
        bidentate complexes)
     220083-46-5
                   220197-87-5
                                 400649-58-3
     RL: CPS (Chemical process); FMU (Formation, unclassified); PEP (Physical,
     engineering or chemical process); FORM (Formation, nonpreparative); PROC
     (Process)
        (redox potential; thermodn. and kinetics of cis-trans-isomerization of
        rhodium and iridium tropylidenylphosphine bidentate complexes)
     210969-27-0
                   400608-26-6
                               679843-90-4
     RL: CPS (Chemical process); FMU (Formation, unclassified); PEP (Physical,
     engineering or chemical process); FORM (Formation, nonpreparative); PROC
     (Process)
        (thermodn. and kinetics of cis-trans-isomerization of rhodium and
        iridium tropylidenylphosphine bidentate complexes)
RE.CNT
              THERE ARE 52 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE
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- L19 ANSWER 8 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
- AN 2003:604452 CAPLUS
- DN 139:171867
- ED Entered STN: 07 Aug 2003
- TI Molecular Rectification and Conductance Switching in Carbon-Based Molecular Junctions by Structural \*\*\*Rearrangement\*\*\* Accompanying Electron Injection
- AU McCreery, Richard; Dieringer, Jon; Solak, Ali Osman; Snyder, Brian; Nowak, Aletha M.; McGovern, William R.; DuVall, Stacy
- CS Department of Chemistry, The Ohio State University, Columbus, OH, 43210, USA
- SO Journal of the American Chemical Society (2003), 125(35), 10748-10758 CODEN: JACSAT; ISSN: 0002-7863
- PB American Chemical Society
- DT Journal
- LA English
- CC 76-3 (Electric Phenomena)
  - Section cross-reference(s): 66
- ABMol. junctions were fabricated consisting of a 3.7 nm thick layer of nitroazobenzene (NAB) mols. between a pyrolyzed photoresist substrate (PPF) and a Ti top contact which was protected from oxidn. by a layer of Raman spectroscopy, XPS, and AFM revealed that the NAB layer was 2-3 mols. thick and was bonded to the two conducting contacts by C-C and N-Ti covalent bonds. The current/voltage behavior of the PPF/NAB(3.7)/Ti junctions showed strong and reproducible rectification, with the current at +2 V exceeding that at -2 V by a factor of 600. The obsd. c.d. at +3 V was 0.71 A/cm2, or .apprx.105 e-/s/mol. The i/V response was strongly dependent on temp. and scan rate, with the rectification ratio decreasing for lower temp. and faster scans. Junction cond. increased with time over several seconds at room temp. in response to pos. voltage pulses, with the rate of increase larger for more pos. potentials. Voltage pulses to pos. potentials and back to zero volts revealed that electrons are injected from the Ti to the NAB, to the extent of .apprx.0.1-1 e-/mol. for a +3 V These electrons cause an activated transition of the NAB into a more conductive quinoid state, which in turn causes an increase in cond. The transition to the quinoid state involves nuclear \*\*\*rearrangement\*\*\*

which occurs on a sub-millisecond to several 2nd time scale, depending on the voltage applied. The quinoid state is stable as long as the applied elec. field is present, but reverts back to NAB within several minutes after the field is relaxed. The results are interpreted in terms of a thermally activated, potential dependent electron transfer into the 3.7 nm NAB layer, which brings about a cond. increase of several orders of magnitude. nitroazobenzene mol junction pyrolyzed photoresist titanium contact rectification Electric capacitance Electric current-potential relationship Electric rectification Electric resistance Electric switching Electron transfer Hysteresis Raman spectra Thickness . Tunneling current (of nitroazobenzene mol. junctions) Self-assembled monolayers Surface roughness Thermal decomposition (rectification and switching in nitroazobenzene mol. junctions between pyrolyzed photoresist and titanium top contact with gold layer on silicon) Electric contacts (titanium; rectification and switching in nitroazobenzene mol. junctions between pyrolyzed photoresist and titanium top contact with gold layer on silicon) 9003-53-6, Polystyrene RL: NUU (Other use, unclassified); PEP (Physical, engineering or chemical process); PYP (Physical process); PROC (Process); USES (Uses) \*\*\*mask\*\*\* ; rectification and switching in nitroazobenzene mol. junctions between pyrolyzed photoresist and titanium top contact with gold layer on silicon) 195460-20-9, AZ P4330RS RL: CPS (Chemical process); NUU (Other use, unclassified); PEP (Physical, engineering or chemical process); PROC (Process); USES (Uses) (photoresist; rectification and switching in nitroazobenzene mol. junctions between pyrolyzed photoresist and titanium top contact with gold layer on silicon) 37703-34-7, Nitroazobenzene RL: CPS (Chemical process); PEP (Physical, engineering or chemical process); PRP (Properties); PYP (Physical process); TEM (Technical or engineered material use); PROC (Process); USES (Uses) (rectification and switching in nitroazobenzene mol. junctions between pyrolyzed photoresist and titanium top contact with gold layer on silicon) 7440-06-4, Platinum, processes 7440-32-6, Titanium, processes 7440-57-5, Gold, processes RL: PEP (Physical, engineering or chemical process); PYP (Physical process); TEM (Technical or engineered material use); PROC (Process); USES (Uses) (rectification and switching in nitroazobenzene mol. junctions between pyrolyzed photoresist and titanium top contact with gold layer on silicon) 7440-21-3, Silicon, uses RL: TEM (Technical or engineered material use); USES (Uses) (rectification and switching in nitroazobenzene mol. junctions between pyrolyzed photoresist and titanium top contact with gold layer on silicon) RE.CNT 71 THERE ARE 71 CITED REFERENCES AVAILABLE FOR THIS RECORD (1) Anariba, F; Anal Chem, in press 2003, V75 CAPLUS (2) Anariba, F; J Phys Chem B 2002, V106, P10355 CAPLUS (3) Aviram, A; Chem Phys Lett 1974, V29, P277 CAPLUS (4) Biswas, N; J Phys Chem A 2000, V104, P2734 CAPLUS

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L19
ΑN
     2003:377893
                 CAPLUS
DN
     138:393663
ED
     Entered STN:
                  18 May 2003
     Lateral epitaxial overgrowth of InAs on (100) GaAs substrates
TI
     Suryanarayanan, Ganesan; Khandekar, Anish A.; Hawkins, Brian E.; Kuech,
ΑU
     Thomas F.; Babcock, Susan E.
     Materials Science Program, University of Wisconsin - Madison, Madison, WI,
CS
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53706, USA
     Materials Research Society Symposium Proceedings (2003), 744 (Progress in
SO
     Semiconductors II--Electronic and Optoelectronic Applications), 9-14
     CODEN: MRSPDH; ISSN: 0272-9172
PB
     Materials Research Society
DT
     Journal
LА
     English
     76-3 (Electric Phenomena)
CC
     The microstructure of epitaxial InAs thin films grown by MOCVD on
AB
                  -patterned "LEO" (lateral epitaxial overgrowth) GaAs and on
     unpatterned GaAs substrates was studied using double-crystal x-ray
     diffraction, SEM, and cross-sectional TEM. This paper describes the
     improvement in crystal quality (factor of 20 redn. in x-ray rocking curve
     width), the order of magnitude redn. in dislocation d., and the
       ***rearrangement***
                             of the remaining extended defects that were obsd. in
     the LEO material when compared to the film grown on the unpatterned wafer.
     indium arsenide lateral epitaxial overgrowth gallium arsenide substrate
ST
IT
     Crystal defects
     Crystallinity
     Epitaxy
     Semiconductor films
     Semiconductor heterojunctions
        (lateral epitaxial overgrowth of InAs on GaAs(100) substrates)
IT
     Vapor deposition process
        (metalorg.; lateral epitaxial overgrowth of InAs on GaAs(100)
        substrates)
     3385-78-2, Trimethyl indium
                                   7784-42-1, Arsine
IT
     RL: CPS (Chemical process); PEP (Physical, engineering or chemical
     process); PROC (Process)
        (lateral epitaxial overgrowth of InAs on GaAs(100) substrates)
     1303-11-3, Indium arsenide, properties
TT
     RL: CPS (Chemical process); PEP (Physical, engineering or chemical
     process); PRP (Properties); PROC (Process)
        (lateral epitaxial overgrowth of InAs on GaAs(100) substrates)
     1303-00-0, Gallium arsenide, processes
     RL: PEP (Physical, engineering or chemical process); PYP (Physical
     process); PROC (Process)
        (lateral epitaxial overgrowth of InAs on GaAs(100) substrates)
RE.CNT 7
              THERE ARE 7 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE
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(3) Kim, S; J Korean Phys Soc 2002, V40(1), P119 CAPLUS
(4) Marchand, H; J Cryst Growth 2000, V209, P581
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(6) Yi, S; Appl Phys Lett 2000, V77(6), P842 CAPLUS
(7) Zheleva, T; Appl Phys Lett 1997, V71, P2472 CAPLUS
     ANSWER 10 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
AN
     2003:294063 CAPLUS
DN
     139:113188
     Entered STN: 16 Apr 2003
ED
     Ribosomal protein S15 represses its own translation via adaptation of an
TI
     rRNA-like fold within its mRNA
ΑU
     Serganov, Alexander; Polonskaia, Ann; Ehresmann, Bernard; Ehresmann,
     Chantal; Patel, Dinshaw J.
     Cellular Biochemistry and Biophysics Program, Memorial Sloan-Kettering
CS
     Cancer Center, New York, NY, 10021, USA
SO
     EMBO Journal (2003), 22(8), 1898-1908
     CODEN: EMJODG; ISSN: 0261-4189
PB
     Oxford University Press
DΤ
     Journal
LA
     English
CC
     6-1 (General Biochemistry)
     Section cross-reference(s): 10
     The 16S rRNA-binding ribosomal protein S15 is a key component in the
AB
     assembly of the small ribosomal subunit in bacteria. We have shown that
     S15 from the extreme thermophile Thermus thermophilus represses the
     translation of its own mRNA in vitro, by interacting with the leader
     segment of its mRNA. The S15 mRNA-binding site was characterized by
     footprinting expts., deletion anal. and site-directed mutagenesis. S15
     binding triggers a conformational ***rearrangement***
                                                               of its mRNA into
```

a fold that mimics the conserved three-way junction of the S15 rRNA-binding site. This conformational change \*\*\*masks\*\*\* ribosome entry site, as demonstrated by direct competition between the ribosomal subunit and S15 for mRNA binding. A comparison of the T.thermophilus and Escherichia coli regulation systems reveals that the two regulatory mRNA targets do not share any similarity and that the mechanisms of translational inhibition are different. Our results highlight an astonishing plasticity of mRNA in its ability to adapt to evolutionary constraints, that contrasts with the extreme conservation of the rRNA-binding site.

ribosomal protein S15 mRNA recognition translation repression Thermus ST IT

Conformation

(RNA; rRNA-like fold in mRNA by binding of ribosomal protein S15 resulted in repression of its own translation)

IT Ribosomal proteins

> RL: BSU (Biological study, unclassified); BIOL (Biological study) (S15; ribosomal protein S15 represses its own translation via adaptation of rRNA-like fold within mRNA)

IT mRNA

> RL: BSU (Biological study, unclassified); BIOL (Biological study) (for ribosomal protein S15; ribosomal protein S15 represses its own translation via adaptation of rRNA-like fold within mRNA)

IT Molecular recognition

(of rRNA and mRNA by ribosomal protein S15; rRNA-like fold in mRNA by binding of ribosomal protein S15 resulted in repression of its own translation)

IT

RL: BSU (Biological study, unclassified); BIOL (Biological study) (recognition by ribosomal protein S15 of conformation of; rRNA-like fold in mRNA by binding of ribosomal protein S15 resulted in its own translation)

Thermus thermophilus

(ribosomal protein S15 from; ribosomal protein S15 represses its own translation via adaptation of rRNA-like fold within mRNA)

Translation, genetic

(ribosomal protein S15 represses its own translation via adaptation of rRNA-like fold within mRNA)

IT Escherichia coli

> (translation repression mechanism compared with; rRNA-like fold in mRNA by binding of ribosomal protein S15 resulted in its own translation)

RE.CNT THERE ARE 47 CITED REFERENCES AVAILABLE FOR THIS RECORD RE

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- ANSWER 11 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN L19
- 2003:274156 CAPLUS AN
- DN 139:199702
- Entered STN: 09 Apr 2003 ED
- TI Maturity-related variation in the bulk-transformation kinetics of a suite of compositionally related New Zealand coals
- Killops, Steve; Jarvie, Dan; Sykes, Richard; Funnell, Rob AU
- Institute of Geological and Nuclear Sciences, Lower Hutt, 30368, N. Z. CS
- Marine and Petroleum Geology (2002), 19(9), 1151-1168 SO CODEN: MPEGD8; ISSN: 0264-8172
- PB Elsevier Science Ltd.
- DT Journal
- LA English

AB

- CC
- 51-15 (Fossil Fuels, Derivatives, and Related Products) Bulk HI transformation kinetics were detd. by open-system pyrolysis for a suite of compositionally related Late Cretaceous to Paleocene coals from Tara-1 well, Great South Basin, New Zealand. These coals span a maturity range encompassing the onset of significant oil generation and expulsion. Kinetic parameters were also obtained for one of the immature samples following artificial maturation by hydrous pyrolysis. Kinetic models were based on three modes of optimization of kinetic parameters: discrete-Eact distribution with single variable A value; discrete-Eact distribution with fixed A (1014 s-1); and Gaussian-Eact distribution with single variable A value. HI transformation-rate vs. temp. envelopes for the naturally matured coals exhibited an abrupt jump to higher temp. near Rank(Sr) 12.5, apparently coinciding with the onset of significant paraffinic oil expulsion, for all optimization modes. The artificially matured sample does not predict this shift in transformation envelopes, which suggests that certain of the reactions that occur under natural maturation do not occur during lab. pyrolysis. The structural \*\*\*rearrangements\*\*\* occurring up to the expulsion threshold, some or all of which are responsible for the increase in HI up to Rank(Sr).apprx.11, are not manifested in changes in HI transformation-rate envelopes. However, the \*\*\*mask\*\*\* presence of adsorbed bitumen may the influence of \*\*\*rearrangements\*\*\* during optimization of the kinetic data, which could explain the behavior of the transformation-rate envelopes in the Rank(Sr) 11.0-12.5 range obtained from the discrete-Eact free-A optimization. This behavior involves a regression in transformation-rate envelopes to lower temps. as the amt. of retained bitumen increases prior to expulsion. The almost perfect nesting of transformation-rate envelopes subsequent to oil expulsion suggests either \*\*\*rearrangement\*\*\* does not produce a that any further structural significant change in the A and Eact distributions of hydrocarbongenerating bonds, or that the expulsion drastically reduces the degree of \*\*\*rearrangements\*\*\* involving hydrocarbon-generating moieties within the kerogen. Kinetic parameters for immature coals should not be considered ideal for modeling the whole phase of hydrocarbon generation. Nevertheless, the kinetic parameters for the least mature Tara coal (Rank(Sr).apprx.8.5) reproduced the normalized HI trend for the entire suite of coals with reasonable accuracy over the maturity range considered (Rank(Sr).apprx.8.5-15.0), only slightly underestimating conversion at the lower maturity levels and overestimating it slightly at the higher levels. coal petroleum genesis transformation kinetics New Zealand

ST

Petroleum genesis Reaction kinetics

(maturity-related variation in the bulk-transformation kinetics of a suite of compositionally related New Zealand coals)

IT Coal, processes

RL: GFM (Geological or astronomical formation); GPR (Geological or astronomical process); FORM (Formation, nonpreparative); PROC (Process) (maturity-related variation in the bulk-transformation kinetics of a suite of compositionally related New Zealand coals)

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- (2) Armstrong, P; American Association of Petroleum Geologists Bulletin 1996, V80, P1216 CAPLUS
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- L19 ANSWER 12 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
- AN 2002:812699 CAPLUS
- ED Entered STN: 25 Oct 2002
- TI Production method of pattern formation method and semiconductor integrated circuit device. [Machine Translation].
- IN Terasawa, Tsuneo; Tanaka, Toshihiko; Hasegawa, Takao; Hattori,
   Koji

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Hitachi Ltd., Japan
PA
SO
    Jpn. Kokai Tokkyo Koho, 11 pp.
    CODEN: JKXXAF
דת
    Patent
LΑ
    Japanese
IC
    ICM H01L021-027
    ICS G03F001-08; G03F007-20; H01L021-3205; H01L023-12
FAN.CNT 1
                                       APPLICATION NO.
                                                              DATE
                     KIND DATE
    PATENT NO.
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                                                              _____
    JP 2002313696
                      A2 20021025 JP 2001-114762
                                                             20010413
PΙ
                            20010413
PRAI JP 2001-114762
CLASS
 PATENT NO. CLASS PATENT FAMILY CLASSIFICATION CODES
               ____
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 JP 2002313696 ICM H01L021-027
               ICS G03F001-08; G03F007-20; H01L021-3205; H01L023-12
               IPCI H01L0021-027 [ICM,7]; G03F0001-08 [ICS,7]; G03F0007-20
                      [ICS,7]; H01L0021-3205 [ICS,7]; H01L0023-12 [ICS,7]
     [Machine Translation of Descriptors]. In formation process of the bonding
AB
    pad and ***rearrangement*** wiring, the semiconductor integrated
    circuit device is produced low the price which designates the mercury lamp
    as the illuminant making use of the exposure device and the
    ***photomask*** which designates organic photopolymer as the substantial shade material. ***Mask*** cost can be decreased. In addition, the
    high performance it is possible in the little multi kinds according to
    customer use to raise the productivity of the semiconductor device.
    ANSWER 13 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
AN
    2002:812537 CAPLUS
ED
    Entered STN: 25 Oct 2002
    Bulk acoustic resonator and method and system for wafer level alignment of
ΤI
    filter. [Machine Translation].
IN
    [NAME NOT TRANSLATED], [NAME NOT TRANSLATED]; [NAME NOT TRANSLATED],
    [NAME NOT TRANSLATED]; [NAME NOT TRANSLATED], [NAME NOT TRANSLATED]
    [NAME NOT TRANSLATED], Japan
PA
    Jpn. Kokai Tokkyo Koho, 9 pp.
SO
    CODEN: JKXXAF
DT
    Patent
LΑ
    Japanese
    ICM G10K011-02
    ICS H01L041-22; H03H003-04
FAN.CNT 1
                     KIND DATE APPLICATION NO.
                                                           DATE
    PATENT NO.
    JP 2002311959
                     ----
                                        -----
                                                              -----
                      A2 20021025
                                        JP 2002-18553
                                                             20020128
PRAI US 2001-784634
                      Α
                            20010215
CLASS
            CLASS PATENT FAMILY CLASSIFICATION CODES
 PATENT NO.
               _____
 JP 2002311959 ICM G10K011-02
               ICS
                      H01L041-22; H03H003-04
               IPCI
                      G10K0011-02 [ICM,7]; H01L0041-22 [ICS,7]; H03H0003-04
                      [ICS, 7]
AB
     [Machine Translation of Descriptors]. Method and the system in order to
    achieve the resonance frequency of desire of the bulk acoustic wave device
    inside allowance of specification are offered. Being the method of making
    the bulk acoustic wave device align which is produced from plural acoustic
    wave generation and control which were formed on the baseplate layer,
    approaching the ***mask*** which possesses the aperture to the surface
    of the aforementioned device, offering the beam of the particle with
    respect to process and the ***mask*** which it provides, the
    aforementioned particle beam making one part the aperture pass at least,
    the aforementioned device surface substantially making the contact area
    contact which is demarcated by the aforementioned aperture,
      ***rearranging*** the aperture of process and the aforementioned
      ***mask*** which change the thickness of the aforementioned device
    substantially in cross direction vis-a-vis the aforementioned device
    surface, changes the aforementioned contact area the process which The
    method of including.
```

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DN
     137:227381
ED
     Entered STN: 16 Jun 2002
     The t(4;22)(q12;q11) in atypical chronic myeloid leukaemia fuses BCR to
TI
ΑU
     Baxter, E. Joanna; Hochhaus, Andreas; Bolufer, Pascual; Reiter, Andreas;
     Fernandez, Jose M.; Senent, Leonor; Cervera, Jose; Moscardo, Federico;
     Sanz, Miguel A.; Cross, Nicholas C. P.
     Wessex Regional Genetics Laboratory, Salisbury District Hospital,
CS
     Salisbury, SP2 8BJ, UK
     Human Molecular Genetics (2002), 11(12), 1391-1397
SO
     CODEN: HMGEE5; ISSN: 0964-6906
PΒ
     Oxford University Press
DT
     Journal
LA
     English
     3-3 (Biochemical Genetics)
CC
     Section cross-reference(s): 6, 14
     Chronic myeloid leukemia (CML) is characterized by the presence of the
AB
     BCR-ABL fusion gene, usually in assocn. with the t(9;22)(q34;q11)
     translocation. We report here the identification and cloning of a rare
     variant translocation, t(4;22)(q12;q11), in two patients with a CML-like
     myeloproliferative disease (MPD). RT-PCR indicated that both patients
     were neg. for BCR-ABL, but FISH anal. suggested that the BCR gene was
       ***rearranged*** . Since other translocations in MPDs frequently involve
     tyrosine kinases, we designed a multiplex PCR to search for mRNA fusions
     between BCR and three potential partner genes at 4q12: KIT, KDR and
     PDGFRA. An unusual inframe BCR-PDGFRA fusion mRNA was identified in both
     patients, with either BCR exon 7 or exon 12 fused to short BCR
     intron-derived sequences, which were in turn fused to part of PDGFRA exon
          Sequencing of the genomic breakpoint junctions showed that the
     chromosome 22 breakpoints fell in BCR introns whereas the chromosome 4
     breakpoints were within PDGFRA exon 12. This is the first report of a
     fusion gene that involves PDGFRA. Our findings indicate that apparently
     simple cytogenetic variants of t(9;22) do not always
                                                            ***mask***
     cryptic BCR-ABL fusion, even when found in assocn. with clin. and hematol.
     indications of CML.
     human chronic myeloid leukemia BCR PDGFRA gene fusion; chromosome
     translocation BCR PDGFRA human leukemia
IT
     Chimeric gene
     RL: BSU (Biological study, unclassified); DGN (Diagnostic use); BIOL
     (Biological study); USES (Uses)
        (BCR exon 7 or exon 12 fused to PDGFRA exon 12; translocations
        t(4;22)(q12;q11) in atypical chronic myeloid leukemia fuses BCR to
        PDGFRA)
IT
     RL: BSU (Biological study, unclassified); DGN (Diagnostic use); BIOL
     (Biological study); USES (Uses)
        (BCR-PDGFRA fusion; translocations t(4;22)(q12;q11) in atypical chronic
        myeloid leukemia fuses BCR to PDGFRA)
IT
     Gene, animal
     RL: BSU (Biological study, unclassified); DGN (Diagnostic use); BIOL
     (Biological study); USES (Uses)
        (BCR; translocations t(4;22)(q12;q11) in atypical chronic myeloid
        leukemia fuses BCR to PDGFRA)
     Gene, animal
     RL: BSU (Biological study, unclassified); DGN (Diagnostic use); BIOL
     (Biological study); USES (Uses)
        (PDGFRA; translocations t(4;22)(q12;q11) in atypical chronic myeloid
        leukemia fuses BCR to PDGFRA)
IT
     Leukemia
        (chronic myelocytic; translocations t(4;22)(q12;q11) in atypical
        chronic myeloid leukemia fuses BCR to PDGFRA)
IT
     Genetic element
     RL: BSU (Biological study, unclassified); DGN (Diagnostic use); BIOL
     (Biological study); USES (Uses)
        (exon, 127, of PDGFRA; translocations t(4;22)(q12;q11) in atypical
        chronic myeloid leukemia fuses BCR to PDGFRA)
IT
     Genetic element
     RL: BSU (Biological study, unclassified); DGN (Diagnostic use); BIOL
     (Biological study); USES (Uses)
        (exon, 7 and 12, of BCR; translocations t(4;22)(q12;q11) in atypical
```

chronic myeloid leukemia fuses BCR to PDGFRA)

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IT
     Diagnosis
        (genetic; translocations t(4;22)(q12;q11) in atypical chronic myeloid
        leukemia fuses BCR to PDGFRA)
IT
     Chromosome
        (human 22; translocations t(4;22)(q12;q11) in atypical chronic myeloid
        leukemia fuses BCR to PDGFRA)
IT
     Chromosome
        (human 4, breakpoint, PDGFRA disruption by; translocations
        t(4;22)(q12;q11) in atypical chronic myeloid leukemia fuses BCR to
        PDGFRA)
     PCR (polymerase chain reaction)
IT
        (multiplex; translocations t(4;22)(q12;q11) in atypical chronic myeloid
        leukemia fuses BCR to PDGFRA)
ΙT
     Molecular cloning
        (of translocation, t(4;22)(q12;q11); translocations t(4;22)(q12;q11) in
        atypical chronic myeloid leukemia fuses BCR to PDGFRA)
IT
     Recombination, genetic
        (translocation, t(4;22) (q12;q11); translocations t(4;22) (q12;q11) in
        atypical chronic myeloid leukemia fuses BCR to PDGFRA)
IT
     Genetic mapping
     Human
        (translocations t(4;22)(q12;q11) in atypical chronic myeloid leukemia
        fuses BCR to PDGFRA)
IT
     Platelet-derived growth factor receptors
     RL: BSU (Biological study, unclassified); DGN (Diagnostic use); BIOL
     (Biological study); USES (Uses)
        (.alpha., PDGFRA; translocations t(4;22)(q12;q11) in atypical chronic
        myeloid leukemia fuses BCR to PDGFRA)
RE.CNT
        26
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    P15
L19
    ANSWER 15 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     2002:290033 CAPLUS
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ED Entered STN: 18 Apr 2002 ΤI Molecular dynamics characterization of the C2 domain of protein kinase

DN

137:2387

AU Banci, Lucia; Cavallaro, Gabriele; Kheifets, Viktoria; Mochly-Rosen, Daria

CS Centro di Risonanze Magnetiche, University of Florence, Florence, 50019,

Italy

Journal of Biological Chemistry (2002), 277(15), 12988-12997 SO CODEN: JBCHA3; ISSN: 0021-9258 PB American Society for Biochemistry and Molecular Biology DTJournal LА English CC 7-5 (Enzymes) Protein kinase C (PKC) isoenzymes comprise a family of related enzymes AB that play a central role in many intracellular eukaryotic signaling events. Isoenzyme specificity is mediated by assocn. of each PKC isoenzyme with specific anchoring proteins, termed RACKs. The C2 domain of .beta.PKC contains at least part of the RACK-binding sites. Because the C2 domain contains also a RACK-like sequence (termed pseudo-RACK), it was proposed that this pseudo-RACK site mediates intramol. interaction with one of the RACK-binding sites in the C2 domain itself, stabilizing the inactive conformation of .beta.PKC. .beta.PKC depends on calcium for its activation, and the C2 domain contains the calcium-binding sites. The x-ray structure of the C2 domain of .beta.PKC shows that three Ca2+ ions can be coordinated by two opposing loops at one end of the domain. Starting from this x-ray structure, we have performed mol. dynamics (MD) calcns. on the C2 domain of .beta.PKC bound to three Ca2+ ions, to two Ca2+ ions, and in the Ca2+-free state, in order to analyze the effect of calcium on the RACK-binding sites and the pseudo-RACK sites, as well as on the loops that constitute the binding site for the Ca2+ ions. The results show that calcium stabilizes the .beta.-sandwich structure of the C2 domain and thus affects two of the three RACK-binding sites within the C2 domain. Also, the interactions between the third RACK-binding site and the pseudo-RACK site are not notably modified by the removal of Ca2+ ions. On that basis, we predict that the pseudo-RACK site within the C2 domain \*\*\*masks\*\*\* a RACK-binding site in another domain of .beta.PKC, possibly the V5 domain. Finally, the MD modeling shows that two Ca2+ ions are able to interact with two mols. of O-phospho-L-serine. These data suggest that Ca2+ ions may be directly involved in PKC binding to phosphatidylserine, an acidic lipid located exclusively on the cytoplasmic face of membranes, that is required for PKC activation. STprotein kinase Cbeta dynamics C2 domain RACK binding site; calcium protein kinase Cbeta phosphatidylserine membrane mol dynamics simulation IT Membrane, biological (involvement of Ca2+ ions in protein kinase C binding to phosphatidylserine of membrane) ITPhosphatidylserines RL: BSU (Biological study, unclassified); BIOL (Biological study) (involvement of Ca2+ ions in protein kinase C binding to phosphatidylserine of membrane) Simulation and Modeling (mol. dynamics; mol. dynamics characterization of C2 domain of protein kinase C.beta.) IT (protein kinase C.beta. C2 domain pseudo-RACK motif; role of calcium in protein kinase C.beta. structure and binding to the membrane) IT Protein motifs (protein kinase C.beta. RACK-binding sites; role of calcium in protein kinase C.beta. structure and binding to the membrane) IT Conformation (protein; involvement of Ca2+ ions in protein kinase C binding to phosphatidylserine of membrane) TT Conformational transition (structural \*\*\*rearrangement\*\*\* in protein kinase C.beta. upon calcium binding) IT Conformation (.beta.-; stabilization of .beta.-sandwich structure of protein kinase C.beta. C2 domain by calcium) IT 7440-70-2, Calcium, biological studies RL: BSU (Biological study, unclassified); BIOL (Biological study) (role of calcium in protein kinase C.beta. structure and binding to the membrane) IT 141436-78-4 RL: BSU (Biological study, unclassified); PRP (Properties); BIOL (Biological study) (.beta.; mol. dynamics characterization of C2 domain of protein kinase C.beta.) RE.CNT THERE ARE 60 CITED REFERENCES AVAILABLE FOR THIS RECORD

RE

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- L19 ANSWER 16 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
- AN 2002:106453 CAPLUS
- DN 136:325726
- ED Entered STN: 10 Feb 2002
- TI Efficient Synthesis of the A-Ring Phosphine Oxide Building Block Useful for 1.alpha., 25-Dihydroxy Vitamin D3 and Analogues
- AU Daniewski, Andrzej R.; Garofalo, Lisa M.; Hutchings, Stanley D.; Kabat, Marek M.; Liu, Wen; Okabe, Masami; Radinov, Roumen; Yiannikouros, George P.
- CS Chemical Synthesis-Process Research Non-Clinical Development Pre-Clinical

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Journal of Organic Chemistry (2002), 67(5), 1580-1587
     CODEN: JOCEAH; ISSN: 0022-3263
PB
     American Chemical Society
DT
     Journal
     English
LA
CC
     32-7 (Steroids)
     CASREACT 136:325726
OS
GI
/ Structure 5 in file .gra /
     The 1.alpha.-hydroxy A-ring phosphine oxide I (TBDMS = SiMe2CMe3), a
AB
     useful building block for vitamin D analogs, was synthesized from
     (S)-carvone in nine synthetic operations and a single chromatog. purifn.
     in 25% overall yield. The synthesis features two novel efficient
     synthetic transformations: the Criegee
                                              ***rearrangement***
     .alpha.-methoxy hydroperoxyacetate II in methanol to obtain directly the
     desired secondary 3.beta.-alc. III and the highly chemo- and
     stereoselective isomerization of diene oxide ester (E)-IV to the
     1.alpha.-allylic alc. with an exocyclic double bond (E)-V. Further
     insight into the selectivity control of the latter ***rearrangement***
     was obtained from the reactions of (2)-epimeric substrates. The new
     synthetic approach leading to the 1.alpha.-hydroxy epimers complements our
     previously reported synthesis of the corresponding 1.beta.-epimers, thus
     producing all stereoisomers of these versatile building blocks efficiently
     from carvone.
     phosphine oxide building block A ring vitamin D3 analog; carvone
ST
     conversion vitamin D3 analog phosphine oxide chiron; stereoselective
     isomerization diene oxide ester vitamin D3 precursor; Criegee
       ***rearrangement*** methoxy hydroperoxyacetate vitamin D3 precursor
IT
     Synthons
        (chiral; efficient synthesis of the A-ring phosphine oxide building
        block useful for 1.alpha.,25-dihydroxy vitamin D3 and analogs)
IT
     9,10-Secosteroids
     RL: PNU (Preparation, unclassified); PREP (Preparation)
        (efficient synthesis of the A-ring phosphine oxide building block
        useful for 1.alpha.,25-dihydroxy vitamin D3 and analogs)
IT
     Phosphines
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (oxides, chiral building blocks; efficient synthesis of the A-ring
        phosphine oxide building block useful for 1.alpha.,25-dihydroxy vitamin
        D3 and analogs)
       ***Rearrangement***
IT
        (stereoselective, Criegee; efficient synthesis of the A-ring phosphine
        oxide building block useful for 1.alpha., 25-dihydroxy vitamin D3 and
        analogs)
IT
     Isomerization
        (stereoselective; efficient synthesis of the A-ring phosphine oxide
        building block useful for 1.alpha., 25-dihydroxy vitamin D3 and analogs)
IT
     Safety
                                       to prevent lithium hydride powder
                          ***mask***
        (use protective
        inhalation and use well-ventilated hood for triphosgene)
IT
     410075-41-1P
     RL: BYP (Byproduct); PREP (Preparation)
        (efficient synthesis of the A-ring phosphine oxide building block
        useful for 1.alpha., 25-dihydroxy vitamin D3 and analogs)
     867-13-0, Triethyl phosphonoacetate
                                           2244-16-8, (S)-Carvone
                                                                     326496-97-3
IT
     326496-98-4
                   410075-47-7
                                 410075-54-6
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (efficient synthesis of the A-ring phosphine oxide building block
        useful for 1.alpha., 25-dihydroxy vitamin D3 and analogs)
                                                              137693-94-8P
TT
     39903-97-4P
                   81506-23-2P
                                 81506-24-3P
                                               81506-25-4P
                                                  326496-92-8P
     227961-42-4P
                    326496-90-6P
                                   326496-91-7P
                                                                  326496-93-9P
     326496-94-0P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (efficient synthesis of the A-ring phosphine oxide building block
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Research and Development, Hoffmann-La Roche Inc., Nutley, NJ, 07110, USA

so

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useful for 1.alpha.,25-dihydroxy vitamin D3 and analogs)
                                                              410075-49-9P
IT
                  326496-99-5P
                                 326497-00-1P
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     81522-68-1P
     410075-56-8P
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (efficient synthesis of the A-ring phosphine oxide building block
        useful for 1.alpha., 25-dihydroxy vitamin D3 and analogs)
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L19
AN
     2001:727210 CAPLUS
ED
     Entered STN: 05 Oct 2001
TΙ
                           ***photomask*** . [Machine Translation].
     Production method of
IN
    Touji
PA
     Toshiba Corp., Japan
SO
     Jpn. Kokai Tokkyo Koho, 6 pp.
     CODEN: JKXXAF
DТ
     Patent
LA
     Japanese
IC
     ICM G03F001-08
     ICS G03F001-08; H01L021-027
FAN.CNT 1
     PATENT NO.
                        KIND
                                DATE
                                           APPLICATION NO.
                                                                   DATE
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PΙ
     JP 2001272766
                                                                   20000327
                         A2
                                20011005
                                            JP 2000-87652
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PRAI JP 2000-87652 20000327

CLASS

CLASS PATENT FAMILY CLASSIFICATION CODES PATENT NO.

\_\_\_\_ \_\_\_\_\_

JP 2001272766 ICM G03F001-08

> ICS G03F001-08; H01L021-027

G03F0001-08 [ICM, 7]; G03F0001-08 [ICS, 7]; H01L0021-027 IPCI [ICS, 7]

[Machine Translation of Descriptors]. Degradation of resolving power of AB the resist which originates in the stray light and amount of exposure tolerance and the dependency for the extent of degradation of depth of focus are grasped accurately, influence of the stray light is decreased. In the production method of the \*\*\*photomask\*\*\* , C % with it does the covering ratio in the territory within difference R from the central coordinate of test pattern, after exposing the pattern of the for measurement which changes the value of R and C to the resist, measures the pattern line width L where, value of R and C differs from the resist pattern which was formed from the amount of exposure of line width L and the value which measured the dependency of depth of focus in the matrix state, measures the process tolerance with the territory of C and R, is sought from the process tolerance which was measured, maximum depth of focus with specified amount of exposure tolerance C and R Draws up the contour line graph as function, range Cn of difference Rn and the covering ratio which satisfy this when specified maximum depth of focus is necessary % seeks, in order the territory inside the Rn the Cn % to be satisfied at the time of the pattern design of the \*\*\*photomask\*\*\* \*\*\*rearranges\*\*\* the pattern.

- ANSWER 18 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN L19
- AN2001:388472 CAPLUS
- DN 136:113325
- ED Entered STN: 30 May 2001
- TТ New concepts to improve resolution and sensitivity of molecular cytogenetic diagnostics by multicolor fluorescence in situ hybridization
- ΑU Saracoglu, K.; Brown, J.; Kearney, L.; Uhrig, S.; Azofeifa, J.; Fauth, C.; Speicher, M. R.; Eils, R.
- CS Deutsches Krebsforschungszentrum (DKFZ) Heidelberg, Division "Intelligent Bioinformatics Systems, "Heidelberg, Heidelberg, D-69120, Germany
- so Cytometry (2001), 44(1), 7-15 CODEN: CYTODQ; ISSN: 0196-4763
- PB Wiley-Liss, Inc.
- DT Journal
- LA English
- CC 3-1 (Biochemical Genetics)
  - Section cross-reference(s): 14
- AΒ Background: Routine application of multicolor fluorescence in situ hybridization (M-FISH) technol. for mol. cytogenetic diagnostics has been hampered by several tech. limitations. First, when using chromosome-specific painting probes, there is a limit in cytogenetic resoln. of approx. 2-3 Mb, which can \*\*\*mask\*\*\* hidden structural abnormalities that have a significant clin. effect. Second, using whole chromosome painting probes, intrachromosomal \*\*\*rearrangements\*\*\* cannot be detected and the exact localization of breakpoints is often not possible. Methods: We suggest the use of multiplex-labeled region or locus-specific probes in combination with an optimal probe design to improve the sensitivity and resoln. of the M-FISH technol. To allow the application of this assay in routine diagnostics, we developed a multipurpose image anal. system. Results: goldFISH was applied to the study of cryptic translocations in mental retardation patients and to the study of high-resoln. breakpoint mapping in non-small cell lung cancer patients. For an individual with mental retardation, who had an apparently normal karyotype by G-banding, we detected an unbalanced translocation involving chromosomes 2 and 7. Conclusions: In combination with optimally designed probe kits, goldFISH overcomes most of the present limitations of the M-FISH technol. and results in virtually 100% reliability for detecting interchromosomal and intrachromosomal \*\*\*rearrangements\*\*\*
- ST cytogenetic diagnostics multicolor fluorescence in situ hybridization goldFISH
- IT Mental retardation

(cryptic (2,7)-translocation detection in patient with; improved resoln. and sensitivity of mol. cytogenetic diagnostics by multicolor

```
goldFISH)
IT
     Imaging
     Karyotyping
        (improved resoln. and sensitivity of mol. cytogenetic diagnostics by
        multicolor goldFISH)
IT
     Nucleic acid hybridization
        (in situ, fluorescence, multicolor, goldFISH; improved resoln. and
        sensitivity of mol. cytogenetic diagnostics by multicolor goldFISH)
     Probes (nucleic acid)
IT
     RL: ARG (Analytical reagent use); DGN (Diagnostic use); ANST (Analytical
     study); BIOL (Biological study); USES (Uses)
        (locus-specific; improved resoln. and sensitivity of mol. cytogenetic
        diagnostics by multicolor goldFISH)
     Diagnosis
IT
        (mol.; improved resoln. and sensitivity of mol. cytogenetic diagnostics
        by multicolor goldFISH)
     Lung, neoplasm
IT
        (non-small-cell carcinoma, high-resoln. breakpoint mapping in patients
        with; improved resoln. and sensitivity of mol. cytogenetic diagnostics
        by multicolor goldFISH)
IT
     Carcinoma
        (pulmonary non-small-cell, high-resoln. breakpoint mapping in patients
        with; improved resoln. and sensitivity of mol. cytogenetic diagnostics
        by multicolor goldFISH)
     Recombination, genetic
        (translocation, cryptic, detection; improved resoln. and sensitivity of
        mol. cytogenetic diagnostics by multicolor goldFISH)
RE.CNT
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(22) Tvarusko, W; Proc Natl Acad Sci USA 1999, V96, P7950 CAPLUS
(23) Uhrig, S; Am J Hum Genet 1999, V65, P448 MEDLINE
     ANSWER 19 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
     2001:299881 CAPLUS
ΑN
ED
     Entered STN: 27 Apr 2001
                    and its production method for semiconductor lithography.
       ***Mask***
TT
     [Machine Translation].
TN
             Koji; Marumoto,
                               Kenji; Aya,
                                             Atsushi; Murakami,
                                                                  Takaki
PA
     Mitsubishi Electric Corp., Japan
     Jpn. Kokai Tokkyo Koho, 11 pp.
SO
     CODEN: JKXXAF
DT
     Patent
     Japanese
LA
     ICM H01L021-027
     ICS G03F001-16; G03F009-00
FAN.CNT 1
                                            APPLICATION NO.
     PATENT NO.
                         KIND
                                DATE
                                                                   DATE
     ______
                         _ _ _ _
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                                            _____
                                                                    _____
     JP 2001118770
                         A2
                                20010427
                                            JP 1999-294678
                                                                   19991018
PRAI JP 1999-294678
                                19991018
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CLASS

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CLASS PATENT FAMILY CLASSIFICATION CODES
 PATENT NO.
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                ICM
                       H01L021-027
 JP 2001118770
                 ICS
                       G03F001-16; G03F009-00
                 IPCI
                       H01L0021-027 [ICM,7]; G03F0001-16 [ICS,7]; G03F0009-00
                        [ICS, 7]
     [Machine Translation of Descriptors]. It designates that the X-ray
AB
       ***mask*** of high accuracy or the ***mask*** for semiconductor
     lithography is obtained as purpose. Beforehand the process S 11 which on
           ***mask***
                       produces the plural 1st marks with the system of
     coordinates of desire and the above-mentioned
                                                   ***mask***
                                                                 inside the EB
     drawing device, after temperature reaching to the balanced state, with the
     above-mentioned EB drawing device the measurement method it does the site
     relationship of the above-mentioned plural 1st marks, this measurement
     method value and related to site, in the system of coordinates of
     above-mentioned desire detects the site strain of the ***mask***
                                                                          which
     is a 1st assistant conditioned weight from the gap
                                                         ***rearranging***
     the above-mentioned copying pattern in the site which compensates the
     above-mentioned site strain, administering with process S12 which draws,
     produces the
                   ***mask*** for semiconductor lithography.
     ANSWER 20 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
AN
     2001:241122 CAPLUS
DN
     135:37623
ED
     Entered STN: 05 Apr 2001
     Catalytic CO oxidation over pumice supported Pd-Ag catalysts
ΤI
     Venezia, A. M.; Liotta, L. F.; Deganello, G.; Schay, Z.; Horvath, D.;
ΑU
     Guczi, L.
CS
     Istituto di Chimica e Tecnologia dei Prodotti Naturali (ICTPN-CNR),
     Palermo, 90146, Italy
     Applied Catalysis, A: General (2001), 211(2), 167-174
so
     CODEN: ACAGE4; ISSN: 0926-860X
PB
     Elsevier Science B.V.
DT
     Journal
LA
     English
     67-1 (Catalysis, Reaction Kinetics, and Inorganic Reaction Mechanisms)
CC
     Section cross-reference(s): 51, 59
     The results of expts. on the catalytic oxidn. of CO at 523 K over
AB
     bimetallic Pd-Ag catalysts supported on pumice are reported and compared
     with those obtained from monometallic Pd and Ag catalysts. The catalysts
     were prepd. from organometallic precursors and were characterized by x-ray
     diffraction (XRD) and XPS after different treatments with air and with
     hydrogen. The activity of the catalysts decreases with increasing Ag/Pd
     at. ratio, the monometallic palladium exhibiting the highest activity.
     Furthermore, the treatment with air and with hydrogen always results in a
     better catalytic performance. On the basis of the structural
     characterization by XRD and the surface at. compn. obtained from XPS
     measurements, Ag has tendency to segregate at the surface of the
     catalysts, except in an air environment at 623 K. In this case, an inward
     diffusion of silver atoms occurs. With hydrogen treatment at high temp.,
     silver reappears at the surface, with further increase of the catalytic
     activity. The results are explained in terms of
                                                       ***rearrangement***
     of the bimetallic particles, with the most active situation represented by
     clean particles of pure palladium next to dispersed silver particles.
ST
     carbon monoxide oxidn pumice supported palladium silver catalyst
IT
     Oxidation
     Oxidation catalysts
     X-ray diffraction
     X-ray photoelectron spectroscopy
        (carbon monoxide oxidn. over pumice-supported Pd-Ag catalysts and
        catalyst characterization)
IT
     Pumice
     RL: CAT (Catalyst use); USES (Uses)
        (carbon monoxide oxidn. over pumice-supported Pd-Ag catalysts and
        catalyst characterization in relation to)
IT
     Respirators
              ***masks*** ; carbon monoxide oxidn. over pumice-supported
        Pd-Ag catalysts and catalyst characterization in relation to use in)
IT
     Exhaust gases (engine)
        (treatment of; carbon monoxide oxidn. over pumice-supported Pd-Ag
        catalysts and catalyst characterization in relation to)
IT
     7440-05-3, Palladium, uses 7440-22-4, Silver, uses
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RL: CAT (Catalyst use); USES (Uses) (carbon monoxide oxidn. over pumice-supported Pd-Ag catalysts and catalyst characterization) 630-08-0, Carbon monoxide, reactions RL: RCT (Reactant); REM (Removal or disposal); PROC (Process); RACT (Reactant or reagent) (carbon monoxide oxidn. over pumice-supported Pd-Ag catalysts and catalyst characterization) THERE ARE 25 CITED REFERENCES AVAILABLE FOR THIS RECORD RE.CNT (1) Bond, G; Proceedings of the 6th International Congress on Catalysis 1977 (2) Bond, G; Proceedings of the 6th International Congress on Catalysis 1977, V1, P356 CAPLUS (3) Cai, Y; J Catal 1996, V161, P123 CAPLUS (4) Gadgil, M; J Mol Catal 1994, V87, P297 CAPLUS (5) Gardner, S; J Catal 1991, V129, P114 CAPLUS (6) Gravelle, P; Adv Catal 1969, V20, P168 (7) Gulari, E; Appl Catal A 1999, V182, P147 CAPLUS (8) Herz, R; J Catal 1980, V65, P281 CAPLUS (9) Klug, H; X-Ray Diffraction Procedures for Polycrystalline and Amorphous Materials 1954 (10) Kochubey, D; J Catal 1996, V161, P500 CAPLUS (11) Liotta, L; J Catal 1996, V164, P322 CAPLUS (12) Moss, R; Adv Catal 1972, V22, P115 CAPLUS (13) Nagy, A; Appl Catal A 1999, V188, P337 CAPLUS (14) Pavlova, S; J Catal 1996, V161, P517 CAPLUS (15) Petrov, L; Stud Surf Sci Catal 2000, V130, P2345 (16) Ponec, V; Stud Surf Sci Catal 1995, V95 (17) Razon, L; Catal Rev-Sci-Eng 1986, V28, P89 CAPLUS (18) Sachtler, W; Adv Catal 1977, V26, P69 CAPLUS (19) Soma-Nota, Y; J Catal 1974, V32, P315 (20) Steiner, P; Solid State Commun 1981, V73, P79 (21) Tascon, J; Adv Catal 1989, V36, P237 (22) Venezia, A; Appl Catal A 1995, V125, P113 CAPLUS (23) Venezia, A; J Catal 1999, V182, P449 CAPLUS (24) Venezia, A; Surf Interface Anal 1992, V18, P532 CAPLUS (25) Voorhoeven, R; Advanced Materials in Catalysis 1997 ANSWER 21 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN 2001:120984 CAPLUS 135:339920 Entered STN: 18 Feb 2001 Identification of a subtle t(16;19) (p13.3;p13.3) in an infant with multiple congenital abnormalities using a 12-colour multiplex FISH telomere assay, M-TEL Brown, Jill; Horsley, Sharon W.; Jung, Christine; Saracoglu, Kaan; Janssen, Bart; Brough, Michaela; Daschner, Markus; Beedgen, Bernd; Kerkhoffs, Guido; Eils, Roland; Harris, Peter C.; Jauch, Anna; Kearney, Lyndal MRC Molecular Haematology Unit, Institute of Molecular Medicine, Oxford, OX3 9DS, UK European Journal of Human Genetics (2000), 8(12), 903-910 CODEN: EJHGEU; ISSN: 1018-4813 Nature Publishing Group Journal English 3-1 (Biochemical Genetics) Section cross-reference(s): 14 There is increasing evidence that cytogenetically invisible chromosome are an important cause of genetic disease. \*\*\*rearrangements\*\*\* to the chromosomal location of these \*\*\*rearrangements\*\*\* may be provided by a specific clin. diagnosis, which can then be investigated by targeted FISH or mol. studies. However, the phenotypic features of some microdeletion syndromes are difficult to recognize, particularly in infants. In addn., the presence of other chromosome aneuploidy may \*\*\*mask\*\*\* the typical clin. features. In the present study, the presence of tubers on cranial magnetic resonance imaging (MRI) of a 5-wk-old infant prompted an investigation, by FISH, with probes from the tuberous sclerosis gene, TSC2. This and further FISH deletion mapping studies revealed a submicroscopic deletion encompassing the entire TSC2

gene and the adjacent PKD1 gene on one chromosome 16, confirming a

del(16)(p13.3). Because of the large no. of abnormal phenotypic features

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in this infant, we performed a 12-color FISH assay (M-TEL) to screen for subtelomeric \*\*\*rearrangements\*\*\* involving the del(16p). The M-TEL assay revealed a cryptic der(16)t(16;19)(p13.3;p13.3). Further FISH with 19p and 19q subtelomeric probes demonstrated that this was derived from a balanced maternal t(16;19)(p13.3;p13.3). Importantly, 24-color painting by multiplex FISH (M-FISH) failed to detect the translocation in either the infant or his mother. Based on our FISH mapping studies, we est. the size of the trisomic region from 19p13.3 to be approx. 2Mb, and the region of monosomy for 16p13.3 as 2.25 Mb. This case adds to the growing literature which indicates that many apparent chromosomal deletions are unbalanced translocations. The M-TEL assay provides a sensitive alternative to M-FISH for the detection of these subtle telomeric \*\*\*rearrangements\*\*\*

ST chromosome telomere \*\*\*rearrangement\*\*\* infant FISH

IT Gene, animal

RL: ADV (Adverse effect, including toxicity); BIOL (Biological study) (PKD1; identification of subtle t(16;19)(p13.3;p13.3) in infant with multiple congenital abnormalities using 12-color multiplex FISH telomere assay, M-TEL)

IT Gene, animal

RL: ADV (Adverse effect, including toxicity); BIOL (Biological study) (TSC2; identification of subtle t(16;19) (p13.3;p13.3) in infant with multiple congenital abnormalities using 12-color multiplex FISH telomere assay, M-TEL)

TT Mutation

(deletion; identification of subtle t(16;19) (p13.3;p13.3) in infant with multiple congenital abnormalities using 12-color multiplex FISH telomere assay, M-TEL)

IT Disease, animal

(genetic; identification of subtle t(16;19) (p13.3;p13.3) in infant with multiple congenital abnormalities using 12-color multiplex FISH telomere assay, M-TEL)

T Chromosome

(human 16; identification of subtle t(16;19) (p13.3;p13.3) in infant with multiple congenital abnormalities using 12-color multiplex FISH telomere assay, M-TEL)

TT Chromosome

(human 19; identification of subtle t(16;19) (p13.3;p13.3) in infant with multiple congenital abnormalities using 12-color multiplex FISH telomere assay, M-TEL)

IT Nucleic acid hybridization

(in situ, fluorescence; identification of subtle t(16;19) (p13.3;p13.3) in infant with multiple congenital abnormalities using 12-color multiplex FISH telomere assay, M-TEL)

IT Development, mammalian postnatal

(infant; identification of subtle t(16;19)(p13.3;p13.3) in infant with multiple congenital abnormalities using 12-color multiplex FISH telomere assay, M-TEL)

IT Diagnosis

(mol.; identification of subtle t(16;19) (p13.3;p13.3) in infant with multiple congenital abnormalities using 12-color multiplex FISH telomere assay, M-TEL)

IT Telomeres (chromosome)

(telomeric \*\*\*rearrangements\*\*\* detection; identification of subtle t(16;19) (p13.3;p13.3) in infant with multiple congenital abnormalities using 12-color multiplex FISH telomere assay, M-TEL)

IT Recombination, genetic

(translocation, reciprocal, t(16;19) (p13.3;p13.3); identification of subtle t(16;19) (p13.3;p13.3) in infant with multiple congenital abnormalities using 12-color multiplex FISH telomere assay, M-TEL)

RE.CNT 27 THERE ARE 27 CITED REFERENCES AVAILABLE FOR THIS RECORD RE

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(27) Uhrig, S; Am J Hum Genet 1999, V65, P448 MEDLINE
    ANSWER 22 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
AN
    2000:865924 CAPLUS
    Entered STN: 12 Dec 2000
ED
    Method for manufacturing a spacer for a flat panel display
ΤI
    Jung, Sung Jae; Woo, Kwang Je; Kim, Kwan Soo; Moon, Gwon Jin
IN
    Orion Electric Co., Ltd., S. Korea
PA
SO
    U.S., 15 pp.
    CODEN: USXXAM
DT
    Patent
    English
LA
     ICM H01J009-00
     ICS H01J009-24
INCL 445024000; 445023000
FAN.CNT 1
                       KIND
                                         APPLICATION NO.
                                                                 DATE
                             DATE
     PATENT NO.
                                          ______
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                                                                 _ _ _ _ _ _ _
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    US 6159065
                             20001212
                                          US 1998-143497
                                                                19980828
                       Α
PΙ
    KR 1997-43046 A
KR 1997-50242 A
KR 1997-50243 A
KR 1998-34068 A
                             19970829
PRAI KR 1997-43046
                             19970930
19970930
                               19980821
CLASS
                CLASS PATENT FAMILY CLASSIFICATION CODES
 PATENT NO.
                ____
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US 6159065
               ICM
                       H01J009-00
                ICS
                       H01J009-24
                INCL
                       445024000; 445023000
                       H01J0009-00 [ICM, 7]; H01J0009-24 [ICS, 7]
                IPCI
                       445/024.000; 445/023.000
                NCL
                       H01J009/18B; H01J009/24D; H01J029/02K
                ECLA
    The present invention relates to a method for manufacturing a spacer used
AΒ
     in a flat panel display. At the first printing process, a printing
      ***mask*** produces a primary spacer on a substrate. After removing the
    printing ***mask*** , a supporting plate having a hole to excess the
     primary spacer is placed on the substrate and then the printing
       ***mask*** is ***rearranged*** on the supporting plate.
     subsequent printing process is applied repeatedly to the printing
       ***mask*** with the supporting plate to extend the height of the primary
     spacer to the amount of the thickness of the supporting plate, thereby
     producing an elongated finished spacer.
             THERE ARE 3 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE.CNT 3
RE
(1) Lowrey; US 5205770 1993
(2) Miyake; US 5136207 1992 CAPLUS
(3) Ohoshi; US 5949184 1999
    ANSWER 23 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
T.19
    2000:700869 CAPLUS
AN
DN
     134:24009
    Entered STN: 05 Oct 2000
ED
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Effects of post-ion-milling, pre-annealing, and post-annealing on the

characteristics of high-Tc ramp-edge junctions

TI

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Sung, Gun Yong; Choi, Chi Hong; Kang, Kwang-Yong; Lee, Moon-Chul; Lee,
AU
     Soon-Gul
     Electronics and Telecommunications Research Institute, Taejon, 305-350, S.
CS
     Korea
     Institute of Physics Conference Series (2000), 167 (Applied
SO
     Superconductivity 1999, Vol. 2), 217-220
     CODEN: IPCSEP; ISSN: 0951-3248
     Institute of Physics Publishing
PB
DT
     Journal
     English
LA
CC
     76-4 (Electric Phenomena)
     Section cross-reference(s): 66, 74
     We fabricated high-Tc superconducting YBa2Cu307-x(YBCO)/YBa2Cu0.79Co0.2107-
AB
     x(Co-YBCO)/YBCO ramp-edge Josephson junctions on (001) SrTiO3 single
     crystal substrates and studied the effects of post-ion-milling and
     pre-annealing of the ramp-edge prior to the top layer and post annealing
     process. The ion-beam voltage, the ion-beam incident angle, and the
                   ***mask***
                                angle to yield smooth slopes with an angle of
     photoresist
     about 30.degree. were optimized. The morphol. of the edge was improved by
     the post-ion-milling, as were the edge-surface-induced epitaxial growth
     and the small interface resistance between the top YBCO layer and the
     Co-YBCO barrier. Annealing prior to barrier deposition recovered the
     ramp-edge surface and increased the Tc of the edge. Annealing assisted an
     epitaxial growth of the top YBCO layer on the ramp edge. Post-annealing
     at a temp. above the deposition temp. and cooling at 500 torr O2 induced
                     ***rearrangement***
                                          of Co-YBCO at a high oxygen vapor
     the epitaxial
     pressure. The current-voltage characteristics of the junctions showed
     RSJ-like behavior.
     barium yttrium cobalt cuprate Josephson junction ion milling annealing
st
IT
     Annealing
     Controlled atmospheres
     Electric current-potential relationship
     Electric resistance
     Josephson junctions
     Photolithography
     Surface structure
        (effects of post-ion-milling, pre-annealing, and post-annealing on the
        characteristics of high-Tc ramp-edge junctions)
IT
        (ion-beam milling; effects of post-ion-milling, pre-annealing, and
        post-annealing on the characteristics of high-Tc ramp-edge junctions)
     Vapor deposition process
        (laser ablation; effects of post-ion-milling, pre-annealing, and
        post-annealing on the characteristics of high-Tc ramp-edge junctions)
IT
        (plasma; effects of post-ion-milling, pre-annealing, and post-annealing
        on the characteristics of high-Tc ramp-edge junctions)
     7782-44-7, Oxygen, processes
     RL: PEP (Physical, engineering or chemical process); PROC (Process)
        (annealing ambient; effects of post-ion-milling, pre-annealing, and
        post-annealing on the characteristics of high-Tc ramp-edge junctions)
     109064-29-1D, Barium copper yttrium oxide Ba2Cu3Y07, oxygen-deficient
     229315-90-6D, Barium cobalt copper yttrium oxide Ba2Co0.21Cu0.79Y07,
     oxygen-deficient
     RL: DEV (Device component use); PEP (Physical, engineering or chemical
     process); PROC (Process); USES (Uses)
        (effects of post-ion-milling, pre-annealing, and post-annealing on the
        characteristics of high-Tc ramp-edge junctions)
IT
     14791-69-6, Argon 1+, processes
     RL: PEP (Physical, engineering or chemical process); PROC (Process)
        (effects of post-ion-milling, pre-annealing, and post-annealing on the
        characteristics of high-Tc ramp-edge junctions)
IT
     12060-59-2, Strontium titanate
     RL: DEV (Device component use); PEP (Physical, engineering or chemical
     process); PROC (Process); USES (Uses)
        (substrate; effects of post-ion-milling, pre-annealing, and
        post-annealing on the characteristics of high-Tc ramp-edge junctions)
              THERE ARE 13 CITED REFERENCES AVAILABLE FOR THIS RECORD
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RE
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(3) Char, K; Appl Phys Lett 1994, V65, P904 CAPLUS
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(4) Gao, J; Physica C 1990, V171, P126 CAPLUS
(5) Hunt, B; Appl Phys Lett 1991, V59, P982 CAPLUS
(6) Hunt, B; IEEE Trans Appl Supercon 1999, V9, P3362
(7) Moeckly, B; Appl Phys Lett 1997, V71, P2526 CAPLUS
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(13) Yoshida, J; IEEE Trans Appl Supercon 1999, V9, P3366
     ANSWER 24 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
     2000:634417 CAPLUS
AN
DN
     133:338779
ED
     Entered STN: 13 Sep 2000
TI
     The high temperature tensile and compressive deformation characteristics
     of magnesia doped alumina
ΙΙΑ
     Kottada, R. S.; Chokshi, A. H.
CS
     Department of Metallurgy, Indian Institute of Science, Bangalore, 560 012,
     India
     Acta Materialia (2000), 48(15), 3905-3915
SO
     CODEN: ACMAFD; ISSN: 1359-6454
PB
     Elsevier Science Ltd.
\mathtt{DT}
     Journal
LA
     English
CC
     57-2 (Ceramics)
     The mech. characteristics of alumina have not yet been characterized
AB
     completely in tension due in part to strain hardening accompanying grain
     growth and premature cavitation failure. Tensile tests were conducted on
     fine grained magnesia doped alumina over a range of strain rates, grain
     sizes and temps. to evaluate the stress exponent, inverse grain size
     exponent and activation energy. Const. stress compression creep tests
     were also carried out under a similar range of exptl. conditions.
     Extensive microstructural characterization after deformation indicated
     that there was considerable grain growth during deformation; however, the
     grains retained their initially equiaxed structure after significant
     deformation. Although a std. plot of strain rate vs. stress indicated a
     stress exponent of .apprx.2, a complete anal. including the compensation
     of data for concurrent grain growth revealed that true stress exponent was
     .apprx.1, consistent with diffusion creep. It is argued that grain
       ***rearrangement***
                             processes accompanying grain growth will tend to
       ***mask***
                    the development of an elongated grain structure predicted by
     diffusion creep processes. In contrast to several ceramics with a
     significant amt. of glassy phase, there is no significant difference
     between the elevated temp. tensile and compressive behavior of alumina.
st
     alumina magnesia doping high temp deformation
IT
        (failure mechanism; high-temp. tensile creep and compressive
        deformation characteristics of magnesia-doped alumina ceramic)
IT
     Stress, mechanical
        (flow; high-temp. tensile creep and compressive deformation
        characteristics of magnesia-doped alumina ceramic)
IT
     Ceramics
     Compressive strength
     Creep
     Doping
     Grain boundary diffusion
     Grain growth
        (high-temp. tensile creep and compressive deformation characteristics
        of magnesia-doped alumina ceramic)
IT
     1309-48-4, Magnesia, properties
     RL: MOA (Modifier or additive use); PRP (Properties); USES (Uses)
        (high-temp. tensile creep and compressive deformation characteristics
        of magnesia-doped alumina ceramic)
IT
     1344-28-1, Alumina, processes
     RL: PEP (Physical, engineering or chemical process); PRP (Properties);
     PROC (Process)
        (high-temp. tensile creep and compressive deformation characteristics
        of magnesia-doped alumina ceramic)
RE.CNT
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    ANSWER 25 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
    2000:622358 CAPLUS
AN
DN
     133:185653
ED
                  07 Sep 2000
    Entered STN:
ΤI
    Method of fabricating a front plate for a plasma display panel
    Sung, Wen-Fa; Lu, Jin-Yuh; Su, Yao-Ching
IN
PA
    Acer Display Technology, Inc., Taiwan
SO
    U.S., 12 pp.
    CODEN: USXXAM
DT
     Patent
LA
    English
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INCL 445024000
    74-13 (Radiation Chemistry, Photochemistry, and Photographic and Other
    Reprographic Processes)
    Section cross-reference(s): 76
FAN.CNT 1
                      KIND
                             DATE
                                     APPLICATION NO.
                                                                DATE
    PATENT NO.
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                            20000905 US 1999-351969
                       Α
                                                               19990712
    US 6113449
PΙ
PRAI TW 1998-87111339 A
                             19980713
CLASS
            CLASS PATENT FAMILY CLASSIFICATION CODES
PATENT NO.
               _____
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US 6113449 ICM H01J009-02
                INCL
                     445024000
                IPCI
                      H01J0009-02 [ICM,7]
                NCL
                      445/024.000; 430/315.000
                ECLA H01J009/02
    A front plate for a plasma display panel (PDP) and its modified
AB
    fabricating method are provided using a backside exposure process and an
    appropriate processing sequence ***rearrangement*** to reduce the no.
         ***photomasks*** required and improve the accuracy of exposure and
    of
    developing process. First, a light-shielding layer is patterned by
    performing a mesh printing process, or by performing an exposure and
    developing process using a 1st ***photomask*** , so as to form a
    light-shielding structure including black stripes and transparent
    electrodes' gaps. Next, using the light-shielding structure as a
      ***mask*** , a backside exposure and developing process as well as an
    etching process was performed to form a plurality of pairs of transparent
    electrodes on the substrate. Then, using a 2nd ***photomask***
    another set of exposure, developing and etching processes were performed
    to form a plurality of pairs of metal electrodes on the corresponding
    transparent electrodes.
ST
    fabricating front plate plasma display panel
        (elec. conductive, transparent; in method of fabricating front plate
       for plasma display panel)
IT
    Transparent films
        (elec. conductive; in method of fabricating front plate for plasma
       display panel)
IT
    Electric conductors
    Electric conductors
        (films, transparent; in method of fabricating front plate for plasma
       display panel)
    Etching
    Etching
              ***masks***
    Light shields
    Negative photoresists
    Photolithography
    Photoresists
        (in method of fabricating front plate for plasma display panel)
IT
    Metals, processes
    Plate glass
    RL: DEV (Device component use); PEP (Physical, engineering or chemical
    process); PROC (Process); USES (Uses)
        (in method of fabricating front plate for plasma display panel)
IT
    Electronic device fabrication
    Plasma display panels
        (method of fabricating front plate for plasma display panel)
IT
    Electrodes
        (method of fabricating front plate for plasma display panel with)
IT
    Electrodes
        (transparent; method of fabricating front plate for plasma display
       panel with)
IT
    7429-90-5, Aluminum, processes 7440-47-3, Chromium, processes
    7440-50-8, Copper, processes 18282-10-5, Tin dioxide 50926-11-9, ITO
    117944-65-7, Indium zinc oxide
    RL: DEV (Device component use); PEP (Physical, engineering or chemical
    process); PROC (Process); USES (Uses)
       (in method of fabricating front plate for plasma display panel)
RE.CNT
             THERE ARE 2 CITED REFERENCES AVAILABLE FOR THIS RECORD
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ICM H01J009-02

IC

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    ANSWER 26 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
AN
     2000:435690 CAPLUS
DN
     133:95913
ED
     Entered STN: 29 Jun 2000
    Nanometer-scale copper electrodeposition from an on-chip source
TI
    Wu, Mingshaw W.; Sohn, Lydia L.
AU
     Physics Department, Princeton University, Princeton, NJ, 08544, USA
CS
SO
     IEEE Electron Device Letters (2000), 21(6), 277-279
     CODEN: EDLEDZ; ISSN: 0741-3106
     Institute of Electrical and Electronics Engineers
PB
DT
     Journal
LA
     English
CC
     72-2 (Electrochemistry)
     Using both an on-chip anode as a source of Cu and a Cu-free, acidic
AB
     electroplating soln., electrodes with sepns. on the order of 10 nm or less
     were fabricated. During the electrodeposition process, steplike increases
     in conductance was obsd., corresponding to at.
                                                      ***rearrangement***
     These conductance steps indicate that the sepn. between the electrodes is
     on the at. length scale. Applications of this technique include the
     fabrication of electrodes with nanometer sepns. and the repair of both
     malformed bus lines and damaged
                                       ***masks***
ST
     copper nanoscale electroplating onchip anode
IT
     Electrodeposition
     Nanostructures
        (nanometer-scale copper electroplating from an on-chip source)
     Anodes
        (on-chip; nanometer-scale copper electroplating from)
     7440-50-8, Copper, properties
     RL: PEP (Physical, engineering or chemical process); PRP (Properties);
     PROC (Process)
        (nanometer-scale copper electroplating from an on-chip source)
              THERE ARE 17 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE.CNT
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L19
     ANSWER 27 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
     1999:732026 CAPLUS
AN
     131:325980
DN
ED
     Entered STN: 17 Nov 1999
TΙ
     Is there diffusion creep in alumina?
     Kottada, R. S.; Chokshi, A. H.
AU
     Department Metallurgy, Indian Institute Science, Bangalore, 560012, India
CS
SO
     Key Engineering Materials (2000), 171-174 (Creep and Fracture of
     Engineering Materials and Structures), 779-786
     CODEN: KEMAEY; ISSN: 1013-9826
PB
     Trans Tech Publications Ltd.
DT
     Journal; General Review
LA
     English
CC
     57-0 (Ceramics)
     A review with 38 refs. on the characterization of mech. properties of
AB
     alumina-based ceramics and then describes new exptl. results on alumina
     doped with 300 ppm magnesia. Tensile expts. at elevated temp. were
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carried out on alumina doped magnesia, followed by SEM which revealed a considerable concurrent grain growth during tensile deformation of polycryst. alumina. A stress exponent for deformation of 1.3 was found together with an inverse grain size exponent of .apprx.3. It is argued that the occurrence of concurrent grain growth and the assocd. grain \*\*\*mask\*\*\* \*\*\*rearrangement\*\*\* the appearance of grain will elongation, so that microstructural observations, indicating a retention of an equiaxed grain shape as well as grain boundary sliding, are consistent with deformation by diffusion creep. review alumina ceramic diffusion creep Ceramics (diffusion creep in alumina ceramics) Creep (diffusion-controlled; diffusion creep in alumina ceramics) 1344-28-1, Alumina, processes RL: PEP (Physical, engineering or chemical process); PRP (Properties); TEM (Technical or engineered material use); PROC (Process); USES (Uses) (diffusion creep in alumina ceramics) THERE ARE 37 CITED REFERENCES AVAILABLE FOR THIS RECORD · RE.CNT 37 (1) Ashby, M; Acta Metall 1973, V21, P149 CAPLUS (2) Burke, J; Prog Metal Phys 1952, V3, P220 CAPLUS (3) Cannon, R; J Am Ceram Soc 1980, V63, P46 CAPLUS (4) Cannon, W; Structure and Properties of MgO and Al2O3 Ceramics 1984, P741 CAPLUS (5) Chokshi, A; J Am Ceram Soc 1987, V70, P197 CAPLUS (6) Chokshi, A; J Am Ceram Soc 1991, V74, P869 CAPLUS (7) Chokshi, A; J Mater Sci 1986, V21, P705 CAPLUS (8) Chokshi, A; J Mater Sci 1990, V25, P3231 (9) Chokshi, A; Mater Sci Eng 1993, VR10, P238 (10) Chokshi, A; Mater Sci Tech 1991, V7, P577 CAPLUS (11) Coble, R; J Am Ceram Soc 1956, V39, P377 (12) Coble, R; J Am Ceram Soc 1963, V46, P353 CAPLUS (13) Coble, R; J App Phys 1961, V32, P793 CAPLUS (14) Coble, R; J App Phys 1963, V34, P1670 (15) Folweiler, R; J App Phys 1961, V32, P773 CAPLUS (16) Fridez, J; Structure and Properties of MgO and Al203 Ceramics 1984, P720 CAPLUS (17) Greenwood, G; Creep Behavior of Advanced Materials for the 21st Century 1999, P413 CAPLUS (18) Greenwood, G; Scripta Metall Mater 1994, V30, P1527 CAPLUS (19) Herring, C; J App Phys 1950, V21, P437 (20) Heuer, A; Ultrafine-Grain Ceramics 1970, P339 CAPLUS (21) Kottada, R; to be published (22) Krause, R; J Am Ceram Soc 1992, V75, P1307 CAPLUS (23) Nabarro, F; Report on a Conference on Strength of Solids 1948, P75 CAPLUS (24) Nieh, T; Superplasticity in Metals and Ceramics 1997 (25) Owen, D; J Am Ceram Soc 1997, V80, P2433 CAPLUS

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- ANSWER 28 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN L19
- 1999:494228 CAPLUS AN
- DN 131:270790

ST IT

IT

IT

RE

- ED Entered STN: 10 Aug 1999
- TI Gene targeting of the KI-KII sequence elements in a model pre-B cell line: \*\*\*rearrangement\*\*\* effects on germline transcription and .kappa. locus
- ΑU Liu, Xiangdong; Van Ness, Brian
- CS Department of Biochemistry and the Cancer Center, University of Minnesota, Minneapolis, MN, 55455, USA

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so
     Molecular Immunology (1999), 36(7), 461-469
     CODEN: MOIMD5; ISSN: 0161-5890
PR
     Elsevier Science Ltd.
DТ
     Journal
LA
     English
CC
     15-7 (Immunochemistry)
     Section cross-reference(s): 3
     To study the role of individual sequence elements in the coordinate
AB
                     ***rearrangement***
                                          and germline transcription of the
     regulation of
     .kappa. locus, we have developed a gene targeting system with a mouse
     model pre-B cell line, 38B9. This line can be induced to initiate .kappa.
     germline transcription and V-J ***rearrangement*** . Importantly, the
     effects of gene disruption in the cell line can be analyzed independent of
     selective pressures that may ***mask***
                                               effects in the developing
     immune system of the mouse. We focused our study on targeting mutation of
     the endogenous KI-KII sequence elements to allow a direct comparison with
     the same gene disruption reported in mouse studies. Mutations were
     targeted to one allele, and effects on induced transcription and
       ***rearrangement***
                            were compared to the remaining wild type allele.
     Our results show that KI-KII mutation has little effect on germline
     transcription, and reduced the frequency of
                                                   ***rearrangement***
     fold compared to the wild type allele. This report demonstrates that the
     use of model pre-B cell lines for targeted gene disruption is an
     attractive alternative to targeting the germline of the mouse.
     gene targeting KI KII element mutation B cell; kappa gene transcription
                            KI KII element mutation
       ***rearrangement***
IT
     Animal cell line
        (38B9, model pre-B cell; gene targeting of KI-KII sequence elements in
        model pre-B cell line: effects on germline transcription and
          ***rearrangement*** of .kappa. locus)
     Gene, animal
     RL: BPR (Biological process); BSU (Biological study, unclassified); BIOL
     (Biological study); PROC (Process)
        (Iq..kappa.; gene targeting of KI-KII sequence elements in model pre-B
        cell line: effects on germline transcription and ***rearrangement***
        of .kappa. locus)
     Genetic element
     RL: BPR (Biological process); BSU (Biological study, unclassified); REM
     (Removal or disposal); BIOL (Biological study); PROC (Process)
        (KI-KII sequence, mutation in; gene targeting of KI-KII sequence
        elements in model pre-B cell line: effects on germline transcription
              ***rearrangement***
                                   of .kappa. locus)
     B cell (lymphocyte)
IT
     Gene targeting
     V(D)J recombination
        (gene targeting of KI-KII sequence elements in model pre-B cell line:
        effects on germline transcription and
                                               ***rearrangement***
        .kappa. locus)
     Immunoglobulins
IT
     RL: BSU (Biological study, unclassified); BIOL (Biological study)
        (gene targeting of KI-KII sequence elements in model pre-B cell line:
        effects on germline transcription and
                                               ***rearrangement***
        .kappa. locus)
     Mutation
        (in KI-KII sequence; gene targeting of KI-KII sequence elements in
        model pre-B cell line: effects on germline transcription and
          ***rearrangement***
                                of .kappa. locus)
     Transcription, genetic
        (of .kappa. locus, KI-KII mutation has little effect on; gene targeting
        of KI-KII sequence elements in model pre-B cell line: effects on
        germline transcription and
                                   ***rearrangement***
                                                           of .kappa. locus)
IT
     Recombination, genetic
           ***rearrangement*** , of .kappa. locus, KI-KII mutation reduced
        frequency of; gene targeting of KI-KII sequence elements in model pre-B
        cell line: effects on germline transcription and
                                                           ***rearrangement***
        of .kappa. locus)
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     1999:443614 CAPLUS
AN
     131:207402
DN
     Entered STN: 20 Jul 1999
ED
     Micropyramidal hillocks on KOH-etched {100} silicon surfaces: formation,
TΙ
     prevention and removal
     Schroder, H.; Obermeier, E.; Steckenborn, A.
AU
     Technical University of Berlin, MAT, Secr. TIB 3.1, Berlin, D-13355,
CS
     Journal of Micromechanics and Microengineering (1999), 9(2), 139-145
     CODEN: JMMIEZ; ISSN: 0960-1317
     Institute of Physics Publishing
DT
     Journal
     English
LA
     76-3 (Electric Phenomena)
CC
     The formation, prevention, and removal of micropyramids at the {100}
AΒ
     bottom of anisotropically etched cavities are investigated and discussed.
     In the case of pure KOH solns., the base of the micropyramids has been
     found to be always rectangular or octagonal-shaped. The formation is
     independent of the KOH supplier and the etch- ***mask***
                     ***rearrangement***
                                           of the rectangular-based
              The
     micropyramids on the {100} etch bottom depends on the etching time,
     etching position of the chip (vertical or horizontal), and on the oxygen
     content in connection with the thermal history of the wafer material.
     both types of micropyramid, the surface d. and size increase with
     decreasing KOH concn. and etching temp. Moreover, the proportion of
     octagonal micropyramids rises under these conditions. The origin is
     discussed in terms of micromasking by H2-bubbles in connection with
     plateau generation and layer-by-layer peeling of the {111} planes.
     mechanisms which are suggested in the literature are discussed. Further,
     it was exhibited that already arisen micropyramids can be removed by a
     short re-etching in the same etch bath under the same conditions.
ST
     silicon surface etching micropyramidal hillock
IT
     Etching
        (micropyramidal hillocks on KOH-etched {100} silicon surfaces)
TT
     1310-58-3, Potassium hydroxide, uses
     RL: NUU (Other use, unclassified); USES (Uses)
        (micropyramidal hillocks on KOH-etched {100} silicon surfaces)
     7440-21-3, Silicon, properties
     RL: PEP (Physical, engineering or chemical process); PRP (Properties);
     PROC (Process)
        (micropyramidal hillocks on KOH-etched {100} silicon surfaces)
RE.CNT
              THERE ARE 24 CITED REFERENCES AVAILABLE FOR THIS RECORD
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L19
     1999:336027 CAPLUS
AN
DN
     131:95692
     Entered STN: 02 Jun 1999
ED
     Characteristics of high-Tc ramp-edge junctions with Co-doped YBa2Cu3O7-x
TI
ÄU
     Lee, Moon-Chul; Sung, Gun Yong; Kang, Kwang-Yong; Lee, Soon-Gul
     Department of Physics, Korea University, Seoul, 136-701, S. Korea
CS
     Ungyong Mulli (1999), 12(2), 123-131
SO
     CODEN: HMHMEY; ISSN: 1013-7009
PB
     Korean Physical Society
DT
     Journal
LΑ
     Korean
CC
     76-4 (Electric Phenomena)
     The authors fabricated high-Tc superconducting YBa2Cu3O7-
AΒ
     x/YBa2Cu0.79Co0.2107-x/YBa2Cu3O7-x ramp-edge Josephson junctions on (001)
     SrTiO3 single-crystal substrates and studied the effects of post
     ion-milling and pre-annealing of the ramp-edge prior to the top layer and
     post-annealing process. The ion beam voltage, the ion beam incident
                         ***mask***
                                     angle to yield smooth slopes with an
     angle, and the PR
     angle of .apprx.30.degree. were optimized. The morphol. of the edge was
     improved by the post ion-milling, as were the edge-surface-induced
     epitaxial growth and the small interface resistance between the top YBCO
     layer and the Co-doped YBCO barrier. Annealing prior to barrier
     deposition recovered the ramp-edge surface and increased the Tc of the
     edge. Annealing helped epitaxial growth of the top YBCO layer on the ramp
     edge. Post-annealing at a temp. above the deposition temp. and cooling at
     500 torr O2 induced the epitaxial
                                         ***rearrangement***
                                                              of Co-doped YBCO
     at a high O vapor pressure. The current-voltage characteristics of the
     junctions showed RSJ-like behavior.
     barium cobalt copper yttrium oxide ramp junction fabrication
     Annealing
     Cooling
     Dopants
     Electric current-potential relationship
     Electronic device fabrication
     Josephson junctions
     Laser epitaxy
     Surface resistance
        (fabrication and characteristics of high-Tc ramp-edge junctions with
        cobalt-doped barium copper yttrium oxide barriers)
     Machining
        (ion-beam milling; fabrication and characteristics of high-Tc ramp-edge
        junctions with cobalt-doped barium copper yttrium oxide barriers)
     Vapor deposition process
        (laser ablation; fabrication and characteristics of high-Tc ramp-edge
        junctions with cobalt-doped barium copper yttrium oxide barriers)
     7440-48-4, Cobalt, uses
     RL: MOA (Modifier or additive use); USES (Uses)
        (fabrication and characteristics of high-Tc ramp-edge junctions with
        cobalt-doped barium copper yttrium oxide barriers)
IT
     7440-37-1D, Argon, ions, processes
                                          7782-44-7, Oxygen, processes
     RL: NUU (Other use, unclassified); PEP (Physical, engineering or chemical
     process); PROC (Process); USES (Uses)
        (fabrication and characteristics of high-Tc ramp-edge junctions with
        cobalt-doped barium copper yttrium oxide barriers)
IT
     109064-29-1D, Barium copper yttrium oxide (Ba2Cu3Y07), oxygen-deficient
     229315-90-6D, Barium cobalt copper yttrium oxide (Ba2Co0.21Cu0.79YO7),
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RL: PEP (Physical, engineering or chemical process); PRP (Properties); TEM

(Technical or engineered material use); PROC (Process); USES (Uses)

oxygen-deficient

(fabrication and characteristics of high-Tc ramp-edge junctions with cobalt-doped barium copper yttrium oxide barriers) IT 12060-59-2, Strontium titanate RL: PEP (Physical, engineering or chemical process); TEM (Technical or engineered material use); PROC (Process); USES (Uses) (fabrication and characteristics of high-Tc ramp-edge junctions with cobalt-doped barium copper yttrium oxide barriers) ANSWER 31 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN L19 1999:87254 CAPLUS ANDN 130:231353 ED Entered STN: 11 Feb 1999 One- and Two-Electron Oxidative Pathways Leading to Cyclopropane-ΤI Containing Oxidized Porphyrinogens and C-C-Coupled Porphyrinogens from Alkali Cation- and Transition Metal-meso-Octaethylporphyrinogen Complexes Crescenzi, Raffaella; Solari, Euro; Floriani, Carlo; Chiesi-Villa, ΑU Angiola; Rizzoli, Corrado Institut de Chimie Minerale et Analytique BCH, Universite de Lausanne, CS Lausanne, CH-1015, Switz. SO Journal of the American Chemical Society (1999), 121(8), 1695-1706 CODEN: JACSAT; ISSN: 0002-7863 PB American Chemical Society DTJournal LA English 78-7 (Inorganic Chemicals and Reactions) CC Section cross-reference(s): 26, 67, 75 AB This report deals with the different transition metal- and alkali cation-assisted oxidn. pathways of the meso-octaethylporphyrinogen tetraanion [Et8N4]4-. The two-electron oxidn. of [Et8N4Mn{Na(THF)2}2], 4, with Cp2FeBPh4 led to the corresponding monocyclopropane deriv. [Et8N4(.DELTA.)Mn], 6, [.DELTA. = cyclopropane], while the 1-electron oxidn. with CuCl2 or O2 led to the Mn(III)-porphyrinogen [Et8N4Mn] [Li(THF)4], 5, which can be further oxidized by an excess of CuCl2 to [Et8N4(.DELTA.)2Mn-Cl]+[Cu9Cl11]0.5, 7. The formation of 7 does not follow the expected sequence Mn(II) .fwdarw. Mn(III) .fwdarw. Mn(II)-monocyclopropane .fwdarw. Mn(II)-biscyclopropane-porphyrinogen. the case of Fe(II)-porphyrinogen, [Et8N4Fe{Li(THF)2}2], 9, the oxidn. led in a preliminary stage to the Fe(III) deriv. [Et8N4Fe] [Li(THF)4], 10, then to the metalated form of the biscyclopropane-porphyrinogen [Et8N4(.DELTA.)2Fe-Cl][{.mu.-Cu4Cl5}], 11. The supposed stabilization of the biscyclopropane by the Cu(I) cluster was ruled out by carrying the oxidn. of [Cy4N4Fe{Li(THF)2}2] to [Cy4N4(.DELTA.)2Fe-Cl][Cu2Cl4], 14. stepwise oxidn. of [Et8N4M(THF)4] [M = Li, 1; M = Na, 2] with Cp2FeBPh4 led to [Et8N4(.DELTA.)Li2THF2], 15, [Et8N4(.DELTA.)Li]BPh4, 16, and [Et8N4(.DELTA.)Na]BPh4, 17. The reaction of 1 with 16 leading to 15 showed how the C-C moiety in cyclopropane can be engaged in an intermol. electron transfer. The reaction of 17 with 18-crown-6 allowed the release of biscyclopropane-porphyrinogen [Et8N4(.DELTA.2)]. Particularly interesting is the thermal \*\*\*rearrangement\*\*\* of 15 occurring via intra- and intermol. electron transfers with the transposition of the C-C bond of the cyclopropane to a C-C bridge across the .beta. position of two adjacent pyrroles. In the case of metals, such as Ni(II), which do not undergo oxidn. state changes, the primary oxidn. product of a metalla-meso-octaalkylporphyrinogen is the monocyclopropane deriv., which reacting with the starting material \*\*\*masks\*\*\* an overall 1-electron In fact, the reaction of [Et8N4Ni{Li(THF)2}2], 20, with 2 equiv of Cp2FeBPh4 led to the expected [Et8N4(.DELTA.)Ni], 21, while the reaction of 20 with 1 equiv of Cp2FeBPh4 led to the dimer [(.beta.-.beta.)(Et8N4)2Ni2], 22, which forms equally well from the reaction of 20 and 21. Complex 22 is a quite unique metallaporphyrinogen dimer, where the two monomeric units are joined via a C-C bond in the .beta. position of a pyrrole. Such a reaction shows that the methodol. can accede to oligomeric forms of metallaporphyrinogens. The crystal structures of 5, \*\*\*rearranged\*\*\* 7, 11, 14 and the thermally product of 15 were detd. stcrystal structure transition metal porphyrinogen deriv complex; porphyrinogen deriv alkali metal transition metal prepn; cyclopropane contg oxidized porphyrinogen metal complex prepn; mechanism oxidn porphyrinogen alkali transition metal complex IT Bond formation (carbon-carbon; during oxidn. of alkali metal complexes with octaalkylporphyrinogen)

IT

Oxidation

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(mechanism; of alkali metal complexes with octaalkylporphyrinogen with
        intra- and intermol. C-C bond formation)
IT
     Crystal structure
     Molecular structure
    NMR (nuclear magnetic resonance)
        (of alkali metal/transition metal complexes with porphyrinogen derivs.)
IT
     148420-63-7
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (oxidn. for prepn. of transition metal complexes of cyclopropane contg.
        porphyrinogens)
IT
     156025-36-4
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (oxidn. with/without dimerization)
                    221096-90-8P
IT
     156025-37-5P
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (prepn. and NMR)
IT
     221027-97-0P
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (prepn. and NMR and crystal structure)
IT
     221027-94-7P
     RL: PRP (Properties); RCT (Reactant); SPN (Synthetic preparation); PREP
     (Preparation); RACT (Reactant or reagent)
        (prepn. and NMR and demetalation)
IT
     221027-81-2P
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (prepn. and crystal structure)
     221027-68-5P
     RL: PRP (Properties); RCT (Reactant); SPN (Synthetic preparation); PREP
     (Preparation); RACT (Reactant or reagent)
        (prepn. and crystal structure and oxidn.)
     221027-73-2P
     RL: PRP (Properties); RCT (Reactant); SPN (Synthetic preparation); PREP
     (Preparation); RACT (Reactant or reagent)
        (prepn. and crystal structure and reaction with bipyridine)
IT
     221027-84-5P
     RL: PRP (Properties); SPN (Synthetic preparation); PREP (Preparation)
        (prepn. and crystal structure of)
                    139376-54-8P
                                   221027-65-2P
                                                   221027-87-8P
IT
     139376-49-1P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (prepn. and oxidn.)
IT
     221027-60-7P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (prepn. and oxidn. for prepn. of transition metal complexes of
        cyclopropane contg. porphyrinogens)
IT
     35320-70-8P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (prepn. and reaction with butyllithium)
IT
     221027-79-8P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (prepn. and reaction with copper chloride)
                    221027-63-0P
                                   221027-70-9P
                                                   221027-75-4P
                                                                  221028-01-9P
     156025-44-4P
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (prepn. of)
     108-94-1, Cyclohexanone, reactions
                                           109-97-7, Pyrrole
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (reactant for prepn. of iron complex of cyclohexyl-contg.
        porphyrinogens)
                               22393-36-8, (2,2'-Bipyridine)dichlorocopper
IT
     12562-70-8
                  12562-71-9
     216297-47-1
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (reactant for prepn. of transition metal complexes of cyclopropane
        contg. porphyrinogens)
     135388-37-3
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (reaction with sodium)
              THERE ARE 43 CITED REFERENCES AVAILABLE FOR THIS RECORD
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- L19 ANSWER 32 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
- AN 1998:505434 CAPLUS
- DN 129:92521
- ED Entered STN: 15 Aug 1998
- TI Photoactivatable Cross-Linked Polyacrylamide for the Site-Selective Immobilization of Antigens and Antibodies
- AU Sanford, Melanie S.; Charles, Paul T.; Commisso, Sarah M.; Roberts, Jenna C.; Conrad, David W.
- CS Center for Biomolecular Science and Engineering, Naval Research Laboratory, Washington, DC, 20375-5348, USA
- SO Chemistry of Materials (1998), 10(6), 1510-1520 CODEN: CMATEX; ISSN: 0897-4756
- PB American Chemical Society
- DT Journal
- LA English
- CC 9-16 (Biochemical Methods)
- AB This paper describes the synthesis, characterization, and photochem. behavior of a new light-activated material for the photoimmobilization of antigens. The material is a deriv. of cross-linked polyacrylamide that incorporates photoactive o-nitrobenzyl carbamates. When irradiated, the polymer undergoes a photochem. \*\*\*rearrangement\*\*\* to produce primary amines that can be used as mol. attachment sites. We monitored the photoconversion of thin (1-2 .mu.m) polymer films that were deposited on silicon wafers or fused silica substrates using FT IR spectroscopy and UV-vis spectroscopy. To produce patterned polymer-modified substrates, we irradiated the material using a photolithog. \*\*\*mask\*\*\* This process

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yielded 10-.mu.m lines of photogenerated amines, to which an
     amine-reactive antigen (2,4,6-trinitrobenzenesulfonic acid) was covalently
     bound. When we used this antigen-patterned substrate in a competitive
     fluorescence immunoassay contg. tetramethylrhodamine-labeled
     anti-2,4-dinitrophenyl antibodies and 2,4-dinitrophenol, concns. of
     2,4-dinitrophenol as low as 2.3 .mu.g/mL were detectable.
     photoactivatable crosslinked polyacrylamide immobilization antigen
     antibody
     Immunoassay
        (fluorescence; photoactivatable cross-linked polyacrylamide for
        site-selective immobilization of antigens and antibodies)
     Immobilization, biochemical
        (photo-; photoactivatable cross-linked polyacrylamide for
        site-selective immobilization of antigens and antibodies)
     Antibodies
     Antigens
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (photoactivatable cross-linked polyacrylamide for site-selective
        immobilization of antigens and antibodies)
     51-28-5, 2,4-Dinitrophenol, analysis
                                            2508-19-2, 2,4,6-
     Trinitrobenzenesulfonic acid
     RL: ANT (Analyte); ANST (Analytical study)
        (photoactivatable cross-linked polyacrylamide for site-selective
        immobilization of antigens and antibodies)
                                               70281-37-7, Tetramethylrhodamine
     9003-05-8D, Polyacrylamide, crosslinked
     RL: NUU (Other use, unclassified); USES (Uses)
        (photoactivatable cross-linked polyacrylamide for site-selective
        immobilization of antigens and antibodies)
                1476-23-9, Allyl isocyanate
                                              96839-34-8
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (photoactivatable cross-linked polyacrylamide for site-selective
        immobilization of antigens and antibodies)
                    184533-06-0P
     184533-05-9P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (photoactivatable cross-linked polyacrylamide for site-selective
        immobilization of antigens and antibodies)
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- L19 ANSWER 33 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
- AN 1997:795719 CAPLUS
- DN 128:124445
- ED Entered STN: 20 Dec 1997
- TI NotI linking/jumping clones of human chromosome 3: mapping of the TFRC, RAB7 and HAUSP genes to regions \*\*\*rearranged\*\*\* in leukemia and deleted in solid tumors
- AU Kashuba, V. I.; Gizatullin, R. Z.; Protopopov, A.I.; Allikmets, R.; Korolev, S.; Li, J.; Boldog, F.; Tory, K.; Zabarovska, V.; Marcsek, Z.; Sumeqi, J.; Klein, G.; Zabarovsky, E. R.; Kisselev, L.
- CS Doktorsringen 13, Microbiology and Tumor Biology Center, Karolinska Institute, Stockholm 17177, Swed.
- SO FEBS Letters (1997), 419(2,3), 181-185 CODEN: FEBLAL; ISSN: 0014-5793
- PB Elsevier Science B.V.
- DT Journal
- LA English
- CC 3-4 (Biochemical Genetics)
  Section cross-reference(s): 14
- By applying the 'recognition \*\*\*mask\*\*\* ' strategy to 300 mammalian sequences contg. NotI sites we demonstrated that 5' ends of genes are highly enriched in NotI sites. A NotI linking clone NL2-252 (D3S1678) contq. transferrin receptor (TFRC) gene was used as an initial point for chromosomal jumping. One of the jumping clones, J21-045 traverses 210 kbp and links NL2-252 to NL26 (D3S1632), a NotI linking clone contg. highly polymorphic sequences. The TFRC gene was mapped to 3q29, close to the telomeric marker D3S2344, by linkage anal., a panel of hybrid cell lines, GeneBridge 4 panel and FISH. Clone NLM-007 (D3S4302) was found to contain ras-homologous gene RAB7. By FISH and a panel of hybrid cell lines this gene was mapped to 3q21. This region is of particular interest due to \*\*\*rearrangements\*\*\* in different types of leukemia. Clone L2-081 (D3S4283) contg. new member of ubiquitin-specific proteases (HAUSP gene) was localized in 3p21 inspiring further investigation of involvement of this gene in development of lung and renal carcinomas.
- ST mapping TFRC RAB7 HAUSP gene human; NotI clones human chromosome 3 leukemia; tumor leukemia gene human chromosome 3
- IT Gene, animal
  - RL: BOC (Biological occurrence); BSU (Biological study, unclassified); BIOL (Biological study); OCCU (Occurrence)
    - (HAUSP; NotI linking/jumping clones of human chromosome 3: mapping of the TFRC, RAB7 and HAUSP genes to regions \*\*\*rearranged\*\*\* in leukemia and deleted in solid tumors)
- IT Genetic mapping

(NotI linking/jumping clones of human chromosome 3: mapping of the TFRC, RAB7 and HAUSP genes to regions \*\*\*rearranged\*\*\* in leukemia and deleted in solid tumors) IT Gene, animal RL: BOC (Biological occurrence); BSU (Biological study, unclassified); BIOL (Biological study); OCCU (Occurrence) (RAB7; NotI linking/jumping clones of human chromosome 3: mapping of the TFRC, RAB7 and HAUSP genes to regions \*\*\*rearranged\*\*\* leukemia and deleted in solid tumors) IT Gene, animal RL: BOC (Biological occurrence); BSU (Biological study, unclassified); BIOL (Biological study); OCCU (Occurrence) (TFRC; NotI linking/jumping clones of human chromosome 3: mapping of the TFRC, RAB7 and HAUSP genes to regions \*\*\*rearranged\*\*\* leukemia and deleted in solid tumors) Lung, neoplasm IT (carcinoma; NotI linking/jumping clones of human chromosome 3: mapping of the TFRC, RAB7 and HAUSP genes to regions \*\*\*rearranged\*\*\* in leukemia and deleted in solid tumors) IT Chromosome (human 3, 3p21, ubiquitin-specific proteases (HAUSP gene) was localized in 3p21; NotI linking/jumping clones of human chromosome 3: mapping of the TFRC, RAB7 and HAUSP genes to regions \*\*\*rearranged\*\*\* leukemia and deleted in solid tumors) (human 3, 3q2, ras-homologous gene RAB7 was mapped to 3q21; NotI linking/jumping clones of human chromosome 3: mapping of the TFRC, RAB7 and HAUSP genes to regions \*\*\*rearranged\*\*\* in leukemia and deleted in solid tumors) IT Chromosome (human 3, 3q29, TFRC gene was mapped to 3q29, close to the telomeric marker D3S2344; NotI linking/jumping clones of human chromosome 3: mapping of the TFRC, RAB7 and HAUSP genes to regions in leukemia and deleted in solid tumors) Recombination, genetic \*\*\*rearrangement\*\*\* ; NotI linking/jumping clones of human chromosome 3: mapping of the TFRC, RAB7 and HAUSP genes to regions in leukemia and deleted in solid tumors) \*\*\*rearranged\*\*\* IT Kidney, neoplasm (renal cell carcinoma; NotI linking/jumping clones of human chromosome 3: mapping of the TFRC, RAB7 and HAUSP genes to regions \*\*\*rearranged\*\*\* in leukemia and deleted in solid tumors) Transferrin receptors RL: BSU (Biological study, unclassified); BIOL (Biological study) (transferrin receptor TFRC gene was mapped to 3q29, close to telomeric marker D3S2344; NotI linking/jumping clones of human chromosome 3: mapping of the TFRC, RAB7 and HAUSP genes to regions \*\*\*rearranged\*\*\* in leukemia and deleted in solid tumors) 103780-20-7, Restriction endonuclease NotI RL: BAC (Biological activity or effector, except adverse); BSU (Biological study, unclassified); BUU (Biological use, unclassified); BIOL (Biological study); USES (Uses) (NotI linking/jumping clones of human chromosome 3: mapping of the \*\*\*rearranged\*\*\* TFRC, RAB7 and HAUSP genes to regions in leukemia and deleted in solid tumors) 9001-92-7, Protease RL: BSU (Biological study, unclassified); BIOL (Biological study) (Ubiquitin-specific, ubiquitin-specific proteases (HAUSP gene) was localized in 3p21; NotI linking/jumping clones of human chromosome 3: mapping of the TFRC, RAB7 and HAUSP genes to regions \*\*\*rearranged\*\*\* in leukemia and deleted in solid tumors) ANSWER 34 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN L19 AN 1997:669523 CAPLUS DN 127:324219 Entered STN: 22 Oct 1997 ED TISimulation and fabrication of attenuated phase-shifting \*\*\*masks\*\*\* Kim, Eunah; Hong, Seungbum; Kim, Kyong-Sub; Jiang, Zhong-Tao; Kim, Dae ΑU Weon; Lim, Sungchul; Woo, Sang-Gyun; Koh, Young-Bum; No, Kwangsoo

Department of Materials Science and Engineering, Korea Advanced Institute

of Science and Technology, Taejon, S. Korea

CS

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so
     Applied Optics (1997), 36(28), 7247-7256
     CODEN: APOPAI; ISSN: 0003-6935
PR
     Optical Society of America
DT
     Journal
LΑ
     English
     73-11 (Optical, Electron, and Mass Spectroscopy and Other Related
CC
     Properties)
     Section cross-reference(s): 74
     To acquire the required resoln. for 248- and 193-nm lithog., a study of
AB
     attenuated phase-shifting ***mask***
                                              (Att-PSM) technol. is in
     progress. The authors performed a simulation study using a matrix method
     to calc. relative transmittance and the amt. of phase shift of light
     through the PSM. However, the av. film compn. changed with deposition
     time. Accordingly, optical consts. are a strong function of film
     thickness. Therefore the authors ***rearranged***
                                                            the relation
     between deposition parameters (e.g., deposition time or gas flow rate
     ratio) and optical consts. (e.g., refractive index and extinction coeff.)
     to ext. the empirical formula for the optical consts. with respect to film
     compn. To verify the authors' simulation study, the authors fabricated a
     phase shifter based on the authors' simulation result, which has a
     transmittance of 8.3% and a phase shift of 179.5.degree.. Consequently,
     the authors obtained a reliable optimum condition for the deep-UV Att-PSM.
     attenuated phase shifting
                                 ***mask***
                                             chromium fluoride; lithog
ST
       ***mask***
                   optical property
       ***Photomasks***
                                          ***masks*** )
                          (lithographic
IT
        (phase-shifting; simulation and fabrication of attenuated
                        ***masks*** from CrFx)
        phase-shifting
IT
     Optical absorption
     Optical properties
     Refractive index
     Simulation and Modeling, physicochemical
     Thickness
        (simulation and fabrication of attenuated phase-shifting
                                                                   ***masks***
        from CrFx)
     11113-56-7, Chromium fluoride
IT
     RL: DEV (Device component use); PEP (Physical, engineering or chemical
     process); PRP (Properties); PROC (Process); USES (Uses)
        (simulation and fabrication of attenuated phase-shifting
                                                                   ***masks***
        from CrFx)
                                7440-37-1, Argon, uses
IT
     7440-21-3, Silicon, uses
     RL: NUU (Other use, unclassified); USES (Uses)
        (simulation and fabrication of attenuated phase-shifting
                                                                   ***masks***
        from CrFx)
     7440-47-3, Chromium, processes
     RL: PEP (Physical, engineering or chemical process); RCT (Reactant); PROC
     (Process); RACT (Reactant or reagent)
                                                                   ***masks***
        (simulation and fabrication of attenuated phase-shifting
        from CrFx)
     75-73-0, Tetrafluoromethane
     RL: RCT (Reactant); RACT (Reactant or reagent)
                                                                    ***masks***
        (simulation and fabrication of attenuated phase-shifting
        from CrFx)
              THERE ARE 12 CITED REFERENCES AVAILABLE FOR THIS RECORD
RE.CNT
RE
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L19
     1997:468477 CAPLUS
AN
DN
     127:186369
     Entered STN: 26 Jul 1997
ED
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ΤI
     In vivo analyses of upstream promoter sequence elements in the 5 S rRNA
    gene from Saccharomyces cerevisiae
    Lee, Yoon; Wong, William M.; Guyer, David; Erkine, Alexander M.; Nazar,
ΑU
    Department Molecular biology Genetics, University Guelph, Guelph, ON, N1G
CS
     2W1, Can.
     Journal of Molecular Biology (1997), 269(5), 676-683
SO
     CODEN: JMOBAK; ISSN: 0022-2836
PB
    Academic
DT
    Journal
    English
LA
     3-3 (Biochemical Genetics)
CC
     Section cross-reference(s): 10
     Upstream promoter elements of the Saccharomyces cerevisiae 5 S rRNA gene
AB
    have been characterized by genomic DNase I "footprinting" and by in vivo
    mutational analyses using base substitutions and deletions. A high copy
     shuttle-vector was used to efficiently express the mutant 5 S rRNA genes
     in vivo and a structural mutation in the 5 S rRNA, which was previously
     shown to be functionally neutral but easily detected by gel
     electrophoresis, allowed for an accurate measure of gene expression.
     results provide direct evidence for upstream regulatory elements which
     confirms a start site element (sse) from -1 to -8 and identifies a new
     independent upstream promoter element (upe) centered from about -17 to
           In contrast to previous reports with reconstituted systems, both
     elements dramatically affect the efficiency of gene expression and suggest
     that the satd. conditions which are used in reconstituted studies
                    sequence dependence; a dependency that could be physiol.
     significant and play a role in the regulation of 5 S rRNA expression.
     footprint analyses support an extended region of protein interaction as
     recently obsd. in reconstituted systems but again provide evidence of
                              ***rearrangements***
                                                     when the upstream sequence
     significant structural
     is changed.
     promoter sequence element Saccharomyces 5S rRNA
ST
     rRNA
IT
     RL: BSU (Biological study, unclassified); BIOL (Biological study)
        (5 S; upstream promoter sequence elements in 5 S rRNA gene from
        Saccharomyces cerevisiae)
IT
     Gene, microbial
     RL: BPR (Biological process); BSU (Biological study, unclassified); BIOL
     (Biological study); PROC (Process)
        (5S rRNA; upstream promoter sequence elements in 5 S rRNA gene from
        Saccharomyces cerevisiae)
     Genetic element
TT
     RL: BPR (Biological process); BSU (Biological study, unclassified); PRP
     (Properties); BIOL (Biological study); PROC (Process)
        (URE (upstream regulatory element), -17 to -20; upstream promoter
        sequence elements in 5 S rRNA gene from Saccharomyces cerevisiae)
TT
     Genetic element
     RL: BPR (Biological process); BSU (Biological study, unclassified); PRP
     (Properties); BIOL (Biological study); PROC (Process)
        (start site element (sse); -1 to -8; upstream promoter sequence
        elements in 5 S rRNA gene from Saccharomyces cerevisiae)
     DNA sequences
IT
     Saccharomyces cerevisiae
     Transcriptional regulation
        (upstream promoter sequence elements in 5 S rRNA gene from
        Saccharomyces cerevisiae)
     Promoter (genetic element)
     RL: BPR (Biological process); BSU (Biological study, unclassified); PRP
     (Properties); BIOL (Biological study); PROC (Process)
        (upstream promoter sequence elements in 5 S rRNA gene from
        Saccharomyces cerevisiae)
     194304-75-1
     RL: BSU (Biological study, unclassified); PRP (Properties); BIOL
     (Biological study)
        (nucleotide sequence -40 to +5 contg. UPE [-17 to -20] and SSE [-1 to
        -8]; upstream promoter sequence elements in 5 S rRNA gene from
        Saccharomyces cerevisiae)
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RE.CNT
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    ANSWER 36 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
     1996:668814 CAPLUS
AN
DN
     126:52723
ED
     Entered STN: 13 Nov 1996
     Photogenerated base in polymer imaging and curing: novel imaging material
ΤI
     based on an amine-catalyzed isomerization process
     Niu, Q. J.; Urankar, E. J.; Frechet, J. M.
ΑU
     Dep. Chem., Cornell Univ., Ithaca, NY, USA
CS
     Report (1996), Order No. AD-A310 779/4GAR, 4 pp. Avail.: NTIS
     From: Gov. Rep. Announce. Index (U. S.) 1996, 96(22), Abstr. No. 22-00,413
DT
     Report
LA
     English
     74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other
     Reprographic Processes)
     The use of base photogenerated in situ within a polymer coating affords
     attractive possibilities for the imaging or curing or reactive polymeric
     materials. In the case of resists, photogenerated base may provide access
     to materials that are more resistant to airborne contaminants than the
     chem. amplified resists currently available com. today. We have designed
     a family of novel copolymers contg. benzisoxazole pendant groups that
                         to cyanophenols in the presence of a catalytic amt. of
       ***rearrange***
                   ***rearrangement*** ' also occurs thermally at elevated
     temps. and may be easily followed by DSC. Films of the
     benzisoxazole-substituted copolymers contg. a small amt. of photogenerated
                                                            ***mask***
```

photogenerated amine catalyzed isomerization photoresist photoimaging; ST polymer benzisoxazole group photoresist amine photogenerator IT Photoimaging materials

copolymer. At the present time the sensitivity of this resist is relatively low (ca. 100 mJ/sq cm), but this may be optimized.

polymer is more sol. in aq. base than the starting

base may be imaged to afford pos.-tone images of the

\*\*\*rearranged\*\*\*

## Photoresists

(novel imaging material based on photogeneration of amine catalyst and isomerization of benzisoxazole-substituted copolymers)

- L19 ANSWER 37 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
- AN 1996:416466 CAPLUS
- ED Entered STN: 16 Jul 1996
- TI Photogenerated base in polymer imaging and curing: Novel imaging material based on an amine-catalyzed isomerization process.
- AU Niu, Q. Jason; Urankar, Edward J.; Frechet, Jean M. J.
- CS Baker Laboratory, Cornell University, Ithaca, NY, 14853-1301, USA
- SO Book of Abstracts, 212th ACS National Meeting, Orlando, FL, August 25-29 (1996), PMSE-271 Publisher: American Chemical Society, Washington, D. C. CODEN: 63BFAF
- DT Conference; Meeting Abstract
- LA English
- The use of base photogenerated in situ within a polymer coating affords AB attractive possibilities for the imaging or curing or reactive polymeric materials. In the case of resists, photogenerated base may provide access to materials that are more resistant to airborne contaminants than the chem. amplified resists currently available com. today [1]. We have designed a family of novel copolymers contg. benzisoxazole pendant groups to cyanophenols in the presence of a catalytic \*\*\*rearrange\*\*\* \*\*\*rearrangement\*\*\* also occurs thermally at amt. of amine. The elevated temps. and may be easily followed by DSC. Films of the benzisoxazole-substituted copolymers contg. a small amt. of photogenerated base may be imaged to afford pos.-tone images of the \*\*\*mask\*\*\* polymer is more sol. in aq. base than the starting \*\*\*rearranged\*\*\* copolymer. At the present time the sensitivity of this resist is relatively low (ca. 100mJ/cm2), but this may be optimized.
- L19 ANSWER 38 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
- AN 1996:59674 CAPLUS
- DN 124:166910
- ED Entered STN: 30 Jan 1996
- TI Complementation analyses for 45 mutations encompassing the pink-eyed dilution (p) locus of the mouse
- AU Russell, Liane B.; Montgomery, Clyde S.; Cacheiro, N. L. A.; Johnson, Dabney K.
- CS Biology Division, Oak Ridge National Laboratory, Oak Ridge, TN, 37831-8077, USA
- SO Genetics (1995), 141(4), 1547-62
  - CODEN: GENTAE; ISSN: 0016-6731
- PB Genetics Society of America
- DT Journal
- LA English
- CC 3-3 (Biochemical Genetics)
  - Section cross-reference(s): 13
- The homozygous and heterozygous phenotypes are described and characterized AB for 45 new pink-eyed diln. (p) locus mutations, most of them radiation-induced, that affect survival at various stages of mouse development. Cytogenetically detectable aberrations were found in three of the new p mutations (large deletion, inversion, translocation), with band 7C involved in each case. The complementation map developed from the study of 810 types of compd. heterozygotes identifies five functional units: jls and jlm (two distinct juvenile-fitness functions, the latter assocd. with neuromuscular defects), pl-1 and pl-2 (assocd. with early-postimplantation and preimplantation death, resp.), and nl [neonatal lethality assocd. with cleft palate (the frequency of rare "escapers" from this defect varied with the genotype)]. Orientation of these units relative to genetic markers is as follows: centromere, Gas-2, pl-1, jls, jlm p, nl (equatable to cp1 = Gabrb3); pl-2 probably resides in the \*\*\*mask\*\*\* preimplantation lethals c-deletion complex. Pl-1 does not between Gas2 and p; and no genes affecting survival are located between p and cpl. The alleles specifying mottling or darker pigment (generically, pm and px, resp.) probably do not represent deletions of p-coding sequences but could be small \*\*\*rearrangements\*\*\* involving proximal regulatory elements.
- ST gene pink eyed diln mapping mouse; chromosome 7 mouse pink eyed diln
- IT Development, mammalian

Genetic mapping

Mouse

```
(complementation analyses for 45 mutations encompassing pink-eyed diln.
        (p) locus of mouse)
IT
     Gene, animal
     RL: BOC (Biological occurrence); BSU (Biological study, unclassified);
     BIOL (Biological study); OCCU (Occurrence)
        (jlm, juvenile-fitness function assocd. with neuromuscular system;
        complementation analyses for 45 mutations encompassing pink-eyed diln.
        (p) locus of mouse)
IT
     Gene, animal
     RL: BOC (Biological occurrence); BSU (Biological study, unclassified);
     BIOL (Biological study); OCCU (Occurrence)
        (jls, juvenile-fitness function; complementation analyses for 45
        mutations encompassing pink-eyed diln. (p) locus of mouse)
     Gene, animal
IT
     RL: BOC (Biological occurrence); BSU (Biological study, unclassified);
     BIOL (Biological study); OCCU (Occurrence)
        (nl, assocd. with neonate survival and cleft plate; complementation
        analyses for 45 mutations encompassing pink-eyed diln. (p) locus of
        mouse)
ΙT
     Gene, animal
     RL: BOC (Biological occurrence); BSU (Biological study, unclassified);
     BIOL (Biological study); OCCU (Occurrence)
        (pl-1, assocd. with early-postimplantation survival; complementation
        analyses for 45 mutations encompassing pink-eyed diln. (p) locus of
        mouse)
IT
     Gene, animal
     RL: BOC (Biological occurrence); BSU (Biological study, unclassified);
     BIOL (Biological study); OCCU (Occurrence)
        (pl-2, assocd. with preimplantation survival; complementation analyses
        for 45 mutations encompassing pink-eyed diln. (p) locus of mouse)
IT
        (mouse 7, complementation analyses for 45 mutations encompassing
        pink-eyed diln. (p) locus of mouse)
     Gene, animal
     RL: BOC (Biological occurrence); BSU (Biological study, unclassified);
     BIOL (Biological study); OCCU (Occurrence)
        (p, pink-eyed diln.; complementation analyses for 45 mutations
        encompassing pink-eyed diln. (p) locus of mouse)
     ANSWER 39 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
     1995:988948 CAPLUS
AN
DN
     124:51115
     Entered STN: 19 Dec 1995
     Complex gangliosides affect GD3 accessibility to antibody in developing
     neuronal cells
     Allende, Maria L.; Panzetta, Pedro
ΑIJ
     Centro de Investigaciones en Quimica Biologica de Cordoba. CIQUIBIC,
CS
     UNC-CONICET, Departamento de Quimica Biologica, Facultad de Ciencias
     Quimicas, Universidad Nacional de Cordoba, Cordoba, 5016, Argent.
     Developmental Brain Research (1995), 90(1,2), 102-10
     CODEN: DBRRDB; ISSN: 0165-3806
     Elsevier
PB
DT
     Journal
LΑ
     English
CC
     12-3 (Nonmammalian Biochemistry)
     Ganglioside expression of embryonic chick retina cells developed in vitro
AB
     was analyzed by indirect immunofluorescence. Immature neurons were GD3
     pos. cells and the labeling was chiefly distributed all over their cell
     membrane. Mature neurons became GD3 neg. and expressed complex
     gangliosides of the a- and b-pathways; nevertheless, the content of GD3
     accounted for .apprx.40% of the total gangliosides in these cells.
     Neuraminidase hydrolysis pointed out that GD3 was located in membrane of
     differentiated cells. The frequency of cells with the GD3 immunostain
     localized in restricted areas of membrane of undifferentiated neurons
     increased significantly after adding a mixt. of bovine brain gangliosides
     (largely complex gangliosides). Antibody binding to immobilized GD3
     showed a dose-dependent inhibition by adding a mixt. of bovine brain
     gangliosides, GM1, GD1a or asialo-GM1. Glycosphingolipids with shorter
     oligosaccharide chains, as cerebrosides or sulfatides, did not affect this
     binding. Apparently, concomitant with the accretion of content of complex
                                             in the membrane would occur, which
     gangliosides, a
                       ***rearrangement***
```

\*\*\*masks\*\*\*

GD3 to its antibody. This

progressively

might affect putative ganglioside functions involved \*\*\*rearrangement\*\*\* in neuronal differentiation. ST ganglioside GD3 nerve development IT Cell membrane Development, nonmammalian Embryo Nerve (complex gangliosides affect ganglioside GD3 accessibility to antibody in developing neuronal cells) IT Gangliosides RL: BAC (Biological activity or effector, except adverse); BSU (Biological study, unclassified); BIOL (Biological study) (complex gangliosides affect ganglioside GD3 accessibility to antibody in developing neuronal cells) IT (retina, complex gangliosides affect ganglioside GD3 accessibility to antibody in developing neuronal cells) 62010-37-1, Ganglioside GD3 ITRL: BOC (Biological occurrence); BPR (Biological process); BSU (Biological study, unclassified); BIOL (Biological study); OCCU (Occurrence); PROC (Process) (complex gangliosides affect ganglioside GD3 accessibility to antibody in developing neuronal cells) 19553-76-5, Ganglioside GD1b IT12707-58-3, Ganglioside GD1a 37758-47-7, 54827-14-4, Ganglioside GM3 Ganglioside GM1 59247-13-1, Ganglioside GT1b RL: BOC (Biological occurrence); BSU (Biological study, unclassified); BIOL (Biological study); OCCU (Occurrence) (complex gangliosides affect ganglioside GD3 accessibility to antibody in developing neuronal cells) ANSWER 40 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN L19 ΑN 1995:131230 CAPLUS DN122:80951 Entered STN: 08 Nov 1994 ED Efficient Route to the Nine-Membered Cyclic Diyne System: Tuning of the TI \*\*\*Rearrangement\*\*\* Extremely Facile Cope of 1,5-Diyne Iida, Kyoichiro; Hirama, Masahiro ΑU CS Faculty of Science, Tohoku University, Sendai, 980-77, Japan Journal of the American Chemical Society (1994), 116(22), 10310-11 so CODEN: JACSAT; ISSN: 0002-7863 DTJournal LAEnglish CC 26-6 (Biomolecules and Their Synthetic Analogs) os CASREACT 122:80951 GI

## \* STRUCTURE DIAGRAM TOO LARGE FOR DISPLAY - AVAILABLE VIA OFFLINE PRINT \*

- Very recently, a chromophore of both the potent antitumor, antibiotic ABchromoprotein C-1027 and kedarcidin has been shown to possess a highly strained bicyclo[7.3.0] dodecadiyne core structure. A strategy which \*\*\*masks\*\*\* the 3-ene-1,5-diyne system I as a 1,5-diyne II (X =apo-protein) is a fascinating approach from the perspective of the design and synthesis of related DNA-cleaving mols. We developed a general and efficient route to the 9-membered cyclic diyne system through an intramol. acetylide addn. mediated by LiN(TMS)2/CeCl3 from a precursor, such as III (R = TBS), which possess a conformationally nonrigid C4-C5 single bond. Furthermore, we found that the cyclic 1,5-diyne system, such as in bicyclo[7.3.0]dodeca-2,6-diyn-11-ene IV (M = Ce3+, Li+), undergoes an \*\*\*rearrangement\*\*\* below room temp., while the extremely facile Cope isomeric bicyclo[7.3.0]dodeca-2,6-diyn-12-enes V and VI do not. Thus, the \*\*\*rearrangement\*\*\* of the 9-membered cyclic 1,5-diyne system can be suppressed by small structural changes, such as the shift of a double bond.
- ST Cope \*\*\*rearrangement\*\*\* cyclic diyne; antibiotic bicyclododecadiyne system synthesis; cyclononenediyne system synthesis
- IT Cope \*\*\*rearrangement\*\*\*
  Ring closure and formation

```
(synthesis of nine-membered cyclic diyne systems via intramol.
       acetylide addn. and suppression of 1,5-diyne Cope
                                                           ***rearrangement***
IT
    Ring closure and formation
        (stereoselective, synthesis of nine-membered cyclic diyne systems via
        intramol. acetylide addn. and suppression of 1,5-diyne Cope
          ***rearrangement*** )
                                 161697-44-5
                  161697-43-4
                                               161897-37-6
IT
     161697-42-3
    RL: PRP (Properties)
        (mol. mechanics calcn.; synthesis of nine-membered cyclic diyne systems
       via intramol. acetylide addn. and suppression of 1,5-diyne Cope
          ***rearrangement*** )
     4039-32-1, Lithium hexamethyldisilazide
                                             7790-86-5, Cerium trichloride
ΙT
                   160246-40-2
     160246-39-9
    RL: RCT (Reactant); RACT (Reactant or reagent)
        (synthesis of nine-membered cyclic diyne systems via intramol.
        acetylide addn. and suppression of 1,5-diyne Cope
                                                           ***rearrangement***
                                                  160246-45-7P
ΙT
     160246-41-3P
                   160246-42-4P
                                   160246-43-5P
                                                                 160246-46-8P
     160246-47-9P
                   160335-09-1P
                                   160335-10-4P
                                                  160335-11-5P
                                                                 160335-12-6P
     161697-36-5P
                   161697-37-6P
                                   161697-38-7P
                                                  161697-39-8P
                                                                 161697-40-1P
                                   161755-44-8P
                                                  161755-45-9P
                                                                 161755-46-0P
     161697-41-2P
                   161755-43-7P
     161755-47-1P
    RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (synthesis of nine-membered cyclic diyne systems via intramol.
        acetylide addn. and suppression of 1,5-diyne Cope
                                                            ***rearrangement***
     160246-44-6P
                    160246-48-0P
                                   160335-13-7P
                                                  160335-14-8P
    RL: SPN (Synthetic preparation); PREP (Preparation)
        (synthesis of nine-membered cyclic diyne systems via intramol.
        acetylide addn. and suppression of 1,5-diyne Cope. ***rearrangement***
L19
    ANSWER 41 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
     1993:448809 CAPLUS
AΝ
DN
     119:48809
     Entered STN: 07 Aug 1993
ED
    Migratory tendencies for 1,5-sigmatropic shifts in the 1,3-dimethylindene
TΙ
     Jones, David W.; Marmon, Robert J.
ΑU
     Sch. Chem., Univ. Leeds, Leeds, LS2 9JT, UK
CS
     Journal of the Chemical Society, Perkin Transactions 1: Organic and
SO
     Bio-Organic Chemistry (1972-1999) (1993), (6), 681-90
     CODEN: JCPRB4; ISSN: 0300-922X
     Journal
DT
LA
     English
CC
     22-6 (Physical Organic Chemistry)
     The tendency for several groups X to undergo a 1,5-sigmatropic shift in
AΒ
     which 1-X-1,3-dimethylindene is converted into a 2H-indene intermediate
    has been tested. Several of the groups studied are based on the
     carbon-nitrogen double bond [HC:NBut, HC:NPh, HC:NNMe2, 2-pyridyl, and
     1-methylpyridin-2-io]; some were expected to be fast migrators [HC:CHNO2,
     COCOPh, COSPh, C(S)NMe2] and others (1- and 2-naphthyl, 2-furyl,
     2-thienyl, and 1-propylpyrrol-2-yl) showed a variation in arom. character.
    The conjugative electron-withdrawing ability of a group and the
     availability of a low-energy vacant orbital are linked to good migratory
     ability but steric, conformational, and secondary orbital interaction
                  ***mask***
                               the effect, e.g. the 1- and 2-naphthyl groups
    migrate slowly despite very low .pi.* energies. All the arom. groups
    migrate slowly and at similar rates. The results provide further evidence
     against biradical intermediates or transition states in these
       ***rearrangements***
st
     sigmatropic shift dimethylindene; indene dimethyl sigmatropic
       ***rearrangement***
IT
     Functional groups
        (migratory tendencies of, for sigmatropic shifts in dimethylindene
        derivs.)
IT
                   ***rearrangement***
    Kinetics of
        (sigmatropic, of dimethylindenes)
IT
       ***Rearrangement***
        (sigmatropic, of dimethylindenes)
```

```
18742-02-4, 2-(2-Bromoethyl)-1,3-dioxolane
                                                   24157-02-6,
IT
     1-Bromo-4, 4-dimethoxybutane
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (Grignard reaction of, with dimethylindenecarboxaldehyde)
IT
     17668-60-9
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (Wittig reaction of, with dimethylindenecarboxaldehyde)
                                  580-13-2, 2-Bromonaphthalene
     90-11-9, 1-Bromonaphthalene
IT
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (arylation by, of lithiated dimethylindene)
IT
     6072-57-7
     RL: PROC (Process)
        (conversion of, to methylindenone)
IT
     148648-69-5P 148648-85-5P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
                                ***rearrangement***
        (prepn. and attempted
                                                       of)
     148648-80-0P
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (prepn. and conversion of, to (benzoylcarbonyl)dimethylindene)
IT
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (prepn. and conversion of, to dicarbonyl deriv.)
     148648-95-7P
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (prepn. and conversion of, to dimethylnaphthylindene)
     148648-93-5P
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (prepn. and conversion of, to dimethylpyridylindene)
TΤ
     148649-01-8P
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (prepn. and conversion of, to dimethylthienylindene)
IT
     148649-00-7P
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (prepn. and conversion of, to furyldimethylindene)
                    148648-97-9P
IT
     148648-92-4P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (prepn. and oxidn. of)
IT
     148648-91-3P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (prepn. and oximation of)
     148648-99-1P
TT
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (prepn. and reaction of, with propylamine)
IT
     22303-81-7P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (prepn. and reactions of)
                   148648-83-3P
                                   148648-87-7P
     71635-78-4P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
                      ***rearrangement***
                                             of)
         (prepn. and
                                                   148648-79-7P
                                                                   148690-93-1P
     148648-76-4P
                    148648-77-5P
                                    148648-78-6P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
                                                         of, kinetics and
                                   ***rearrangement***
         (prepn. and sigmatropic
        mechanism)
                                                                   148648-71-9P
                                                   148648-68-4P
     148648-65-1P
                    148648-66-2P
                                    148648-67-3P
                                    148648-74-2P
     148648-72-0P
                    148648-73-1P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
                                   ***rearrangement***
                                                         of, kinetics and
         (prepn. and sigmatropic
        mechanism of)
                                                   148648-88-8P
                                                                   148648-89-9P
                                    148648-86-6P
IT
     148648-82-2P
                    148648-84-4P
                                                   148649-02-9P
                                                                   149411-80-3P
     148648-90-2P
                    148648-94-6P
                                    148648-96-8P
     RL: SPN (Synthetic preparation); PREP (Preparation)
         (prepn. of)
     108-98-5, Thiophenol, reactions
     RL: RCT (Reactant); RACT (Reactant or reagent)
```

```
(reaction of, with dimethylindenecarboxylic acid)
IT
     148648-81-1
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (reaction of, with lithiated phenyldithiane)
IT
    -69382-87-2
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (reactions of)
     2177-48-2, 1,3-Dimethylindene
IT
     RL: PRP (Properties)
        (sequential lithiation and arylation of)
     5425-44-5, 2-Phenyl-1,3-dithiane
TT
     RL: PRP (Properties)
        (sequential lithiation and reaction of, with
        (chloroformyl) dimethylindene)
IT
     110-00-9, Furan
                       110-02-1, Thiophene
     RL: PRP (Properties)
        (sequential lithiation and reaction of, with methylindenone)
IT
     57707-36-5
                  69009-36-5
                               69009-38-7 69009-52-5
                                                         74526-94-6
     74526-99-1
                  148648-70-8
                                148648-75-3
     RL: RCT (Reactant); RACT (Reactant or reagent)
                       ***rearrangement***
                                             of, kinetics and mechanism of)
        (sigmatropic
     ANSWER 42 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
AN
     1993:115018 CAPLUS
     118:115018
DN
     Entered STN: 19 Mar 1993
ED
     Structural relaxation and magnetic properties of cobalt-rich amorphous
TI
ΑU
     Gomez-Polo, C.; Vazquez, M.
     Inst. Cienc. de Mater. (CSIC), Serrano 144, Madrid, 28006, Spain
CS
     Journal of Magnetism and Magnetic Materials (1993), 118(1-2), 86-92
SO
     CODEN: JMMMDC; ISSN: 0304-8853
DT
     Journal
LA
     English
CC
     77-1 (Magnetic Phenomena)
     Section cross-reference(s): 56
     Thermal treatment in the presence of either a magnetic field or a magnetic
AΒ
     field and applied tensile stress were carried out in a Co-rich nearly
     nonmagnetostrictive amorphous wire. Structural relaxation is followed by
     an evaluation of the induced magnetic anisotropy and changes in the satn.
     magnetostriction after treatment. The orientation of the easy axis of
     induced anisotropy depends on the annealing conditions. The
     magnetostriction is modified as structural relaxation proceeds, irresp. of
     the orientation of the induced preferred axes. This suggests that
     although the origin of the induced anisotropy (i.e. field-induced
     anisotropy) can be ascribed to the generation of atom pairs, the changes
     in magnetostriction are related to topol.-like at.
                                                          ***rearrangements***
        Both mechanisms develop simultaneously so that overlapping effects can
                 ***mask***
                              the origin of the changes in these quantities.
     Also, as in the case of Co-rich amorphous ribbons, the stress dependence
     of magnetostriction follows the law .lambda. = .lambda.0-.alpha..sigma.,
     for as-cast and annealed wires.
     cobalt alloy amorphous wire magnetism; magnetostriction cobalt alloy
     amorphous wire; structure relaxation cobalt alloy amorphous wire;
     anisotropy magnetic cobalt alloy amorphous wire
IT
        (cobalt-base alloy amorphous, magnetic properties and structural
        relaxation of)
IT
     Magnetic anisotropy
     Magnetostriction
        (of cobalt-rich alloy amorphous wire)
IT
     Metallic glasses
     RL: PRP (Properties)
        (cobalt alloy, magnetic properties and structural relaxation of wire
        of)
IT
     106706-38-1
     RL: PRP (Properties)
        (magnetic properties and structural relaxation of amorphous wire of)
L19
    ANSWER 43 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     1992:601920 CAPLUS
DN
     117:201920
```

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ED
    Entered STN: 15 Nov 1992
    Water-soluble photosensitive compounds, photoresistant compositions
TI
    containing them, and patterning of such photoresists
    Hayashi, Nobuaki; Ito, Masahito; Morishita, Hajime; Nonogaki, Saburo;
IN
    Odaka, Yoshiyuki; Miura, Seiji; Nishizawa, Shoko
PA
    Hitachi, Ltd., Japan
    Jpn. Kokai Tokkyo Koho, 10 pp.
so
    CODEN: JKXXAF
DT
    Patent
LA
    Japanese
IC
     ICM G03F007-038
     ICS G03F007-008; H01J009-227; H01L021-027
     74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other
CC
    Reprographic Processes)
FAN.CNT 1
                        KIND
                               DATE
                                         APPLICATION NO.
    PATENT NO.
                                                                 DATE
     _____
                        ----
                               _____
                                          -----
                                                                 _____
    JP 04026849
                         A2
                               19920130
                                           JP 1990-131283
                                                                 19900523
                               19900523
PRAI JP 1990-131283
CLASS
PATENT NO.
                CLASS PATENT FAMILY CLASSIFICATION CODES
 _____
                ----
                       ______
JP 04026849
                ICM
                       G03F007-038
                       G03F007-008; H01J009-227; H01L021-027
                ICS
                IPCI
                       G03F0007-038 [ICM,5]; G03F0007-008 [ICS,5];
                       H01J0009-227 [ICS,5]; H01L0021-027 [ICS,5]
GΙ
/ Structure 6 in file .gra /
AB
    The title water-sol. photosensitive compds. (I) and (II) [Z = H, OH; M =
    Na, K, NH4] are obtained by condensing an acetophenone
     structure-possessing polymer with an arom. aldehyde possessing an azide
     group and an aliph. aldehyde (e.g. MeCHO, crotonaldehyde). The title
    photoresist compn. comprises the above water-sol. photosensitive compd.
     and a water-sol. polymer which reacts with the former to show reciprocity
     low failure. The title photoresist compn. coated on a substrate is
    patternwise exposed in the presence of O, and developed to produce a
    pattern in which the exposed areas produce a pattern smaller in area than
     the area of the openings in the ***photomask***
ST
    photoresist compn high sensitivity; black matrix CRT manuf; acetophenone
    polymer condensation product
IT
     Cathode-ray tubes
        (color, black matrix, manuf. of, photoresist compn. for)
IT
     Resists
        (photo-, contq. acetophenone polymer aldehyde condensation product)
IT
     24979-70-2D, p-Hydroxystyrene homopolymer, acetylated,
                                                            ***Fries***
       ***rearranged*** , condensation product with 4-azidobenzaldehyde-12-
     sulfonic acid salt and acetaldehyde 25231-54-3, Acrylamide-diacetone
     acrylamide copolymer 25300-64-5D, Maleic acid-styrene copolymer,
     acetylation product, condensation product with sodium potassium or
     ammonium 4-azidobenzaldehyde-2-sulfonate and acetaldehyde or croton
               55305-94-7D, 4-Azidobenzaldehyde-2-sulfonic acid sodium salt,
     condensation product with acetylated styrene polymer
     RL: TEM (Technical or engineered material use); USES (Uses)
        (photoresist compn. contg.)
L19
    ANSWER 44 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     1991:593992 CAPLUS
DN
     115:193992
ED
    Entered STN: 01 Nov 1991
ΤI
    New photoresists based on poly(trans-1,2-cyclohexylene diisocyanate)
ΑU
     Zentel, Rudolf; Willson, C. Grant
CS
    Almaden Res. Cent., IBM, San Jose, CA, 95120-6099, USA
    Makromolekulare Chemie, Rapid Communications (1991), 12(8), 513-16
SO
    CODEN: MCRCD4; ISSN: 0173-2803
DT
    Journal
```

LA

English

```
74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other
     Reprographic Processes)
    trans-1,2-Cyclohexylene diisocyanate, prepd. from the corresponding
AB
     racemic acid by a Curtius
                               ***rearrangement*** was transformed into
    poly(trans-1,2-cyclohexylene diisocyanate) (I) by anionic polymn. with
    NaCN. Polymer I is amorphous, forms transparent films from soln., and
     shows no glass transition temp. or other transitions up to its decompn.
     temp. of about 300.degree.. At this temp. it decomps. completely to
    volatile compds., as detd. by thermogravimetry. I was mixed with a
     triarylsulfonium salt as photoacid generator, dissolved in a mixt. of
     toluene and cyclohexanone, spin casted onto silica wafer and illuminated
     at 255 nm with a dose of 10 mJ/cm2 through a ***mask***
                                                               . The acid
     created thereby strongly reduced the thermal stability of the polymer and
     enabled the development of the pattern by baking the polymer at
     274.degree. for several minutes. At this temp. the illuminated parts of
     the sample decompd. and evapd. much more quickly than the non-illuminated
     parts, thereby creating a pos. image. Doses as low as 5 mJ/cm2 were
     enough for pattern formation with a width of 2 .mu.m.
ST
    photoresist polycyclohexylene isocyanate
IT
     Resists
        (photo-, poly(cyclohexylene diisocyanate), with triarylsulfonium salt
        as photoacid generator)
IT
     143-33-9, Sodium cyanide
     RL: USES (Uses)
        (in anionic polymn. of cyclohexylene diisocyanate)
     136474-39-0P, trans-1,2-Cyclohexylene diisocyanate
IT
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (prepn. and anionic polymn. of)
     36909-95-2P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (prepn. and reaction of, with trimethylsilyl azide)
     136474-40-3P, Poly(trans-1,2-cyclohexylene diisocyanate)
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (prepn. and testing of, as photoresist)
     4648-54-8, Trimethylsilyl azide
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (reaction of, with cyclohexylene diisocyanate)
     ANSWER 45 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
     1990:523643 CAPLUS
AN
     113:123643
DN
     Entered STN: 29 Sep 1990
ED
     Lithography and spectroscopy of ultrathin Langmuir-Blodgett polymer films
TI
     Kuan, S. W.; Martin, P. S.; Kosbar, L. L.; Frank, C. W.; Pease, R. F.
ΑU
CS
     Dep. Chem. Eng., Stanford Univ., Stanford, CA, USA
     Report (1989), Order No. AD-A208970, 23 pp. Avail.: NTIS
SO
     From: Gov. Rep. Announce. Index (U. S.) 1989, 89(20), Abstr. No. 953,208
DT
     Report
LΑ
     English
     74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other
     Reprographic Processes)
     Section cross-reference(s): 37
AB
     Ultrathin (0.9-15.3 nm) PMMA and (30-40 nm) novolak/diazoquinone films
     prepd. by the Langmuir-Blodgett technique have been explored as
     high-resoln. electron beam resists and photoresists, resp. One-eight
     micron lines-and spaces patterns have been achieved in PMMA using the
     Perkin Elmer MEBES I pattern generation system as the exposure tool. The
     etch resistance of PMMA films with thicknesses >4.5 nm is sufficient to
     allow patterning of Cr film suitable for
                                                ***photomask***
                                                                  fabrication.
     One micron lines- and-spaces patterns have been fabricated by optical
     lighog. in 30 nm thick novolak/diazoquinone films, and etched into 50 nm
     of Cr. Monolayer PMMA films contq. 5 mol% pyrenedodecanoic acid (PDA) as
     a probe were prepd. by transfer to a quartz substrate at different surface
     pressures and characterized by fluorescence spectroscopy. The ratio of
     excimer to monomer emission intensity has a max. value at 10 dyn/cm, which
                                     ***rearrangement***
                                                           occurring in the
     is suggestive of a structural
     Langmuir film at the surface.
```

submicron lithog Langmuir Blodgett film; photoresist Langmuir Blodgett

film; electron resist Langmuir Blodgett film; PMMA Langmuir Blodgett

lithog; novolak diazoquinone Langmuir Blodgett lithog

ST

```
IT
     Films
        (Langmuir-Blodgett, for submicron lithog.)
IT
    Resists
        (electron-beam, Langmuir-Blodgett polymer films for)
TT
     Phenolic resins, uses and miscellaneous
     RL: USES (Uses)
        (novolak, Langmuir Blodgett film contg., for submicron lithog.)
IT
    Resists
        (photo-, polymeric, Langmuir-Blodgett films of, for submicron lithog.)
IT
     Lithography
        (submicron, Langmuir-Blodgett polymer films for)
                      53208-22-3
IT
     9011-14-7, PMMA
     RL: USES (Uses)
        (Langmuir Blodgett film contg., for submicron lithog.)
    ANSWER 46 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
AN
     1990:45468 CAPLUS
DN
     112:45468
ED
     Entered STN: 04 Feb 1990
     Lithography and spectroscopy of ultrathin Langmuir-Blodgett polymer films
TI
ΑU
     Kuan, S. W. J.; Martin, P. S.; Kosbar, L. L.; Frank, C. W.; Pease, R. F.
     W.
CS
     Dep. Chem. Eng., Stanford Univ., Stanford, CA, 94305, USA
     ACS Symposium Series (1989), 412 (Polym. Microlithogr.), 349-63
SO
     CODEN: ACSMC8; ISSN: 0097-6156
DT
     Journal
     English
LΑ
     74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other
CC
     Reprographic Processes)
     Section cross-reference(s): 36
     Ultrathin (0.9 - 15:3 nm) PMMA and (30 - 40 nm) novolak/diazoquinone films
AB
    prepd. by the Langmuir-Blodgett (LB) technique were studied as
     high-resoln. electron beam resists and photoresists, resp. One-eighth
     micron line-and-space patterns were achieved in PMMA using a Perkin Elmer
     MEBES I pattern generation system as the exposure tool. The etch
     resistance of PMMA films with thicknesses >4.5 nm was sufficient to allow
     patterning of Cr film suitable for
                                          ***photomask***
                                                            fabrication. One
     micron line-and-space patterns were fabricated by optical lithog. in 30 nm
     thick novolak/diazoguinone films and etched into 50 nm of Cr. Monolayer
     PMMA films contq. 5 mol% pyrenedodecanoic acid (PDA) as a probewere prepd.
     by transfer to a quartz substrate at different surface pressures and
     characterized by fluorescence spectroscopy. The ratio of excimer to
     monomer emission intensity has a max. value at .apprx.10 dyn/cm, which is
     suggestive of a structural
                                  ***rearrangement***
                                                       occurring in the
     Langmuir film at that surface pressure.
     lithog spectroscopy Langmuir Blodgett polymer film; microlithog Langmuir
     Blodgett polymer film
IT
     Fluorescence
        (of ultrathin Langmuir-Blodgett polymer films)
IT
     Resists
        (electron-beam, polymeric, ultrathin Langmuir-Blodgett films as)
ΙT
     Resists
        (photo-, polymeric, ultrathin Langmuir-Blodgett films as)
IT
     Lithography
        (submicron, of ultrathin Langmuir-Blodgett polymer films)
IT
     9011-14-7, PMMA
     RL: USES (Uses)
        (electron-beam resists from ultrathin Langmuir-Blodgett film of, for
        microlithog.)
IT
     25086-36-6, M-Cresol-formaldehyde polymer
                                                 124448-76-6, Fairmount 1010
     RL: USES (Uses)
        (microlithog. photoresist ultrathin Langmuir-Blodgett film contg.)
L19
    ANSWER 47 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
AN
     1989:644034 CAPLUS
DN
    111:244034
ΕD
    Entered STN: 23 Dec 1989
ΤI
     Polymer chain configurations in constrained geometries: ultrathin polymer
     films for microlithography
ΑU
    Kuan, S. W. J.; Martin, P. S.; Frank, C. W.; Pease, R. F. W.
CS
    Dep. Chem. Eng., Stanford Univ., Stanford, CA, 94305, USA
SO
    Proceedings of SPIE-The International Society for Optical Engineering
```

```
CODEN: PSISDG; ISSN: 0277-786X
DT
     English
LA
     74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other
CC
     Reprographic Processes)
     Section cross-reference(s): 35
     Ultrathin (0.9-15.3 nm) PMMA films prepd. by the Langmuir-Blodgett (LB)
AB
     technique were explored as high-resoln. electron-beam resists. One-eighth
     micron lines-and-spaces patterns were achieved by using a Perkin Elmer
     MEBES I pattern generation system as the exposure tool. The etch
     resistance of films with thicknesses >4.5 nm is sufficient to allow
     patterning of Cr film suitable for
                                         ***photomask***
                                                            fabrication.
     Monolayer PMMA films contg. 5 mol% pyrenedodecanoic acid as a probe were
     prepd. by transfer to the substrate at different surface pressures and
     characterized by fluorescence spectroscopy. The ratio of excimer to
     monomer emission intensity has a max. value at .apprx.10 dyn/cm, which may
                                 ***rearrangement*** in the film. Intrinsic
     be related to a structural
     bilayer LB PMMA films prepd. at 1 and 19 dyn/cm were also examd. by
     transmission electron microscopy. The wrinkle-like surface topog. obsd.
     in the 19 dyn/cm sample and not in the 1 dyn/cm sample suggests that the
     structure of the LB PMMA film depends on the transfer pressure.
     microlithog ultrathin polymer chain configuration; electron resist
ST
     ultrathin polymer chain configuration; PMMA resist ultrathin polymer chain
     configuration
       ***Photomasks***
IT
        (prodn. of, polymer chain configurations in constrained geometries of
        ultrathin polymer films for microlithog. in relation to)
TT
     Resists
        (electron-beam, polymer chain configurations in constrained geometries
        of ultrathin films of PMMA, for microlithog.)
     9011-14-7, PMMA
IT
     RL: USES (Uses)
        (chain configurations in constrained geometries of ultrathin film of,
        for microlithog.)
     ANSWER 48 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
     1987:487379 CAPLUS
AN
     107:87379
DN
     Entered STN: 05 Sep 1987
ED
     Laser light assisted deposition of thin films
ΤI
ΑU
     Yokoyama, Hiroyuki
     Opto-Electron. Res. Lab., NEC Corp., Kanagawa, 213, Japan
CS
     Reza Kenkyu (1987), 15(2), 83-97
SO
     CODEN: REKEDA; ISSN: 0387-0200
DT
     Journal; General Review
LA
     Japanese
     75-0 (Crystallography and Liquid Crystals)
CC
     Section cross-reference(s): 73, 76
     A review with 38 refs. Photoassisted chem. vapor deposition of metal
AB
     films, and photoassisted epitaxy of semiconductor films are described with
     an emphasis on several important problems. Successful applications of
     laser induced metal deposition for repairing photolithog.
                                                                  ***masks***
     pinhole defects and for circuit restructuring of semiconductor devices are
     demonstrated. Intrinsic problems are pointed out regarding micropattern
     formation by projection printing deposition using large cross-sectional
     laser light. A new approach that would enable the photolithographyless
     film patterning in large area is shown. Several studies on photoassisted
     epitaxy of semiconductors are discussed from the view point of epitaxy
     temp. lowering. After extg. the expected photoinduced effects, an expt.
     of photoassisted ZnS film deposition is described to clarify the surface
             ***rearrangement***
                                    effect which is essentially important for
     lowering the epitaxial growth temp.
     review laser deposition metal film; epitaxy semiconductor laser assisted
     review
     Laser radiation, chemical and physical effects
IT
        (epitaxy and chem. vapor deposition of metals assisted by)
IT
     Epitaxy
        (of semiconductors, laser-assisted)
IT
     Metals, properties
     RL: PRP (Properties)
        (photoassisted chem. vapor deposition of)
```

(1989), 1086 (Adv. Resist Technol. Process. 6), 251-61

```
IT
     Semiconductor materials
        (photoassisted epitaxy of)
IT
     1314-98-3, Zinc sulfide, properties
     RL: PRP (Properties)
        (photoassisted epitaxial deposition of)
     ANSWER 49 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
     1984:631349 CAPLUS
AN
     101:231349
DN
     Entered STN: 22 Dec 1984
ED
     Study of the morphology and electrical properties of new and thermally
ΤI
     aged biaxially oriented polypropylene films
     Couderc, D.; Crine, J. P.; Umemura, T.
ΑU
     Inst. Rech. Hydro-Quebec, Varennes, QC, Can.
CS
     IEE Conference Publication (1984), 239 (Dielectr. Mater., Meas. Appl.),
SO
     128-31
     CODEN: IECPB4; ISSN: 0018-9405
     Journal
DT
     English
LA
     37-5 (Plastics Manufacture and Processing)
CC
     Biaxially oriented blown polypropylene [9003-07-0] film showed larger
AB
     variation in elec. and phys. properties under thermal aging than did the
     tenter type film. Thermal aging induced morphol. and structural changes
                            ***rearrangement***
                                                   of the amorphous phase and
     such as recrystn. and
     reorganization of the cryst. phase. The conduction is more likely
     governed by an ionic mechanism than by dipolar relaxation processes.
     .beta., relaxation seems to have the same origin regardless of exptl.
                                       ***mask***
                                                   the effect of morphol.
     conditions, which may partially
     variations on the dielec. properties.
ST
     polypropylene morphol aging elec property
     Polymer morphology
IT
        (of polypropylene elec. insulation, elec. properties in relation to)
     Electric insulators and Dielectrics
TT
        (polypropylene, elec. properties of, morphol. and aging effect on)
ŦΤ
     9003-07-0
     RL: USES (Uses)
        (elec. insulators, elec. properties of, morphol. and aging effect on)
     ANSWER 50 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
     1982:447069 CAPLUS
AN
     97:47069
DN
     Entered STN: 12 May 1984
ED
     Poly(N-alkyl-o-nitroamides). A new class of thermally stable,
TI
     photosensitive polymers
     MacDonald, S. A.; Willson, C. G.
AU
     Res. Lab., IBM, San Jose, CA, 95193, USA
CS
     ACS Symposium Series (1982), 184 (Polym. Mater. Electron. Appl.), 73-81
SO
     CODEN: ACSMC8; ISSN: 0097-6156
DT
     Journal
     English
LA
     74-5 (Radiation Chemistry, Photochemistry, and Photographic and Other
     Reprographic Processes)
     Section cross-reference(s): 37
     Poly(N-alkyl-o-nitroamides), a new class of photosensitive, thermally
AB
     stable polymers contg. photolabile arom. amide linkages were prepd. These
     polymers contain a photosensitive anilide in the backbone of the polymer
     and when exposed to UV light, they degrade in a manner that is analogous
     to the ortho-nitroanilides described by Patchornik (1973). This resist
     system can be utilized in lithog. because the photoinduced
                            not only reduces the mol. wt. of the polymer but
       ***rearrangement***
     also converts a hydrophobic disubstituted amide into a carboxylic acid.
     Thus, after exposure to light, the irradiated areas can be dissolved in a
     basic developer soln., leaving the unexposed regions intact. This chem.
     can be exploited to provide lithog. relief images for printing, etch
       ***masks***
                     for microcircuit fabrication, and as contrast media for
     optical information storage.
     polyalkylnitroamide photosensitive polymer resist; photoresist
     polyalkylnitroamide; etch ***mask***
                                             polyalkylnitroamide; optical
     information storage polyalkylnitroamide; polyamide photosensitive polymer
     resist
IT
     Lithographic plates
        (photosensitive compns. contg. thermally stable poly(alkyl nitroamides)
```

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for)
IT
       ***Photomasks***
        (thermally stable poly(alkyl nitroamides) in fabrication of)
IT
     Electric circuits
        (micro-, thermally stable poly(alkyl nitroamides) in fabrication of)
IT
     Resists
        (photo-, poly(alkyl nitroamides) as thermally stable)
IT
     Information science
        (storage and retrieval, thermally stable photosensitive poly(alkyl
        nitroamides) in)
     Polyamides, uses and miscellaneous
IT
     RL: USES (Uses)
        (N-alkyl, nitro, thermally stable photoresists from)
     101-80-4
IT
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (acetylation of)
IT
     81897-02-1
                  81897-19-0
                               81897-20-3
     RL: USES (Uses)
        (photosensitive compns. contg., thermally stable)
     99-63-8
IT
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (polymn. of, with dinitrodimethylamino di-Ph ether)
     41263-74-5P
IT
     RL: RCT (Reactant); PREP (Preparation); RACT (Reactant or reagent)
        (prepn. and chlorination of)
     82357-49-1P
IT
     RL: RCT (Reactant); PREP (Preparation); RACT (Reactant or reagent)
        (prepn. and deacetylation of)
IT
     3070-86-8P
     RL: RCT (Reactant); SPN (Synthetic preparation); PREP (Preparation); RACT
     (Reactant or reagent)
        (prepn. and nitration of)
IT
     82357-48-0P
     RL: RCT (Reactant); PREP (Preparation); RACT (Reactant or reagent)
        (prepn. and polymn. of)
IT
     81871-61-6P
     RL: RCT (Reactant); PREP (Preparation); RACT (Reactant or reagent)
        (prepn. and polymn. of, with isophthaloyl chloride)
IT
     3070-87-9P
     RL: SPN (Synthetic preparation); PREP (Preparation)
        (prepn. and redn. methylation of)
IT
     6319-40-0
     RL: RCT (Reactant); RACT (Reactant or reagent)
        (reaction of, with methylamide)
    ANSWER 51 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
     1981:578713 CAPLUS
AN
DN
     95:178713
     Entered STN: 12 May 1984
ED
     Photopolymerizable composition containing an O-nitroaromatic compound as
TI
     photoinhibitor
IN
    · Pazos, Jose F.
     du Pont de Nemours, E. I., and Co., USA
PA
     Can., 61 pp.
so
     CODEN: CAXXA4
DT
     Patent
LA
     English
     G03C001-70; G03C005-24
IC
CC
     74-8 (Radiation Chemistry, Photochemistry, and Photographic Processes)
FAN.CNT 3
     PATENT NO.
                        KIND
                               DATE
                                           APPLICATION NO.
                                                                    DATE
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                                _____
                                             -----
                                                                    -----
PΙ
     CA 1103084
                         A1
                                19810616
                                            CA 1977-273994
                                                              19770315
                                                                19770316
19770316
                                19770916 BE 1977-175825
19790620 GB 1977-11110
     BE 852517
                         A1
                       A 19790620
A2 19770920
B4 19830223
A 19770920
B 19880701
C 19881201
     GB 1547548
     JP 52111985
                                            JP 1977-28752
                                                                    19770317
     JP 58009936
                                                                    19770317
     NL 7702887
                                            NL 1977-2887
     NL 183583
     NL 183583
     US 4198242
                         Α
                               19780608
                                             US 1978-913906
                                                                    19780608
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US 4269933

Α

19810526

US 1979-80082

19790928

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19830810
                         B2
     GB 2068006
                                19810601
                                            JP 1980-131747
                                                                   19800924
                         A2
     JP 56064338
                         Α
                                19760317
PRAI US 1976-667536
    US 1977-758699
                         Α
                                19770117
     US 1978-913906
                                19780608
                         A3
CLASS
                CLASS PATENT FAMILY CLASSIFICATION CODES
 PATENT NO.
 _____
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                        G03C001-70; G03C005-24
 CA 1103084
                IC
                        G03C0001-70; G03C0005-24
                 IPCI
BE 852517
                 IPCI
                        G03C
                        C08F0002-50; G03C0001-68
 GB 1547548
                 IPCI
                        C08F0002-48; C08F0002-38; C08F0020-06; G03C0001-68;
 JP 52111985
                 IPCI
                        G03C0005-24; G03F0007-08
                 IPCI
                        C08F0220-20; C08F0002-50; C09D0007-12; C09D0003-727;
NL 7702887
                        G03C0001-68
                 IPCI
                        G03C0002-68
 US 4198242
                        430/286.100; 430/301.000; 430/910.000; 430/917.000;
                 NCL
                        522/026.000; 522/028.000; 522/063.000; 522/065.000;
                        522/079.000; 522/109.000; 522/121.000
 US 4269933
                 IPCI
                        G03C0005-00
                        C08F0002-46 [I,C]; C08F0002-50 [I,A]; C09D0004-06
                 IPCR
                        [I,A]; C09D0004-06 [I,C]; G03F0007-027 [I,A];
                        G03F0007-027 [I,C]; G03F0007-031 [I,A]; G03F0007-031
                        [I,C]
                        430/291.000; 430/281.100; 430/302.000; 430/306.000;
                 NCL
                        430/311.000; 430/312.000; 430/325.000; 430/328.000;
                        430/916.000; 430/917.000; 522/004.000; 522/014.000;
                        522/017.000; 522/018.000; 522/065.000; 522/121.000
 GB 2068006
                 IPCI
                        C08F0002-50; G03C0001-68
                        G03C0005-00; G03F0007-00; H01L0021-302; H05K0003-06
 JP 56064338
                 IPCI
/ Structure 7 in file .gra /
     A photopolymerizable compn. and process for the prodn. of pos. images are
AB
     described. In the process a photopolymerizable compn. contg. a normally
     nongaseous, ethylenically unsatd. compd. capable of addn. polymn. by
     free-radical initiated chain propagation, a nitroarom. compd. of formula I
     (R1-R4 = H, OH, halogen, NO2, CN, C1-18 alkyl, C1-18 alkoxy, aryl, PhCH2,
     halophenyl, polyether radical, dialkylamino, thioalkyl, thioaryl, or any 2
     of R1-R4 together form a benzene ring and .ltoreq.1 of R1-R4 is OH or NO2;
     R5 = H, C1-18 alkyl, halogen, Ph, C1-18 alkoxy; R6 = H, OH, C1-18 alkyl,
     Ph, C1-18 alkoxy; or R5R6 together as O, CH6, NPh, or similar devalent
     group), and an org., radiation-sensitive, free radical-generating system
     activatable by actinic radiation that does not significantly
       ***rearrange***
                        the nitroarom. compd. to an inhibitor of free radical
     polymn. is coated on a suitable support, imagewise exposed through a
     transparency to radiation, .gtoreq.20% of which has a wavelength of
                                      ***rearrange***
     .apprx.200 to .apprx.380 nm to
                                                        at least some of the
     nitroarom. compd. to a polymn.-inhibiting nitroso arom. compd., then
     exposed to radiation with a wavelength of >380 nm to produce a pos polymer
     image, and then developed by an appropriate means to give a pos. polymeric
     image. Thus, a typical photopolymerizable compn contained
     1,1,1-trimethylolpropane triacrylate (contg. hydroquinone and/or
     methylhydroquinone 200 ppm) 3.5 mL, o-nitrobenzyl alc 0.153, and
     phenanthrenequinone 0.021 g.
ST
     photopolymer nitro compd pos image; photoinhibitor nitro compd
     photoimaging
IT
     Graphic arts
         ***Photomasks***
        (pos.-working photopolymerizable compns. contg. nitro compd.
        photoinhibitor for)
IT
     Lithographic plates
     Semiconductor devices
        (pos.-working photopolymerizable compns. contg. nitro compd.
        photoinhibitor for fabrication of)
IT
     Nitro compounds
```

19810805

Α

GB 2068006

RL: USES (Uses)

GB 1980-2778

19800128

```
(arom., photoinhibitors, in photopolymerizable compns. for pos. image
       prodn.)
ΙT
    Electric circuits
        (integrated, pos.-working photopolymerizable compns. contg. nitro
       compd. photoinhibitor for fabrication of)
IT
    Resists
        (photo-, pos.-working, photopolymerizable compns. contg. nitro compd.
       photoinhibitors for)
IT
     Photoimaging compositions and processes
        (photopolymerizable, contg. nitroarom. compds. as photoinhibitors for
       pos. image prodn.)
IT
     Printing plates
        (relief, pos.-working photopolymerizable compns. contg. nitro compd.
       photoinhibitor for fabrication of)
     528-75-6 552-89-6 579-71-5
                                    612-25-9
                                               879-55-0
                                                          1016-58-6
IT
     6526-72-3 15862-94-9
                           17064-77-6 20357-25-9 21203-88-3
                                                                   21829-26-5
     39830-70-1 48140-35-8
                              63190-11-4 65907-71-3 65907-73-5
     65907-74-6
                71172-14-0
    RL: USES (Uses)
        (photoinhibitor, in photopolymerizable photoimaging compns. for pos.
       image prodn.)
IT
     84-11-7
             95-71-6
                      106-10-5
                                 109-16-0 111-21-7
                                                      117-81-7
    uses and miscellaneous 128-37-0, uses and miscellaneous
                                                               149-30-4
               603-48-5 1241-94-7 1680-21-3 1707-68-2 3524-68-3
     7440-44-0, uses and miscellaneous 9011-14-7 15625-89-5 24620-40-4
     25086-15-1 25135-39-1 25176-75-4 29777-36-4
                                                       34122-40-2
                39279-99-7
                              53802-03-2
                                          58206-31-8
     38394-52-4
     RL: USES (Uses)
        (photopolymerizable photoimaging compns. contg. nitro compd.
       photoinhibitor and, for pos. image prodn.)
    ANSWER 52 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
L19
     1968:466283 CAPLUS
AN
DN
     69:66283
ED
     Entered STN: 12 May 1984
     Preparation of hard butter for food coatings
TΙ
     Bell, Richard J.; Campbell, Robert L., Jr.; Gibson, Paul; Sims, Jay F.
IN
     Anderson, Clayton and Co.
PA
     U.S., 4 pp.
SO
     CODEN: USXXAM
DT
     Patent
     English
LA
INCL 099118000
     17 (Foods)
ĊC
FAN.CNT 1
                   KIND DATE
                                        APPLICATION NO.
     PATENT NO.
                                                               DATE
                       _ _ _ _
                               _____
                                           -----
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                        Α .
    US 3396037
                               19680806
                                         US 1964-388912
                                                                 19640811
PΤ
PRAI US 1964-388912
                        Α
                               19640811
CLASS
 PATENT NO.
               CLASS PATENT FAMILY CLASSIFICATION CODES
 US 3396037
                INCL
                       099118000
                       426/607.000; 426/313.000; 554/223.000; 554/224.000;
                NCL
                       554/227.000
AB
     Coatings for some baked and frozen foods contain a fat, called hard
     butter, cocoa, sugar, and lecithin. To be desirable they must set
     quickly, melt readily in the mouth, give no waxy feel or residue, not
       ***mask***
                  the taste of the food, or form a "grey" or "bloom" on the
     gloss. The method of prepn. of the hard butter markedly influences these
     coatings qualities. Samples of the butter were prepd. by
       ***rearranging*** palm kernel oil or blends of oil with 0.4% Na
     methylate (I) as catalyst at 190-250.degree.F. for (1) 120 min. at atm.
     pressure, at 200, 100, 50, 20, and 10 mm. pressure, and (2) for 10, 20,
     60, and 120 min. at 10 mm. pressure. In these prepns. I was deactivated
     by conventional methods. Ten coatings were made, each contg. a different
     sample of the hard butter, the other ingredients being const. The
     incipient setting time, i.e., dulling of sheen, and the final setting
     time, detd. by a scratch with plastic, of each coating were measured.
     show the acid deactivation of I, and the importance of maintaining the
       ***rearrangement*** temp. and low pressure during deactivation, a blend
```

of 90% refined palm kernel oil and 10% refined, bleached cottonseed oil

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with 0.4% I at 235.degree.F. and 10 mm. Hg (abs.)
           ***rearranged***
    pressure for 1 hr. After cooling to 180.degree.F. a stoichiometric amt.
    of 85% H3PO4 was added and the mixt. left quiet for 1 hr. at atm.
    pressure. Filtration was difficult and 736 ppm. of salt were found in the
    filtrate because the NaH2PO4 formed was hydrated and sol.
                                                                The same blend
                    ***rearranged*** for 2 hrs., the same amt. of H3PO4
    was similarly
    added at 235.degree.F. and 10 mm. pressure and left for 30 min. After
    cooling to 180.degree.F., filtration with 1% filter aid diatomaceous earth
    gave a complete sepn. of the salt because the NaH2PO4 formed was anhyd.
    and insol. The hard butter used will make the desired coatings if prepd.
              ***rearranging***
                                  a blend of edible oils contg. at least 50%
    oil of the lauric type, i.e., lauric acid being the chief fatty acid, and
    non-lauric type oil, or the Me esters of non-lauric type oils or acids;
     (2) using a small amt. of a low-temp. catalyst, preferably I at
    180-240.degree.F., and pressure <.apprx.20 mm. Hg, during 60-120 min.;
    then deactivating I at that temp. and pressure, with a stoichiometric amt.
    hard butter food coatings; food coatings hard butter; baked foods
    coatings; coatings baked food
    Bakery products
    Food
    Frozen desserts
        (coatings for, hard shortening manuf. for)
    Confectionery
        (coatings, hard shortening manuf. for)
    Coating materials
        (food, hard shortening manuf. for)
    Shortening
    RL: BIOL (Biological study)
        (manuf. of hard, for food coatings)
    Oils
    RL: BIOL (Biological study)
        (palm-kernel, transesterification of, for hard shortening manuf.)
    Esterification catalysts
        (trans-, sodium methoxide as, for hard shortening manuf.)
    Cottonseed oil
    RL: RCT (Reactant); RACT (Reactant or reagent)
        (transesterification of, for hard shortening manuf.)
    RL: BIOL (Biological study)
        (vegetable, transesterification of, for hard shortening manuf.)
    124-41-4
    RL: BIOL (Biological study)
        (as transesterification catalyst in hard shortening manuf.)
    112-61-8
    RL: BIOL (Biological study)
        (in shortening (hard) manuf. by transesterification)
    ANSWER 53 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN
    1950:4673 CAPLUS
     44:4673
OREF 44:907e-h
    Entered STN: 22 Apr 2001
    The dynamic elastic properties of some high polymers
    Hillier, K. W.; Kolsky, H.
    Proceedings of the Physical Society, London (1949), 62B, 111-21
     CODEN: PPSOAU; ISSN: 0370-1328
     Journal
    Unavailable
     2 (General and Physical Chemistry)
    An app. for the investigation of the transmission of sound along filaments
     at frequencies between 1000 and 6000 cycles per sec. is described, both
     for unstrained specimens and while they are being elongated at a const.
     rate of increase of strain. Measurements of the dynamic elasticity and
     damping factors of filaments of polythene, neoprene, and nylon were
     obtained, and the correlation of these results with the mol.
                             during stretching is discussed.
       ***rearrangements***
                                                               In the unstretched
     specimens the dynamic value of Young's modulus obtained from the
     measurements of the velocity of sound is several times as great as the
     limiting gradient of the stress-strain diagram. The values of the dynamic
     moduli for both polythene and nylon, as the filaments are stretched, first
     shows a slight decrease followed by a rapid rise. In the case of
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neoprene, however, the dynamic modulus increases steadily. The gradients of the stress-strain curves for polythene and nylon decrease continually with strain; this fact shows that the effects of plastic flow completely the changes in elastic behavior. For neoprene the gradient \*\*\*mask\*\*\* increases but at a much slower rate than the dynamic modulus. For polythene the damping increases with frequency. The damping coeff. of unstretched neoprene is very much higher than those obtained for polythene and nylon. Polymers (elastic properties (dynamic) of) Rayon and other artificial fibers (from ethylene polymers, sound transmission along) Elasticity (polymer dynamic) Nylon (sound transmission along) Neoprene (sound transmission along filaments of) (transmission of, along polymer filaments) 9002-88-4, Ethylene, homopolymer (sound transmission along filaments of) ANSWER 54 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN 1947:11083 CAPLUS 41:11083 OREF 41:2267f-i,2268c-g Entered STN: 22 Apr 2001 The thermoelastic properties of rubber Meyer, Kurt H.; van der Wyk, A. J. A. Univ. Geneva, Switz. Helvetica Chimica Acta (1946), 29, 1842-53 CODEN: HCACAV; ISSN: 0018-019X Journal French 30 (Rubber and Other Elastomers) To explain, on a mol. basis, the deviation from ideal behavior of rubber when stressed (cf. M., von Susich, and Valk.acte.o, C.A. 26, 5245; M. and Ferri, C.A. 29, 4622.8, 6465.8) the authors derive thermodynamic equations for isothermal deformations. Although changes in vol. during stretching have heretofore been disregarded, part of the work of stretching is expended in changing the vol. against the external pressure; in fact a very small isothermal change in vol. involves a considerable change in entropy and internal energy. This change in entropy is caused not only by the change in vol. but also by mol. \*\*\*rearrangement\*\*\* is stretched slightly, the first influence predominates, and the entropy increases; at elongations around 10%, the 2 influences compensate each other, so there is no change in entropy; at higher elongations mol. \*\*\*rearrangement\*\*\* is the dominant factor, and the entropy decreases. Unilateral compression likewise brings about a change in vol., in this case a decrease, with resultant decrease in entropy. Here too the smaller the deformation, the more the vol. effect \*\*\*masks\*\*\* the effect of \*\*\*rearrangement\*\*\* . When deformation involves simultaneous elongation and compression whereby the increase in vol. caused by stretching compensates for the decrease in vol. caused by compression, the vol. remains const. This is true of rotatory shearing. Increases in vol. at low elongations take place along the mol. plane and involve displacement of groups of atoms, e.g., segments of chains, from their arrangement at equil. This expansion results in an increase in internal energy. With increase in elongation the mol. chains become oriented in the direction of the stress, which acts more intensely on the primary These latter are, however, so strong that the atomic displacement and increase in vol. remain extremely small. Crystn. at higher elongations decreases the entropy and internal energy. When the point of rupture is approached, i.e., when orientation of the chains is a max., the internal energy increases again, for at this point the external force is great enough to deform the primary valence angles, with resulting increase in energy and entropy. Compression decreases the energy and entropy. In general, changes in energy and entropy are very complex because of the concomitant effects of several factors, e.g., expansion against intermol. forces of adhesion, extension, and orientation of the chain mols., crystn., and deformation of the primary-valence angles.

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forces of cohesion depend greatly on the chem. nature of the elastomer; hence the change in internal energy as a function of the elongation is not the same for all elastomers, e.g., butadiene-styrene copolymers behave differently from natural rubber. The exptl. work on which the discussion and deductions are based is described. The work as a whole shows that deviations of rubberlike materials from ideal behavior at low elongations or compressions are explainable by small changes in vol. which bring about changes in internal energy and entropy. On the contrary, in shearing the behavior is ideal even at very small deformations, for shearing does not cause any change in vol. Rubber (elasticity (thermo-) of, and changes in energy and entropy from \*\*\*rearrangement\*\*\* isothermal changes in vol. and mol. Rubber (entropy and internal energy changes from isothermal changes in vol. \*\*\*rearrangement\*\*\* and mol. Cohesion (forces in rubbers at high elongations, effect on entropy and internal energy) \*\*\*Rearrangements\*\*\* (in rubber mols. under tension) Energy (internal, entropy, pressure, vol. and mol. \*\*\*rearrangements\*\*\* in rubbers in relation to) Thermodynamics (of deformations (isothermal) of rubber) \*\*\*rearrangement\*\*\* in (of isothermal change in vol. and mol. rubber under tension) Crystallization (of rubber, at high elongations, effect on entropy and internal energy) Elastic deformation (of rubber, thermodynamic equations for isothermal) ANSWER 55 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN 1938:11754 CAPLUS 32:11754 OREF 32:1679d-i,1680a-b Entered STN: 16 Dec 2001 Chemical effects accompanying hydrogen bonding. I. Acyl derivatives of the 2-hydroxy-5-methylbenzophenone oximes Blatt, A. H. Journal of the American Chemical Society (1938), 60, 205-10 CODEN: JACSAT; ISSN: 0002-7863 Journal Unavailable 10 (Organic Chemistry) It has been shown (C. A. 30, 8155.1) that the isomeric oximes of ketones such as o-HOC6H4Bz differ from each other in that 1 isomer contains a H bond between O and N while the other does not. These oximes offer the most favorable opportunity for learning by direct comparison the chem. effects due to bonding. Pyridine benzoylation furnishes the oximino benzoates. syn-Ph-2-hydroxy-5-methylphenyl ketoxime (I) benzoate (II), m. 148-9.degree.; anti-isomer (III), m. 174-5.degree.. The bonded II is hydrolyzed by NaOH to I; it is \*\*\*rearranged\*\*\* by Na2CO3 to the benzoxazole (IV) and is converted smoothly to the benzisoxazole (V) on pyrolysis. The non-bonded III is hydrolyzed to the parent oxime with NaOH or Na2CO3 and on pyrolysis gives a small quantity of IV. These results confirm and parallel the behavior of the acetates (C. A. 30, 8155.1) with the exception of the pyrolysis of the non-bonded acetate, which was reported to furnish a mixt. of IV and V; it now is believed that IV is the primary pyrolysis product and that V results from a shift of configuration which takes place on heating and which precedes pyrolysis. By the Schotten-Baumann procedure I and its isomer yield di-Bz derivs. 2-Bz deriv. (VI) of II, m. 147-8.degree.; the anti-isomer (VII) m. 132-3.degree.. VI is hydrolyzed by NaOH or Na2CO3 without

\*\*\*rearrangement\*\*\* ; Na2CO3 removes the oximino Bz group preferentially to furnish the phenolic benzoate (VIII), m. 162-3.degree.; NaOH, depending upon the concn., hydrolyzes VI to VIII or I; VIII is hydrolyzed by NaOH to I. VII is not hydrolyzed by Na2CO3 but with NaOH it gives III and then the parent oxime. VIII contains a free oximino group and with PCl5 in

\*\*\*rearrangement\*\*\*

Et20 it undergoes a Beckmann

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quantitatively O, N-dibenzoylaminocresol, m. 190-1.degree.. I with AcCl at room temp. undergoes a Beckmann \*\*\*rearrangement\*\*\* , giving IV; at the b. p., Accl gives the acetate of I, while prolonged boiling gives the di-Ac deriv. of the non-bonded oxime, also obtained from the non-bonded oxime or its acetate and AcCl either cold or at its b. p. Preferential hydrolysis of 1 Ac group could not be effected. When the non-bonded oxime or its acetate the bonded oxime or its acetate or the non-bonded oxime diacetate was treated with Ac20 and H2SO4 the product was O-acetyl-N-benzoylaminocresol. Treatment of the non-bonded oxime in C5H5N or in 20% KOH with PhSO2Cl furnishes p-cresotinic anilide; I in C5H5N gives IV but in 20% KOH the product was V; this indicates that removal even by salt formation of the H atom necessary for bonding can destroy bonding. The 2,4,6-trimethylbenzoate (IX) of I m. 149-50.degree. (1 prepn. m. 108-9.degree. but could not be prepd. again); the anti-isomer (X) m. 176-7.degree.. IX yields IV on treatment with Na2CO3 and pyrolysis furnished V; IV also resulted with NaOH; X decompd. on pyrolysis and was not affected by NaOH or Na2CO3 under conditions in which IX yielded IV; however, extended reaction of NaOH gives IV. Thus, the effect of bonding is primarily to facilitate or retard certain reactions, not to make them inevitable or impossible, and steric factors may either accentuate or \*\*\*mask\*\*\* this effect. Reactions (hydrogen bonding and) (hydrogen, between O and N, chem. effects of) Acylation (of 2-hydroxy-5-methylbenzophenone oximes) 1333-74-0, Hydrogen (bonds, between O and N, chem. effects of) 463-79-6, Carbonic acid (esters) 7727-37-9, Nitrogen (hydrogen bonding between 0 and) 7782-44-7, Oxygen (hydrogen-bond formation between N atoms and) 1470-57-1, Benzophenone, 2-hydroxy-5-methyl-(oximes, and their acyl derivs.) 7007-65-0, 1,2-Benzisoxazole, 5-methyl-3-phenyl-(prepn. of) ANSWER 56 OF 56 CAPLUS COPYRIGHT 2006 ACS on STN 1920:16445 CAPLUS 14:16445 OREF 14:3084h-i,3085a-i Entered STN: 16 Dec 2001 The union of the iron in the prosthetic group of the blood pigment and the constitution of hemin Kuster, William Ber. (1920), 53B, 623-33 Journal Unavailable 10 (Organic Chemistry) For diagram(s), see printed CA Issue. K.'s views on the constitution of hemin and on the union of the Fe to the org. part of the mol. have thus far not received general recognition (cf. Willstatter, C. A. 9, 331), but he still believes they are in better accord with the facts than those of W. In his opinion, the union of Fe in hemin is related with the unsatd. groupings, not of the side chain, but those which condition the color of the porphyrins; it is the chloroferric group which in mesohemin and still more in hemin \*\*\*masks\*\*\* properties of mesoporphyrin and the appearance of basic properties in the formation of the latter is not due to a mol. \*\*\*rearrangement\*\*\* resulting in the production of basic pyrrolene nuclei; all the evidence indicates that the pyrrole nuclei in hemin are substituted in each of their .alpha.-positions, which can be true only if they are united through 4 methin groups. K. does not maintain that his views are correct all the way through, but for the time being they are the best available. The "relations between the acid and basic groups of the hemin mol.," which he

has always maintained as being "present," have been further developed. Hematoporphyrin diethyl ether (A), prepd. like the di-Me compd. (C. A. 9, 2882) a brick-red cryst. powder without m. p., sol. in 5% soda at room temp., takes up 3 mols. NH3 in H2O, forms, trisilver salt. seps. from N

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HCl in vacuo over H2SO4 as the dihydrochloride (B), strongly hygroscopic druses of needles decompd. by H2O. That a betaine union can occur is shown by the fact that when this ether is boiled 0.5 hr. under a reflux in 1% alc. HCl, pptd. with NaOAc, taken up in Et2O, shaken with soda, dried and concd., there is obtained an isomer, bundles of needles, insol. in 12% NaOH at room temp. but sol. on warming; 0.4 g. dissolved in 5 cc. of N HCl only after 5 days and on long standing in vacuo over H2SO4 gave 0.26 g. of In cold EtOH with HCl, on the other hand, A gives the diethyl ester (tetraethylhematoporphyrin), steel-blue powder insol. in 12% NaOH at room temp., sepg. from Et20 in granular cryst. aggregates. Expts. with CH2N2 (C. A. 12, 1471) had already shown the existence of a relationship between the CO2H and chloroferric groups of hemin, for while porphyrins are easily esterified, .alpha.-hemins are esterified to only a slight extent and in .beta.-hemins only one CO2H group is esterified; moreover, the halogen is never removed by CH2N2, while it has now been found that the HCl salts of Ph3CH dyes lose HCl thus, 1 g. crystal violet in 100 cc. Me2CO with the CH2N2 from 2.5 cc. ONNMeCO2Et gives MeCl and 0.8 g. of the leuco base, m. 173-4.degree.. Contrary to the views expressed by K. in 1912, therefore, there is no relation between the Cl and the N of hemin, but the relations between the Fe and the N are different from those assumed by W. While the union of the Cl to the Fe is made highly probable by the above expt., it is rendered certain by the results of cond. detns. in C5H5N at 25.degree. on .alpha.-hemin (.mu. 6.7127, 9.4233, 14.0932, 19.4134 for v 208.48, 416.96, 833.92, 1667.4) and its di-Me ester (.mu. 5.2338, 7.4103, 3.0094 for v 217.44, 434.88, 869.74, resp.); i. e., they behave like inorg. salts so that the CO2H groups take no part in the cond. of hemin. Hemin may therefore be formulated with an ionogenic Cl atom, [C34H32O4N4Fe]Cl, and the Fe in the "cationogen," which explains the relations between hemin and "hematin," which forms a sol. Na salt in which the Fe is in the anion. In the change hemin. .fwdarw. hematin, the Cl is first replaced by OH, with formation of hydroxyhemin, which is not further affected by weak bases (a soln. of hemin in C5H5N poured into dil. AcOH yields a substance which can be reconverted into hemin; the component of methemoglobin is also to be considered as this hydroxyhemin, not as hematin, for the "hematin" remaining after digestion of the globin can likewise be converted into hemin). Strong alkalies, however, effect the transformation into hematin; as an intermediate product is formed the Fe salt of a CO2H acid which, taking up NaOH, e. g., gives off a Na ion while the Fe remains in the anion; the Fe detaches itself from one of the N atoms and is replaced by the H of the OH while the remainder combines with the Fe: On acidification, the hematin is pptd. with elimination of H2O, which may occur in different ways so that the product is not homogeneous. Blood pigments

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(prosthetic group of, union of Fe in)

IT Hematoporphyrin, tetraethyl-

861365-73-3, Hematoporphyrin, diethyl ether

(and derivs. and isomer)

16009-13-5, Hemin

(constitution of)

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AB Lighting lenses and refractors used on HID (high intensity discharge) fixtures are exposed to elevated temps. and high levels of UV light. The

UV irradn. combined with the elevated temp. often causes resin degrdn. in these lenses and refractors, resulting in discoloration and the loss of their ductility. In many cases, it is desirable that the refractors are resistant to breakage can come from either accidental impact from such objects as broom handles, malicious impacts as in the case of stones from vandals or from impacts from gunshots. We have developed resin for refractor products that provide improved resistances to UV light while at the same time maintain high levels of impact strength. SOLLX resin UV resistance lens refractor fluorescent tube Pipes and Tubes (fluorescent; high performance lenses/HID refractors and fluorescent tubes from SOLLX TM resins) Light-resistant materials (high performance lenses/HID refractors and fluorescent tubes from SOLLX TM resins) \*\*\*497883-23-5\*\*\* , SOLLX RL: TEM (Technical or engineered material use); USES (Uses) (high performance lenses/HID refractors and fluorescent tubes from SOLLX TM resins) ANSWER 2 OF 2 CAPLUS COPYRIGHT 2006 ACS on STN 2002:647927 CAPLUS 138:171195 Entered STN: 28 Aug 2002 Zero VOC SOLLX film for weatherable, high-gloss, chemical and scratch resistant performance Brister, Elizabeth; Johnson, Robert; Myers, Randall; Saggese, Luca; Schuering, Kurt; Wang, Hua Plastics Technology Division, General Electric Company, Mt. Vernon, IN, 47620, USA Proceedings of the International Waterborne, High-Solids, and Powder Coatings Symposium (2002), 29th, 261-275 CODEN: PIWCF4 University of Southern Mississippi, Dep. of Polymer Science Journal English 38-3 (Plastics Fabrication and Uses) GE Plastics has developed a polymeric film (SOLLX) as part of its pursuit to provide a truly weatherable polymer system that offers paint-like appearance in a wide variety of metallic colors with Class A finish and exterior application, durability, esp. applicable in automotive exterior panels and trim. SOLLX film with its unique property combination can be applied over a wide range of substrates to yield a Class A finish that offers high-gloss, weatherability, scratch and chem. resistance, and high surface quality without the need for paint. film polycarbonate high gloss scratch resistant insert molding automobile Plastic films (SOLLX film for weatherable, high-gloss, chem. and scratch-resistant performance) Automobiles (bodies; SOLLX film for weatherable, high-gloss, chem. and scratch-resistant performance) Molding of plastics and rubbers (double-shot; SOLLX film for weatherable, high-gloss, chem. and scratch-resistant performance) Polyesters, uses RL: TEM (Technical or engineered material use); USES (Uses)

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\*\*\*497883-23-5\*\*\* , Sollx

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